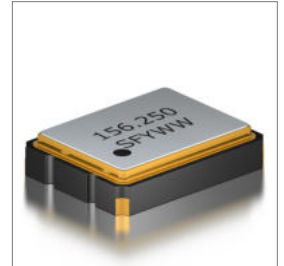


Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Low Current Consumption
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express



Part Numbering Guide

SLO 32 L 3 A 48 1 - 156.250M

SUNTSU LOW CURRENT OSC
3.2mm x 2.5mm

LVDS

SUPPLY VOLTAGE
1 : 1.8V \pm 5%
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

FREQUENCY MHz

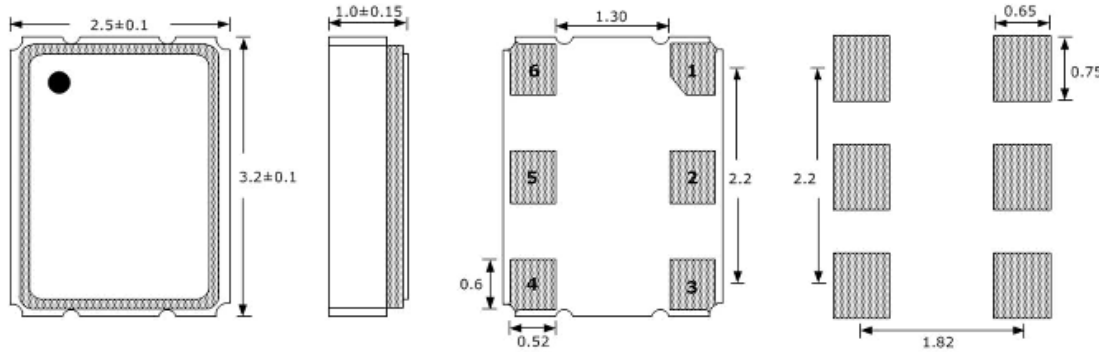
TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	135~175MHz(1.8V), 100~320MHz(2.5&3.3V)
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V Option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA		15	20	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	350	454	
Differential Output Error (pV _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (pV _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns		0.25	0.5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5.0	
Phase Jitter (12kHz ~ 20MHz)	fs		120	150	

Outline Drawing & Land Pattern

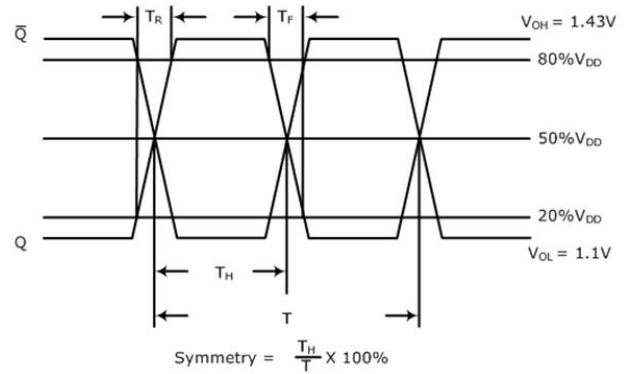
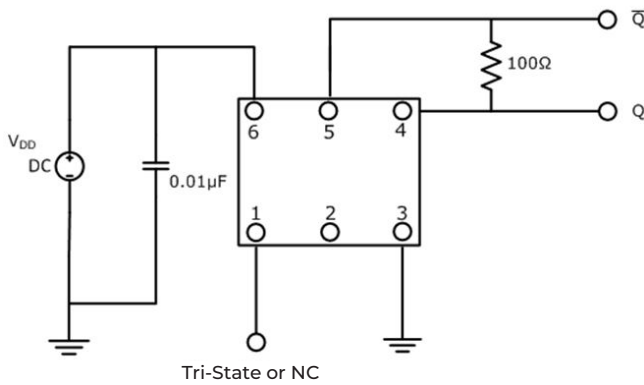
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



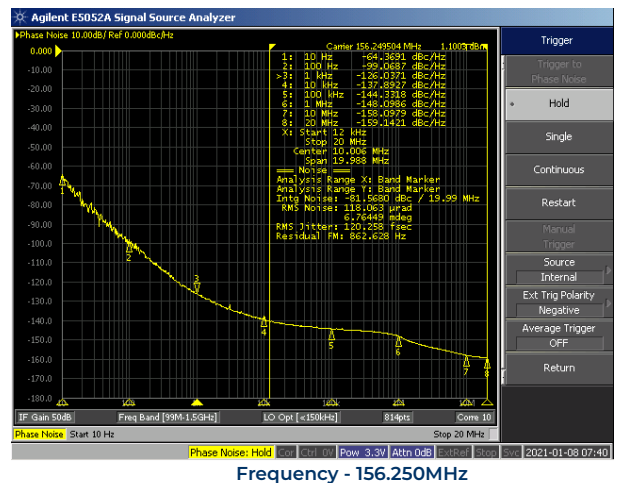
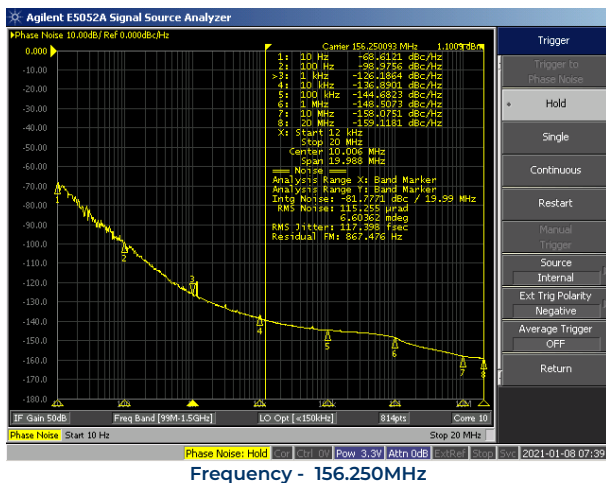
PIN	FUNCTION
1	TRI-STATE or NC
2	NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVDS)

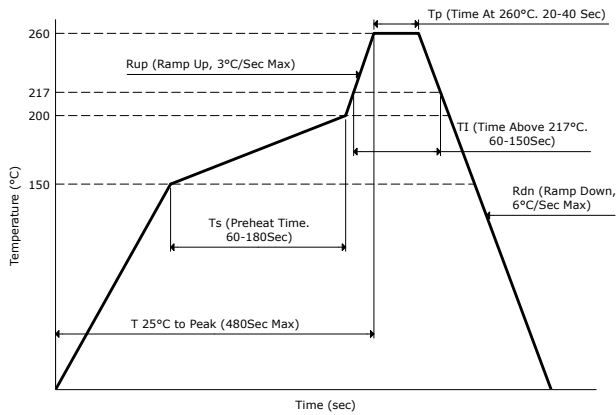
Waveform (LVDS)



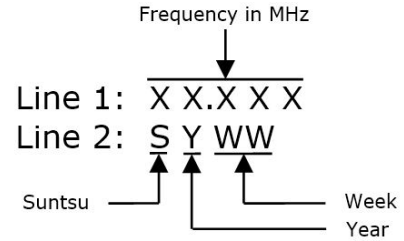
Typical Phase Noise Performance (Measured By Agilent E5052A)



Reflow Profile



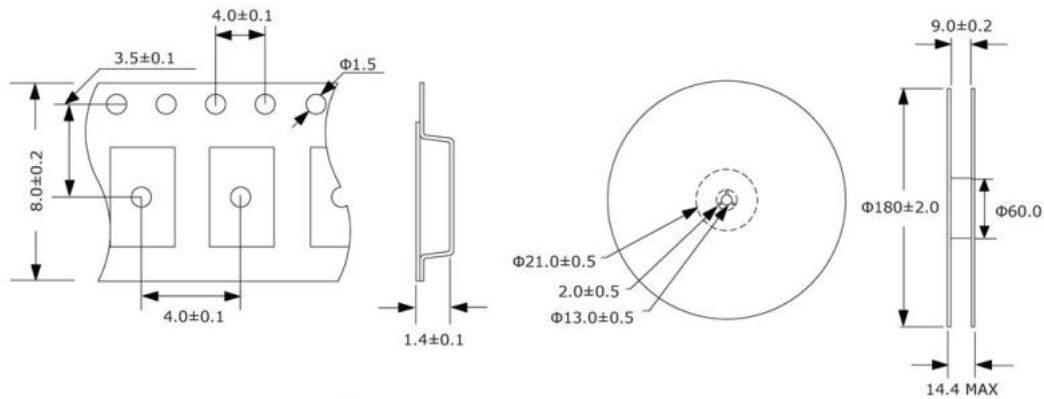
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

3,000pcs/Reel



Environmental Specifications

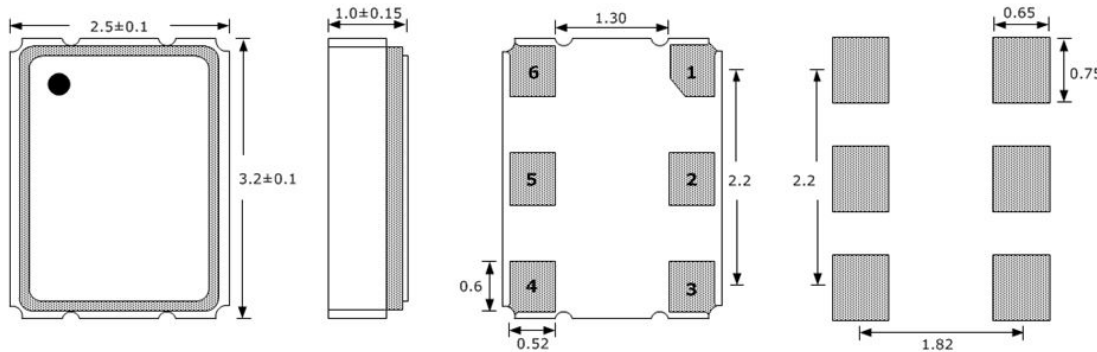
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Outline Drawing & Land Pattern

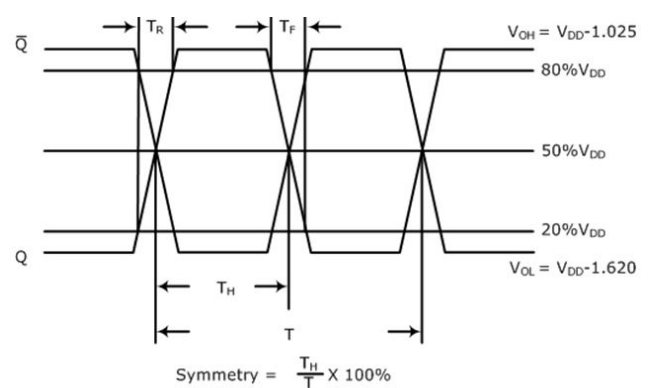
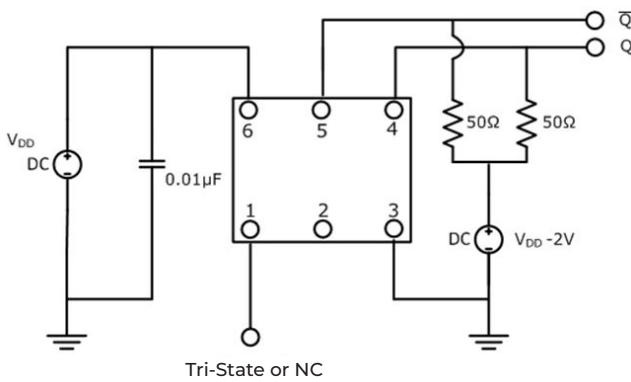
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



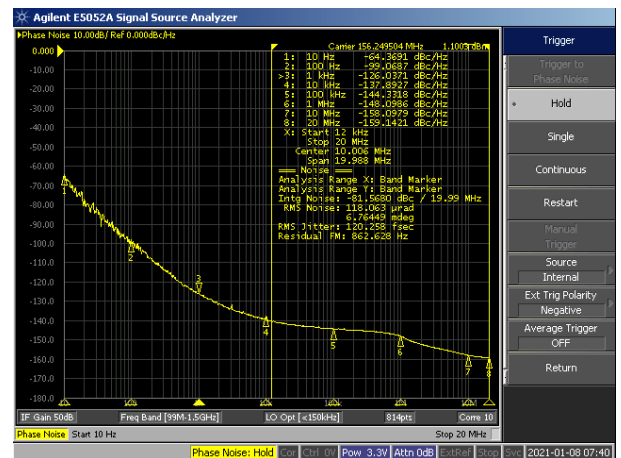
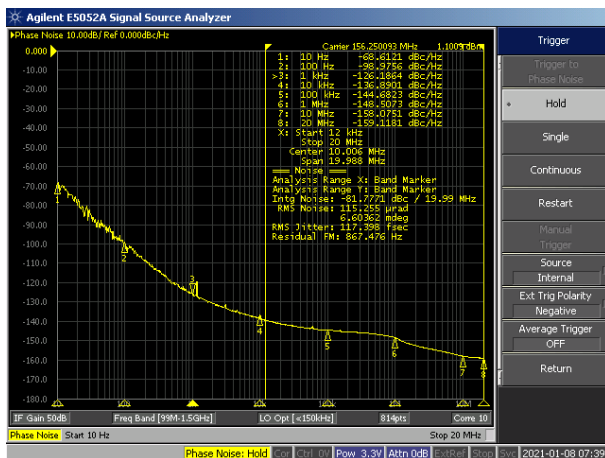
PIN	FUNCTION
1	TRI-STATE or NC
2	NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVPECL)

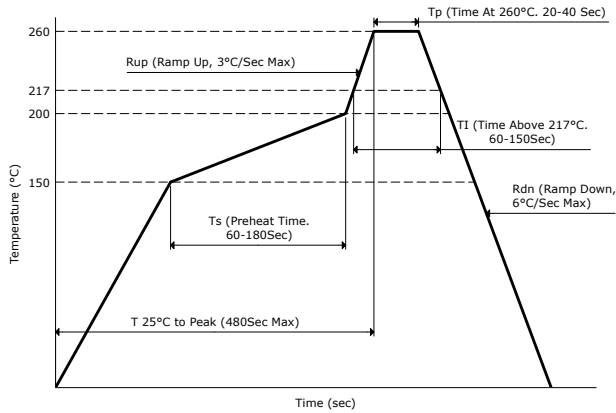
Waveform (LVPECL)



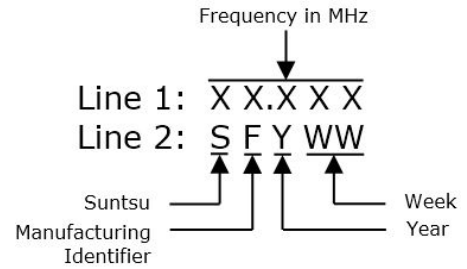
Typical Phase Noise Performance (Measured By Agilent E5052A)



Reflow Profile



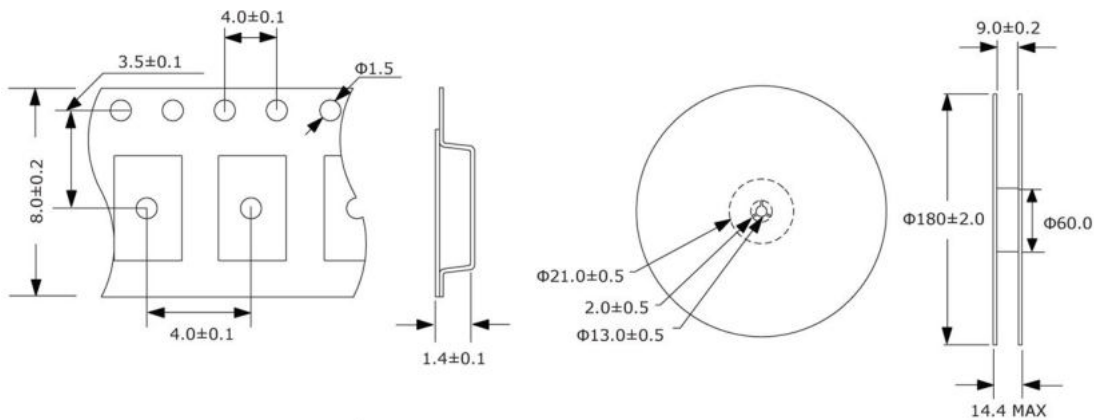
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

3,000pcs/Reel



Environmental Specifications

Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Low Current Consumption
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express



Part Numbering Guide

SLO 53 L 3 A 48 1 - 156.250M

SUNTSU LOW CURRENT OSC
5.0mm x 3.2mm

LVDS

SUPPLY VOLTAGE
1 : 1.8V \pm 5%
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

FREQUENCY MHz
TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

RoHS COMPLIANT

Cage Code : 4GUT4

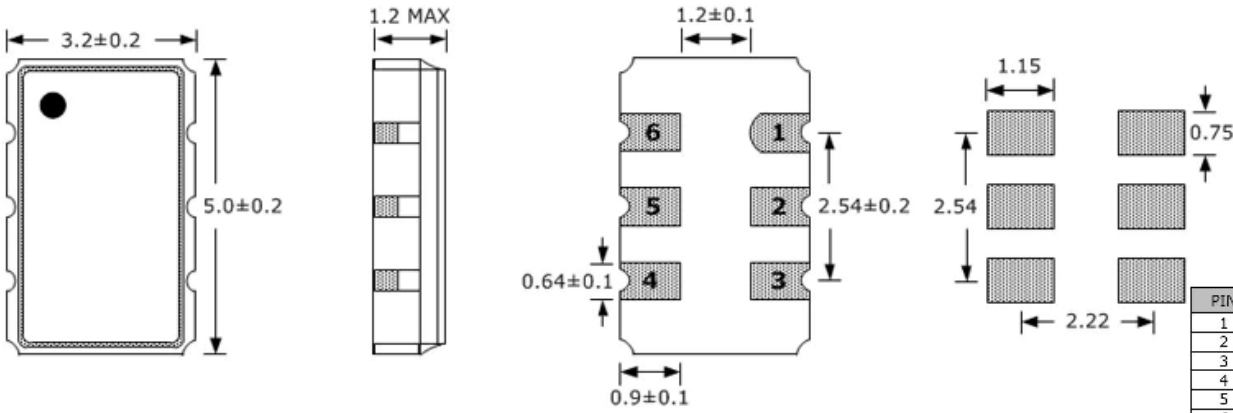
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	135~175MHz(1.8V), 100~320MHz(2.5&3.3V)
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V Option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA		15	20	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	350	454	
Differential Output Error (ρ V _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (ρ V _{OS})	mV	-50		50	
Rise (TR) and Fall (TF) Time	ns		0.25	0.5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5.0	
Phase Jitter (12kHz ~ 20MHz)	fs		120	150	

Outline Drawing & Land Pattern

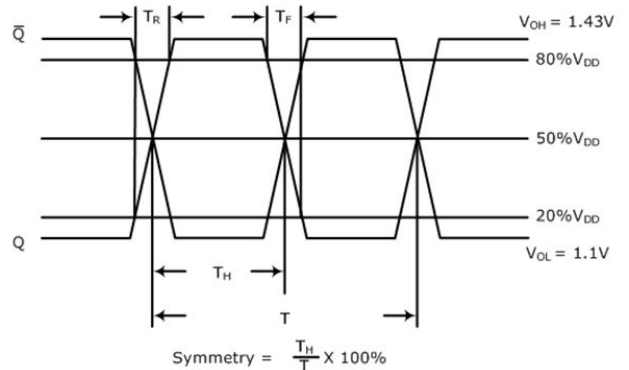
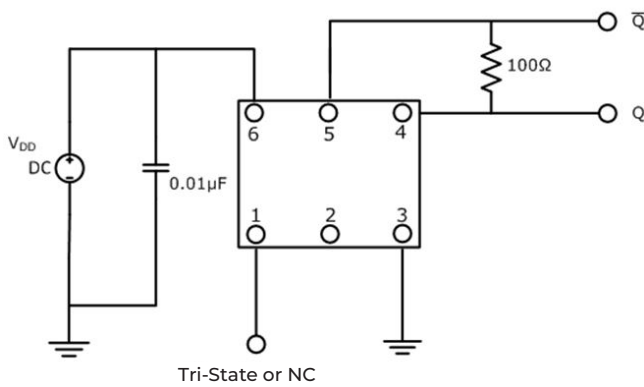
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



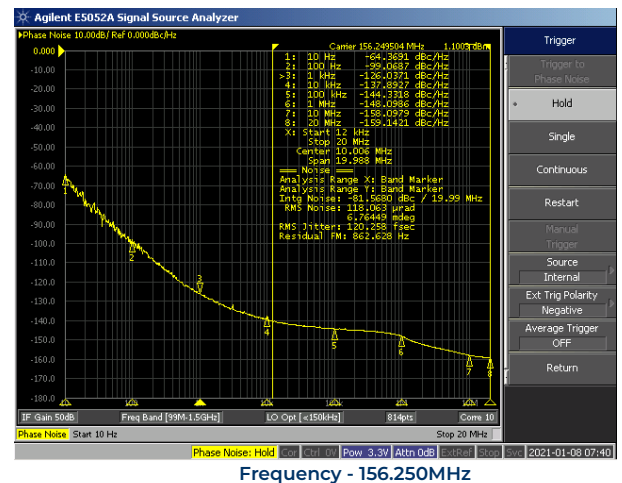
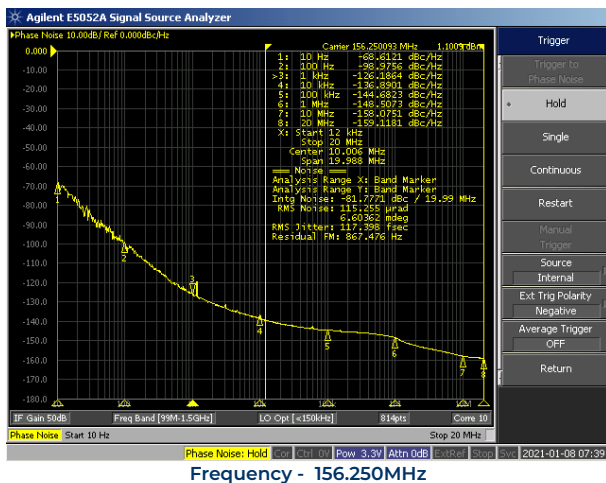
PIN	FUNCTION
1	TRI-STATE or NC
2	NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVDS)

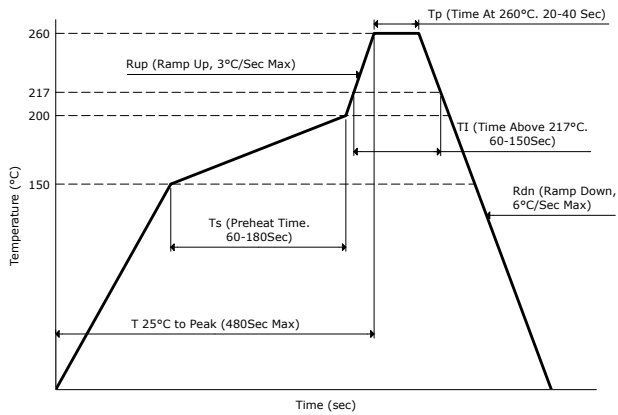
Waveform (LVDS)



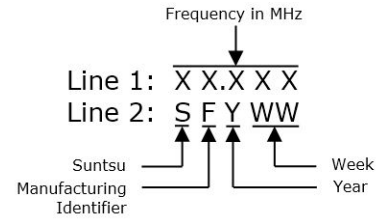
Typical Phase Noise Performance (Measured By Agilent E5052A)



Reflow Profile



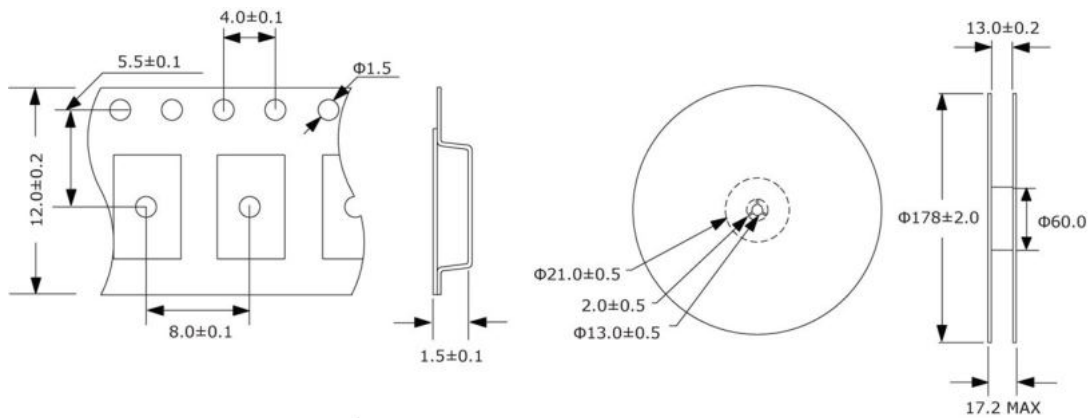
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

1,000pcs/Reel



Environmental Specifications

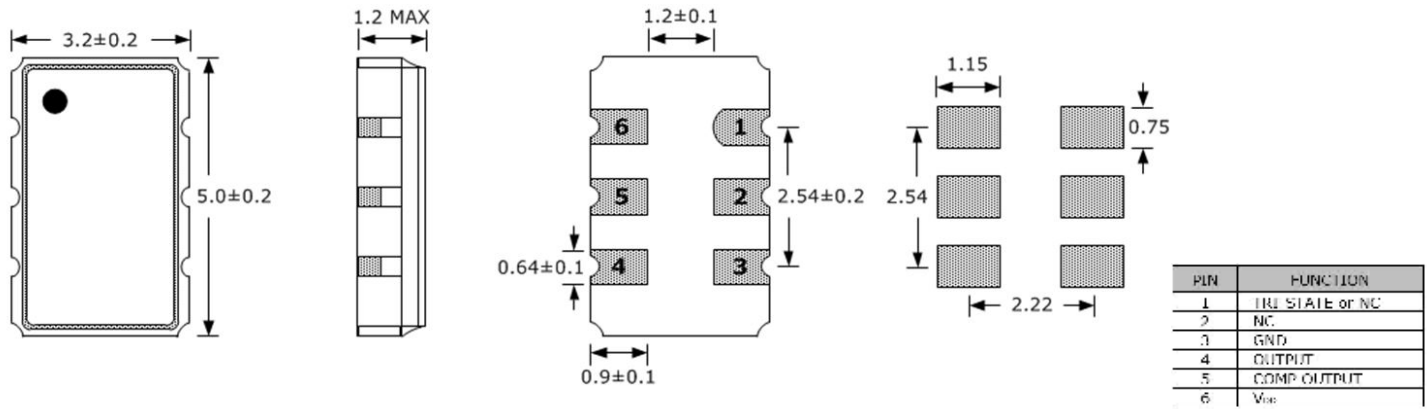
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

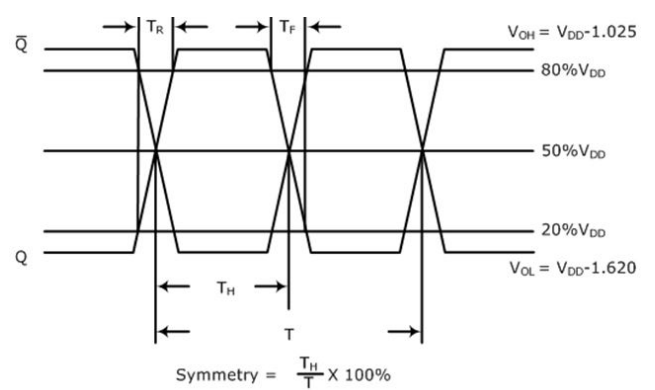
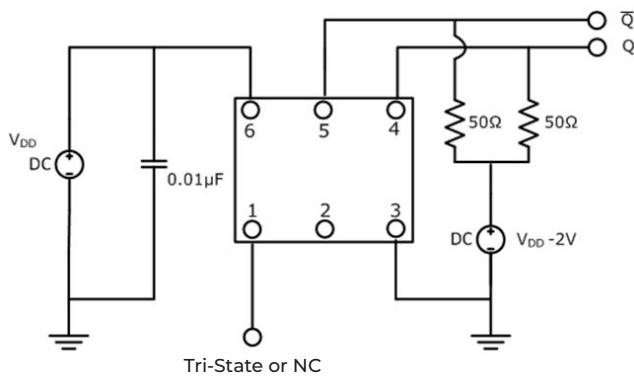
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

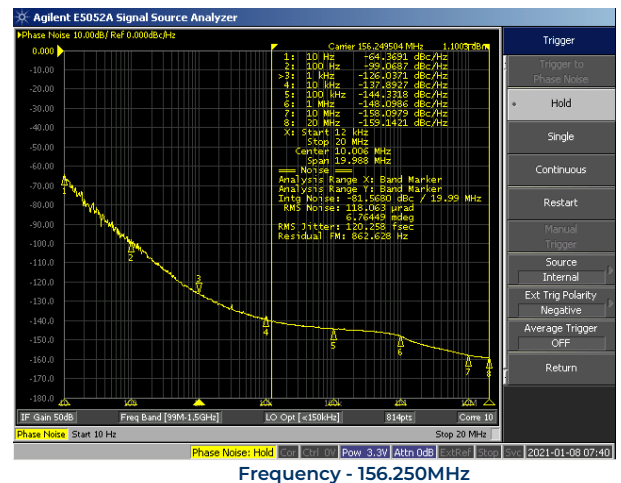
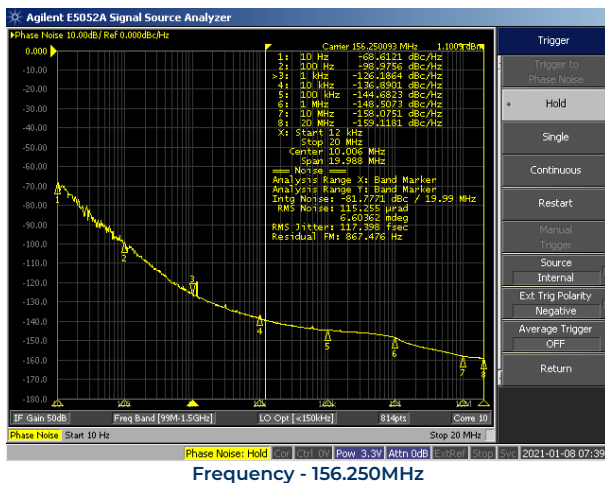


Test Circuit (LVPECL)

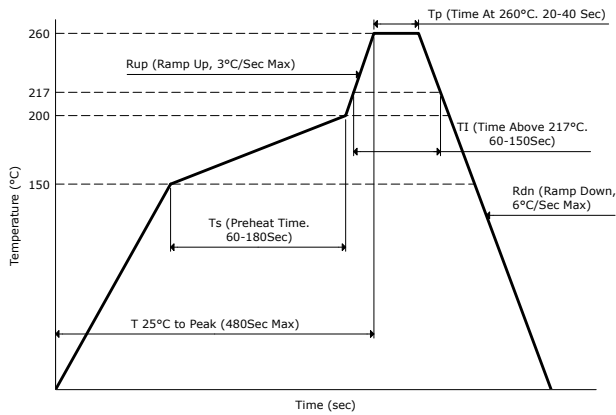
Waveform (LVPECL)



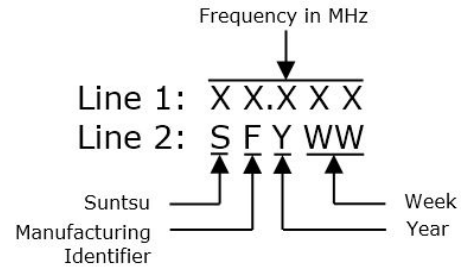
Typical Phase Noise Performance (Measured By Agilent E5052A)



Reflow Profile



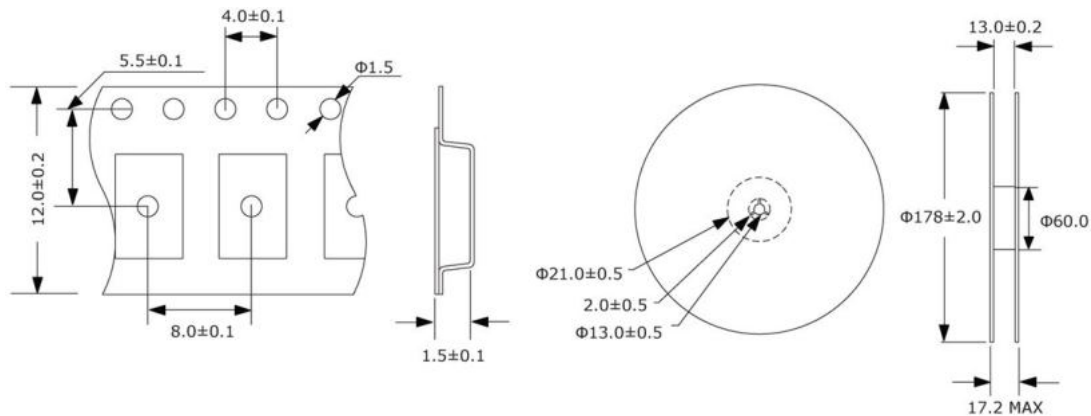
Part Marking



Tape And Reel Dimensions

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1,000pcs/Reel



Environmental Specifications

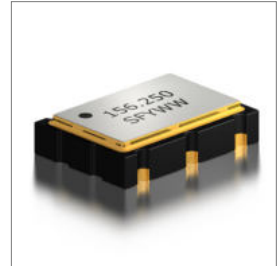
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
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Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Low Current Consumption
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express



Part Numbering Guide

SLO 75 L 3 A 48 1 - 156.250M

SUNTSU LOW CURRENT OSC
7.0mm x 5.0mm

LVDS

SUPPLY VOLTAGE
1 : 1.8V \pm 5%
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY
MHz

TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

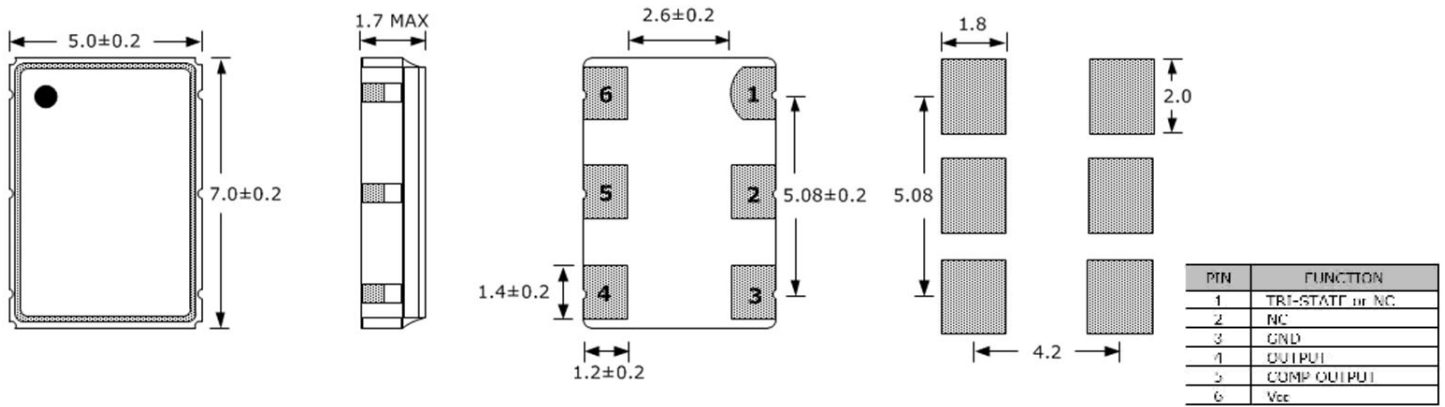
FREQUENCY STABILITY
A : ± 50 ppm
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*D : ± 20 ppm

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range*	MHz	100		320	135~175MHz(1.8V), 100~320MHz(2.5&3.3V)
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V Option	V	1.710	1.8	1.890	
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Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
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Output Load (LVDS)	Ω			100	
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Output Logic Levels Low (V _{OL})	V	0.9	1.1		
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Differential Output Error (Δ V _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (Δ V _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns		0.25	0.5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5.0	
Phase Jitter (12kHz ~ 20MHz)	fs		120	150	

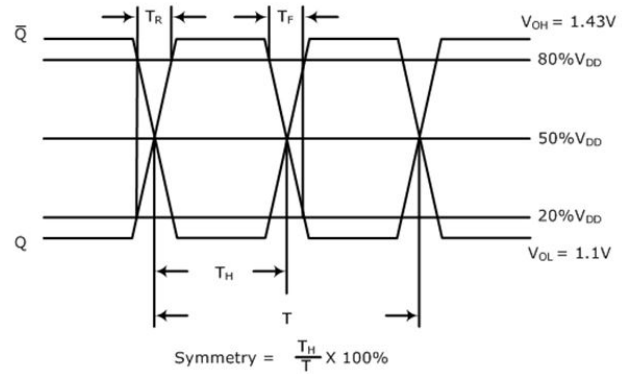
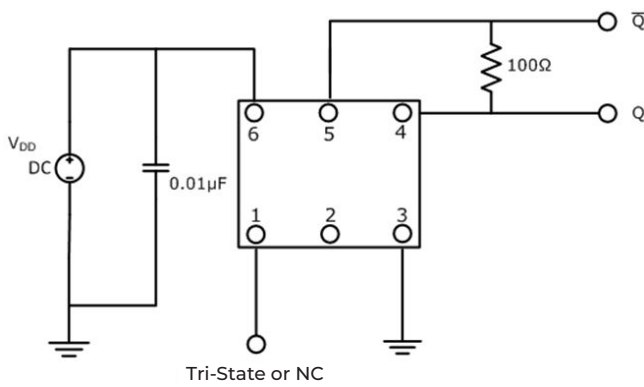
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

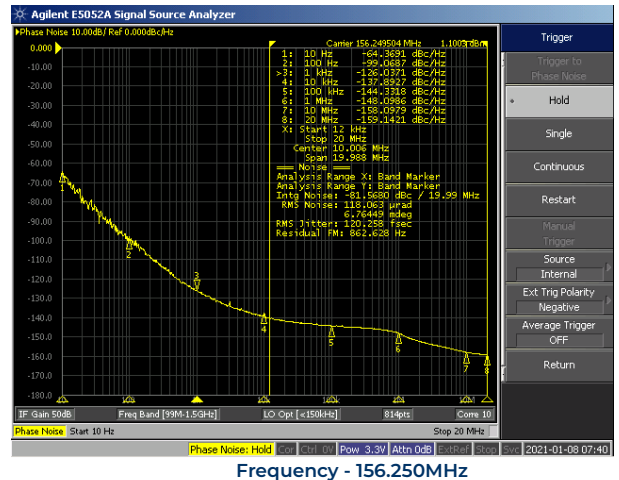
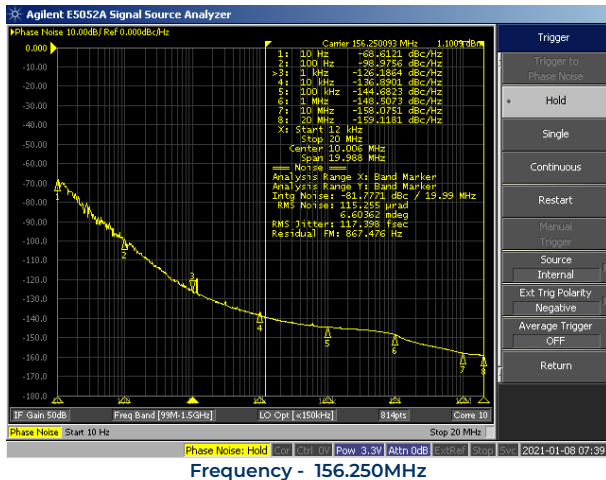


Test Circuit (LVDS)

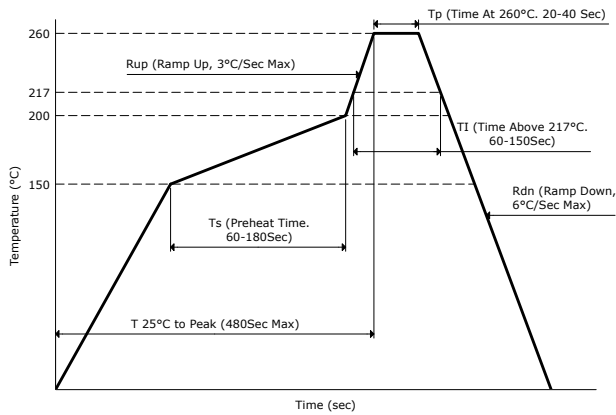
Waveform (LVDS)



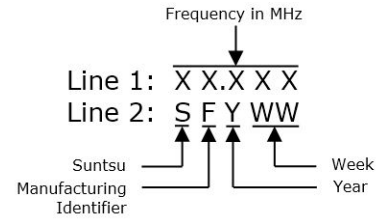
Typical Phase Noise Performance (Measured By Agilent E5052A)



Reflow Profile



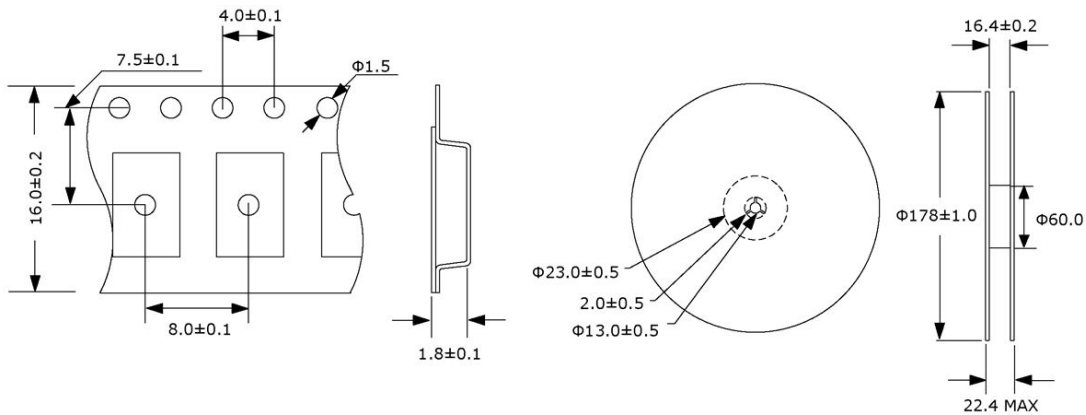
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

1,000pcs/Reel



Environmental Specifications

Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVPECL
• Low Current Consumption
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express



Part Numbering Guide

SLO 75 P 3 A 48 1 - 156.250M

<p>SUNTSU LOW CURRENT OSC 7.0mm x 5.0mm</p> <p>LVPECL</p> <p>SUPPLY VOLTAGE 2: 2.5V\pm5% 3: 3.3V\pm5%</p>	<p>FREQUENCY STABILITY A: ± 50ppm B: ± 30ppm C: ± 25ppm *D: ± 20ppm</p>	<p>FREQUENCY MHz</p> <p>TRI-STATE (ENABLE/DISABLE) BLANK: No Connection 1: Pin 1</p> <p>OPERATING TEMPERATURE RANGE 07: 0°C - +70°C 16: -10°C - +60°C 17: -10°C - +70°C 27: -20°C - +70°C 38: -30°C - +85°C 48: -40°C - +85°C</p>
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RoHS COMPLIANT

Cage Code : 4GUT4

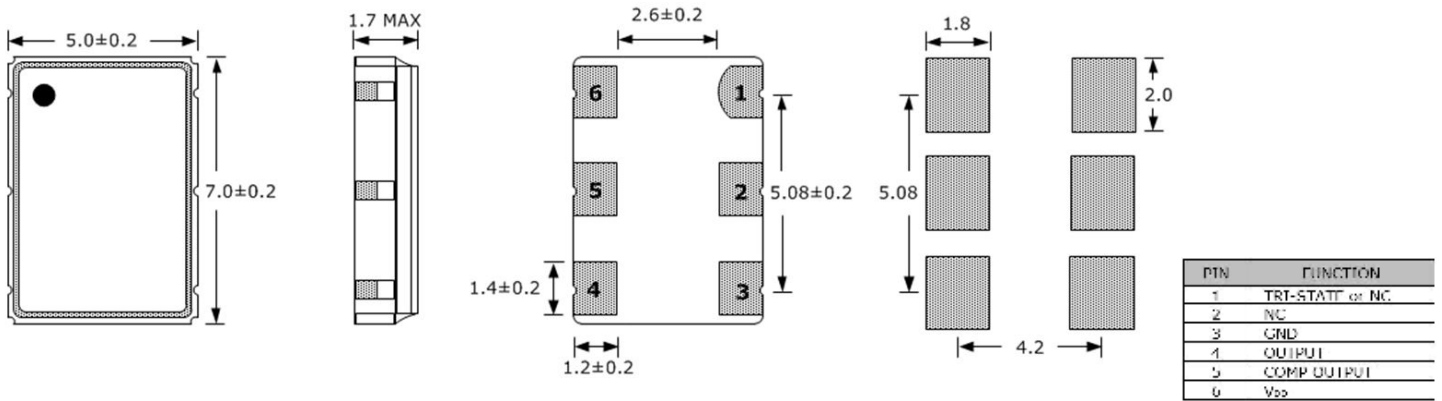
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

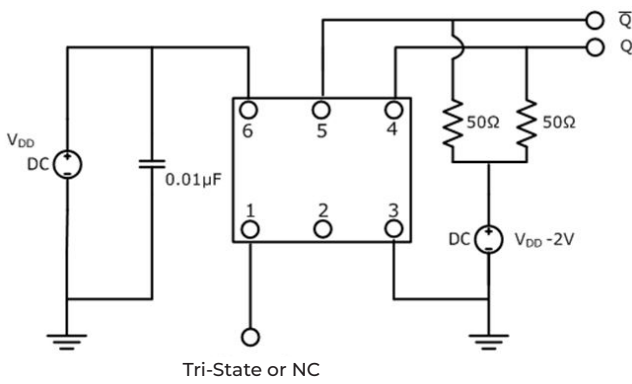
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA			50	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0Vdc
Output Logic Levels High (V _{OH} at 2.5V)	V	1.415		1.760	
Output Logic Levels Low (V _{OL} at 2.5V)	V	0.670		1.195	
Output Logic Levels High (V _{OH} at 3.3V)	V	2.215		2.420	
Output Logic Levels Low (V _{OL} at 3.3V)	V	1.470		1.745	
Rise (TR) and Fall (TF) Time	ns		0.15	0.3	Measured at 20% to 80% of Waveform
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5	
Phase Jitter (12kHz ~ 20MHz)	fs		120	150	

Outline Drawing & Land Pattern

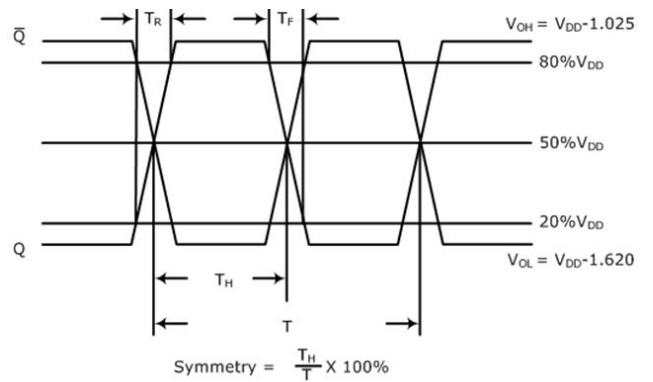
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



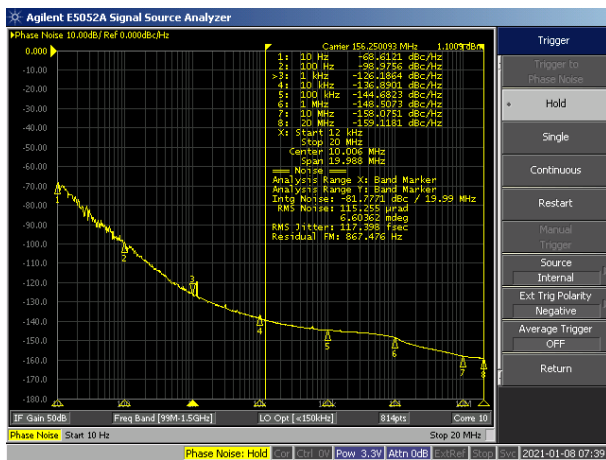
Test Circuit (LVPECL)



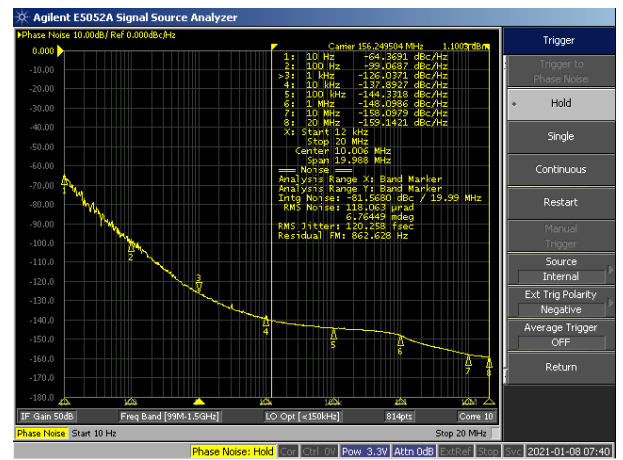
Waveform (LVPECL)



Typical Phase Noise Performance (Measured By Agilent E5052A)

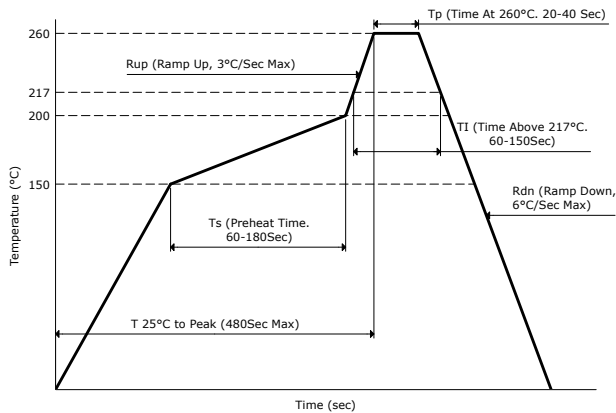


Frequency - 156.250MHz

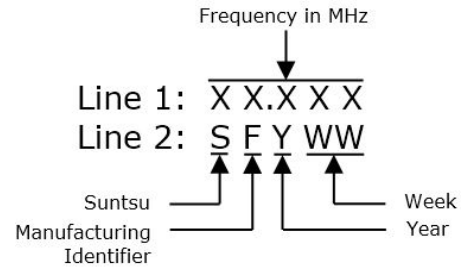


Frequency - 156.250MHz

Reflow Profile



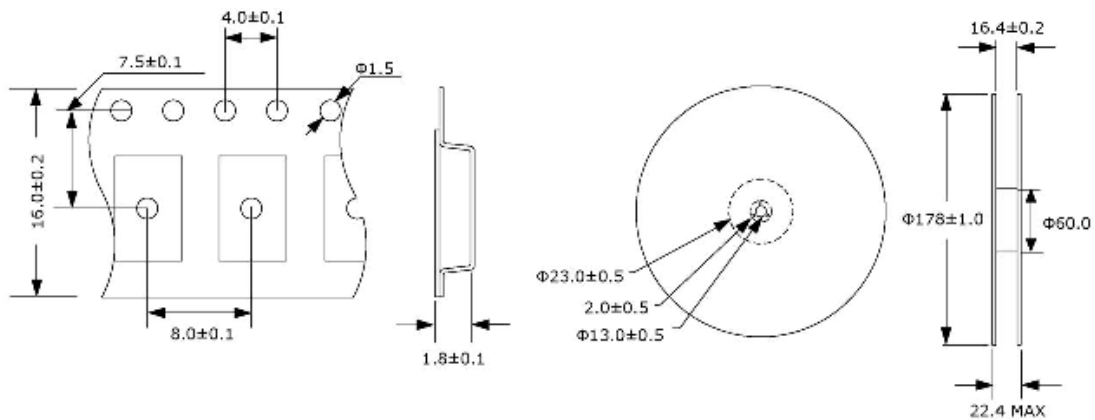
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

1,000pcs/Reel



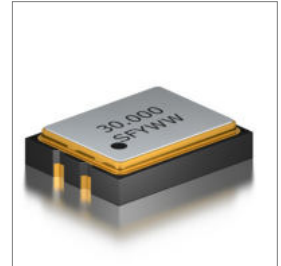
Environmental Specifications

Mechanical Specifications

Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 25 ppm (Frequency Stability) Available
• Ceramic Package 4 Pad
• CMOS
• Programmed Oscillator
• Tape and Reel

Applications
• Micro Processors
• FPGA
• Storage Area/Networking
• Digital Video
• Portable Computers



Part Numbering Guide

SQC 32 C 3 A 48 1 - 30.000M

SUNTSU QUICK TURN OSC

3.2mm x 2.5mm

CMOS

SUPPLY VOLTAGE

3 : 3.3V \pm 5%

5 : 5.0V \pm 5%

FREQUENCY STABILITY

A : ± 50 ppm

B : ± 30 ppm

C : ± 25 ppm

*D : ± 20 ppm

OPERATING TEMPERATURE RANGE

07 : 0°C - +70°C

16 : -10°C - +60°C

17 : -10°C - +70°C

27 : -20°C - +70°C

38 : -30°C - +85°C


48 : -40°C - +85°C

FREQUENCY MHz

TRI-STATE (ENABLE/DISABLE)

BLANK: No Connection

1: Pin 1



Cage Code : 4GUT4

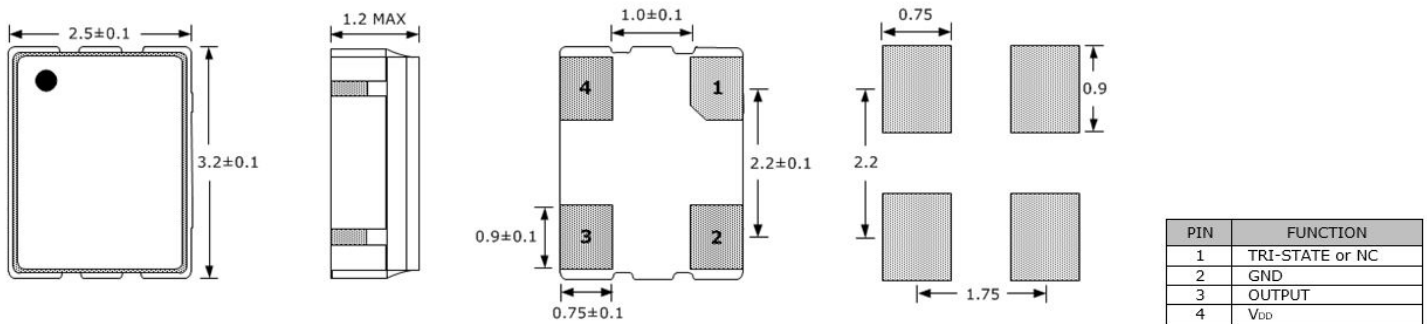
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	1		133	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.750	5.0	5.250	
Current (I _{DD}) - 3.3V option	mA			25	
Current (I _{DD}) - 5.0V option	mA			45	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			4	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage(3.3V) - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage(3.3V) - Disable	V			0.3*V _{DD}	
Tri-State Input Voltage(5.0V) - Enable	V	2.0			No Connection
Tri-State Input Voltage(5.0V) - Disable	V			0.8	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			11	

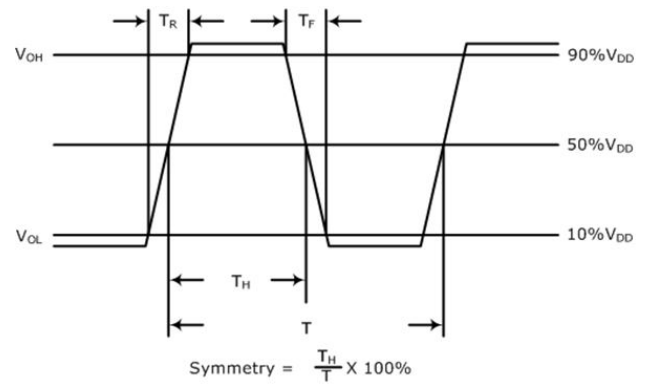
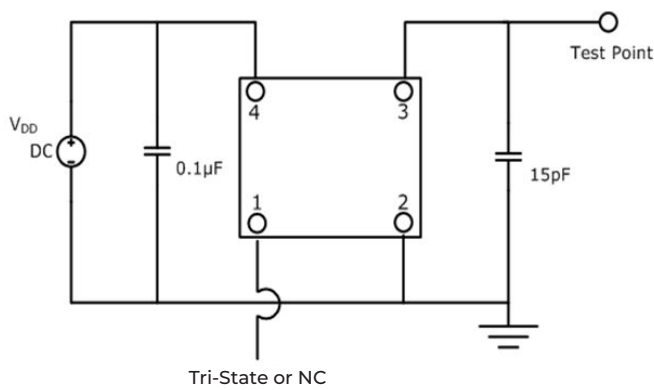
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

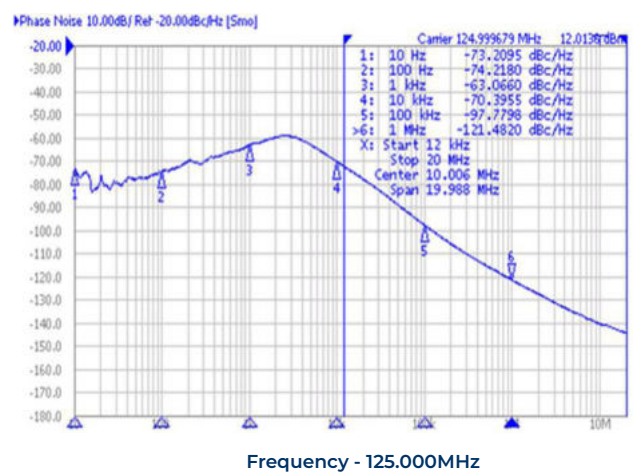
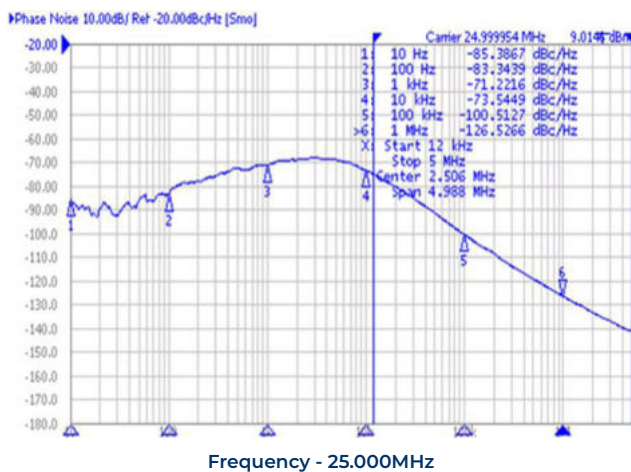


Test Circuit (CMOS)

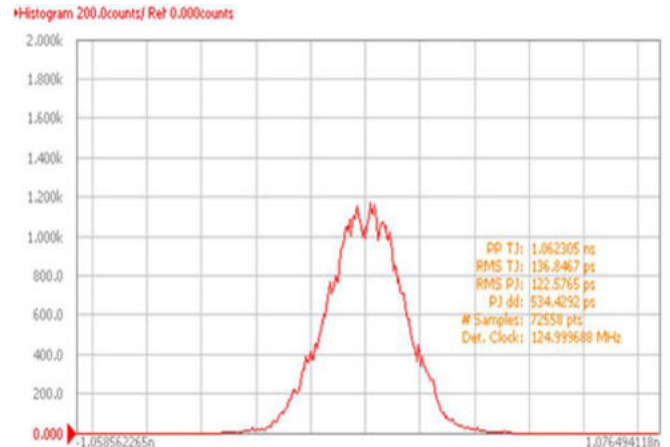
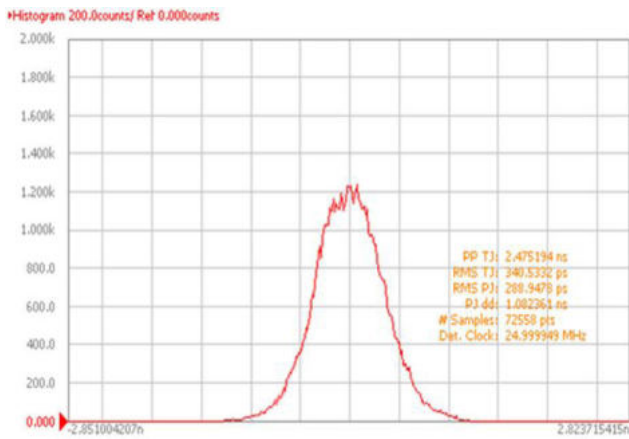
Waveform (CMOS)



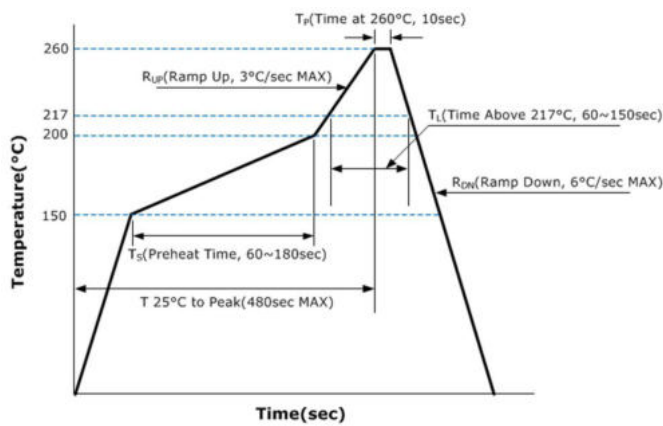
Typical Phase Noise Performance (Measured By Agilent E5052A)



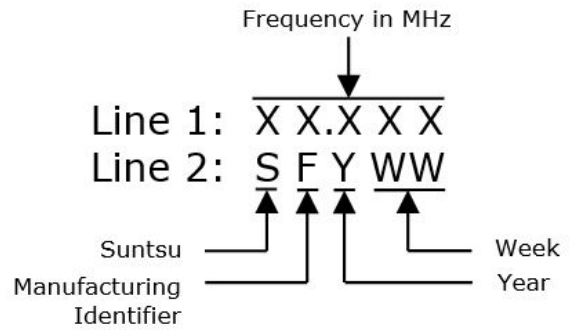
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



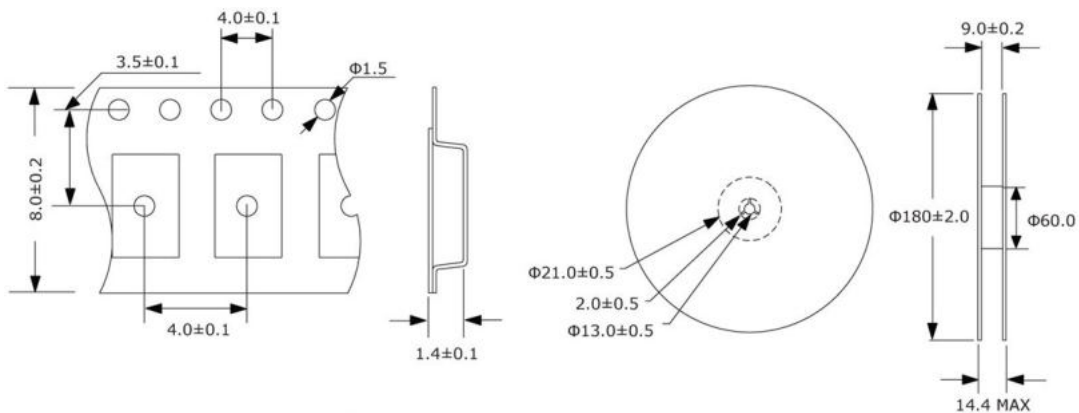
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

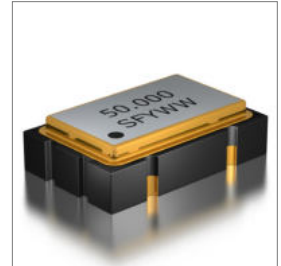
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> • ± 25ppm (Frequency Stability) Available • Ceramic Package 4 Pad • CMOS • Programmed Oscillator • Tape and Reel

Applications
<ul style="list-style-type: none"> • Micro Processors • FPGA • Storage Area/Networking • Digital Video • Portable Computers



Part Numbering Guide

SQC 53 C 3 A 48 1 - 50.000M

SUNTSU QUICK TURN OSC
5.0mm x 3.2mm

CMOS


SUPPLY VOLTAGE
3 : 3.3V \pm 5%
5 : 5.0V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

FREQUENCY
MHz

TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

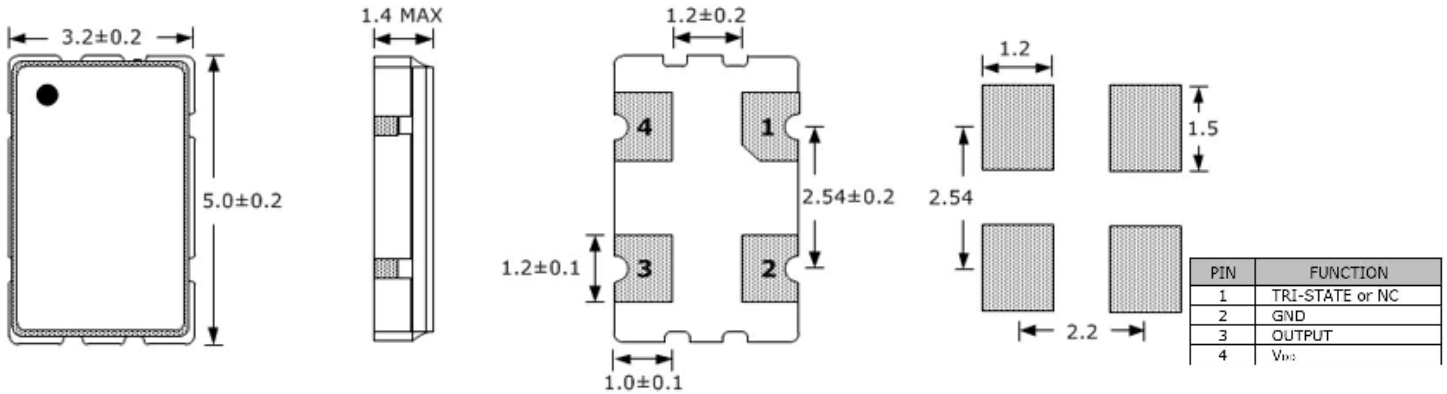


Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	1		133	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.750	5.0	5.250	
Current (I _{DD}) - 3.3V option	mA			25	
Current (I _{DD}) - 5.0V option	mA			45	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			4	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage(3.3V) - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage(3.3V) - Disable	V			0.3*V _{DD}	
Tri-State Input Voltage(5.0V) - Enable	V	2.0			No Connection
Tri-State Input Voltage(5.0V) - Disable	V			0.8	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			11	

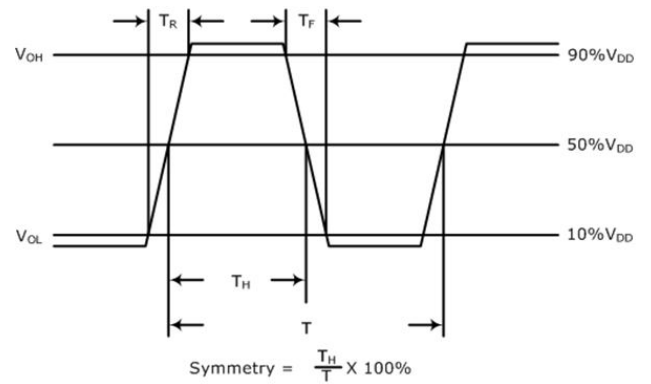
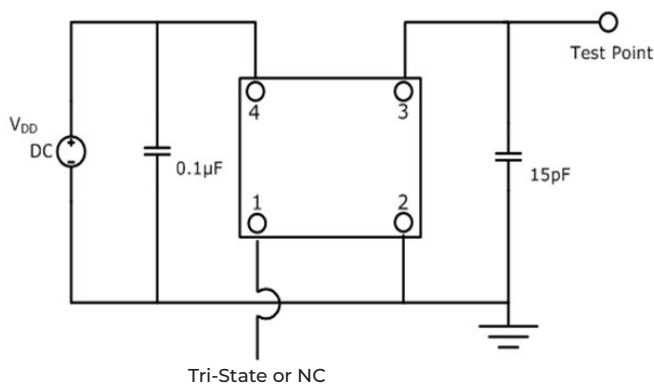
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

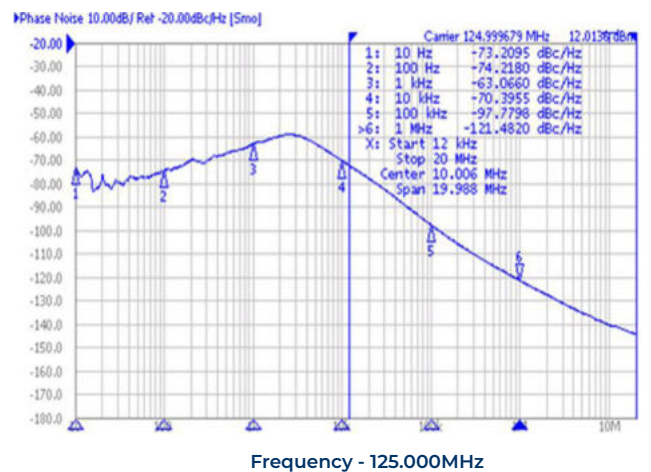
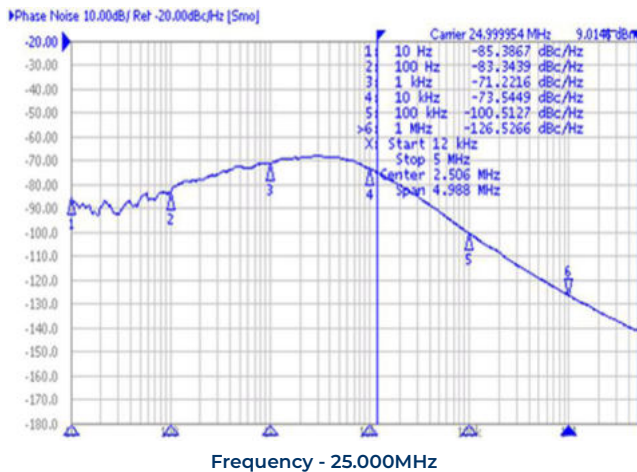


Test Circuit (CMOS)

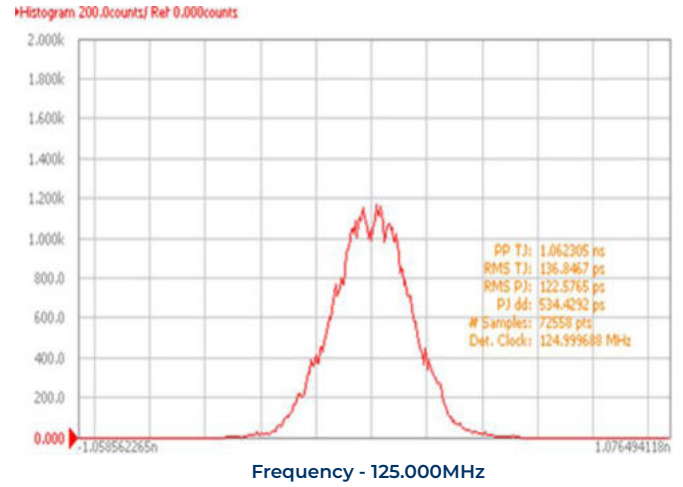
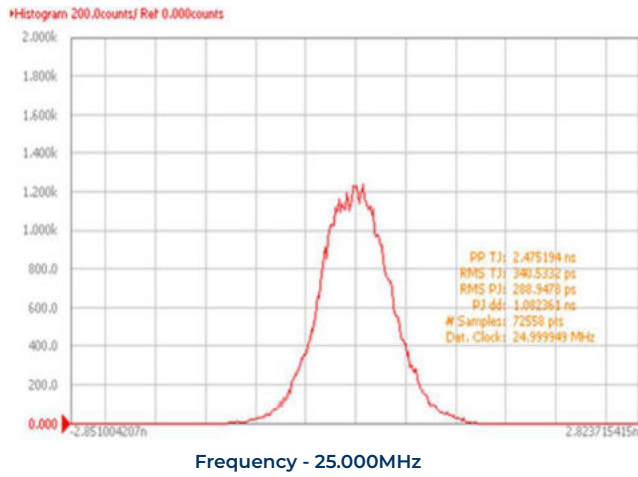
Waveform (CMOS)



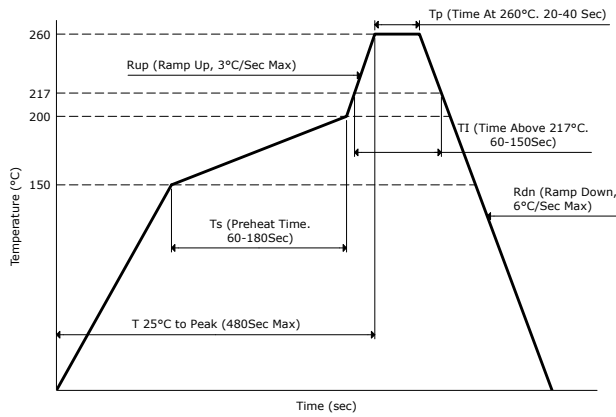
Typical Phase Noise Performance (Measured By Agilent E5052A)



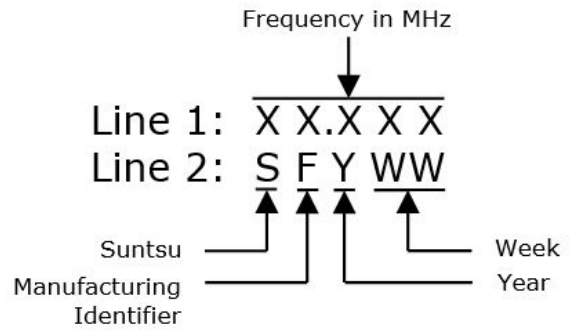
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



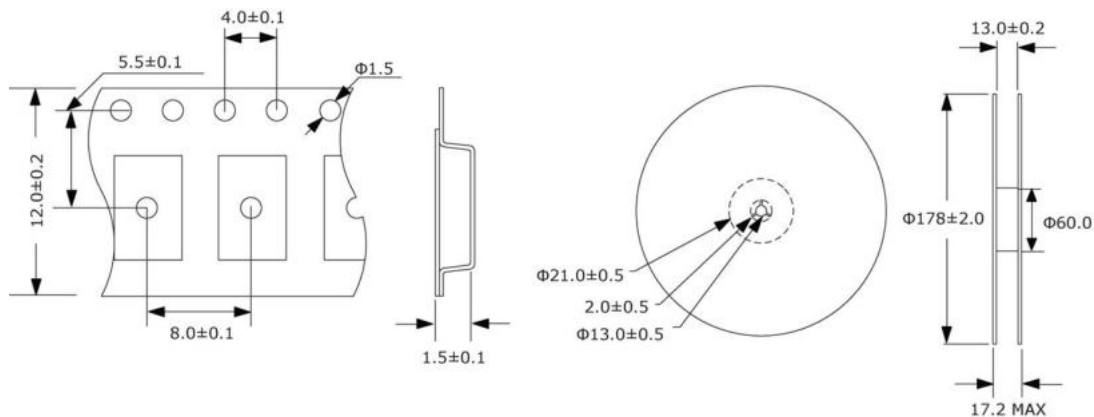
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

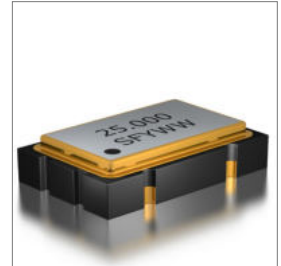
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 25 ppm (Frequency Stability) Available
• Ceramic Package 4 Pad
• CMOS
• Programmed Oscillator
• Tape and Reel

Applications
• Micro Processors
• FPGA
• Storage Area/Networking
• Digital Video
• Portable Computers



Part Numbering Guide

SQC 75 C 3 A 48 1 - 25.000M

SUNTSU QUICK TURN OSC

7.0mm x 5.0mm

CMOS

SUPPLY VOLTAGE
3 : 3.3V $\pm 5\%$
5 : 5.0V $\pm 5\%$

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

FREQUENCY MHz

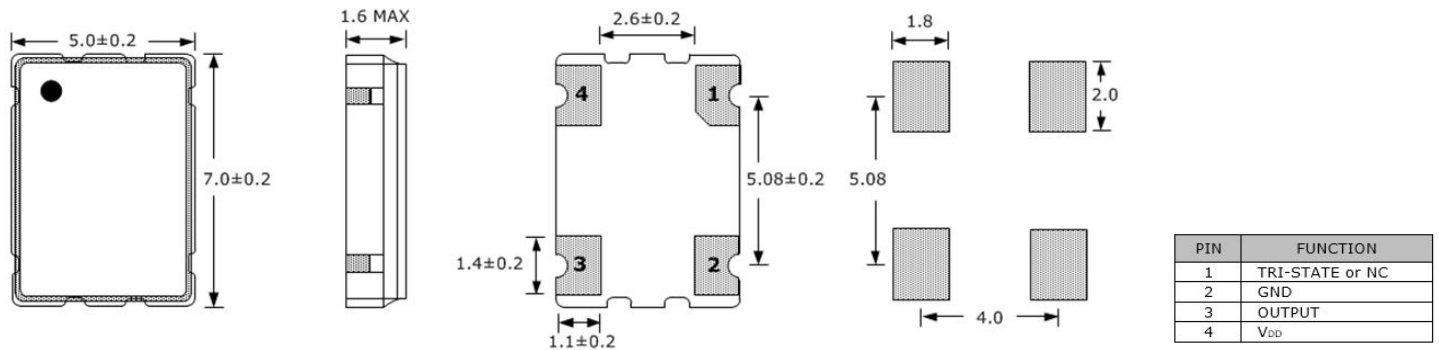
TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

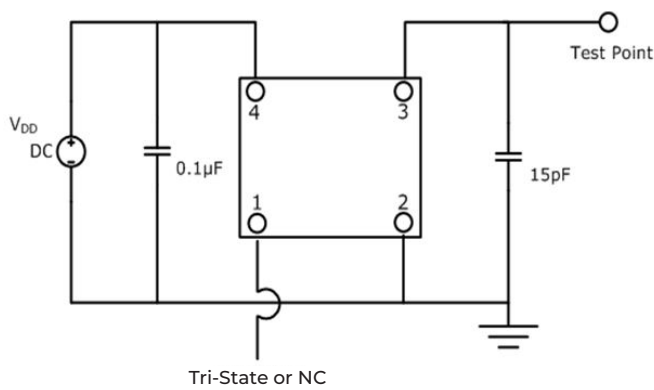
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	1		133	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.750	5.0	5.250	
Current (I _{DD}) - 3.3V option	mA			25	
Current (I _{DD}) - 5.0V option	mA			45	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			4	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage(3.3V) - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage(3.3V) - Disable	V			0.3*V _{DD}	
Tri-State Input Voltage(5.0V) - Enable	V	2.0			No Connection
Tri-State Input Voltage(5.0V) - Disable	V			0.8	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		50	100	

Outline Drawing & Land Pattern

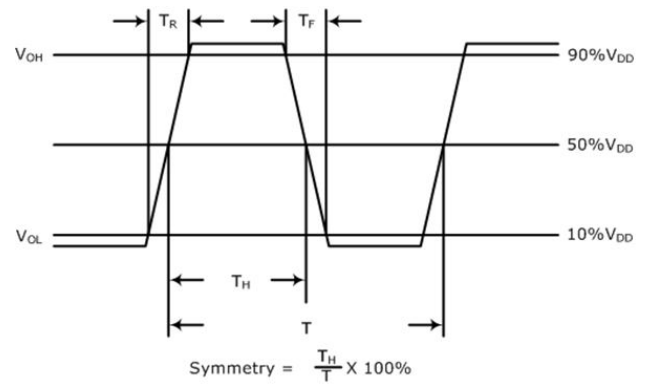
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



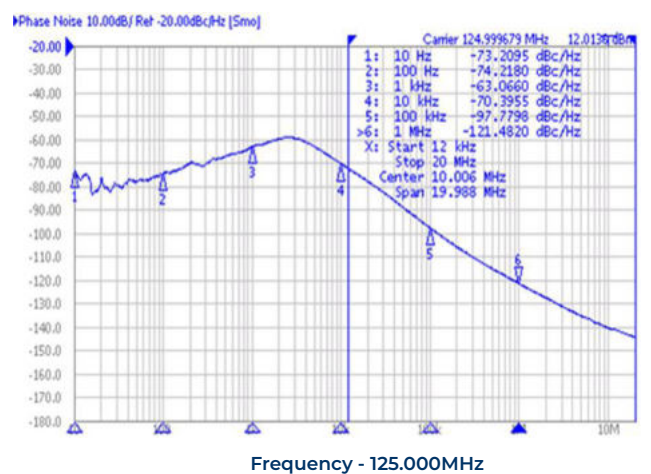
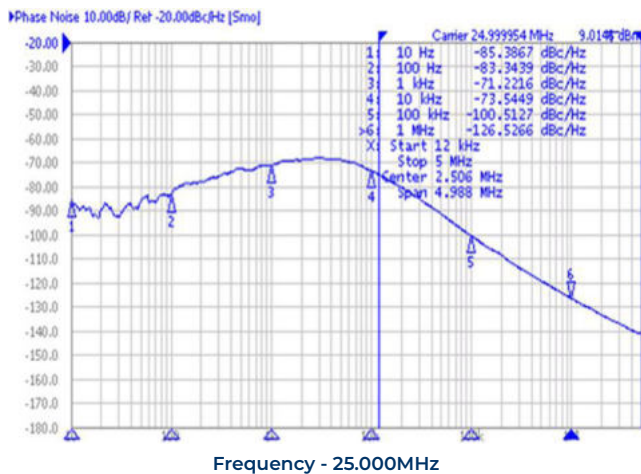
Test Circuit (CMOS)



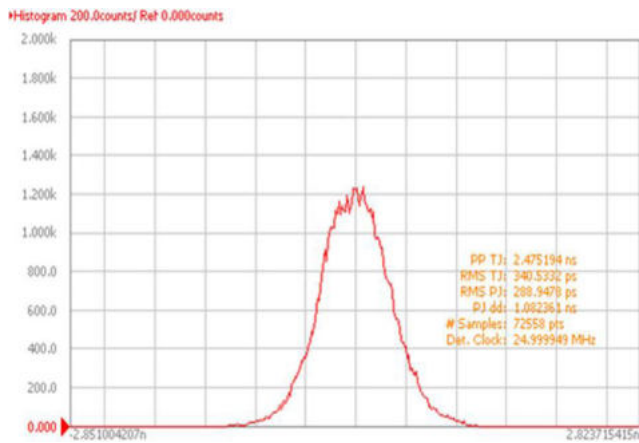
Waveform (CMOS)



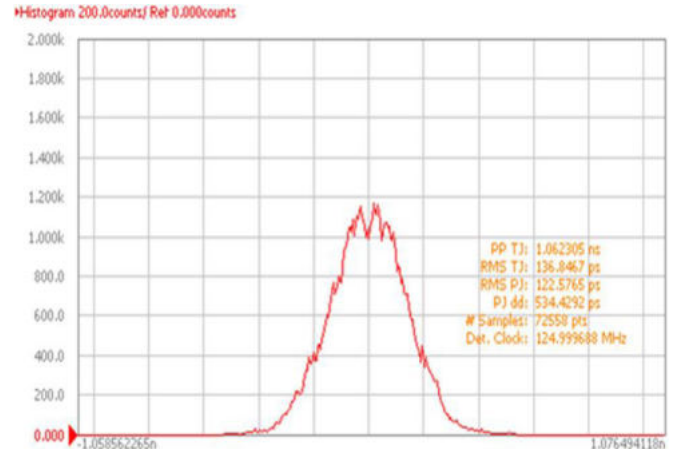
Typical Phase Noise Performance (Measured By Agilent E5052A)



Typical Jitter Performance (Measured By Agilent E5052A)

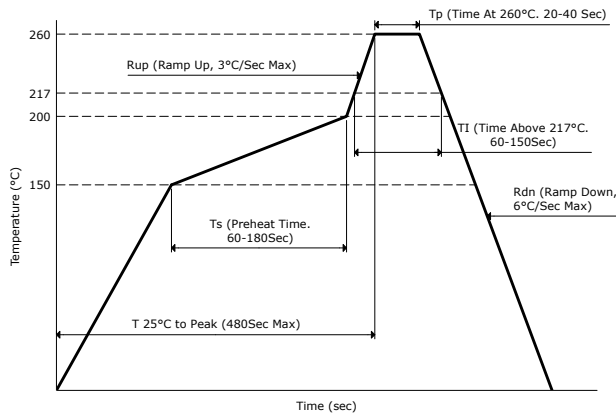


Frequency - 25.000MHz

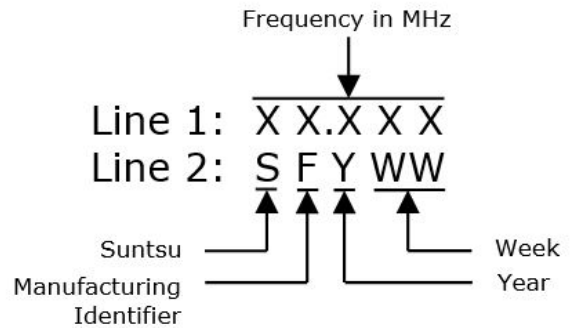


Frequency - 125.000MHz

Reflow Profile



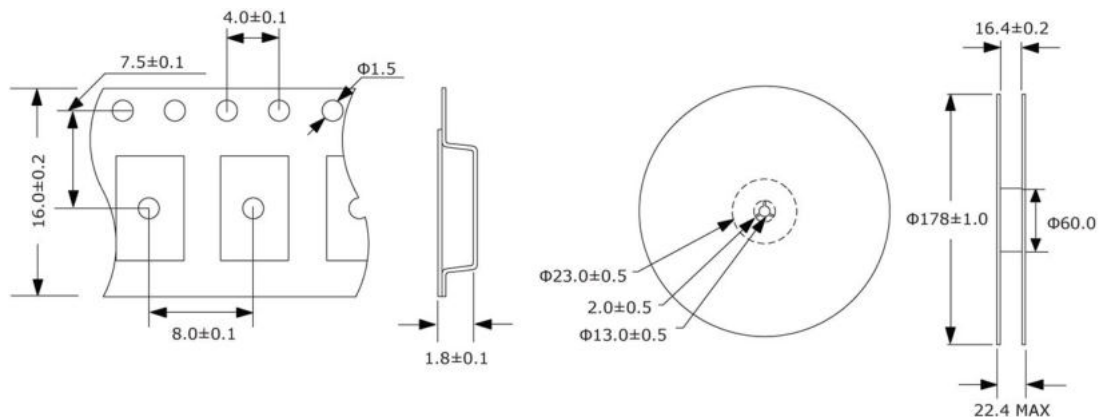
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

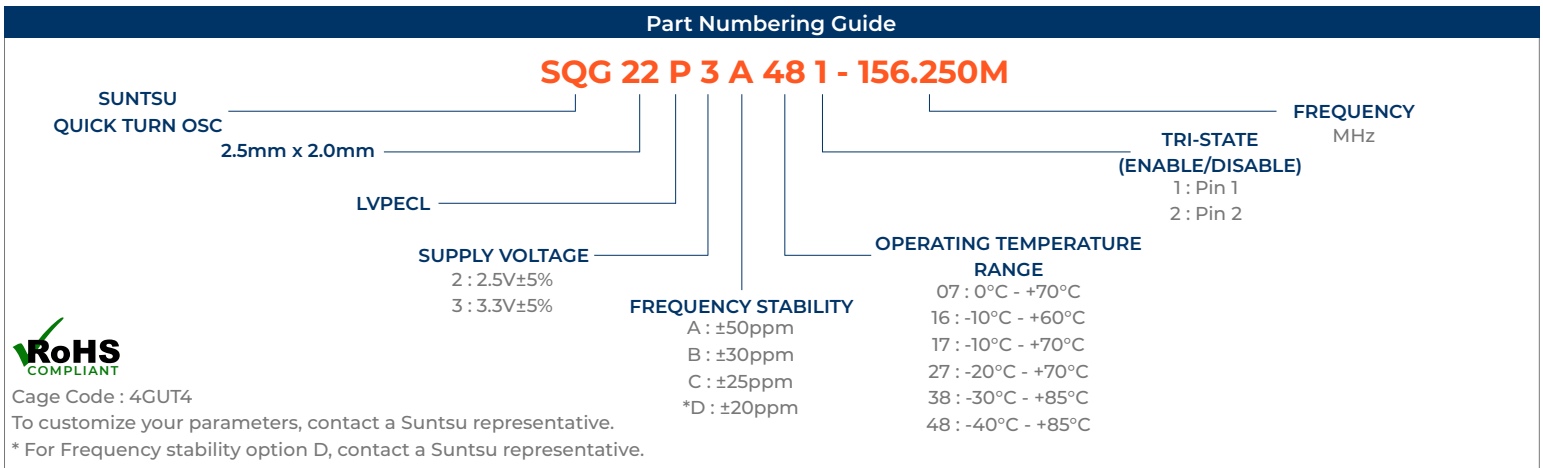
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Wide Frequency Range
• LVPECL
• Programmed Oscillator
• Tape and Reel

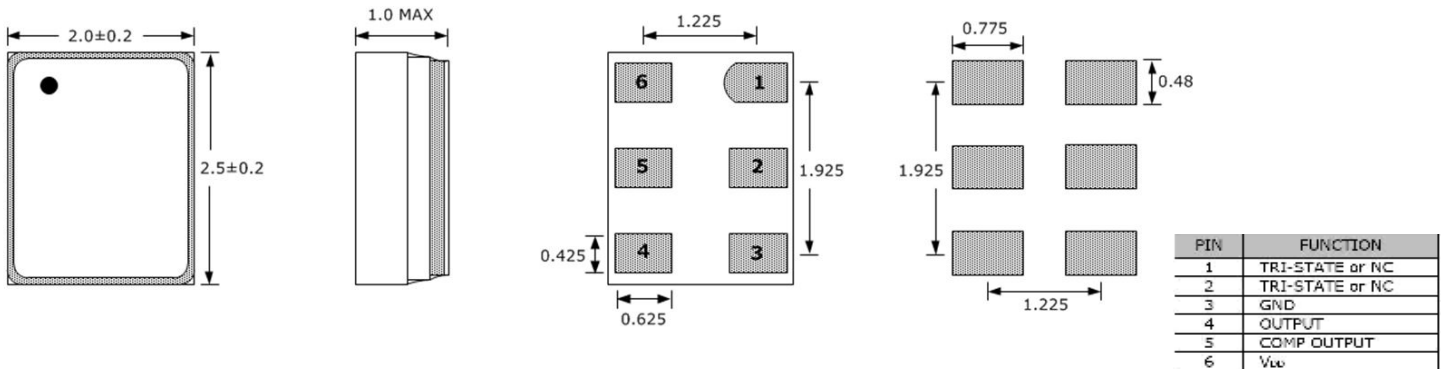
Applications
• Ethernet (10G/40G/100G)
• Base Stations
• Wi-Fi
• DSL/ADSL
• Communications



Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			60	
Current (I _{DD}) - 3.3V option	mA			65	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	V	V _{DD} -1.025			
Output Logic Levels Low (V _{OL})	V			V _{DD} -1.62	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1.5	

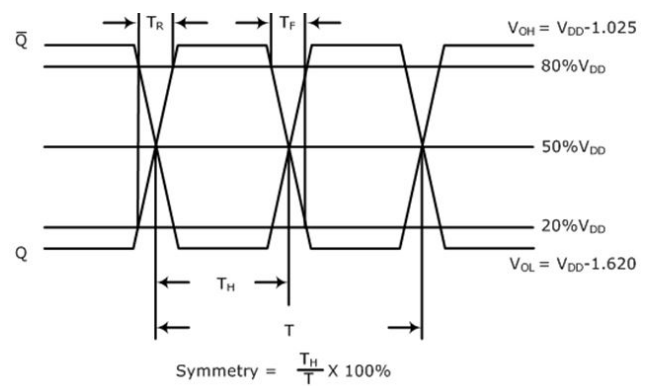
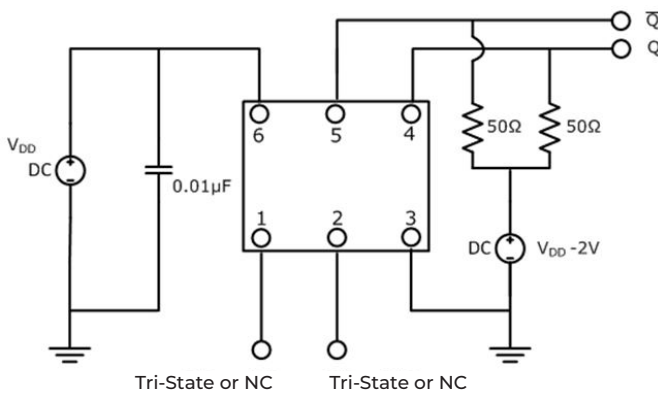
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

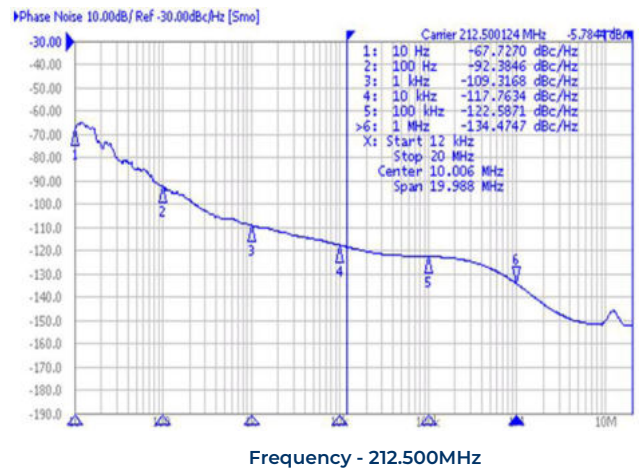
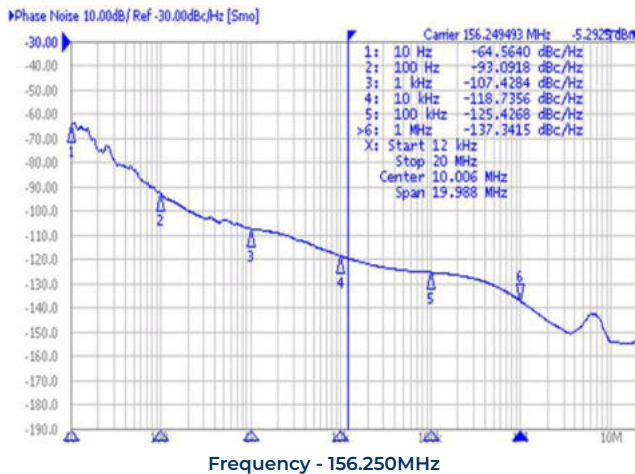


Test Circuit (LVPECL)

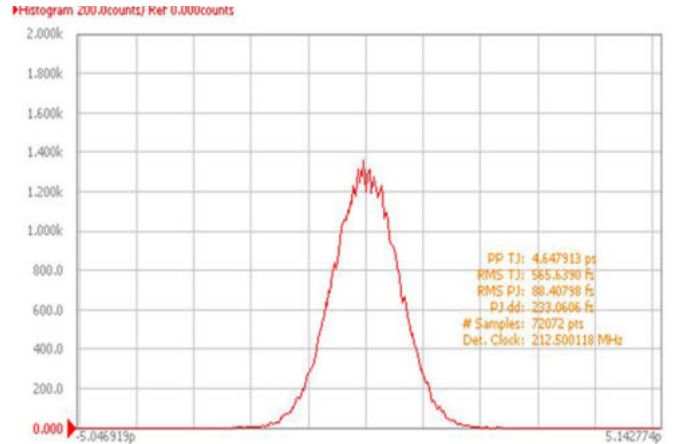
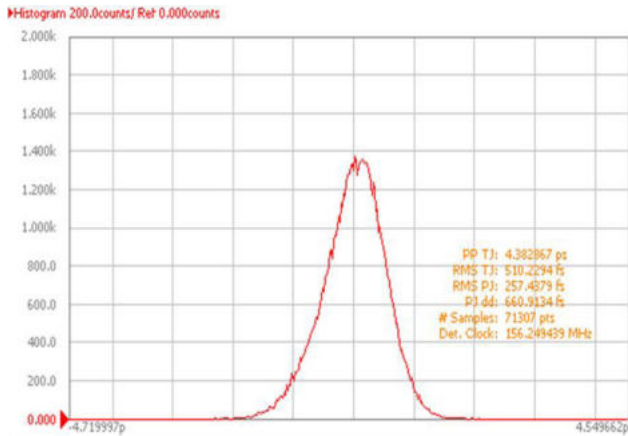
Waveform (LVPECL)



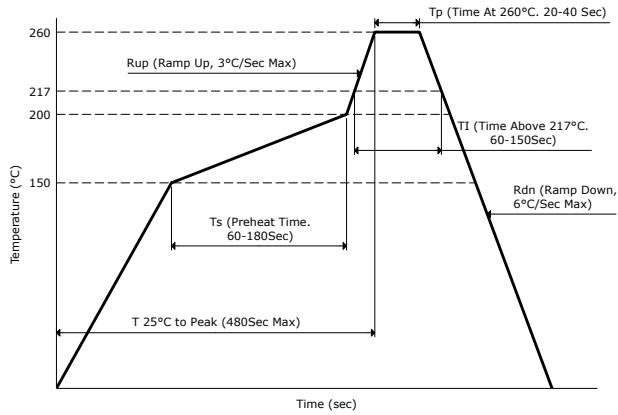
Typical Phase Noise Performance (Measured By Agilent E5052A)



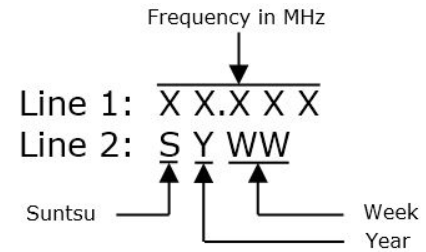
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



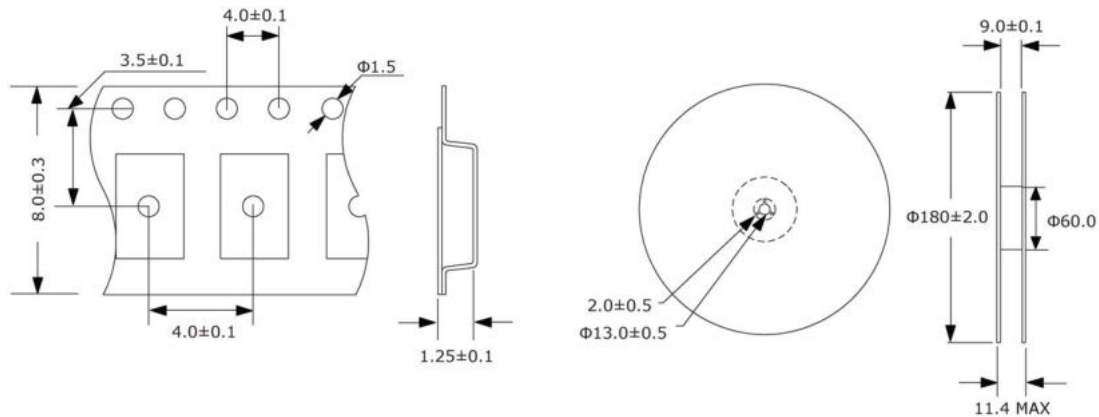
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

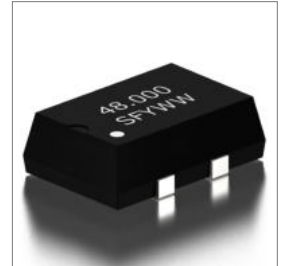
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±25ppm (Frequency Stability) Available Plastic J-Lead Package CMOS Programmed Oscillator Tape and Reel

Applications
<ul style="list-style-type: none"> Micro Processors FPGA Storage Area/Networking Digital Video Portable Computers



Part Numbering Guide

SQC PJC 3 A 48 1 -48.000M

SUNTSU QUICK TURN OSC 14.0mm x 9.8mm PLASTIC J-LEAD CMOS	SUPPLY VOLTAGE 3 : 3.3V±5% 5 : 5.0V±5%	FREQUENCY STABILITY A : ±50ppm B : ±30ppm C : ±25ppm *D : ±20ppm	FREQUENCY MHz
OPERATING TEMPERATURE RANGE 07 : 0°C - +70°C 16 : -10°C - +60°C 17 : -10°C - +70°C 27 : -20°C - +70°C 38 : -30°C - +85°C 48 : -40°C - +85°C		TRI-STATE (ENABLE/DISABLE) BLANK : No Connection 1 : Pin 1	

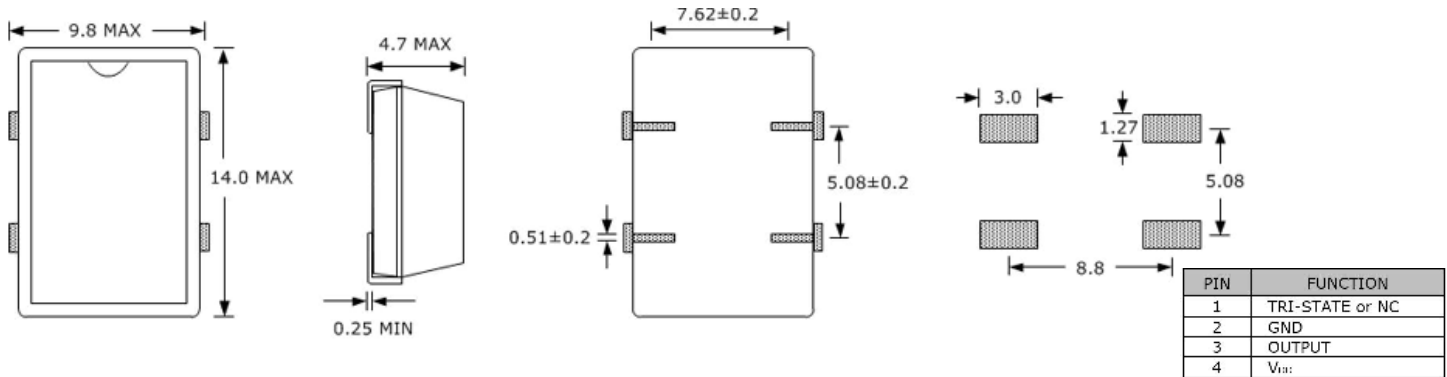
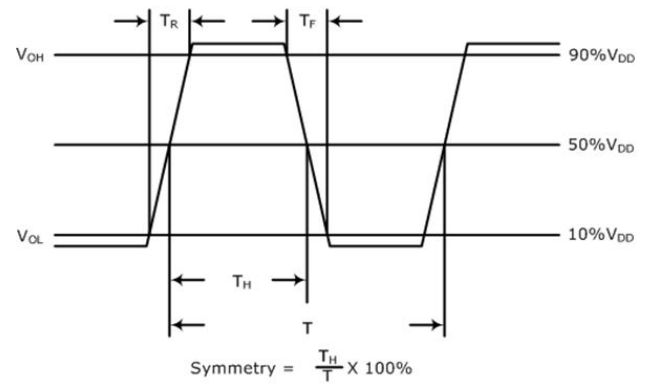
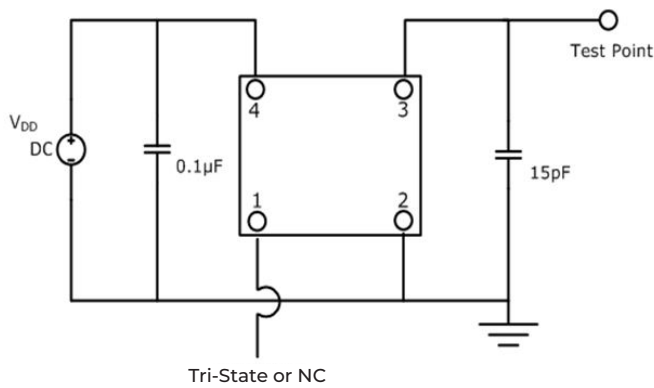
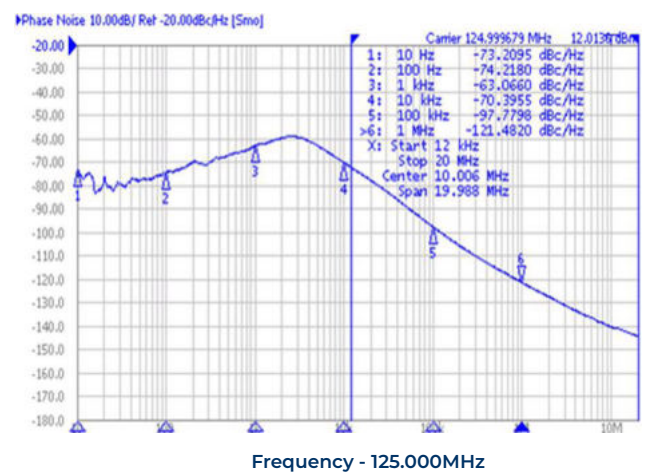
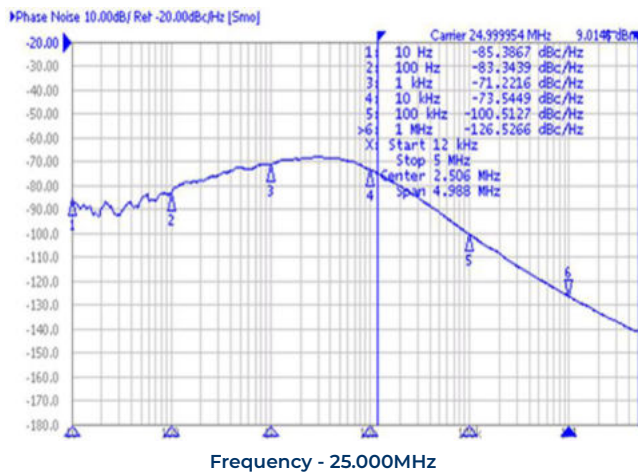
RoHS COMPLIANT

Cage Code : 4GUT4
 To customize your parameters, contact a Suntsu representative.
 * For Frequency stability option D, contact a Suntsu representative.

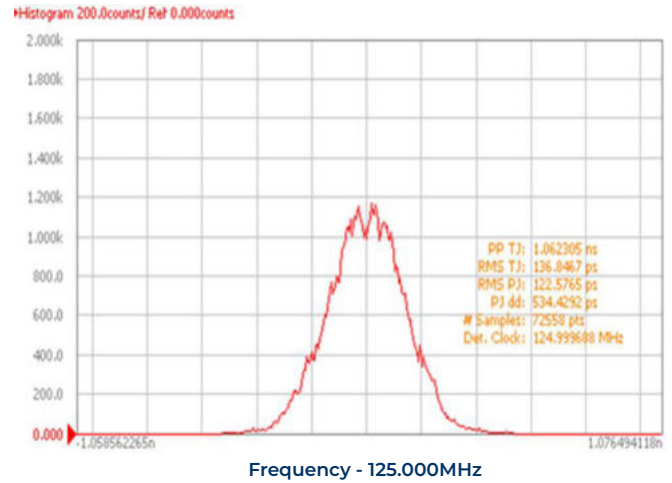
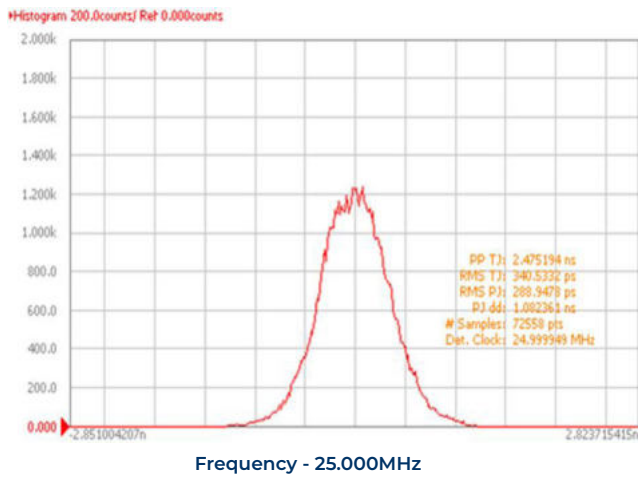
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	1		133	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.750	5.0	5.250	
Current (I _{DD}) - 3.3V option	mA			25	
Current (I _{DD}) - 5.0V option	mA			45	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			4	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage(3.3V) - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage(3.3V) - Disable	V			0.3*V _{DD}	
Tri-State Input Voltage(5.0V) - Enable	V	2.0			No Connection
Tri-State Input Voltage(5.0V) - Disable	V			0.8	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			11	

Outline Drawing & Land Pattern

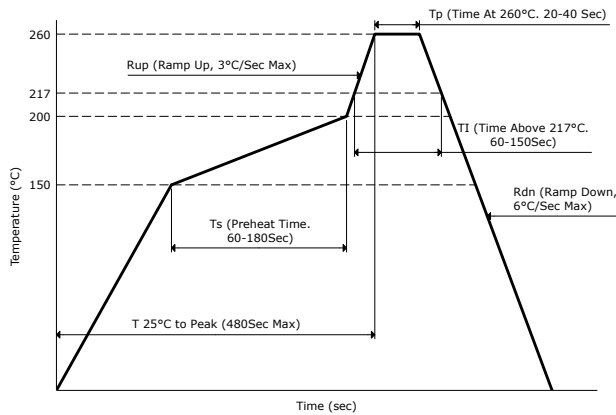
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.


Test Circuit (CMOS)
Waveform (CMOS)

Typical Phase Noise Performance (Measured By Agilent E5052A)


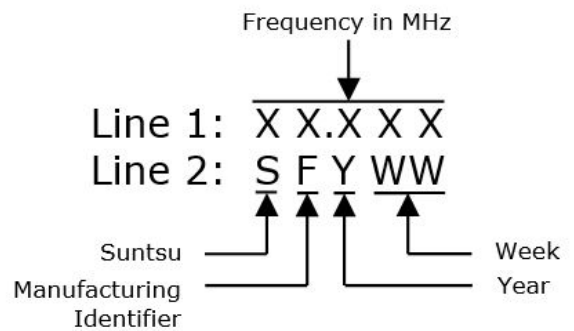
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



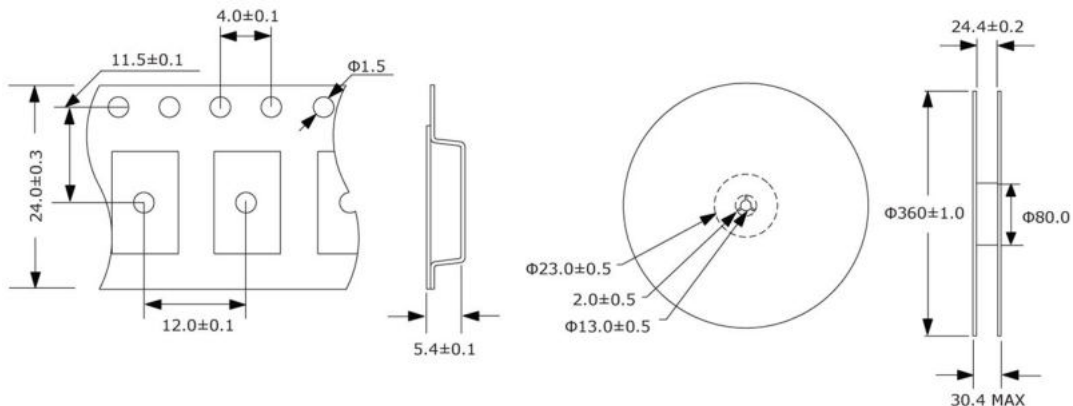
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

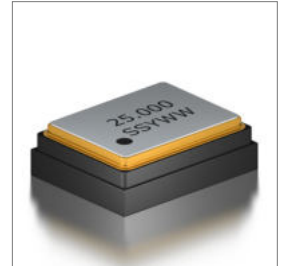
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Wide Frequency Range
• CMOS
• Programmed Oscillator
• Tape and Reel

Applications
• Ethernet (10G/40G/100G)
• Base Stations
• Wi-Fi
• DSL/ADSL
• Communications



Part Numbering Guide

SQG 22 C 3 A 48 1 - 25.000M

SUNTSU QUICK TURN OSC

2.5mm x 2.0mm

CMOS


SUPPLY VOLTAGE
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

FREQUENCY
MHz

TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

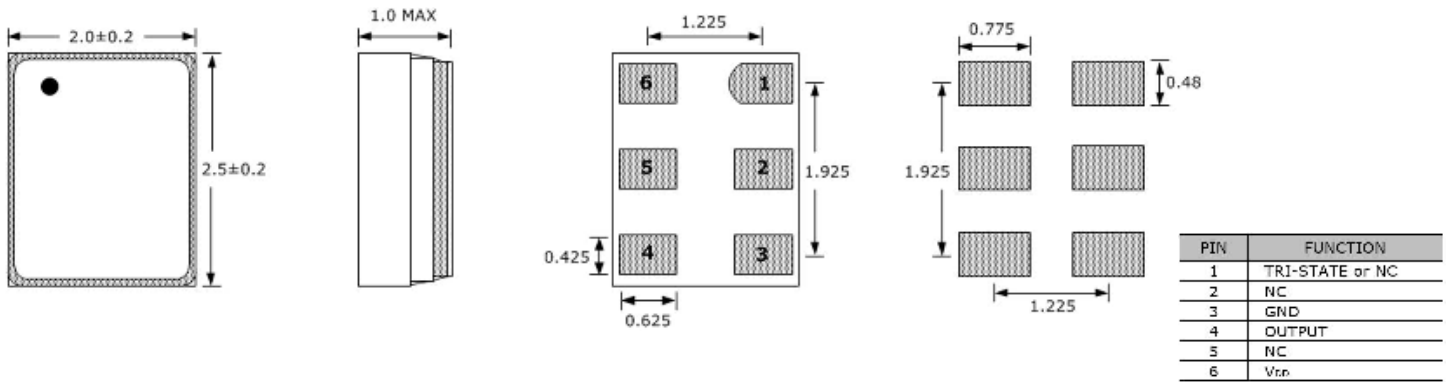


Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		250	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			35	
Current (I _{DD}) - 3.3V option	mA			40	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			3	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1.5	

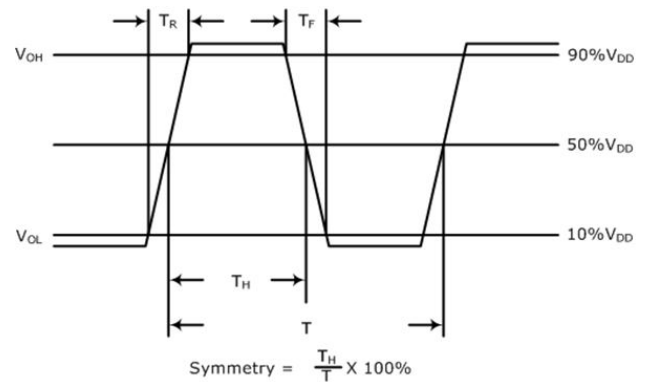
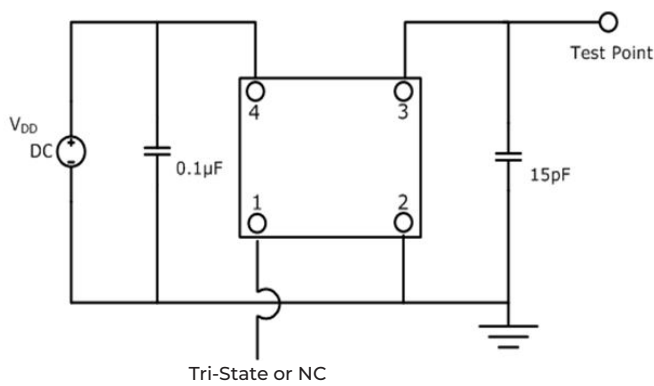
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

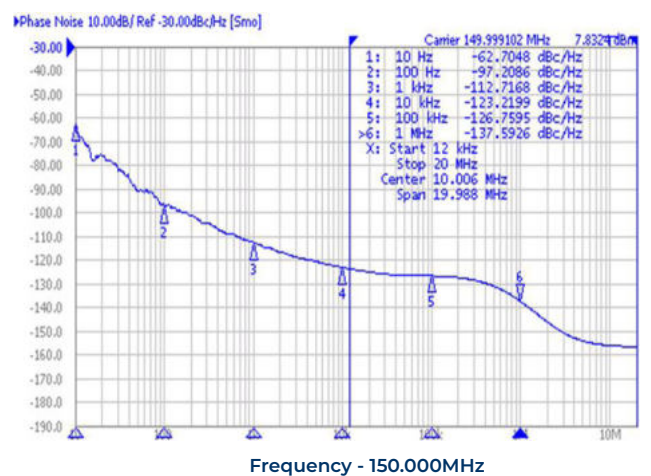
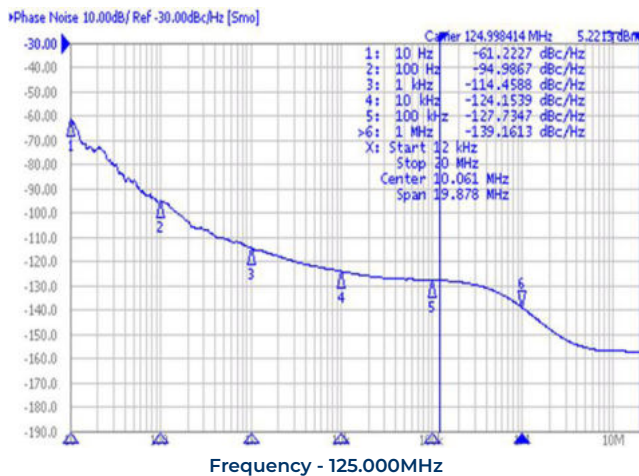


Test Circuit (CMOS)

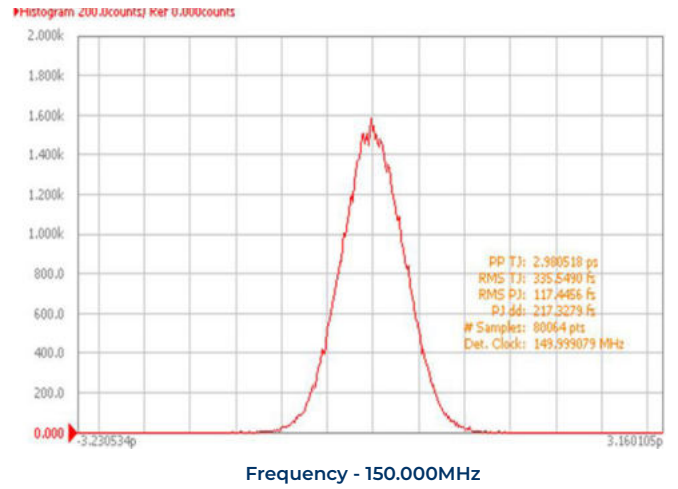
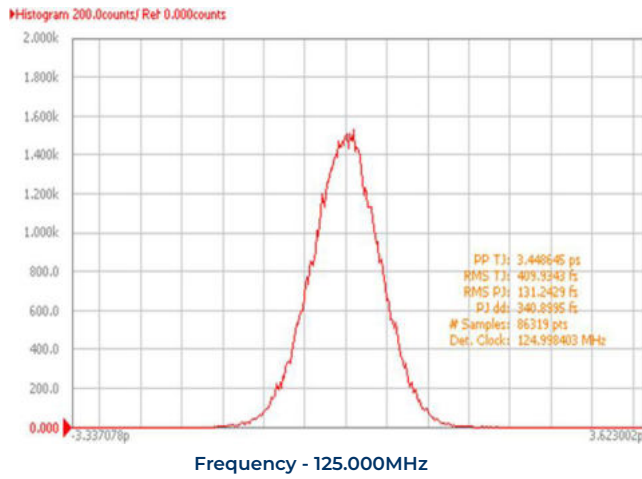
Waveform (CMOS)



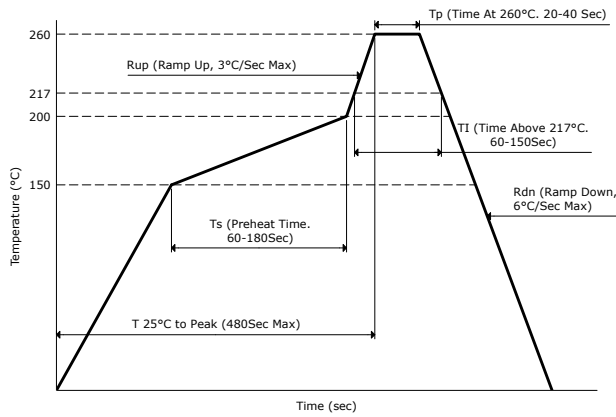
Typical Phase Noise Performance (Measured By Agilent E5052A)



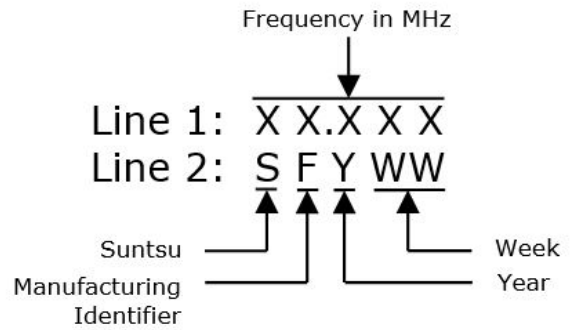
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



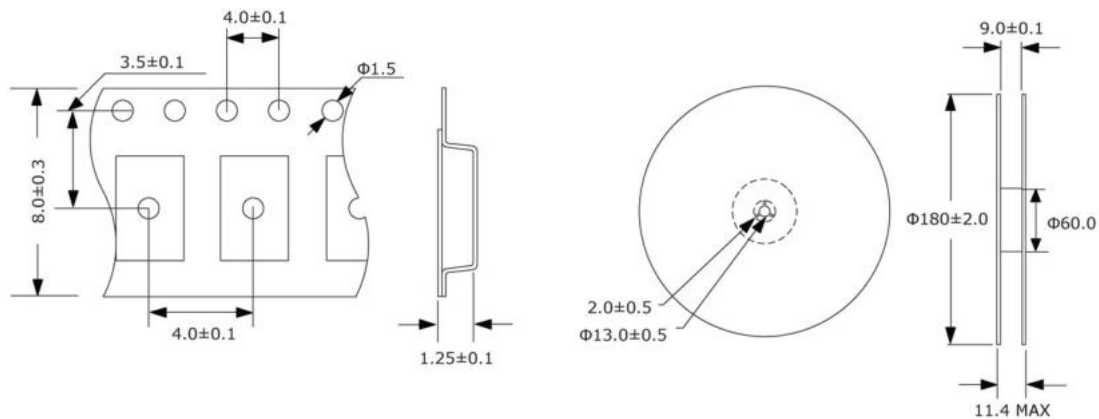
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

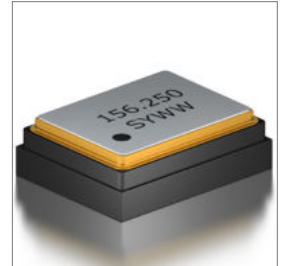
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Wide Frequency Range
• LVDS
• Programmed Oscillator
• Tape and Reel

Applications
• Ethernet (10G/40G/100G)
• Base Stations
• Wi-Fi
• DSL/ADSL
• Communications



Part Numbering Guide

SQG 22 L 3 A 48 1 - 156.250M

SUNTSU
QUICK TURN OSC
2.5mm x 2.0mm

LVDS

SUPPLY VOLTAGE
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

FREQUENCY
MHz

TRI-STATE (ENABLE/DISABLE)
1 : Pin 1
2 : Pin 2

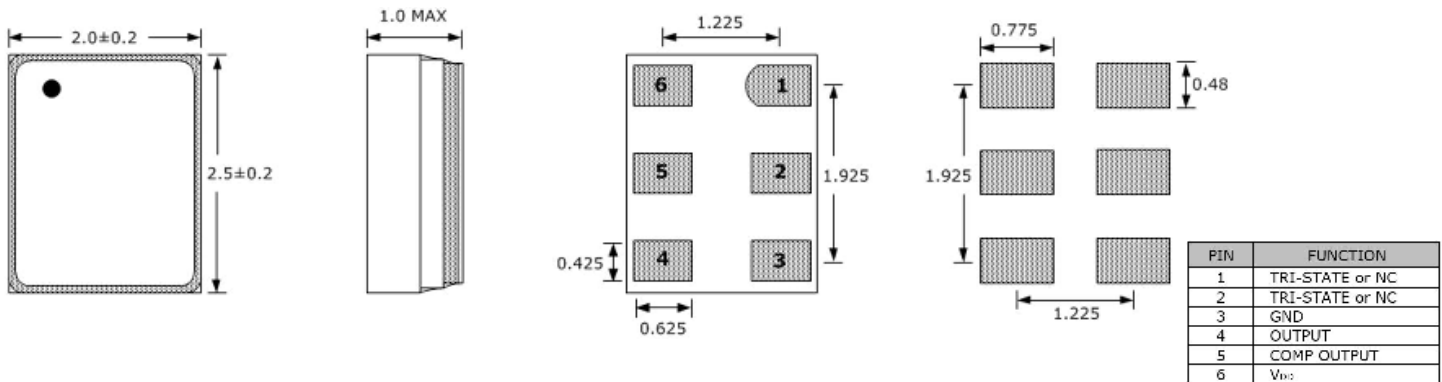
OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

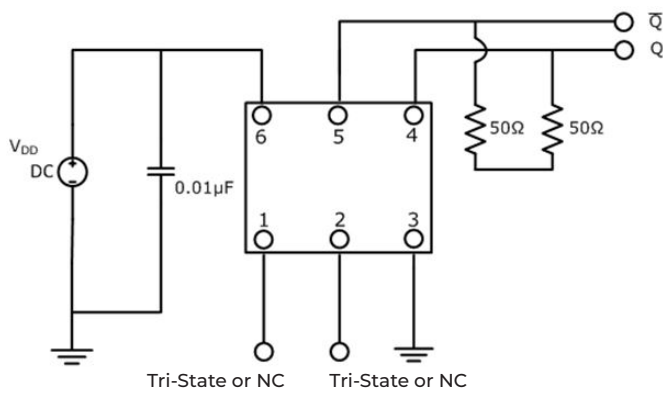
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			35	
Current (I _{DD}) - 3.3V option	mA			40	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	330	454	
Differential Output Error (pV _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (pV _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1.5	

Outline Drawing & Land Pattern

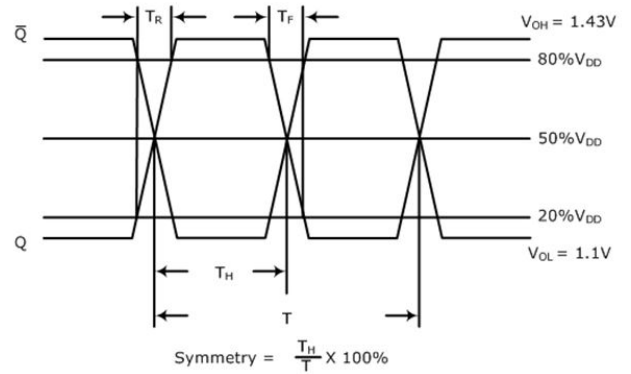
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



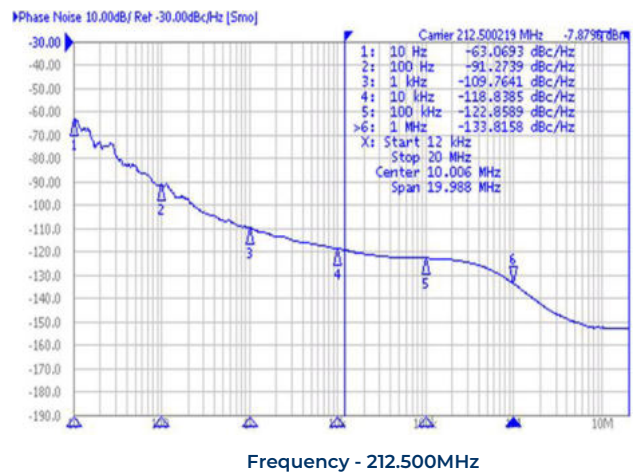
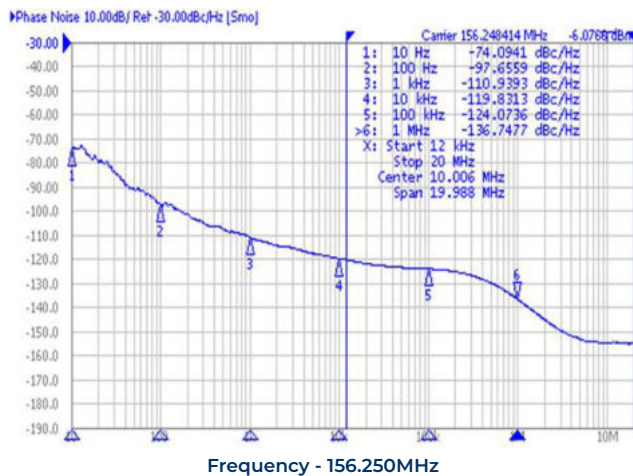
Test Circuit (LVDS)



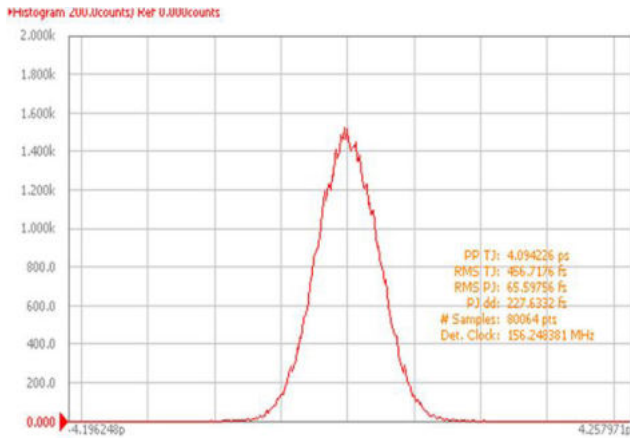
Waveform (LVDS)



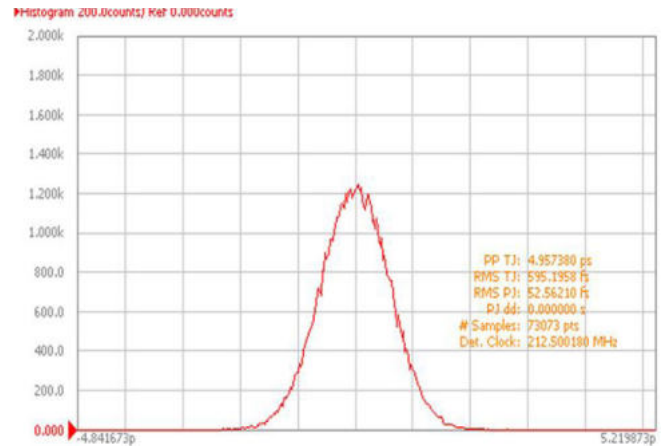
Typical Phase Noise Performance (Measured By Agilent E5052A)



Typical Jitter Performance (Measured By Agilent E5052A)

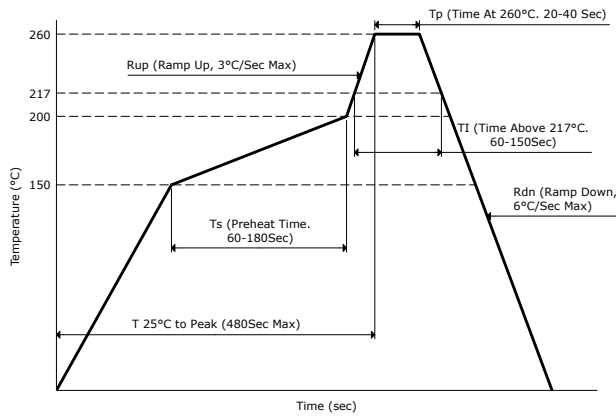


Frequency - 156.250MHz

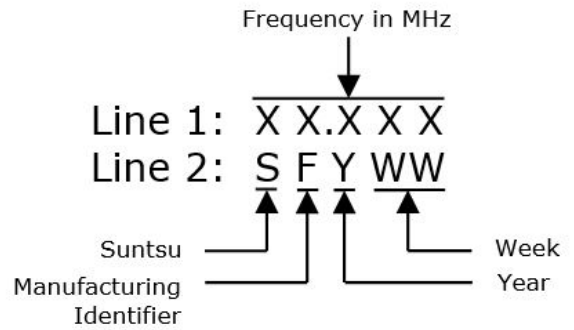


Frequency - 212.500MHz

Reflow Profile



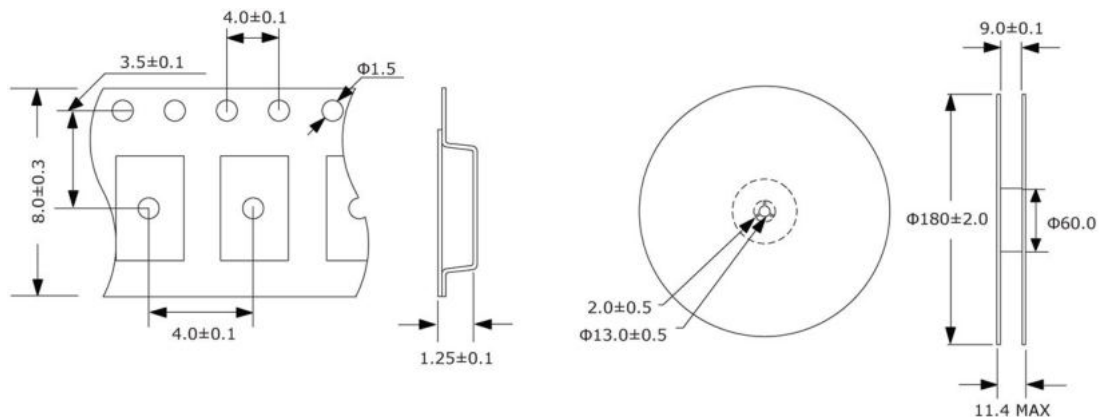
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

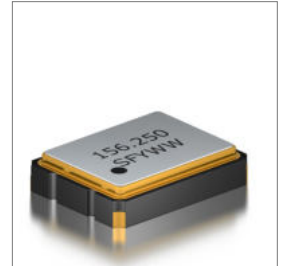
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Wide Frequency Range
• CMOS
• Programmed Oscillator
• Tape and Reel

Applications
• Ethernet (10G/40G/100G)
• Base Stations
• Wi-Fi
• DSL/ADSL
• Communications



Part Numbering Guide

SQG 32 C 3 A 48 1 - 25.000M

SUNTSU QUICK TURN OSC
3.2mm x 2.5mm

CMOS


SUPPLY VOLTAGE
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

FREQUENCY
MHz

TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

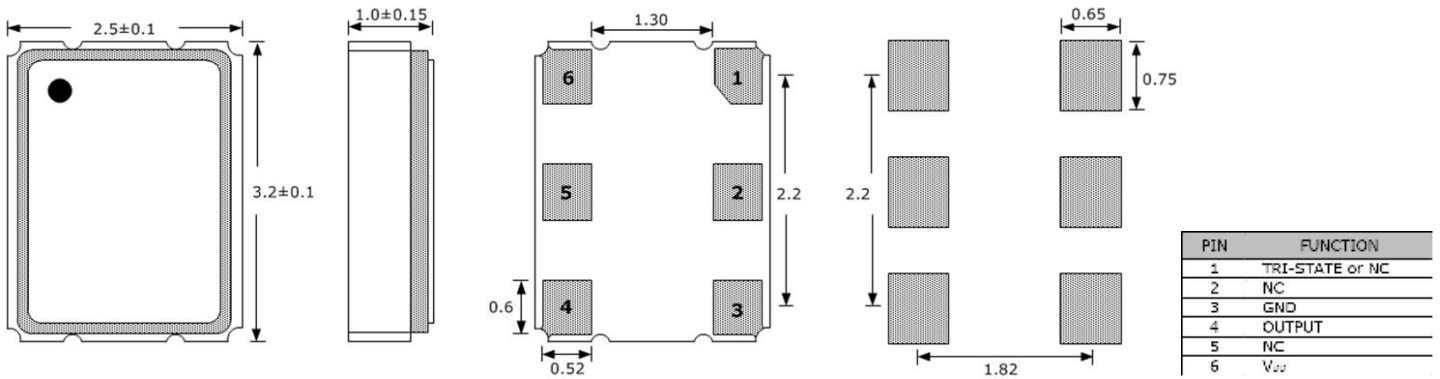


Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		250	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			35	
Current (I _{DD}) - 3.3V option	mA			40	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			3	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1.5	

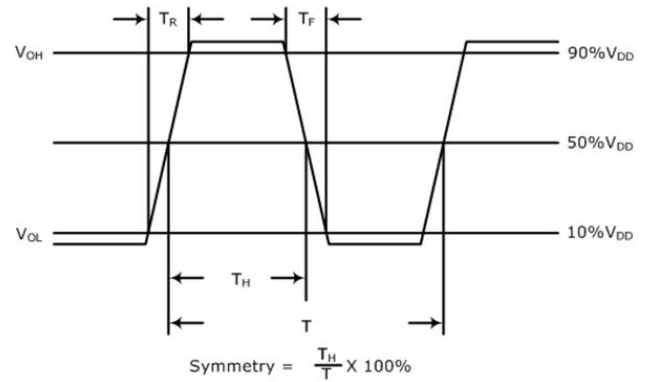
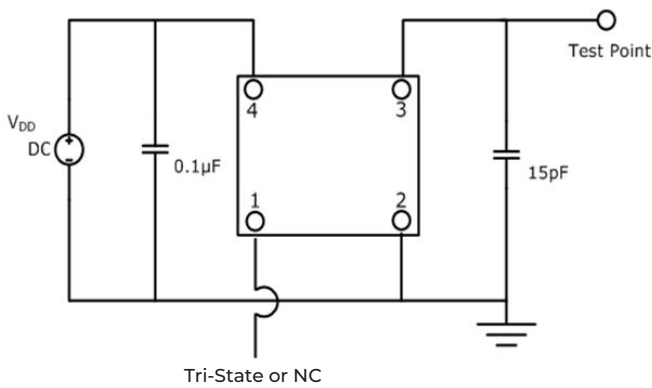
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

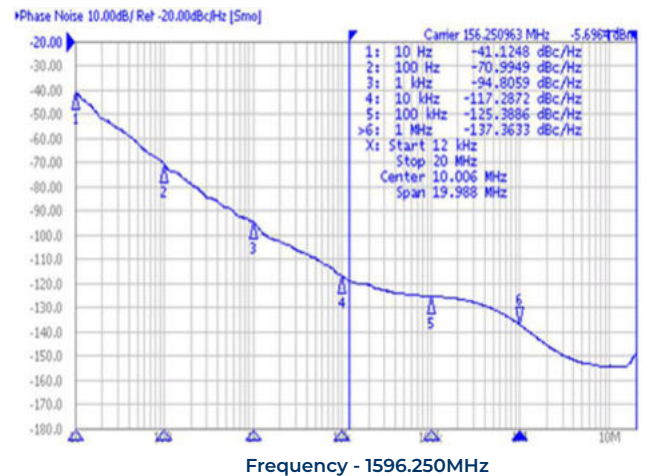
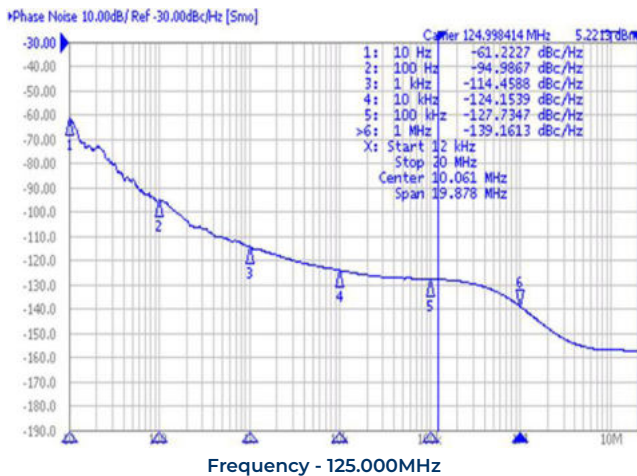


Test Circuit (CMOS)

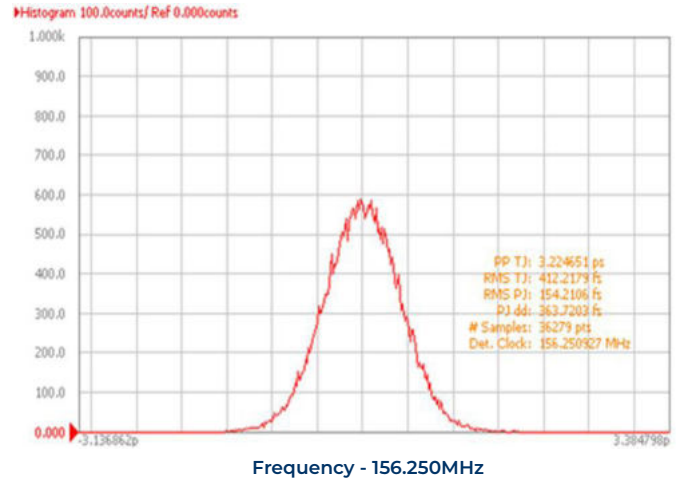
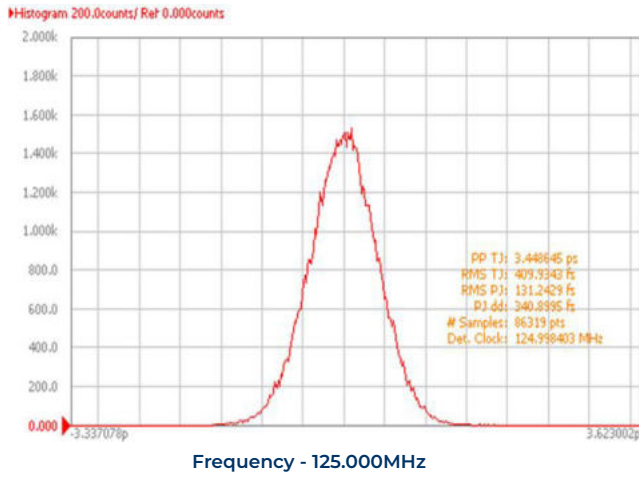
Waveform (CMOS)



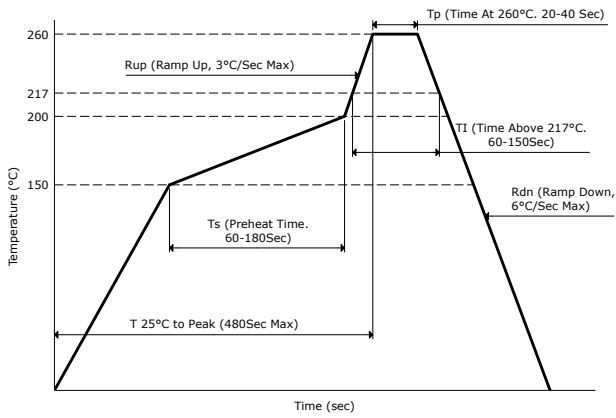
Typical Phase Noise Performance (Measured By Agilent E5052A)



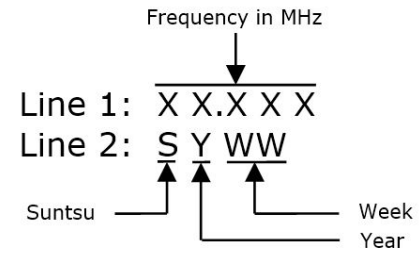
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



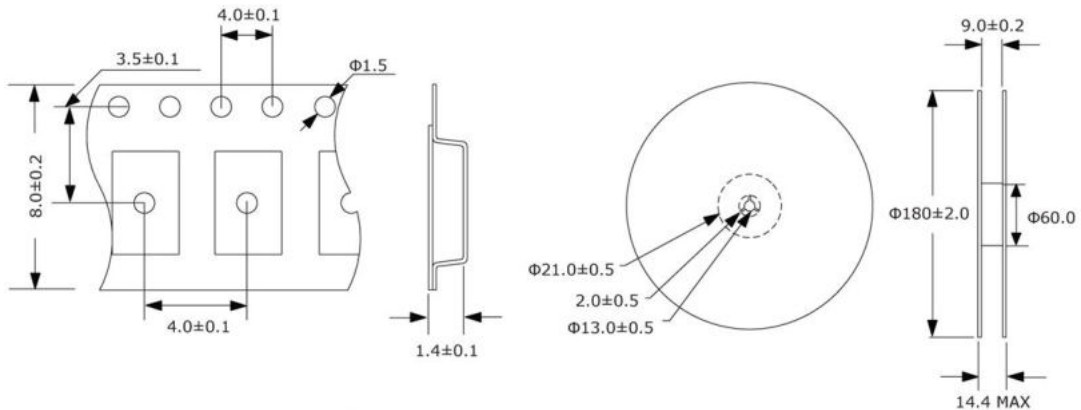
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

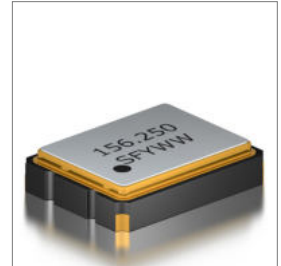
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Wide Frequency Range
• LVDS
• Programmed Oscillator
• Tape and Reel

Applications
• Ethernet (10G/40G/100G)
• Base Stations
• Wi-Fi
• DSL/ADSL
• Communications



Part Numbering Guide

SQG 32 L 3 A 48 1 - 156.250M

SUNTSU QUICK TURN OSC
3.2mm x 2.5mm

LVDS

SUPPLY VOLTAGE
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

FREQUENCY
MHz

TRI-STATE (ENABLE/DISABLE)
1 : Pin 1
2 : Pin 2

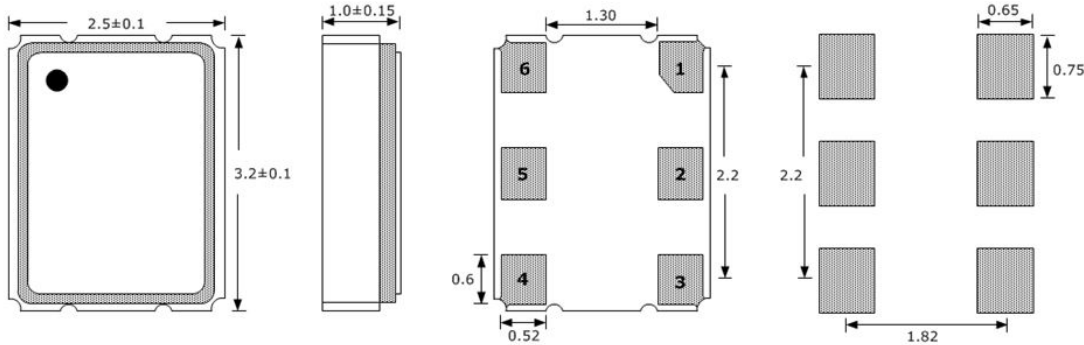
OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			35	
Current (I _{DD}) - 3.3V option	mA			40	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	330	454	
Differential Output Error (ρ V _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (ρ V _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1.5	

Outline Drawing & Land Pattern

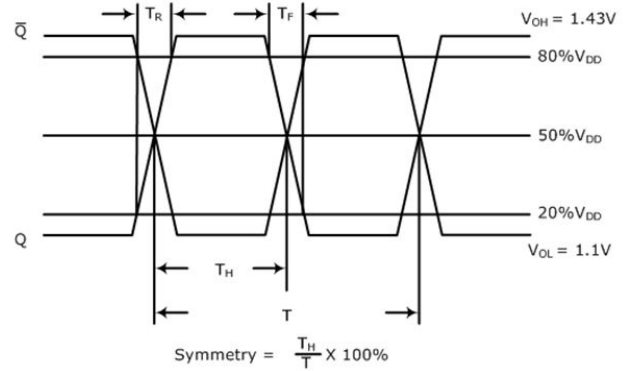
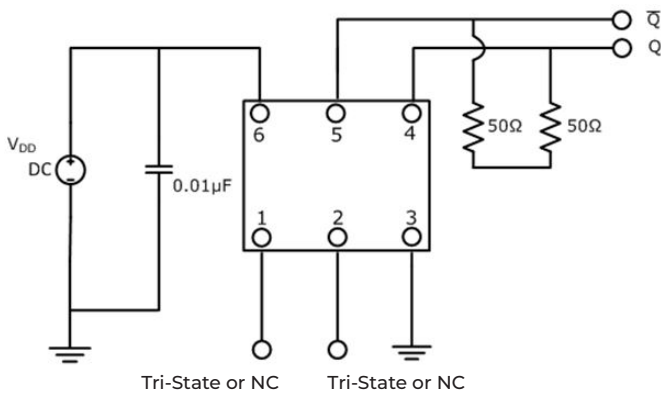
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



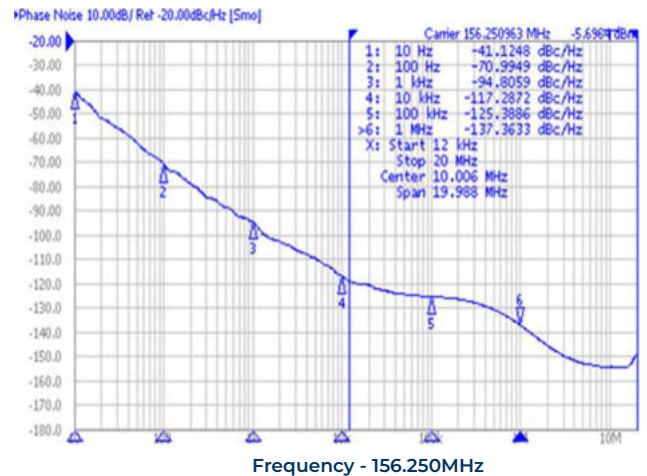
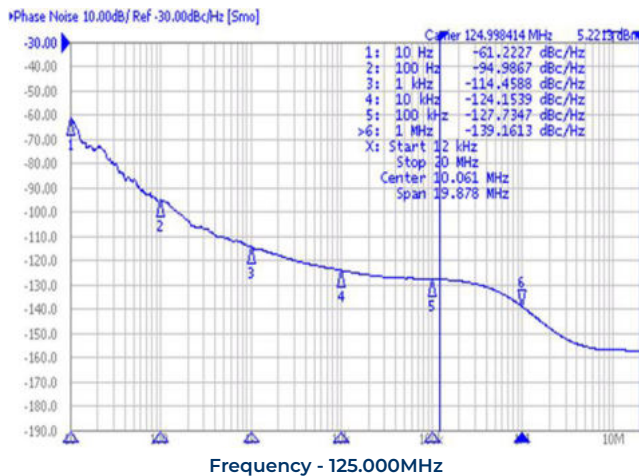
PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVDS)

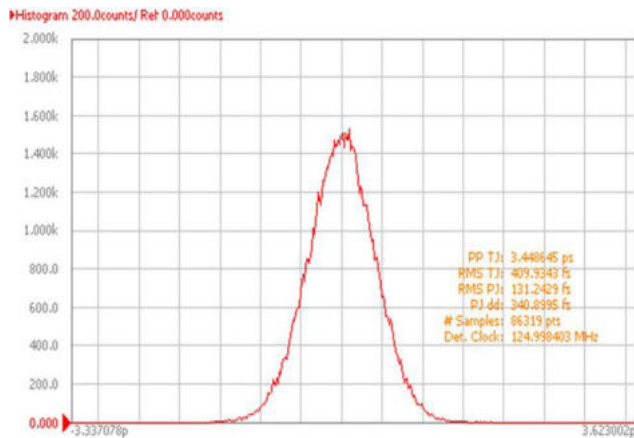
Waveform (LVDS)



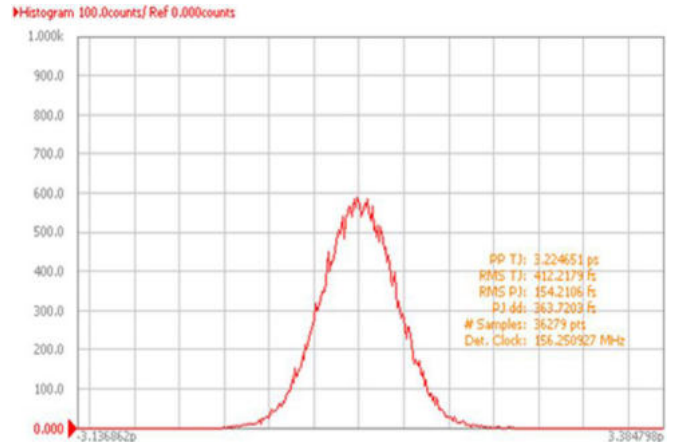
Typical Phase Noise Performance (Measured By Agilent E5052A)



Typical Jitter Performance (Measured By Agilent E5052A)

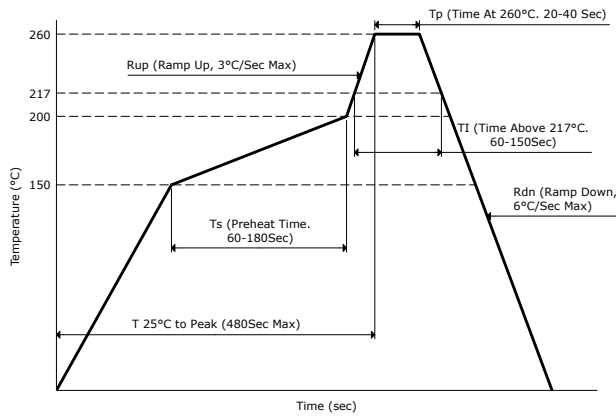


Frequency - 125.000MHz

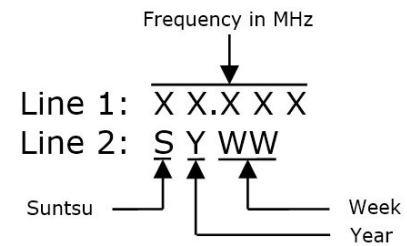


Frequency - 156.250MHz

Reflow Profile



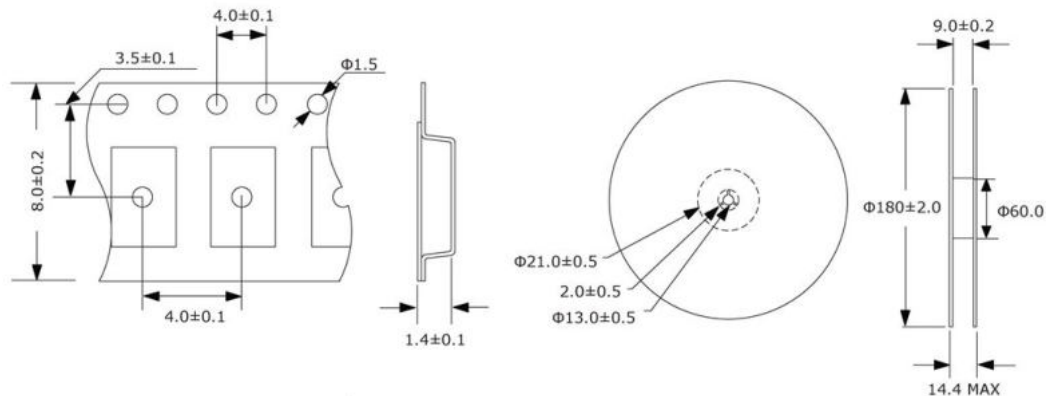
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

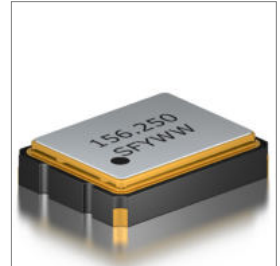
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Wide Frequency Range
• LVPECL
• Programmed Oscillator
• Tape and Reel

Applications
• Ethernet (10G/40G/100G)
• Base Stations
• Wi-Fi
• DSL/ADSL
• Communications



Part Numbering Guide

SQG 32 P 3 A 48 1 - 156.250M

SUNTSU QUICK TURN OSC
3.2mm x 2.5mm

LVPECL

SUPPLY VOLTAGE
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

FREQUENCY
MHz

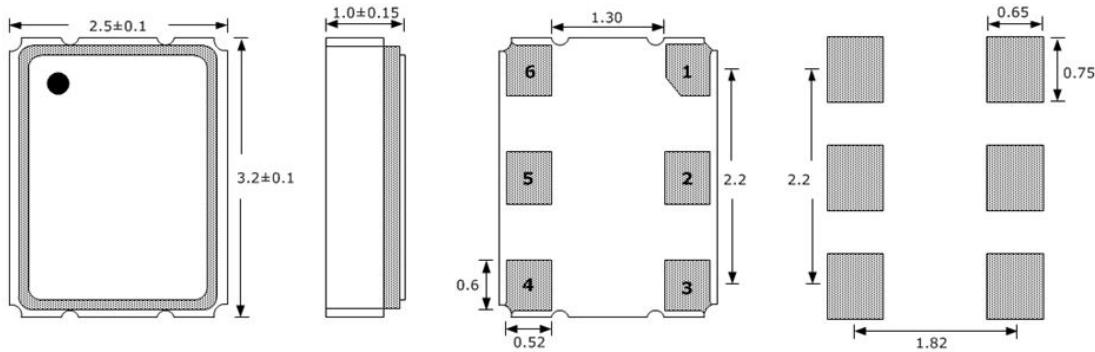
TRI-STATE (ENABLE/DISABLE)
1 : Pin 1
2 : Pin 2

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

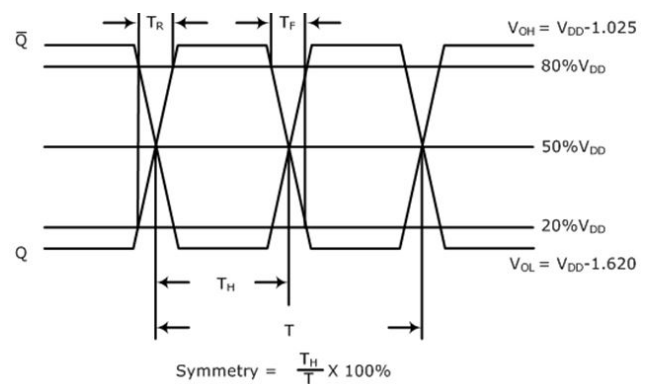
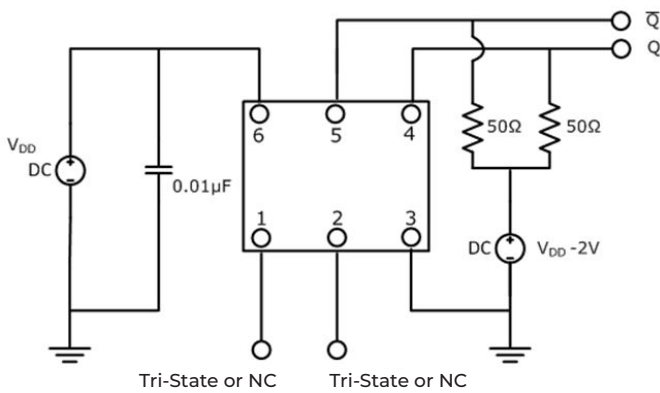
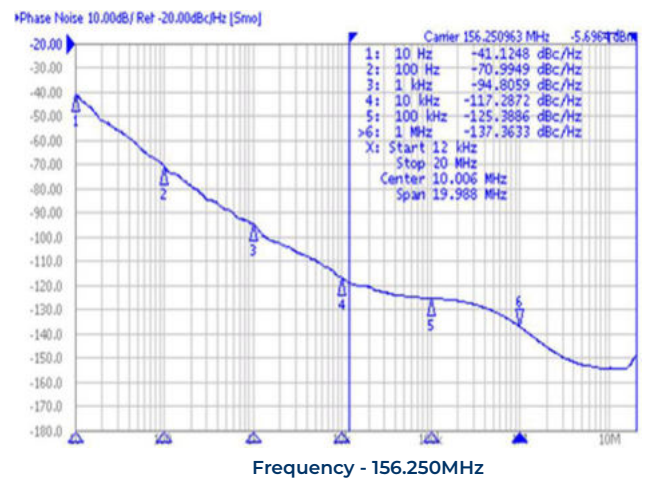
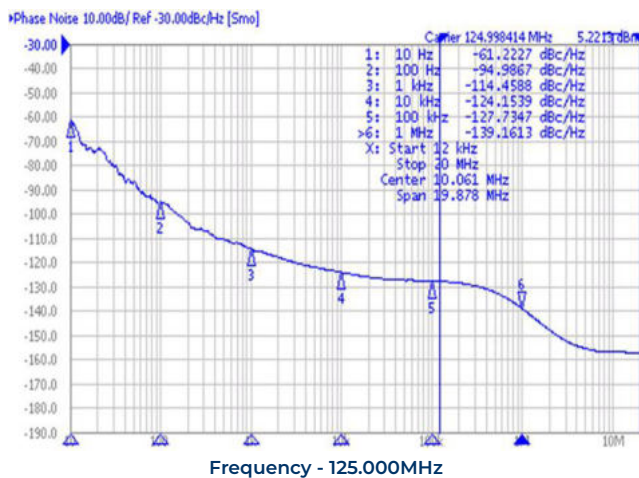
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			60	
Current (I _{DD}) - 3.3V option	mA			65	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	V	V _{DD} -1.025			
Output Logic Levels Low (V _{OL})	V			V _{DD} -1.62	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1.5	

Outline Drawing & Land Pattern

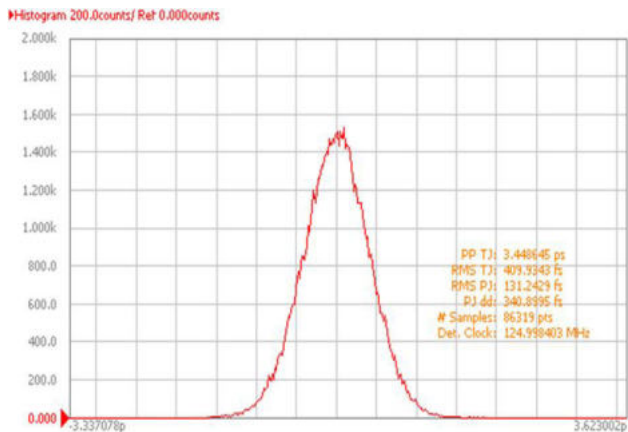
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



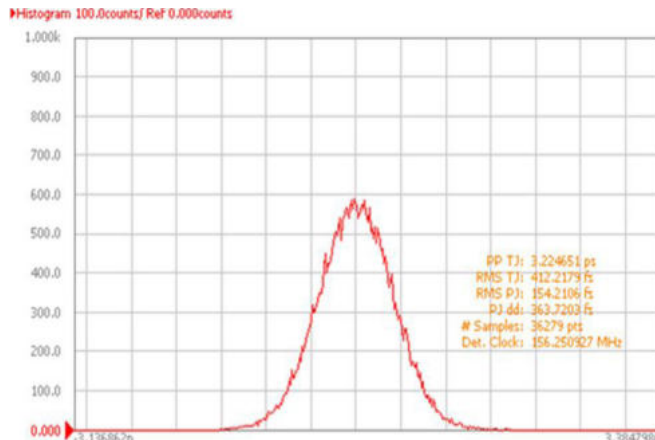
PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVPECL)
Waveform (LVPECL)

Typical Phase Noise Performance (Measured By Agilent E5052A)


Typical Jitter Performance (Measured By Agilent E5052A)

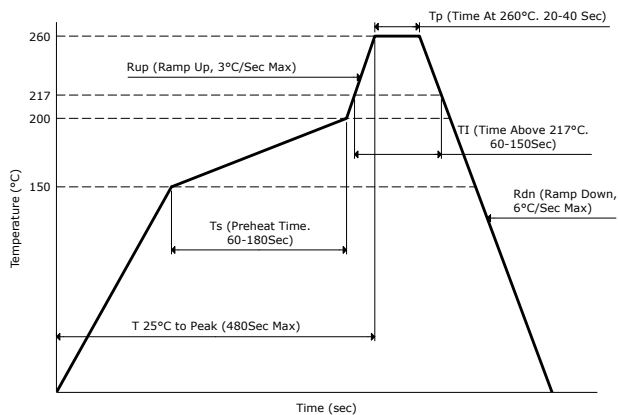


Frequency - 125.000MHz

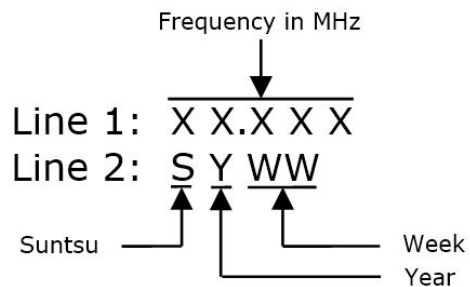


Frequency - 156.250MHz

Reflow Profile



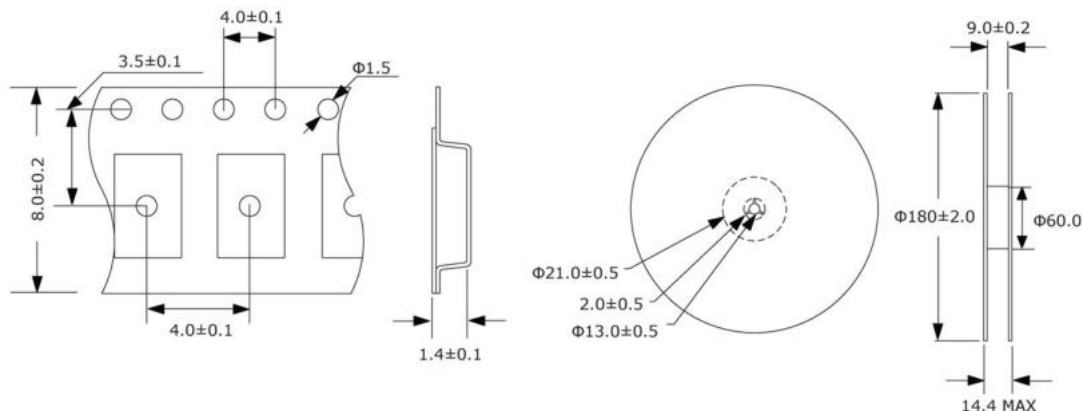
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

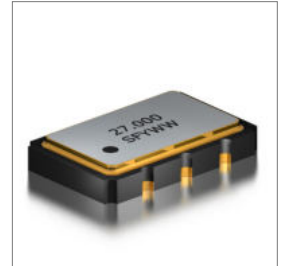
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> • ± 20ppm (Frequency Stability) Available • Wide Frequency Range • CMOS • Programmed Oscillator • Tape and Reel

Applications
<ul style="list-style-type: none"> • Ethernet (10G/40G/100G) • Base Stations • Wi-Fi • DSL/ADSL • Communications



Part Numbering Guide

SQG 53 C 3 A 48 1 - 27.000M

SUNTSU QUICK TURN OSC
5.0mm x 3.2mm

CMOS

SUPPLY VOLTAGE
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

FREQUENCY
MHz

TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1
2 : Pin 2

RoHS COMPLIANT

Cage Code : 4GUT4

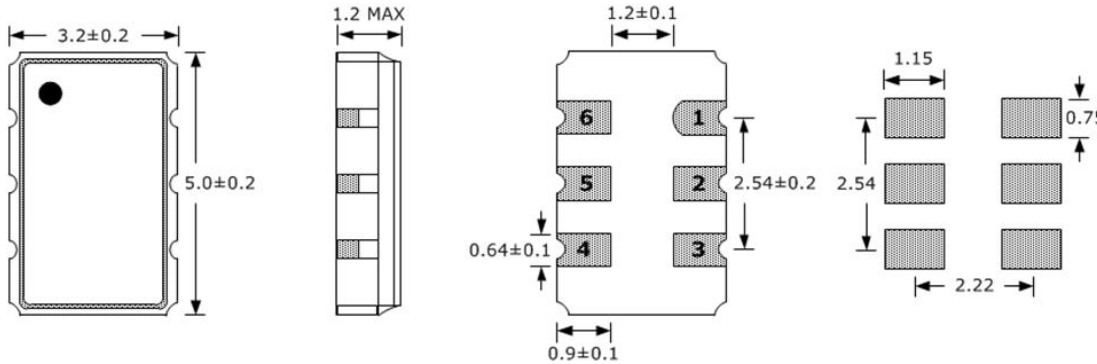
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		250	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			35	
Current (I _{DD}) - 3.3V option	mA			40	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			3	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.7	1.5	

Outline Drawing & Land Pattern

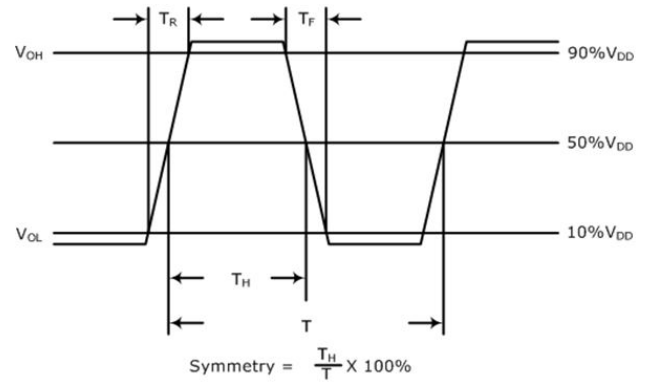
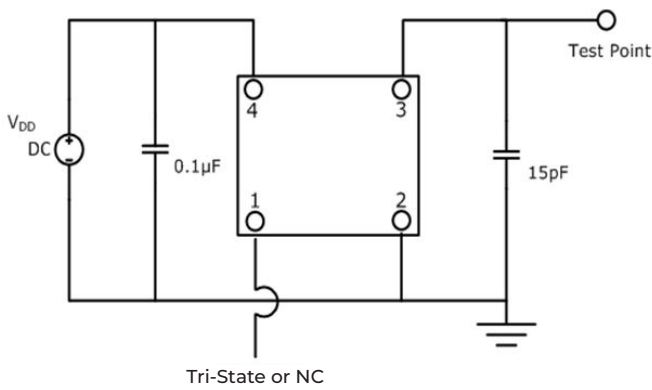
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



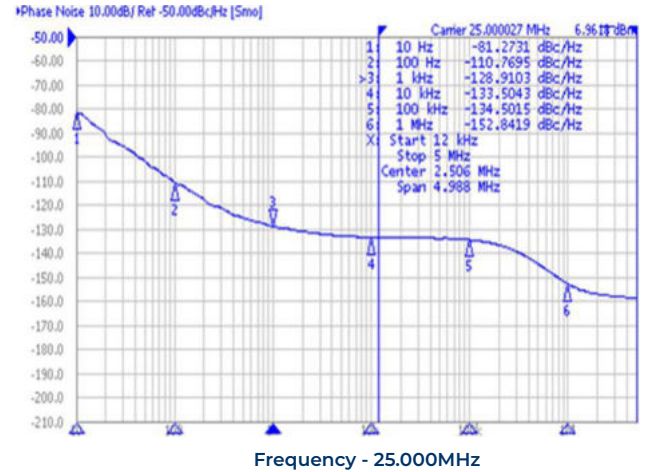
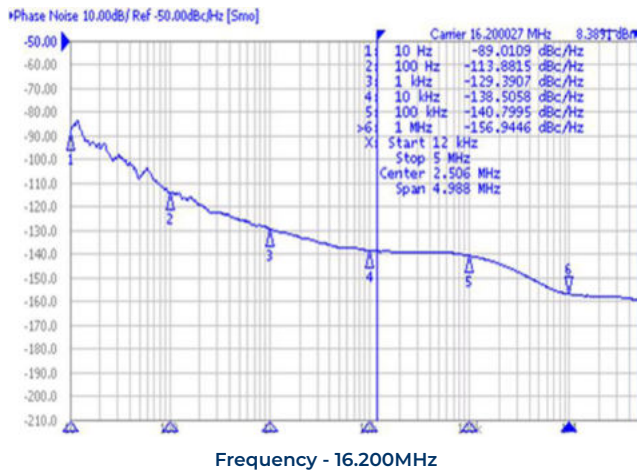
PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	NC
6	V _{DD}

Test Circuit (CMOS)

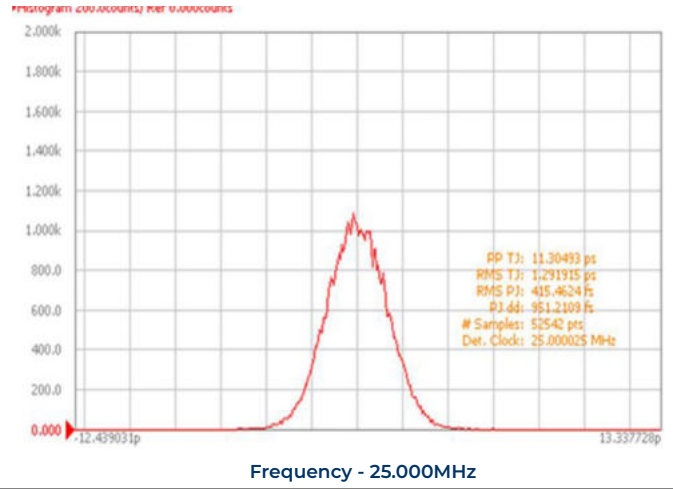
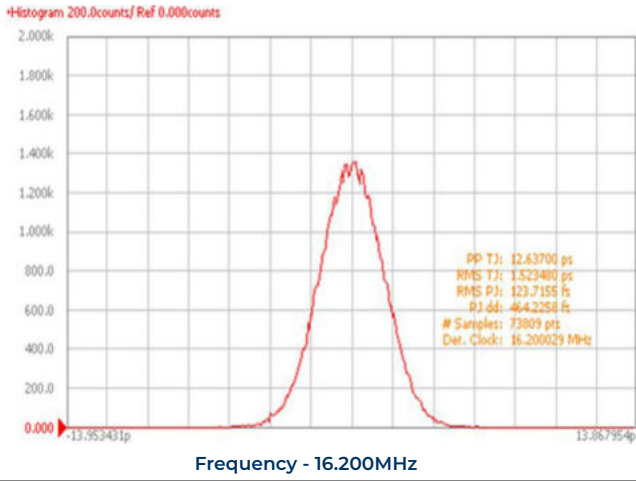
Waveform (CMOS)



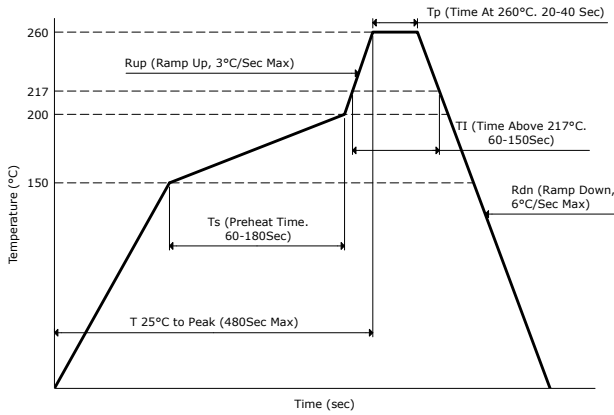
Typical Phase Noise Performance (Measured By Agilent E5052A)



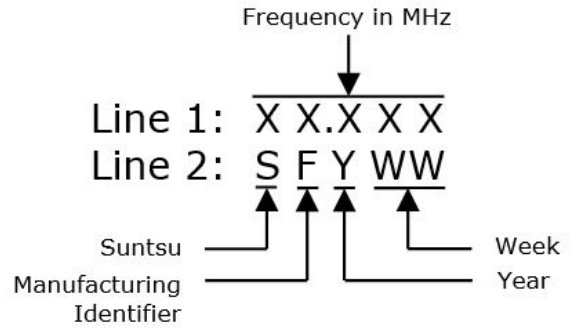
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



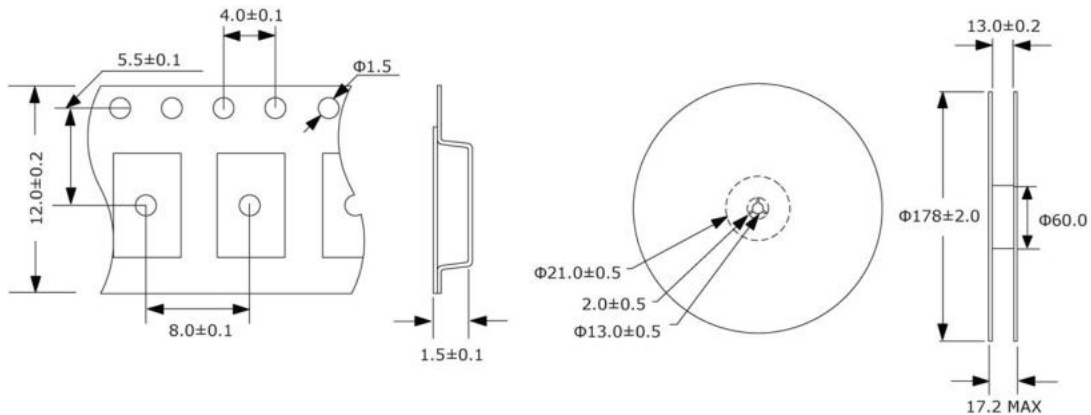
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

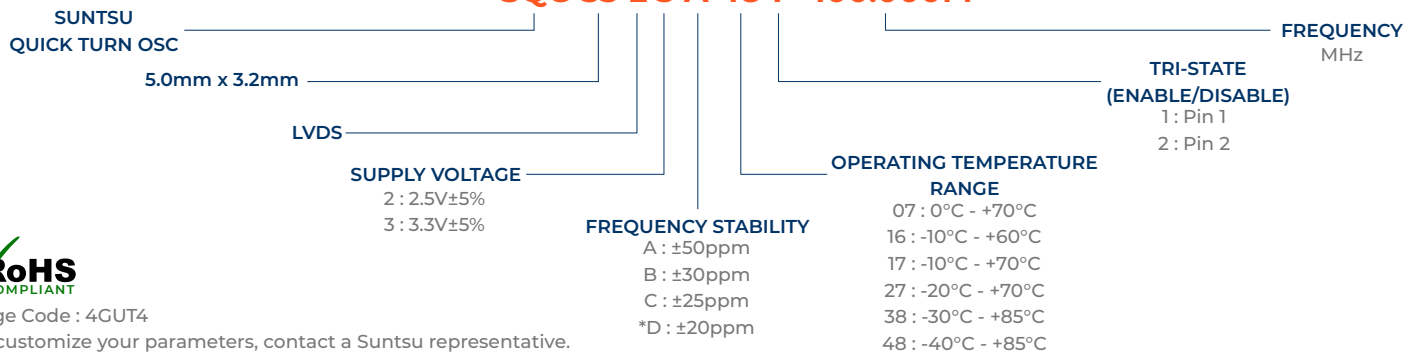
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Programmed Oscillator
• Tape and Reel

Applications
• Micro Processors
• FPGA
• Storage Area/Networking
• Digital Video
• SONET/SDH


Part Numbering Guide
SQG 53 L 3 A 48 1 - 100.000M


Cage Code : 4GUT4

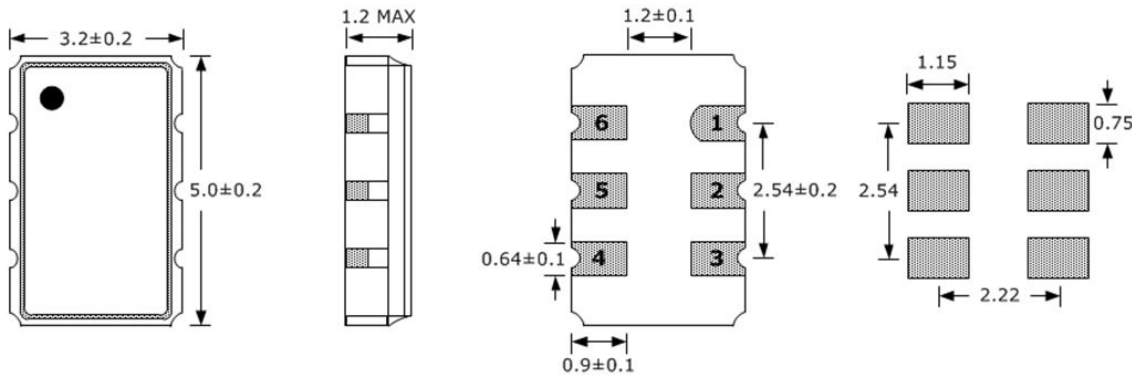
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			65	
Current (I _{DD}) - 3.3V option	mA			70	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	330	454	
Differential Output Error (pV _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (pV _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.7	1.5	

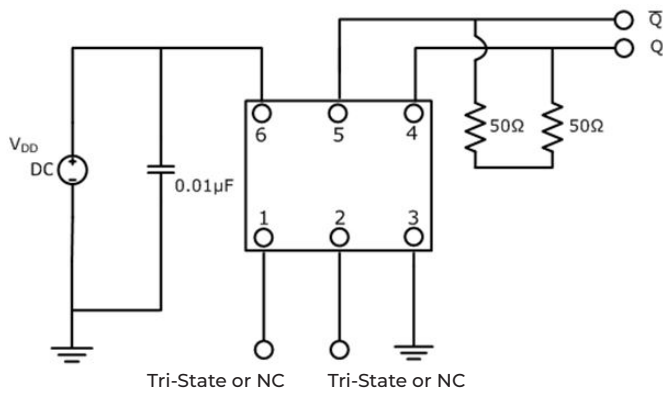
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

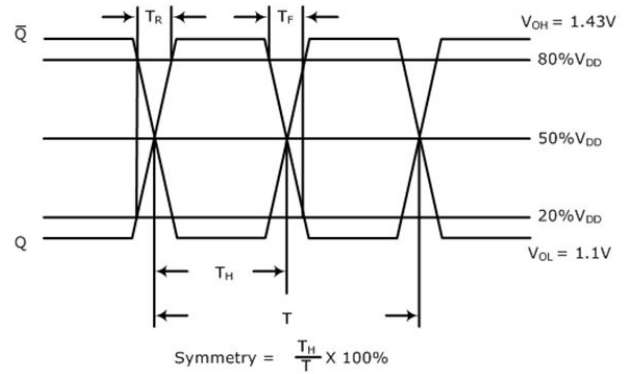


PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

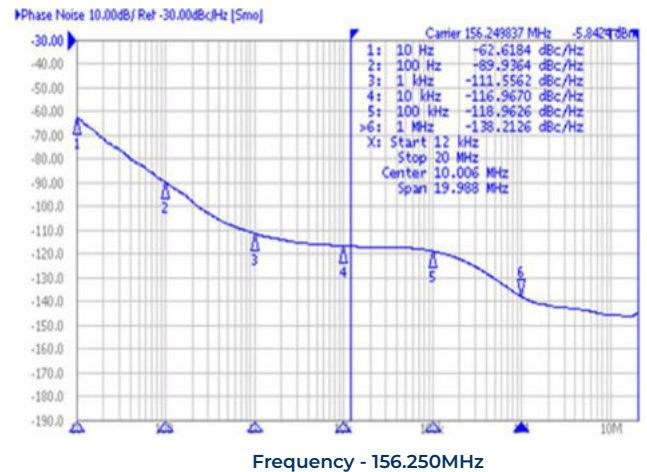
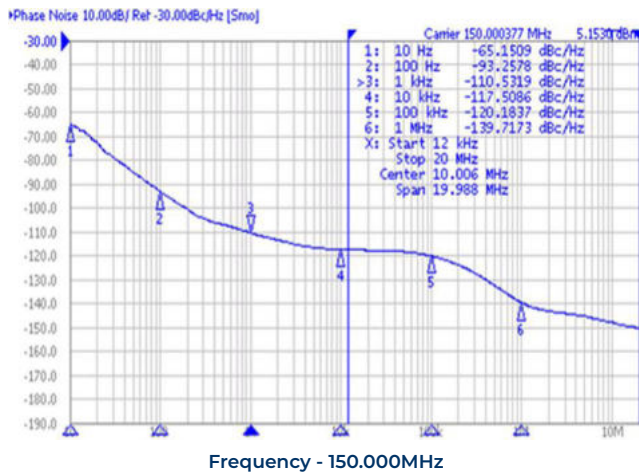
Test Circuit (LVDS)



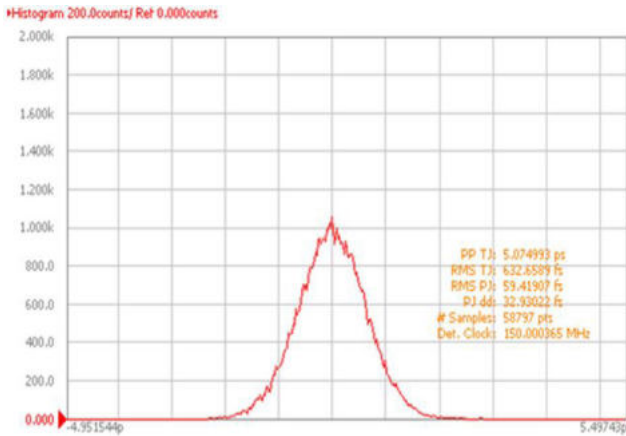
Waveform (LVDS)



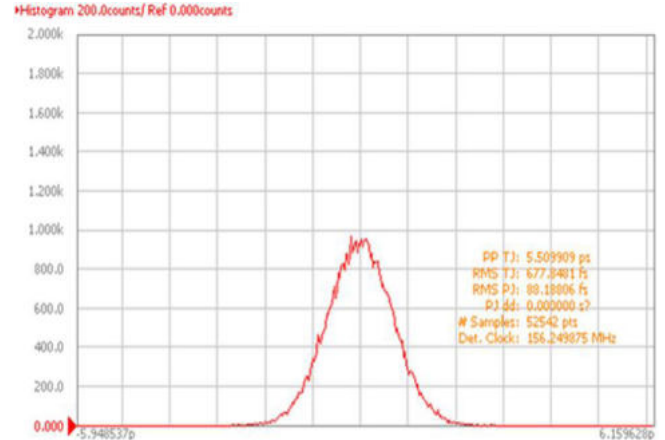
Typical Phase Noise Performance (Measured By Agilent E5052A)



Typical Jitter Performance (Measured By Agilent E5052A)

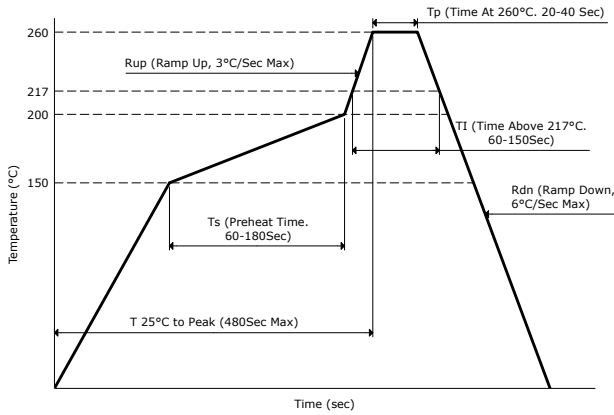


Frequency - 150.000MHz

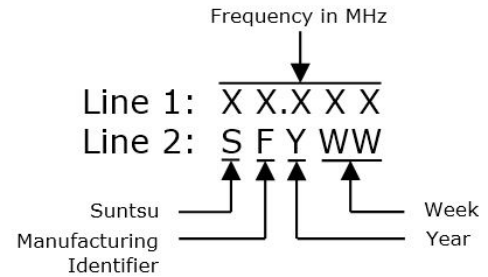


Frequency - 156.250MHz

Reflow Profile



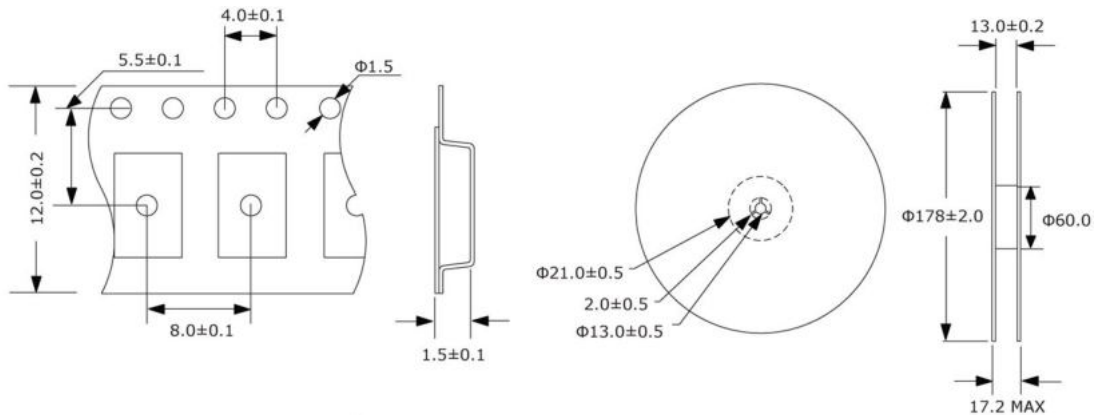
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

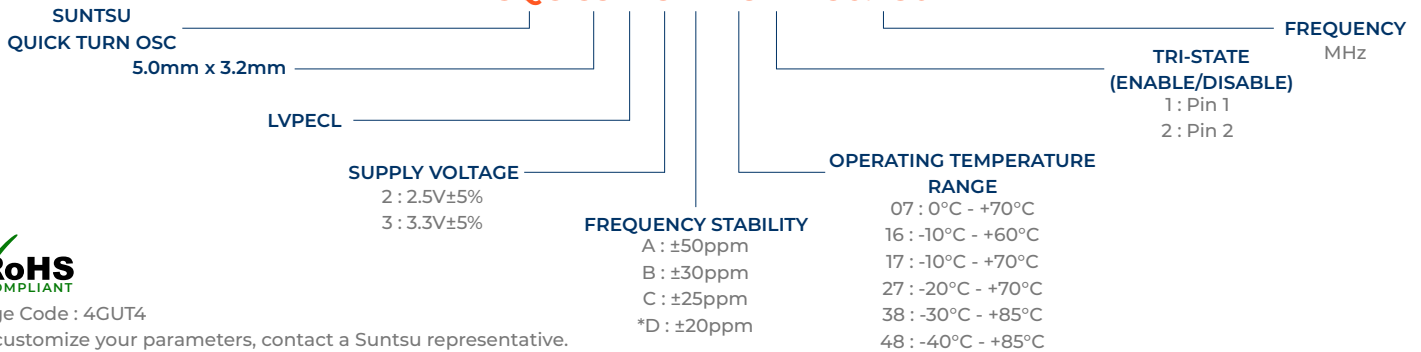
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVPECL
• Programmed Oscillator
• Tape and Reel

Applications
• Micro Processors
• FPGA
• Storage Area/Networking
• Digital Video
• SONET/SDH


Part Numbering Guide
SQG 53 P 3 A 48 1 - 156.250M


Cage Code : 4GUT4

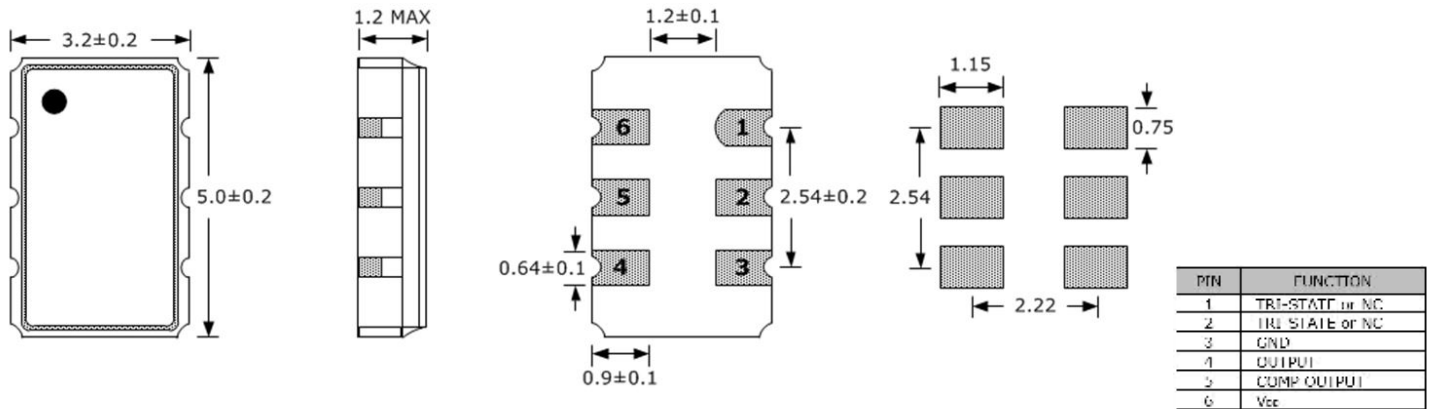
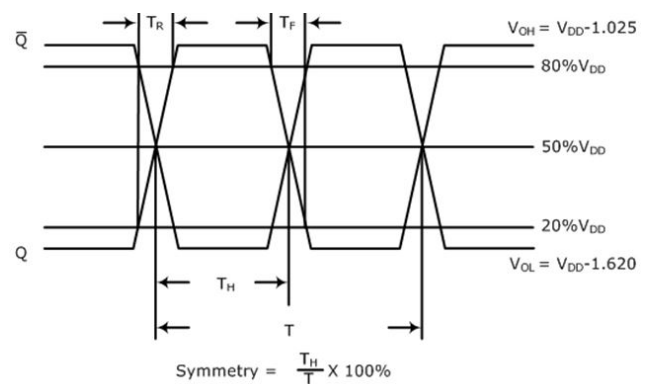
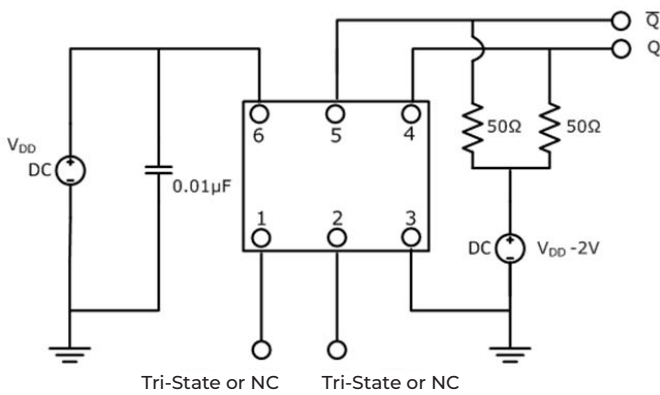
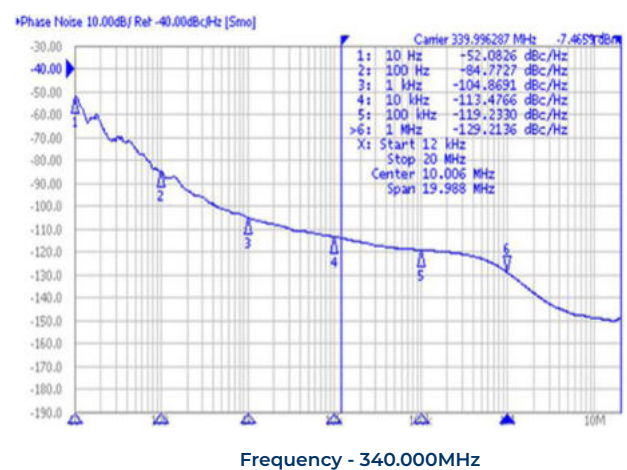
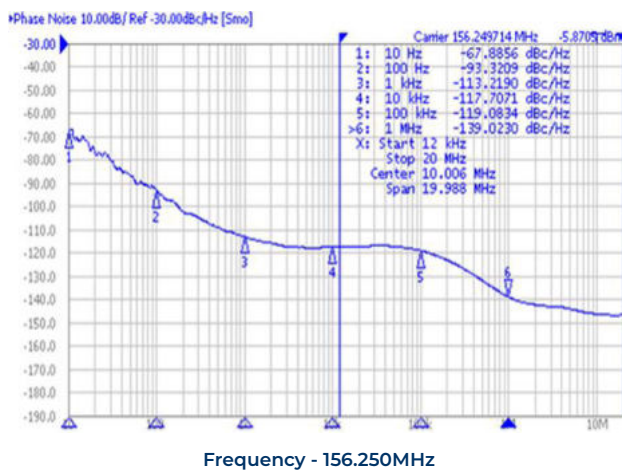
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

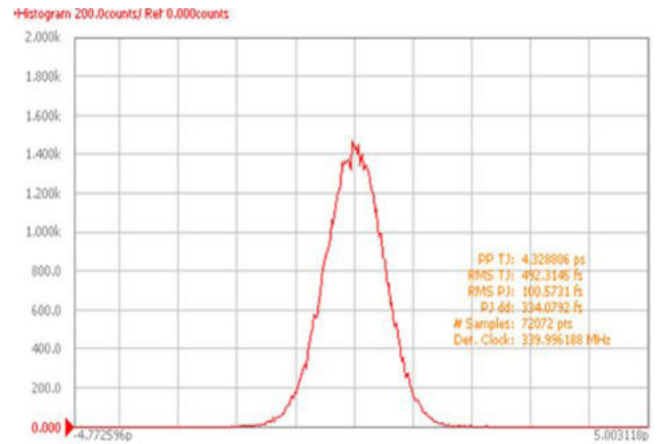
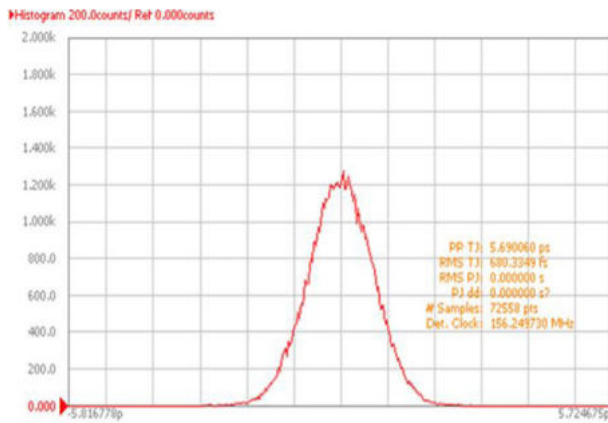
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			65	
Current (I _{DD}) - 3.3V option	mA			70	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	V	V _{DD} -1.025			
Output Logic Levels Low (V _{OL})	V			V _{DD} -1.62	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.7	1.5	

Outline Drawing & Land Pattern

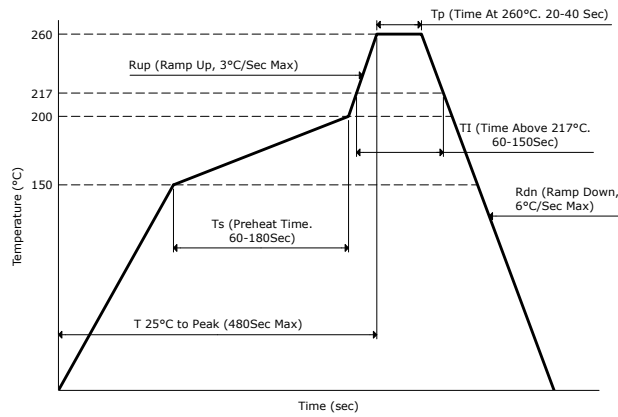
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.


Test Circuit (LVPECL)
Waveform (LVPECL)

Typical Phase Noise Performance (Measured By Agilent E5052A)


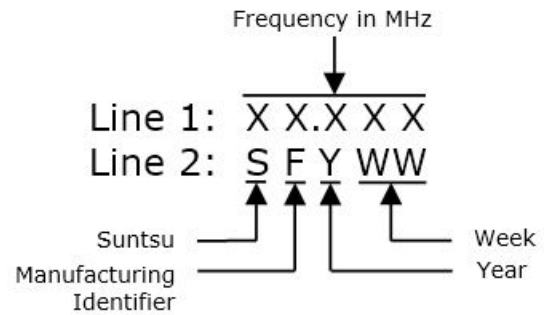
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



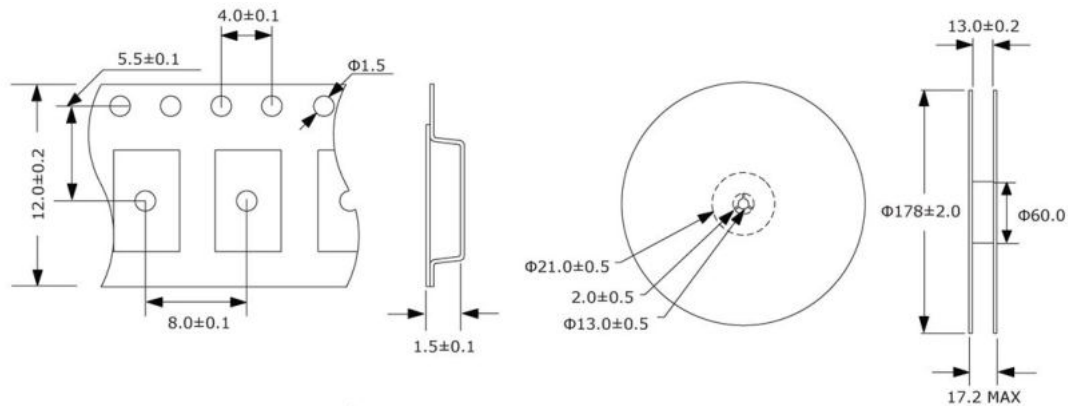
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

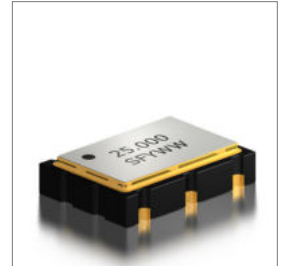
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> • ± 20ppm (Frequency Stability) Available • Wide Frequency Range • CMOS • Programmed Oscillator • Tape and Reel

Applications
<ul style="list-style-type: none"> • Micro Processors • FPGA • Storage Area/Networking • Digital Video • Portable Computers



Part Numbering Guide

SQG 75 C 3 A 48 1 - 25.000M

<p>SUNTSU QUICK TURN OSC 7.0mm x 5.0mm</p>	<p>CMOS</p>	<p>SUPPLY VOLTAGE 2 : 2.5V\pm5% 3 : 3.3V\pm5%</p>	<p>FREQUENCY STABILITY A : ± 50ppm B : ± 30ppm C : ± 25ppm *D : ± 20ppm</p>	<p>OPERATING TEMPERATURE RANGE 07 : 0°C - +70°C 16 : -10°C - +60°C 17 : -10°C - +70°C 27 : -20°C - +70°C 38 : -30°C - +85°C 48 : -40°C - +85°C</p>	<p>FREQUENCY MHz TRI-STATE (ENABLE/DISABLE) BLANK : No Connection 1 : Pin 1 2 : Pin 2</p>
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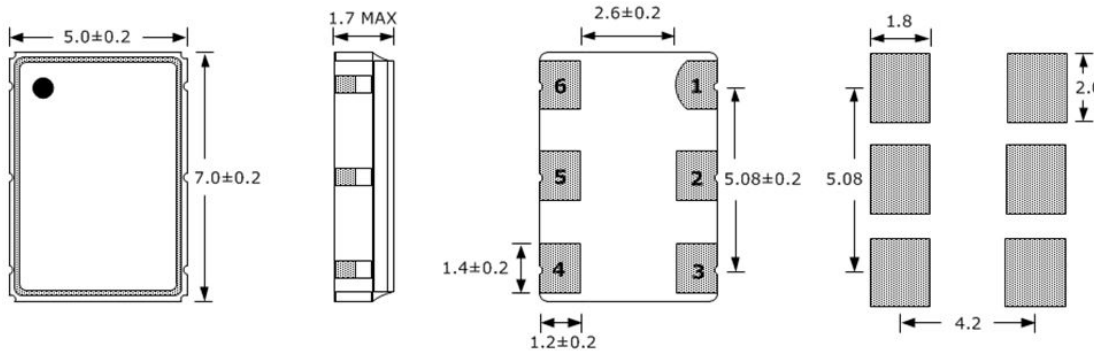
RoHS COMPLIANT

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		250	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			35	
Current (I _{DD}) - 3.3V option	mA			45	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			3	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

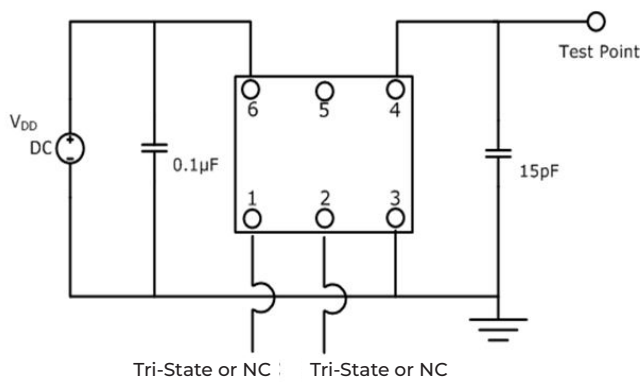
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

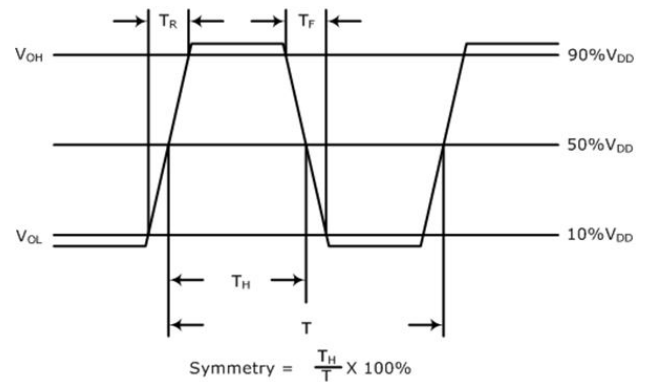


PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	NC
6	V _{DD}

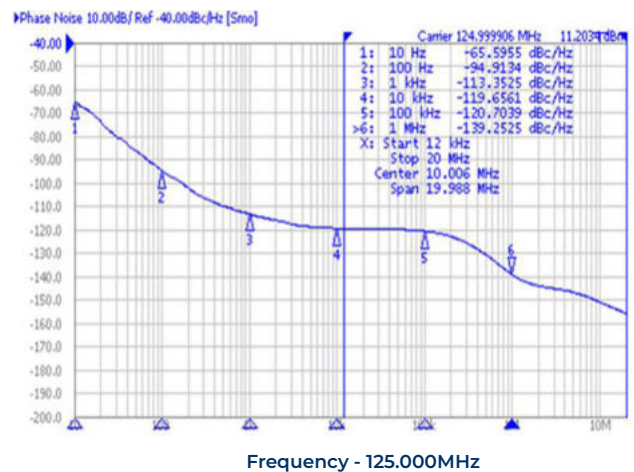
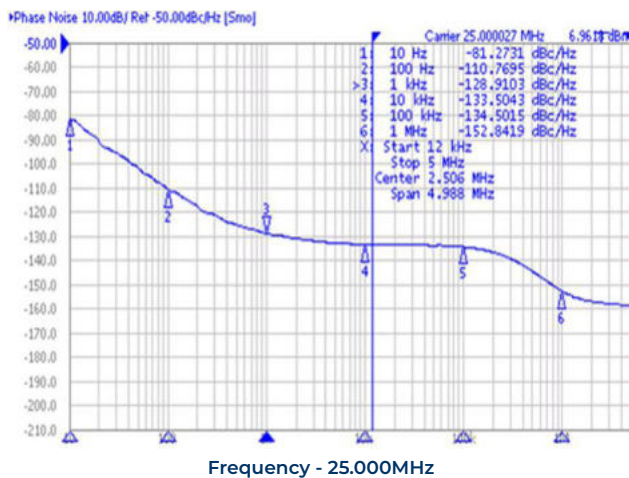
Test Circuit (CMOS)



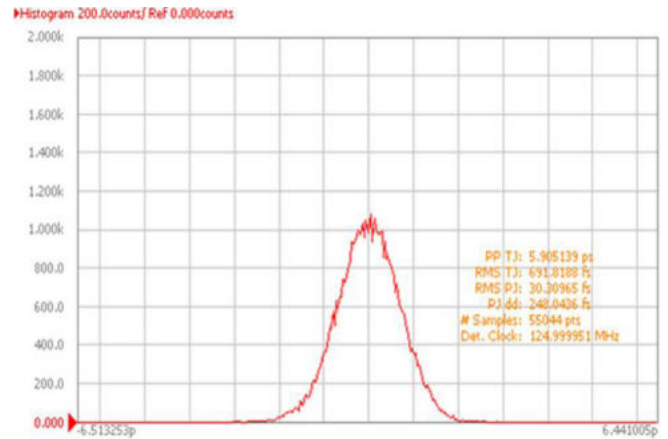
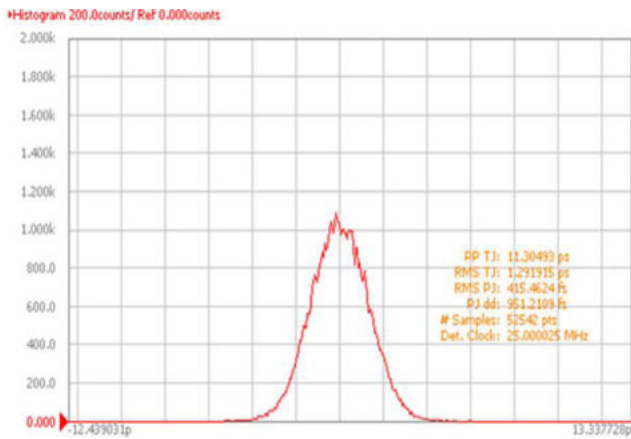
Waveform (CMOS)



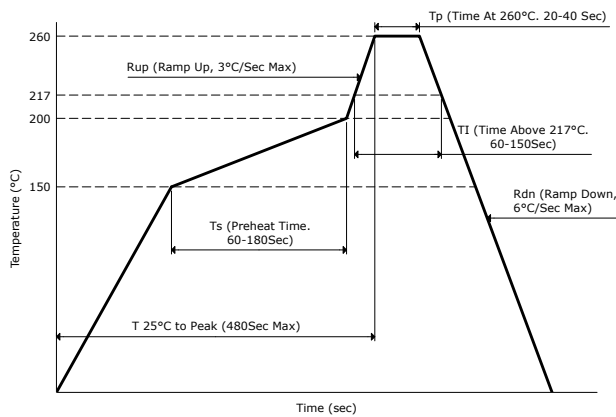
Typical Phase Noise Performance (Measured By Agilent E5052A)



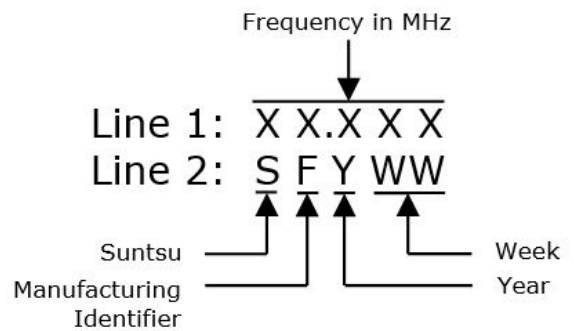
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



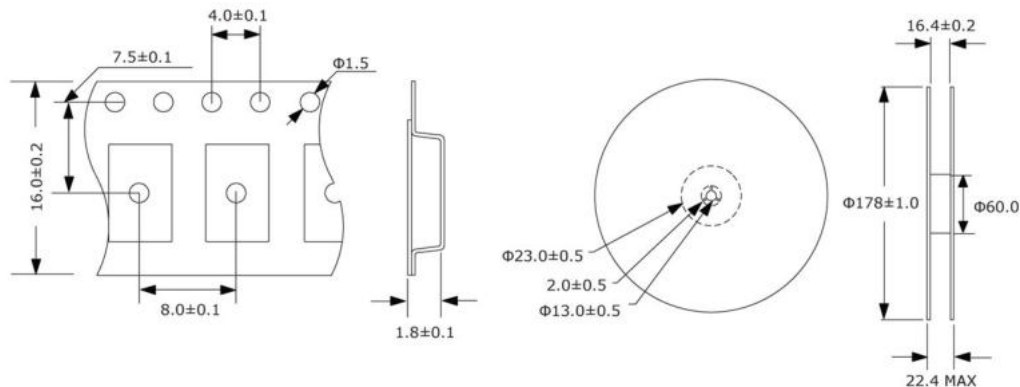
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

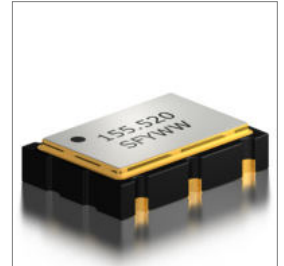
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Programmed Oscillator
• Tape and Reel

Applications
• Micro Processors
• FPGA
• Storage Area/Networking
• Digital Video
• SONET/SDH



Part Numbering Guide

SQG 75 L 3 A 48 1 - 155.520M

SUNTSU QUICK TURN OSC 7.0mm x 5.0mm LVDS SUPPLY VOLTAGE 2 : 2.5V \pm 5% 3 : 3.3V \pm 5%	FREQUENCY STABILITY A : ± 50 ppm B : ± 30 ppm C : ± 25 ppm *D : ± 20 ppm	OPERATING TEMPERATURE RANGE 07 : 0°C - +70°C 16 : -10°C - +60°C 17 : -10°C - +70°C 27 : -20°C - +70°C 38 : -30°C - +85°C 48 : -40°C - +85°C	FREQUENCY MHz TRI-STATE (ENABLE/DISABLE) 1 : Pin 1 2 : Pin 2
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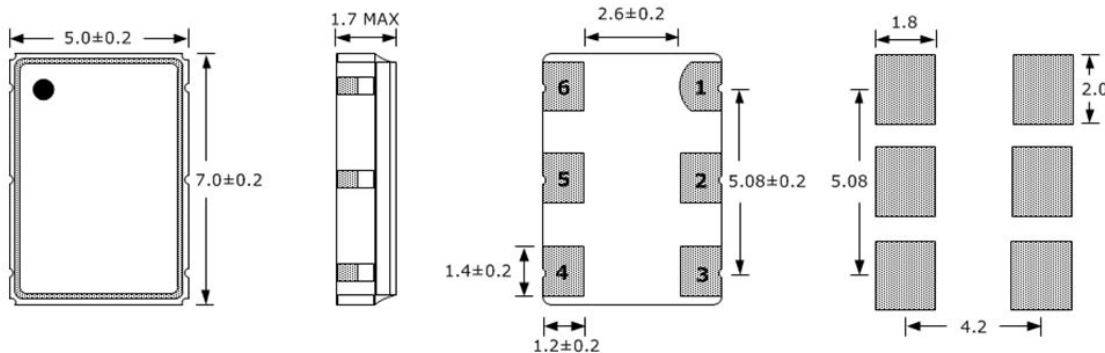
RoHS COMPLIANT

Cage Code : 4GUT4
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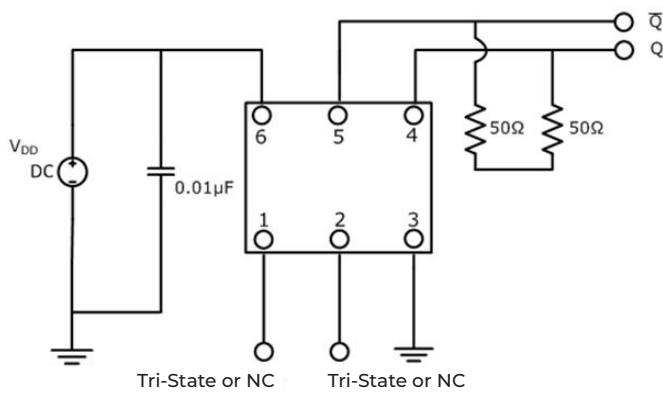
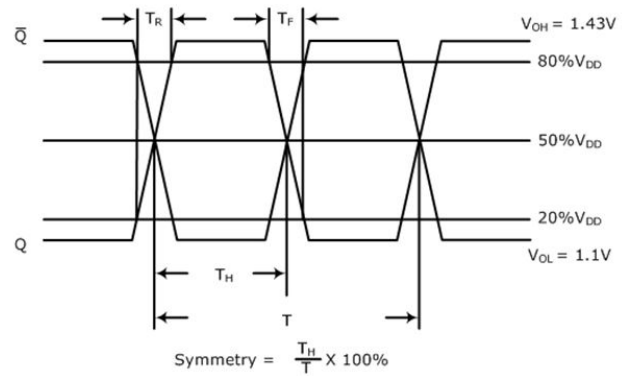
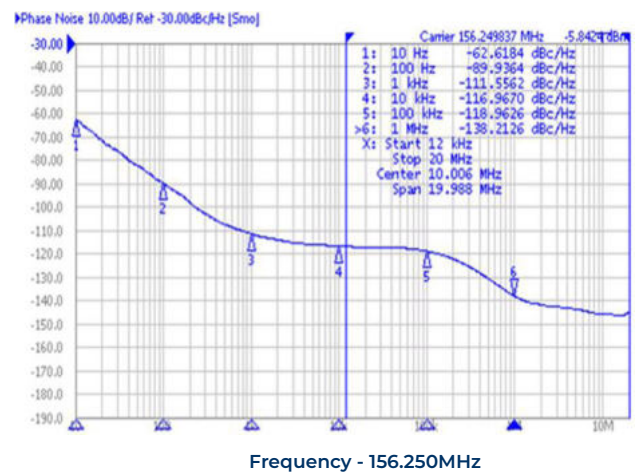
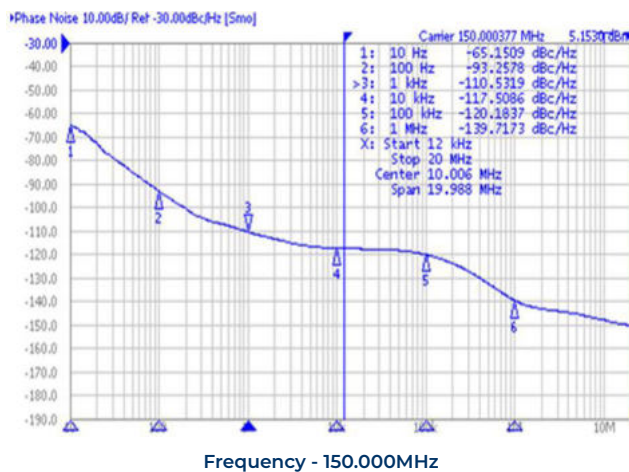
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			50	
Current (I _{DD}) - 3.3V option	mA			60	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	330	454	
Differential Output Error (pV _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (pV _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.7	1.5	

Outline Drawing & Land Pattern

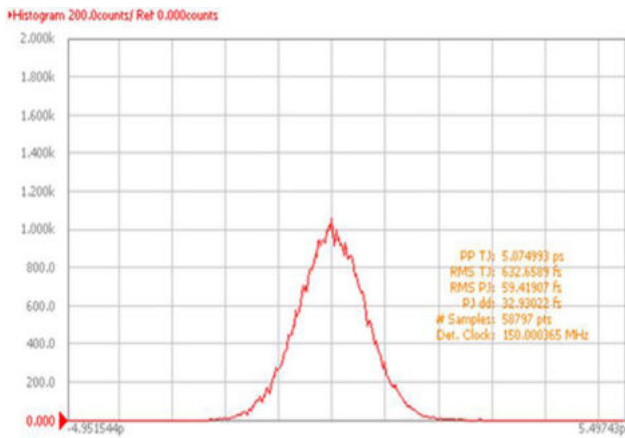
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



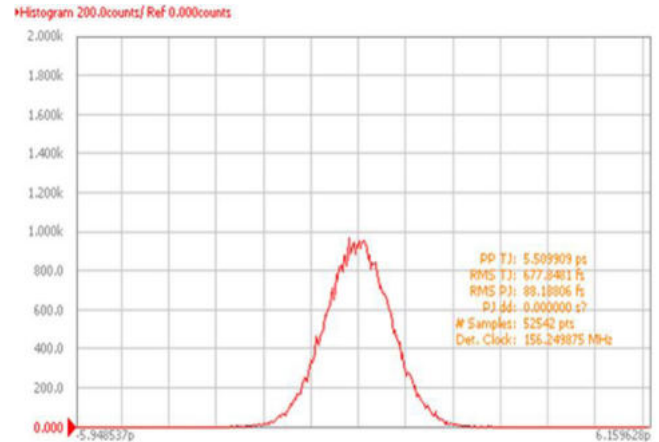
PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVDS)

Waveform (LVDS)

Typical Phase Noise Performance (Measured By Agilent E5052A)


Typical Jitter Performance (Measured By Agilent E5052A)

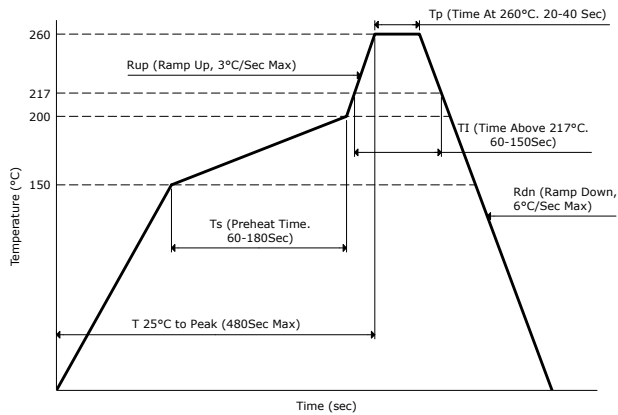


Frequency - 150.000MHz

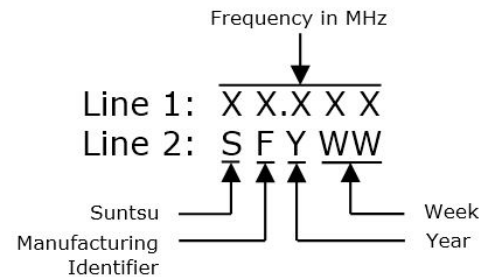


Frequency - 156.250MHz

Reflow Profile



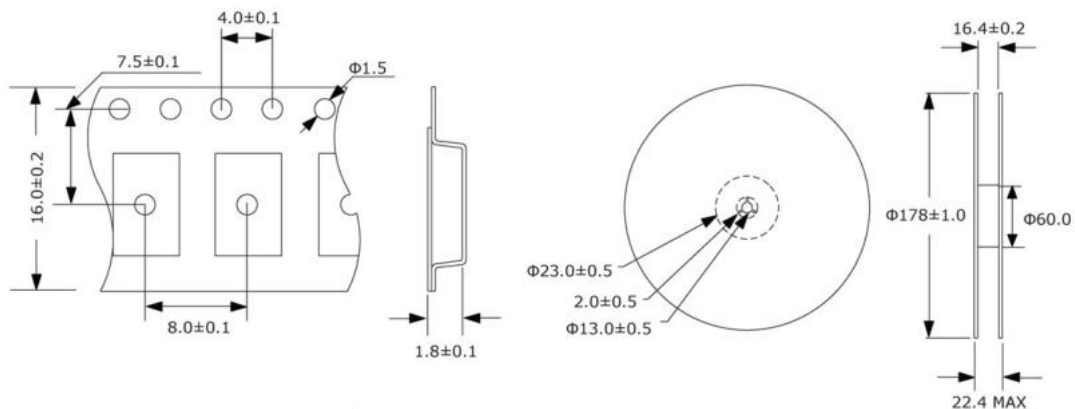
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

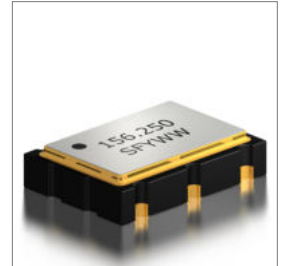
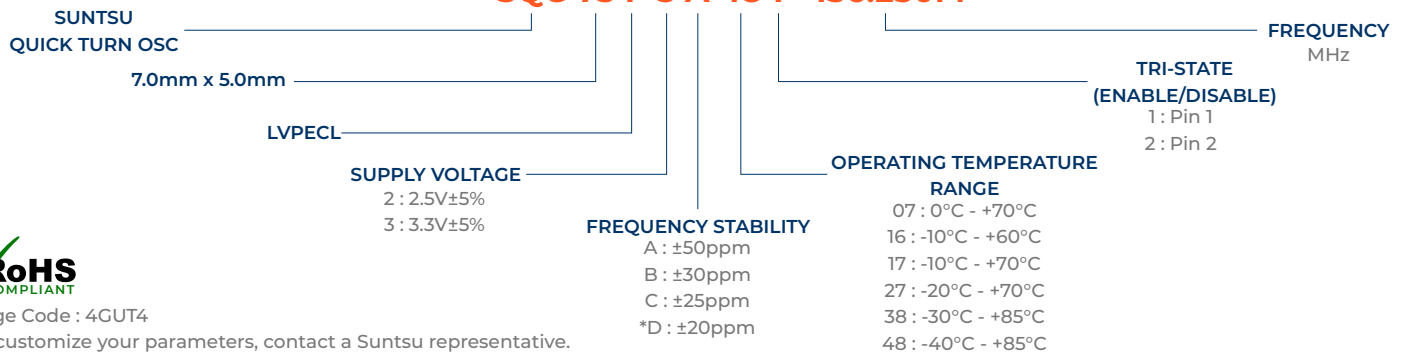
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVPECL
• Programmed Oscillator
• Tape and Reel

Applications
• Micro Processors
• FPGA
• Storage Area/Networking
• Digital Video
• SONET/SDH


Part Numbering Guide
SQG 75 P 3 A 48 1 - 156.250M


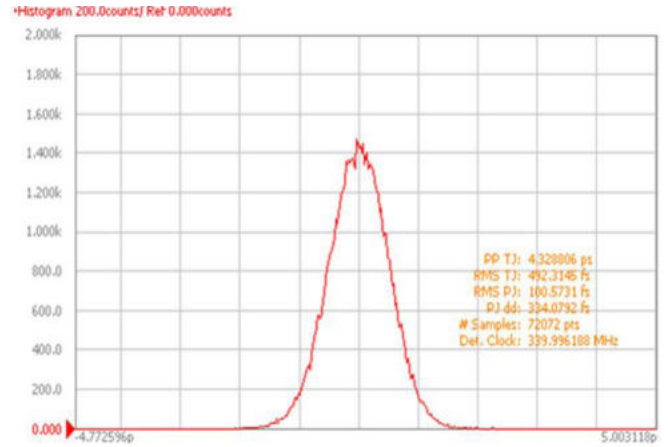
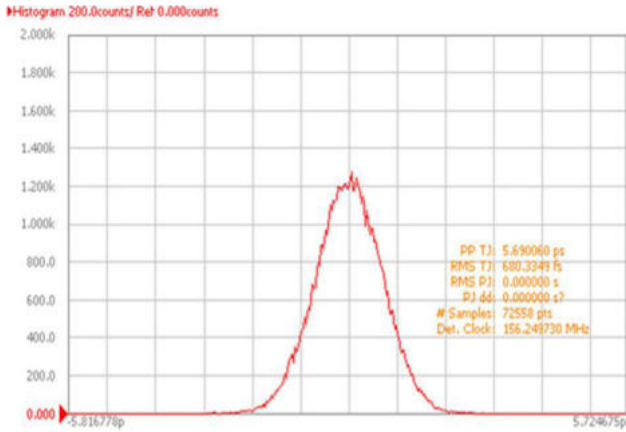
Cage Code : 4GUT4

To customize your parameters, contact a Suntsu representative.

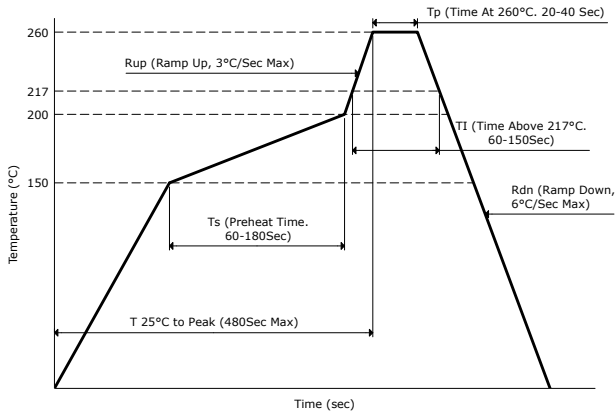
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	8		1500	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			65	
Current (I _{DD}) - 3.3V option	mA			70	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	V	V _{DD} -1.025			
Output Logic Levels Low (V _{OL})	V			V _{DD} -1.620	
Rise (TR) and Fall (TF) Time	ns			1	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.7	1.5	

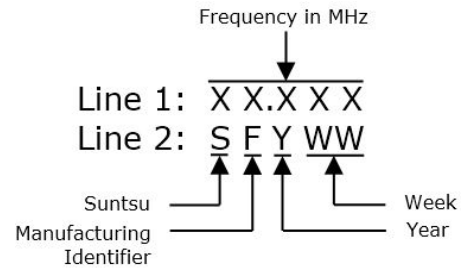
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



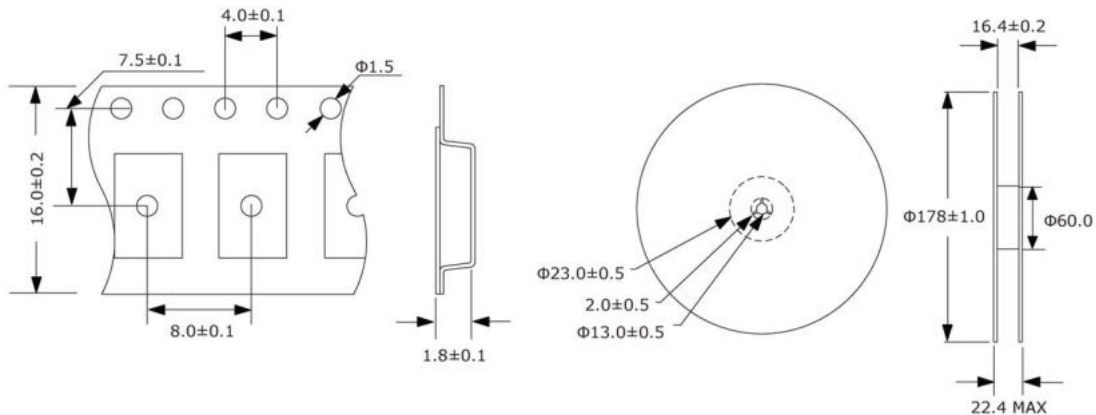
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

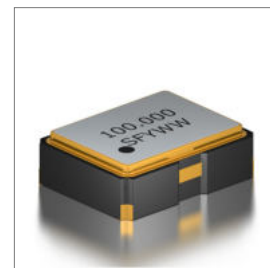
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> • ± 20ppm (Frequency Stability) Available • Ceramic Package • LVDS • Tape and Reel • Ultra Low Phase Jitter

Applications
<ul style="list-style-type: none"> • Fiber Channel • Gigabit Ethernet • PCI Express


Part Numbering Guide
SUO 22 L 3 A 48 1 - 100.000M

 SUNTSU ULTRA
LOW JITTER OSC

2.5mm x 2.0mm

LVDS

SUPPLY VOLTAGE

- 1 : 1.8V \pm 5%
- 2 : 2.5V \pm 5%
- 3 : 3.3V \pm 5%

FREQUENCY STABILITY

- A : ± 50 ppm
- B : ± 30 ppm
- C : ± 25 ppm
- *D : ± 20 ppm

 OPERATING TEMPERATURE
RANGE

- 07 : 0°C - +70°C
- 16 : -10°C - +60°C
- 17 : -10°C - +70°C
- 27 : -20°C - +70°C
- 38 : -30°C - +85°C
- 48 : -40°C - +85°C

 FREQUENCY
MHz

 TRI-STATE
(ENABLE/DISABLE)
1 : Pin 1
2 : Pin 2


Cage Code : 4GUT4

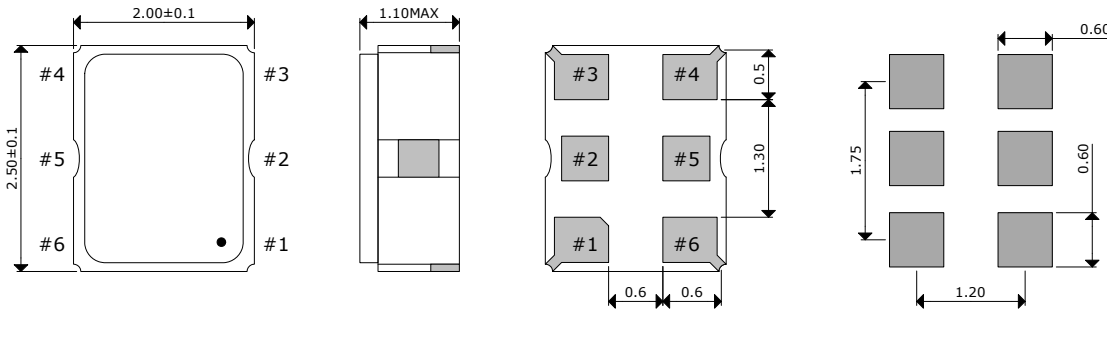
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	13.5		156.25	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V Option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD}) - 1.8V Option	mA			40	
Current (I _{DD}) - 2.5V Option	mA			40	
Current (I _{DD}) - 3.3V Option	mA			40	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	330	454	
Differential Output Error (ρ V _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (ρ V _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns			1	20% - 80% Output Swing Level
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 5MHz)	ps		0.6	1.0	Freq. <40.000M
Phase Jitter (12kHz ~ 20MHz)	ps		0.4	0.8	Freq. 40.000M - 124.999M
Phase Jitter (12kHz ~ 20MHz)	ps		0.1	0.2	Freq. 125.000M - 156.250M

Outline Drawing & Land Pattern

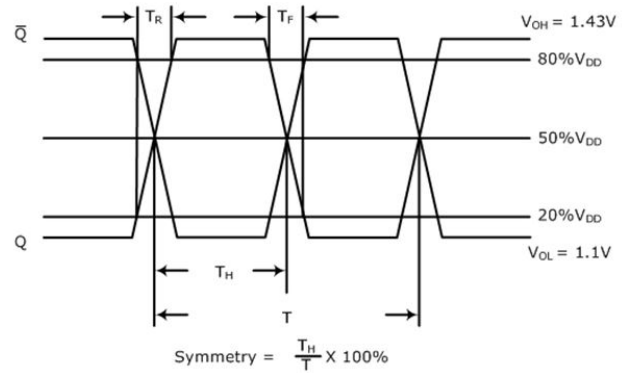
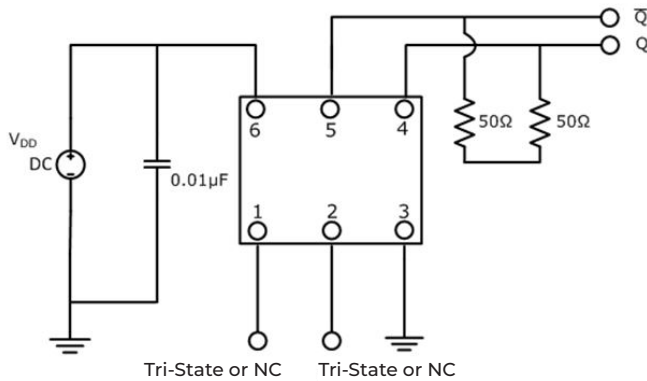
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



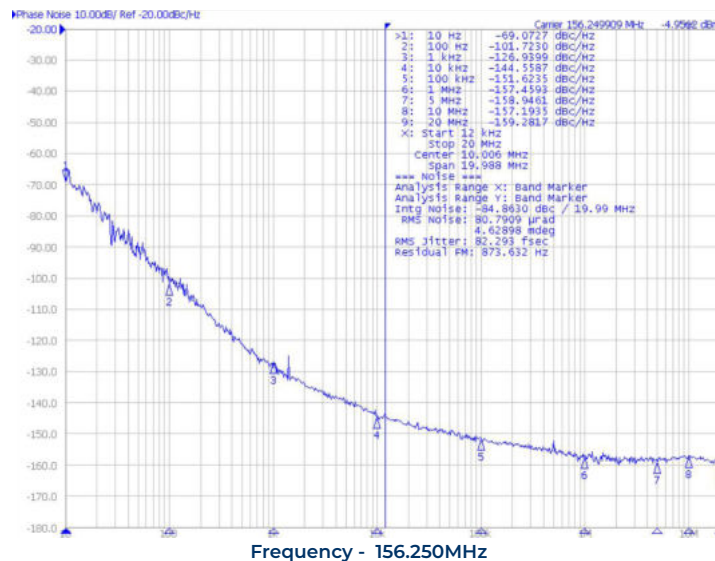
PIN	FUNCTION
1	TRI-STATE or NC
2	NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVDS)

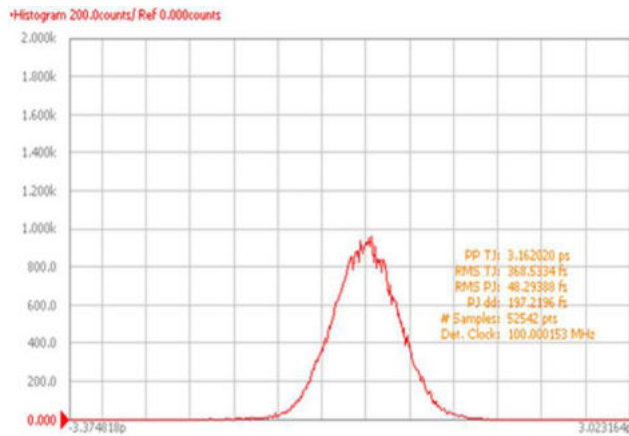
Waveform (LVDS)



Typical Phase Noise Performance (Measured By Agilent E5052A)

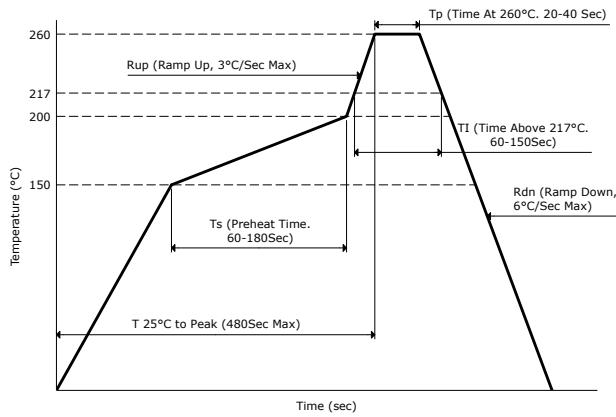


Typical Jitter Performance (Measured By Agilent E5052A)

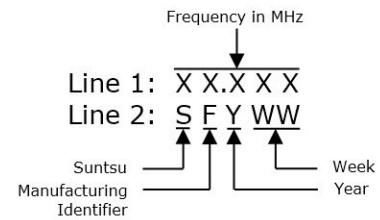


Frequency - 100.000MHz

Reflow Profile



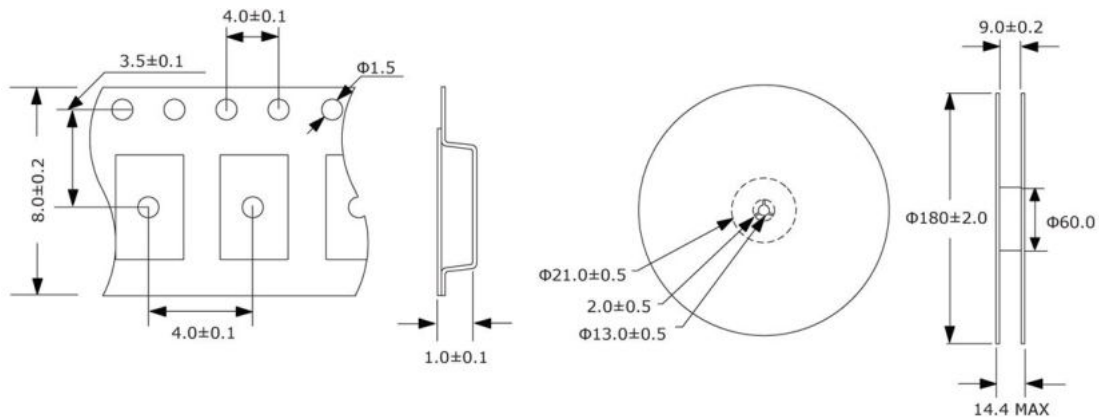
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

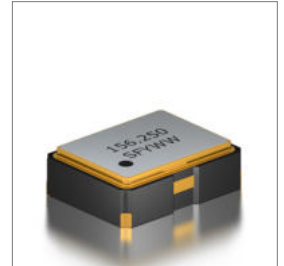
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVPECL
• Tape and Reel
• Ultra Low Phase Jitter

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express



Part Numbering Guide

SUO 22 P 3 A 48 1 - 156.250M

SUNTSU ULTRA LOW JITTER OSC

2.5mm x 2.0mm

LVPECL

SUPPLY VOLTAGE

2 : 2.5V \pm 5%

3 : 3.3V \pm 5%

FREQUENCY STABILITY

A : ± 50 ppm

B : ± 30 ppm

C : ± 25 ppm

*D : ± 20 ppm

FREQUENCY

MHz

TRI-STATE (ENABLE/DISABLE)

1 : Pin 1

2 : Pin 2

OPERATING TEMPERATURE RANGE

07 : 0°C - +70°C

16 : -10°C - +60°C

17 : -10°C - +70°C

27 : -20°C - +70°C

38 : -30°C - +85°C

48 : -40°C - +85°C

Cage Code : 4GUT4

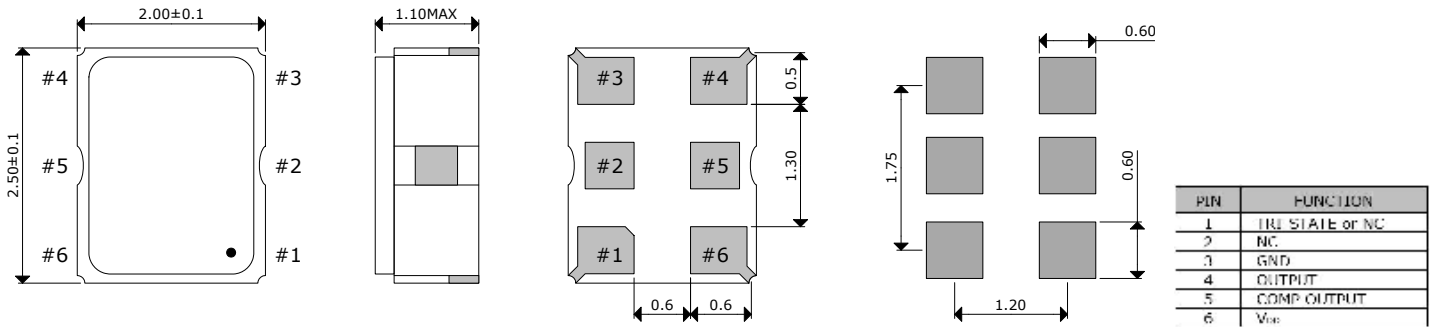
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	13.5		156.25	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			50	
Current (I _{DD}) - 3.3V option	mA			50	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	V	V _{DD} -1.025			
Output Logic Levels Low (V _{OL})	V			V _{DD} -1.62	
Rise (TR) and Fall (TF) Time	ns			1.0	
Symmetry (Duty Cycle)	%	45	50	55	20% - 80% Output Swing Level
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 5MHz)	ps		0.6	1.0	Freq. <40.000M
Phase Jitter (12kHz ~ 20MHz)	ps		0.4	0.8	Freq. 40.000M - 124.999M
Phase Jitter (12kHz ~ 20MHz)	ps		0.1	0.2	Freq. 125.000M - 156.250M

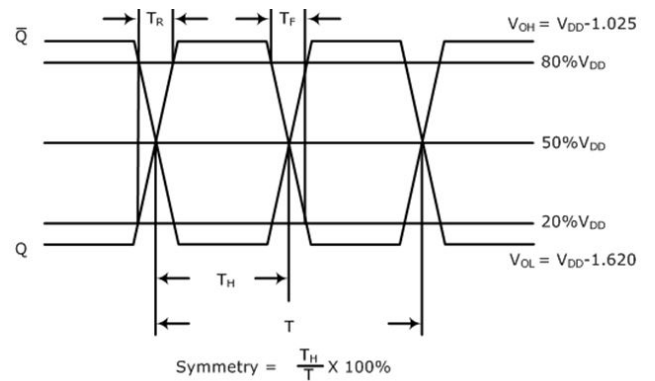
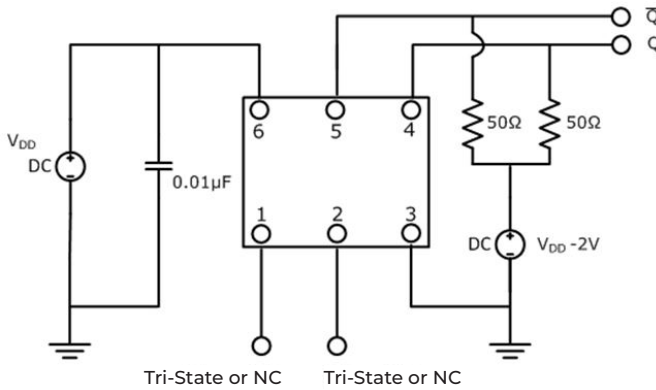
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

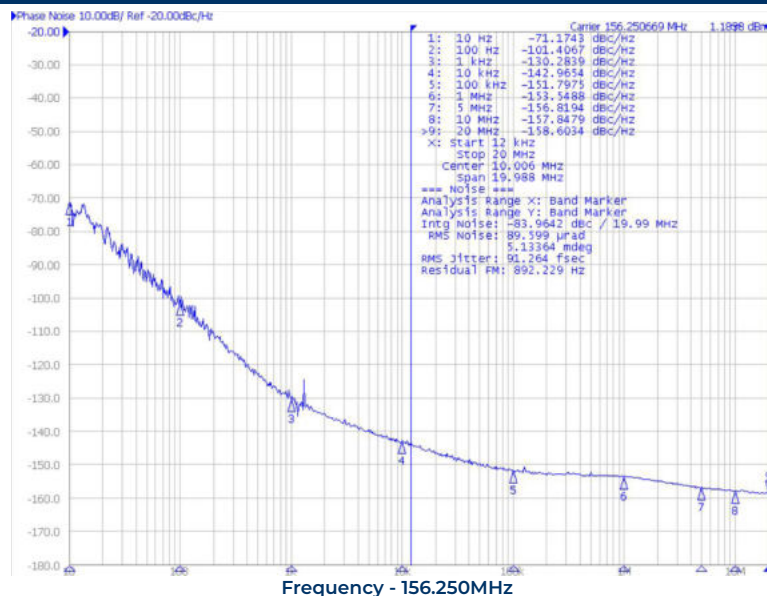


Test Circuit (LVPECL)

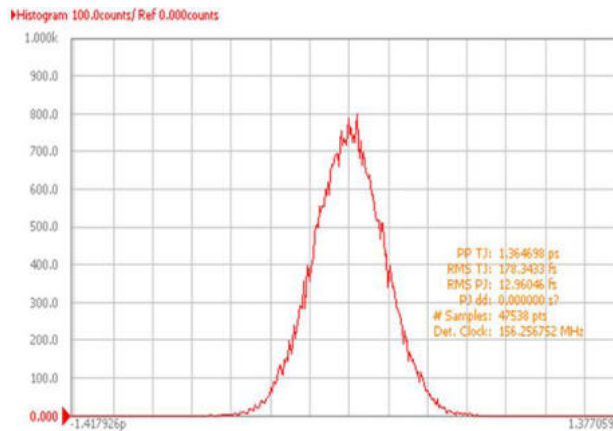
Waveform (LVPECL)



Typical Phase Noise Performance (Measured By Agilent E5052A)

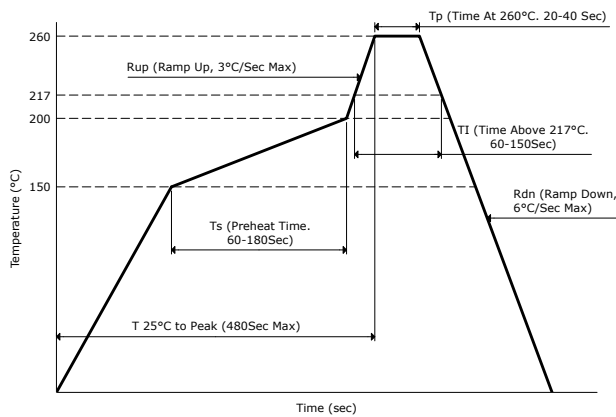


Typical Jitter Performance (Measured By Agilent E5052A)

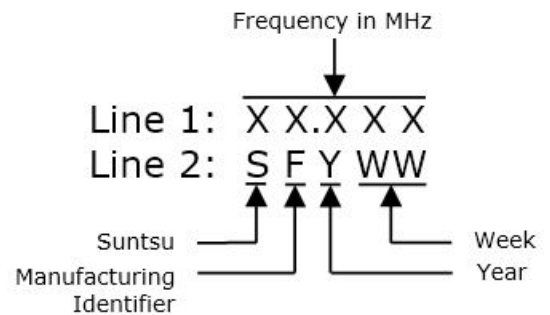


Frequency - 156.250MHz

Reflow Profile



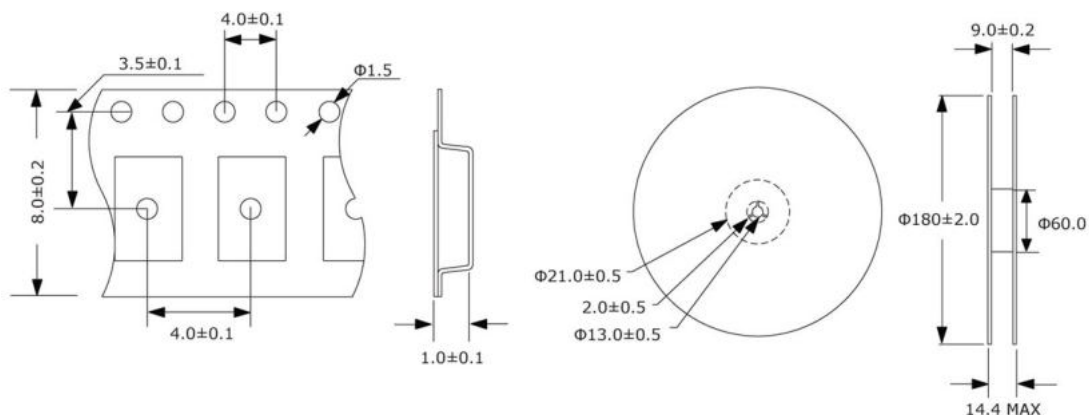
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

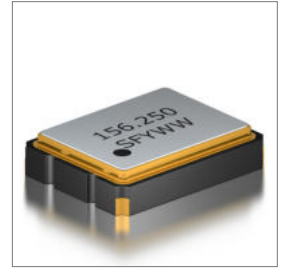
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Ultra Low Phase Jitter (67fs Typical)
• Tape and Reel
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express



Part Numbering Guide

SUO 32 L 3 A 48 1 - 156.250M

SUNTSU ULTRA LOW JITTER OSC
3.2mm x 2.5mm

LVDS

SUPPLY VOLTAGE
 1 : 1.8V \pm 5%
 2 : 2.5V \pm 5%
 3 : 3.3V \pm 5%

FREQUENCY STABILITY
 A : ± 50 ppm
 B : ± 30 ppm
 C : ± 25 ppm
 *D : ± 20 ppm

OPERATING TEMPERATURE RANGE
 07 : 0°C - +70°C
 16 : -10°C - +60°C
 17 : -10°C - +70°C
 27 : -20°C - +70°C
 38 : -30°C - +85°C
 48 : -40°C - +85°C

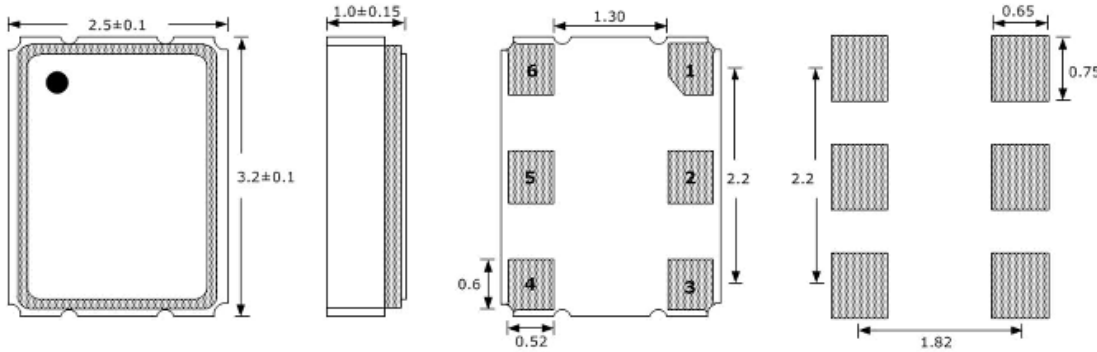
FREQUENCY MHz
TRI-STATE (ENABLE/DISABLE)
 BLANK : No Connection
 1 : Pin 1

Cage Code : 4GUT4
 To customize your parameters, contact a Suntsu representative.
 * For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	135~175MHz(1.8V), 100~320MHz(2.5&3.3V)
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V Option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA			35	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	350	454	
Differential Output Error (pV _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (pV _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns		0.25	0.5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5.0	
Phase Jitter (12kHz ~ 20MHz)	fs		67	100	

Outline Drawing & Land Pattern

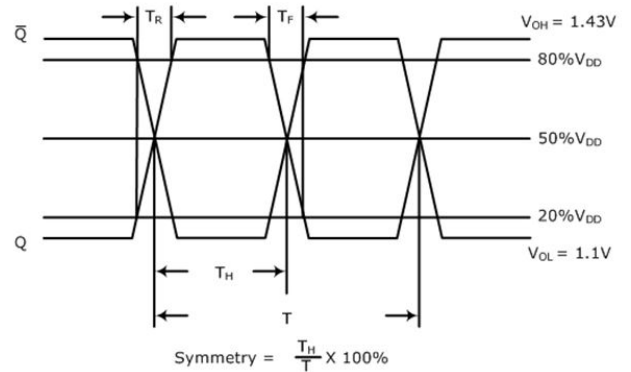
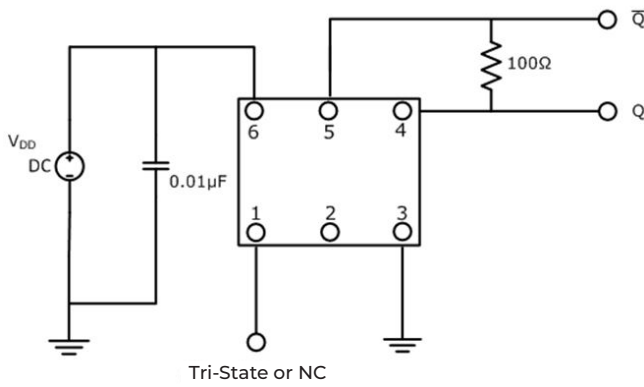
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



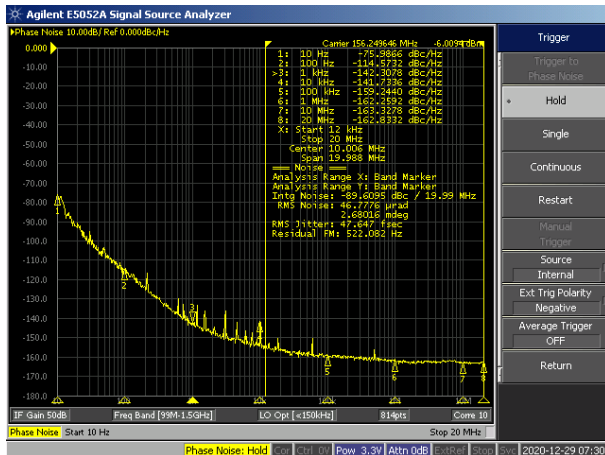
PIN	FUNCTION
1	TRI-STATE or NC
2	NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVDS)

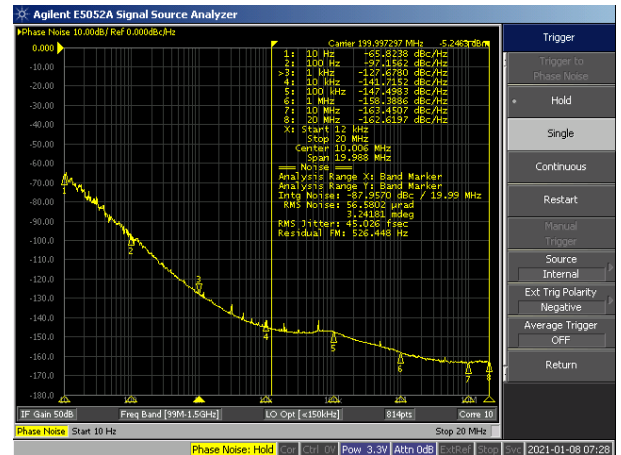
Waveform (LVDS)



Typical Phase Noise Performance (Measured By Agilent E5052A)

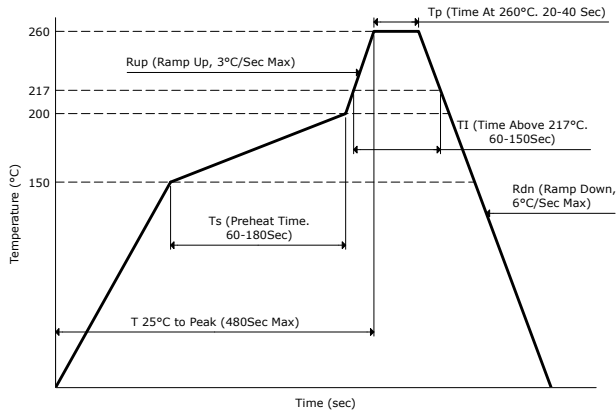


Frequency - 156.250MHz

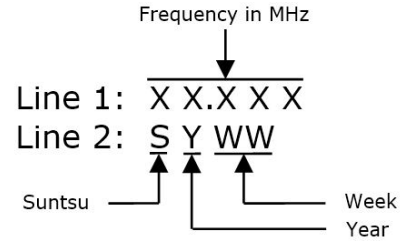


Frequency - 200.000MHz

Reflow Profile



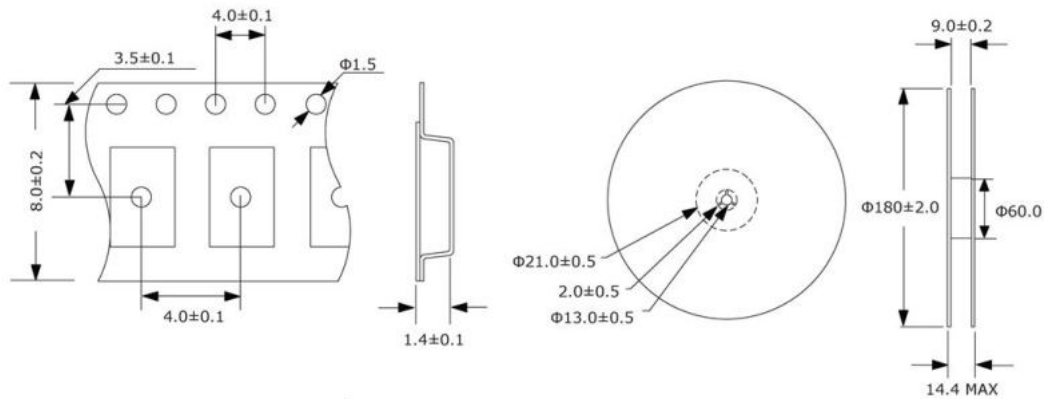
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

3,000pcs/Reel



Environmental Specifications

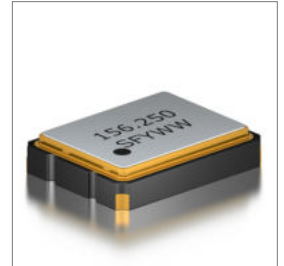
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVPECL
• Ultra Low Phase Jitter (47fs Typical)
• Tape and Reel
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express


Part Numbering Guide
SUO 32 P 3 A 48 1 - 156.250M

 SUNTSU ULTRA
 LOW JITTER OSC

3.2mm x 2.5mm

LVPECL

SUPPLY VOLTAGE

 2 : 2.5V \pm 5%

 3 : 3.3V \pm 5%

FREQUENCY STABILITY

 A : ± 50 ppm

 B : ± 30 ppm

 C : ± 25 ppm

 *D : ± 20 ppm

OPERATING TEMPERATURE

RANGE

07 : 0°C - +70°C

16 : -10°C - +60°C

17 : -10°C - +70°C

27 : -20°C - +70°C

38 : -30°C - +85°C

48 : -40°C - +85°C

 FREQUENCY
 MHz

TRI-STATE

 (ENABLE/DISABLE)
 BLANK : No Connection

1 : Pin 1



Cage Code : 4GUT4

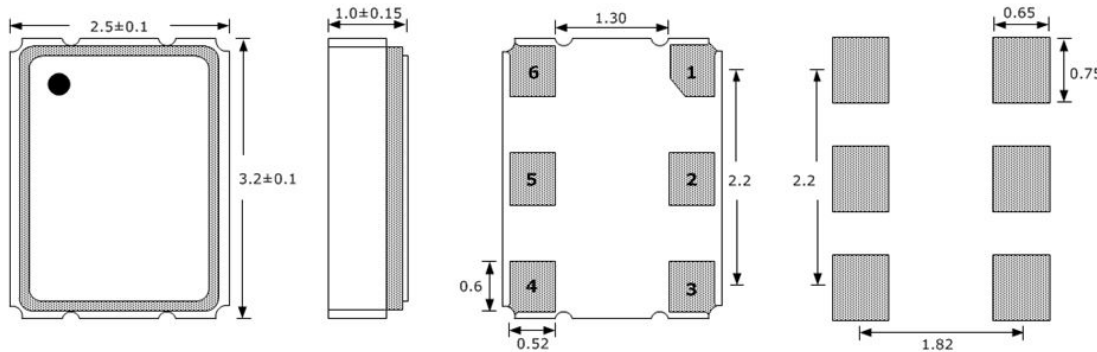
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA			70	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH} at 2.5V)	V	1.415		1.760	
Output Logic Levels Low (V _{OL} at 2.5V)	V	0.670		1.195	
Output Logic Levels High (V _{OH} at 3.3V)	V	2.215		2.420	
Output Logic Levels Low (V _{OL} at 3.3V)	V	1.470		1.745	
Rise (TR) and Fall (TF) Time	ns		0.15	0.3	Measured at 20% to 80% of Waveform
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5	
Phase Jitter (12kHz ~ 20MHz)	fs		47	100	

Outline Drawing & Land Pattern

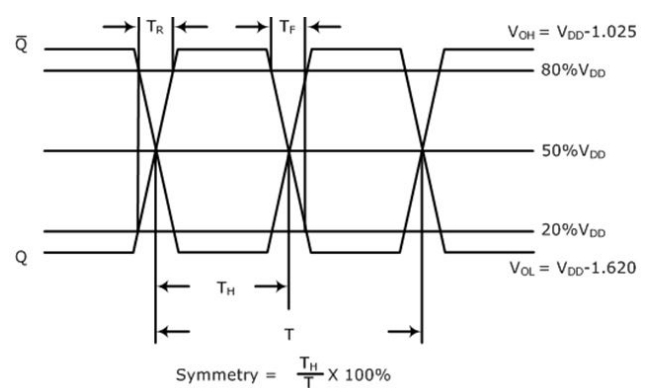
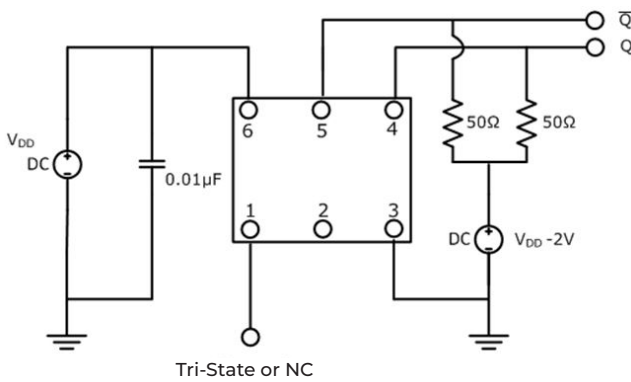
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



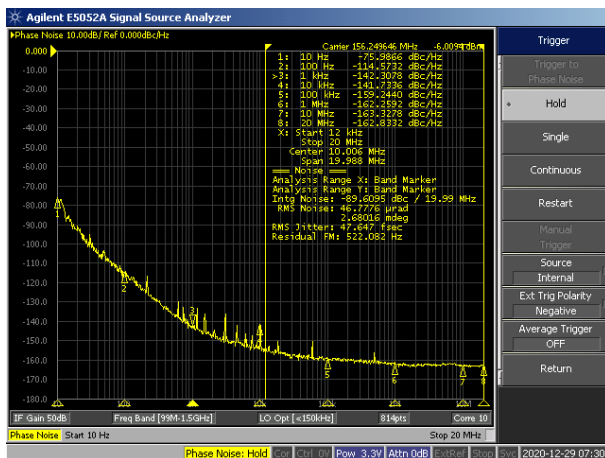
PIN	FUNCTION
1	TRI-STATE or NC
2	NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVPECL)

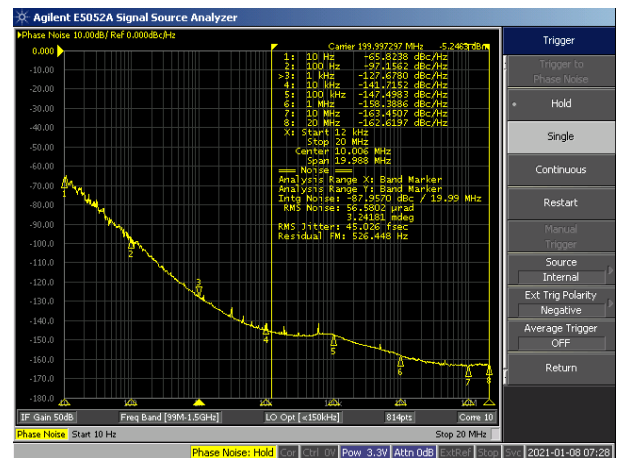
Waveform (LVPECL)



Typical Phase Noise Performance (Measured By Agilent E5052A)

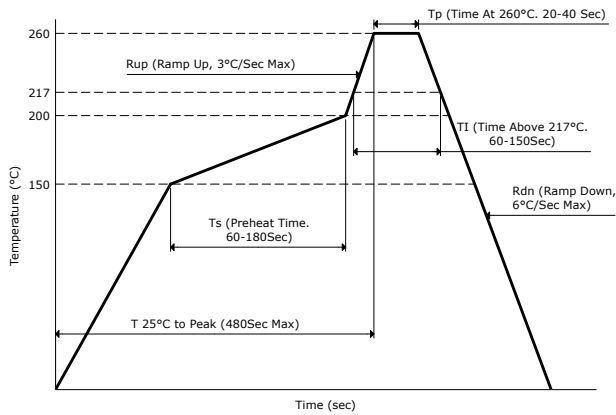


Frequency - 156.250MHz

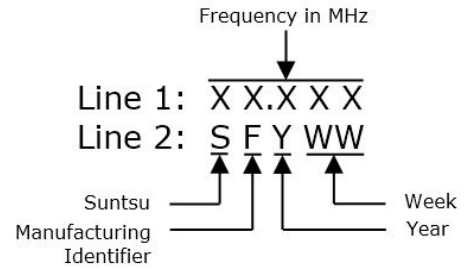


Frequency - 200.000MHz

Reflow Profile



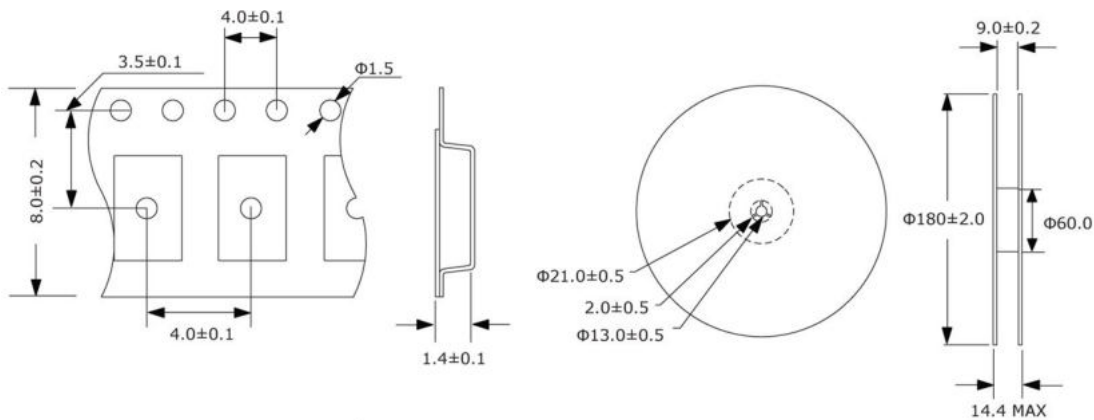
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

3,000pcs/Reel



Environmental Specifications

Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Ultra Low Phase Jitter (67fs Typical)
• Tape and Reel
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express



Part Numbering Guide

SUO 53 L 3 A 48 1 - 156.250M

SUNTSU ULTRA LOW JITTER OSC
5.0mm x 3.2mm

LVDS

SUPPLY VOLTAGE
1 : 1.8V \pm 5%
2 : 2.5V \pm 5%
3 : 3.3V \pm 5%

FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

OPERATING TEMPERATURE RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

FREQUENCY MHz
156.250
53.125M

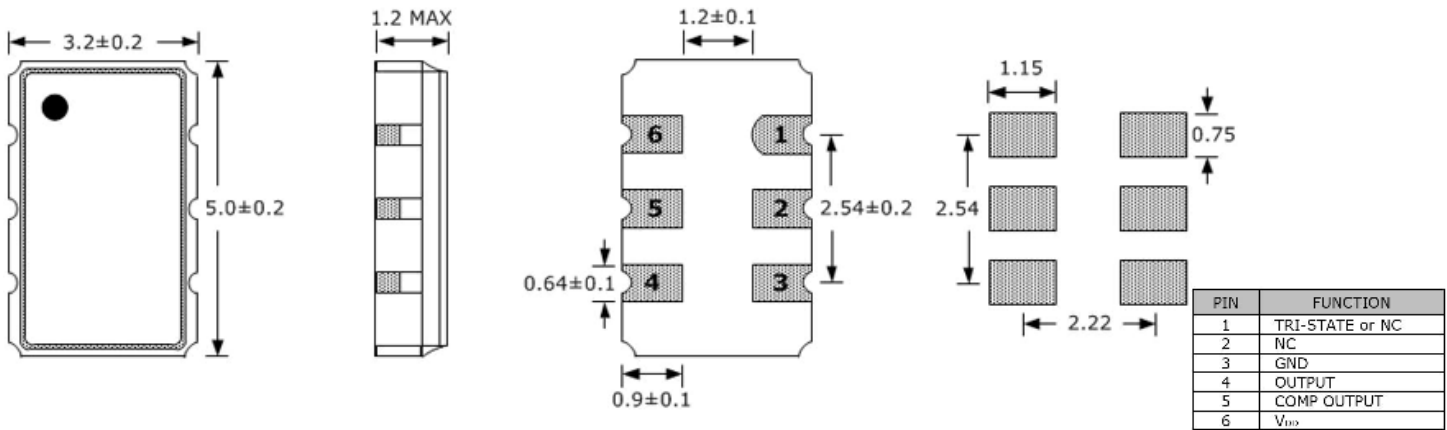
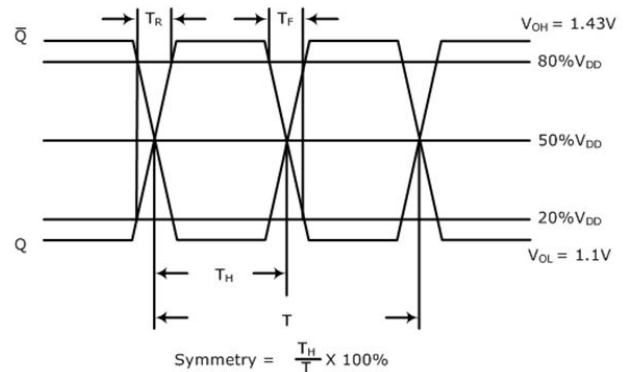
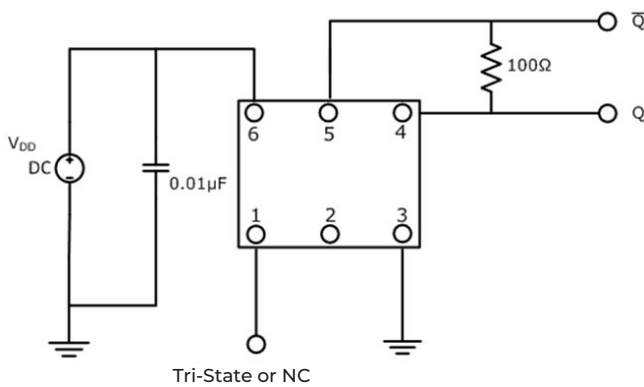
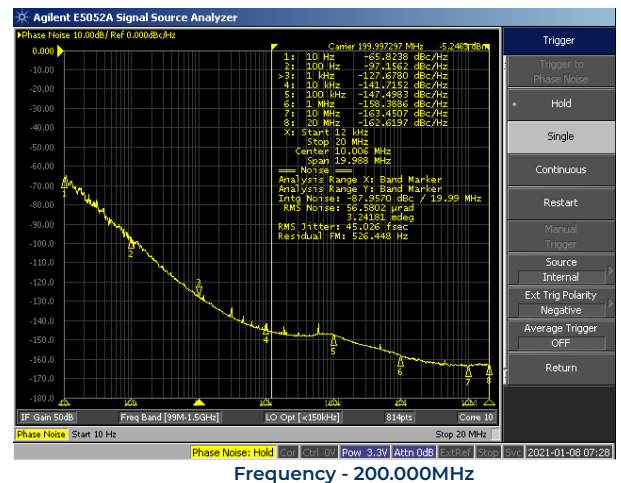
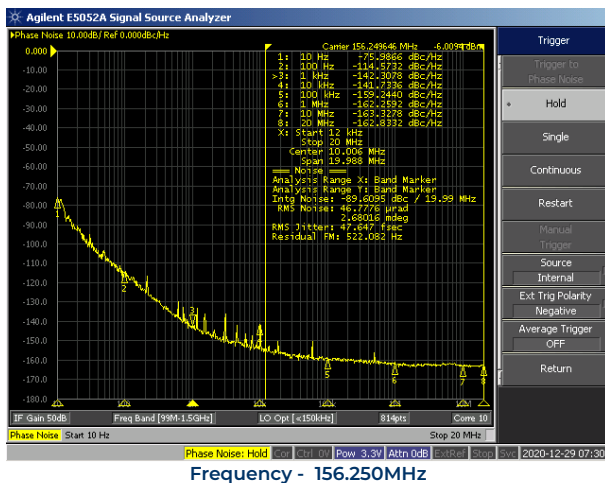
TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

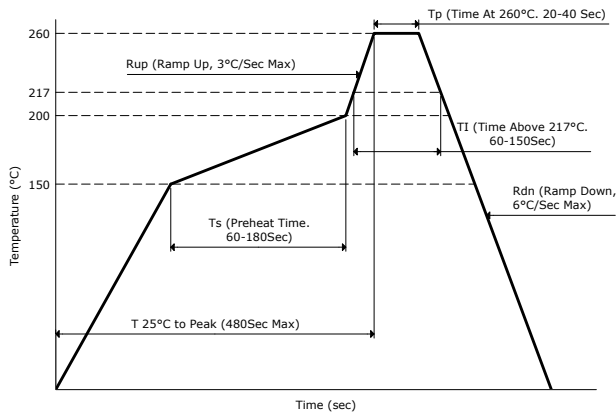
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	135~175MHz(1.8V), 100~320MHz(2.5&3.3V)
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V Option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA			35	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	350	454	
Differential Output Error (ρ V _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (ρ V _{OS})	mV	-50		50	
Rise (TR) and Fall (TF) Time	ns		0.25	0.5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5.0	
Phase Jitter (12kHz ~ 20MHz)	fs		67	100	

Outline Drawing & Land Pattern

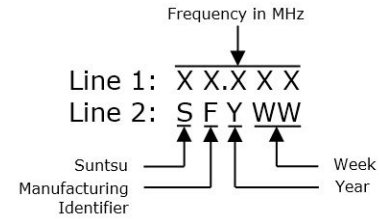
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.


Test Circuit (LVDS)
Waveform (LVDS)

Typical Phase Noise Performance (Measured By Agilent E5052A)


Reflow Profile



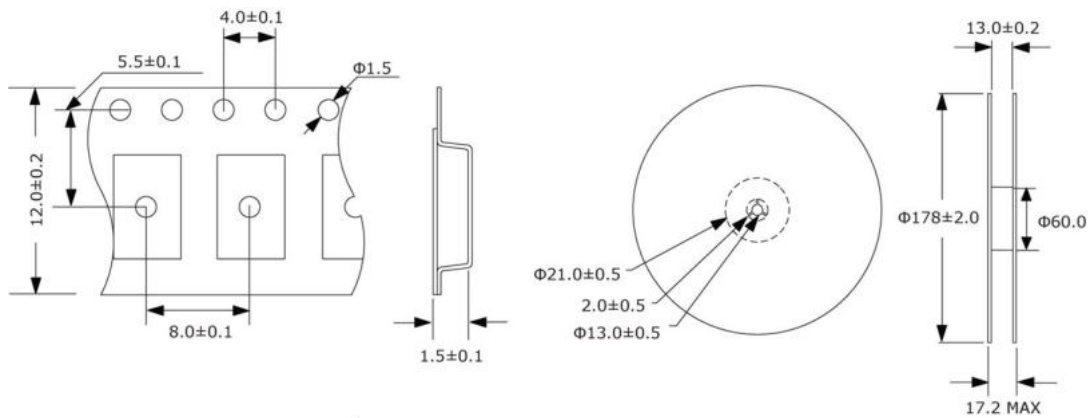
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

1,000pcs/Reel



Environmental Specifications

Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVPECL
• Ultra Low Phase Jitter (47fs Typical)
• Tape and Reel
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express


Part Numbering Guide
SUO 53 P 3 A 48 1 - 156.250M

 SUNTSU ULTRA
LOW JITTER OSC
5.0mm x 3.2mm

LVPECL

 SUPPLY VOLTAGE
2 : 2.5 \pm 5%
3 : 3.3V \pm 5%

 FREQUENCY STABILITY
A : ± 50 ppm
B : ± 30 ppm
C : ± 25 ppm
*D : ± 20 ppm

 OPERATING TEMPERATURE
RANGE
07 : 0°C - +70°C
16 : -10°C - +60°C
17 : -10°C - +70°C
27 : -20°C - +70°C
38 : -30°C - +85°C
48 : -40°C - +85°C

 FREQUENCY
MHz
TRI-STATE
(ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1


Cage Code : 4GUT4

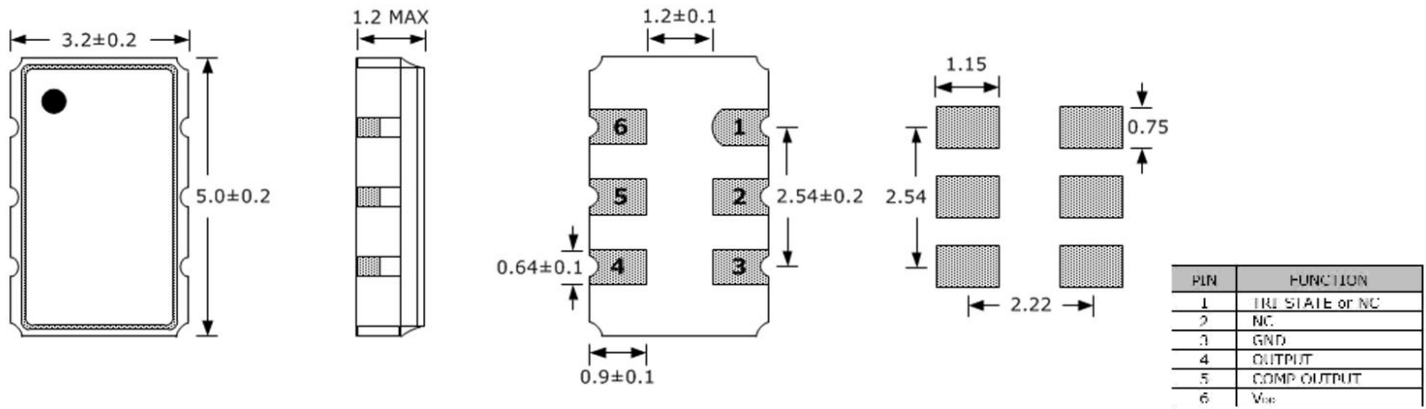
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA			70	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH} at 2.5V)	V	1.415		1.760	
Output Logic Levels Low (V _{OL} at 2.5V)	V	0.670		1.195	
Output Logic Levels High (V _{OH} at 3.3V)	V	2.215		2.420	
Output Logic Levels Low (V _{OL} at 3.3V)	V	1.470		1.745	
Rise (TR) and Fall (TF) Time	ns		0.15	0.3	Measured at 20% to 80% of Waveform
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5	
Phase Jitter (12kHz ~ 20MHz)	fs		47	100	

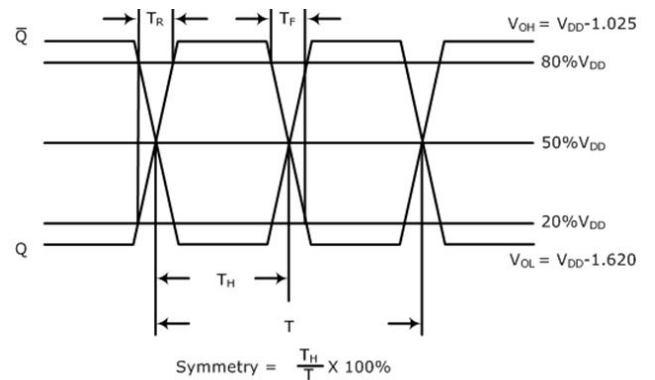
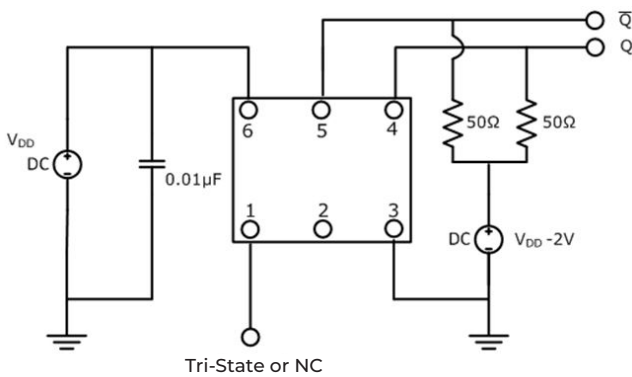
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

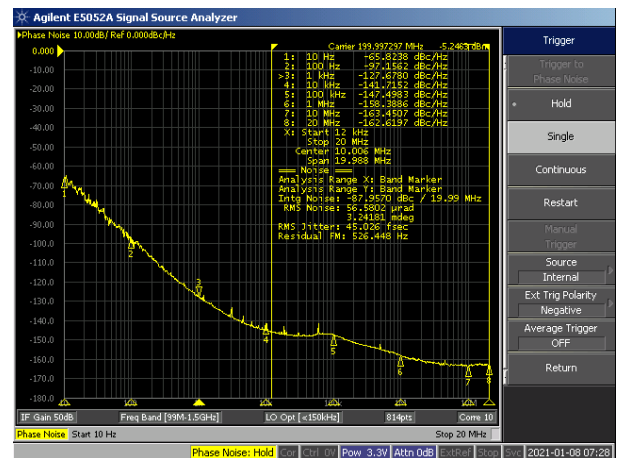
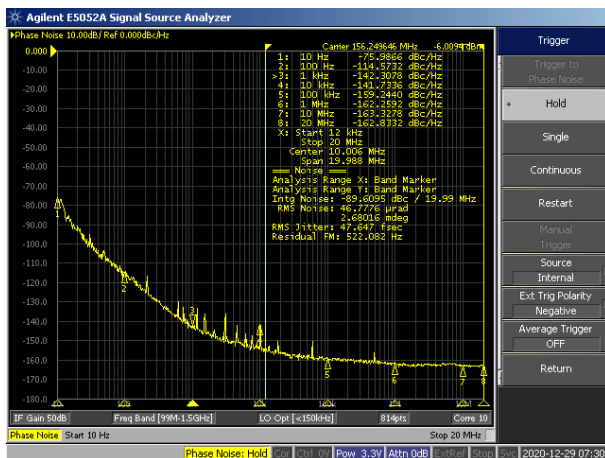


Test Circuit (LVPECL)

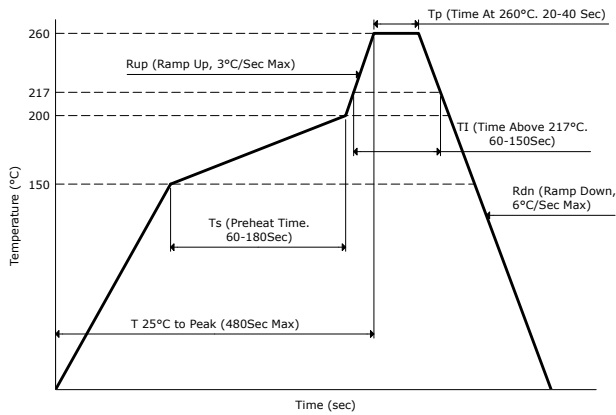
Waveform (LVPECL)



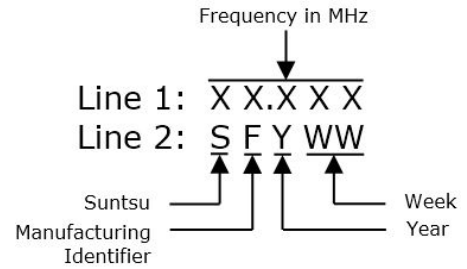
Typical Phase Noise Performance (Measured By Agilent E5052A)



Reflow Profile



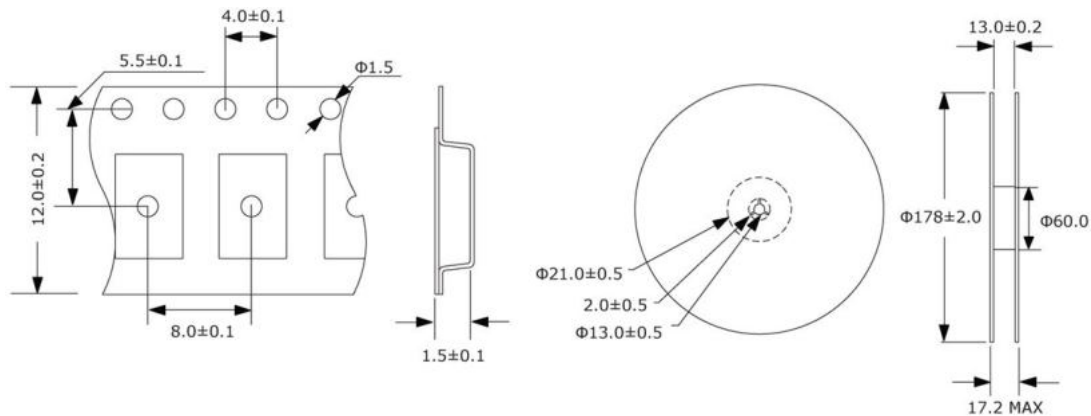
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

1,000pcs/Reel



Environmental Specifications

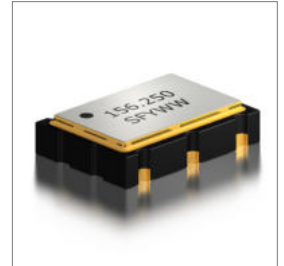
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVDS
• Ultra Low Phase Jitter (67fs Typical)
• Tape and Reel
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express


Part Numbering Guide
SUO 75 L 3 A 48 1 - 156.250M

 SUNTSU ULTRA
 LOW JITTER OSC

7.0mm x 5.0mm

LVDS

SUPPLY VOLTAGE

- 1 : 1.8V \pm 5%
- 2 : 2.5V \pm 5%
- 3 : 3.3V \pm 5%

FREQUENCY STABILITY

- A : ± 50 ppm
- B : ± 30 ppm
- C : ± 25 ppm
- *D : ± 20 ppm

OPERATING TEMPERATURE

RANGE

- 07 : 0°C - +70°C
- 16 : -10°C - +60°C
- 17 : -10°C - +70°C
- 27 : -20°C - +70°C
- 38 : -30°C - +85°C
- 48 : -40°C - +85°C

 FREQUENCY
 MHz

 TRI-STATE
 (ENABLE/DISABLE)
 BLANK : No Connection
 1 : Pin 1


Cage Code : 4GUT4

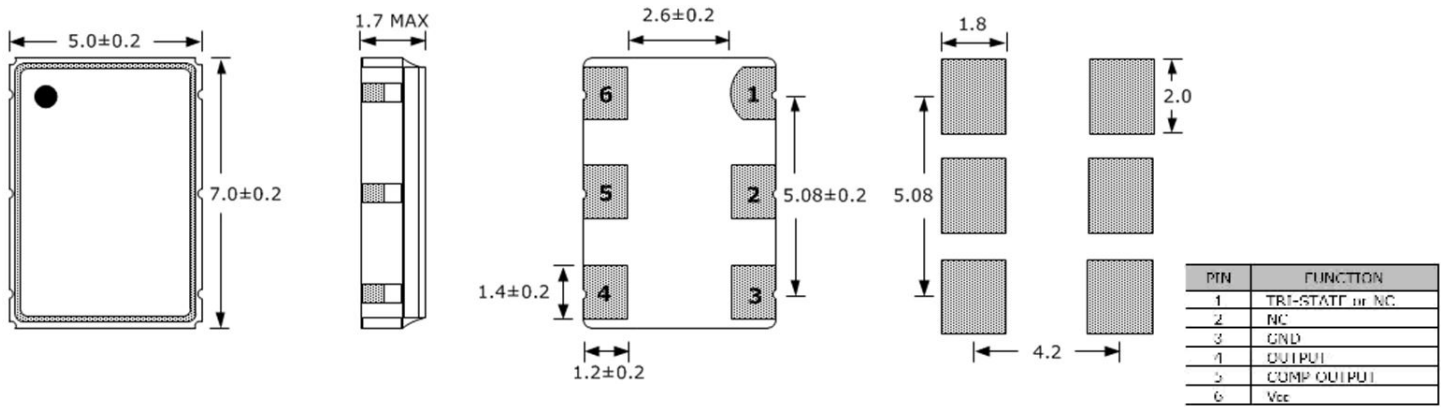
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range*	MHz	100		320	135~175MHz(1.8V), 100~320MHz(2.5&3.3V)
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V Option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})*	mA			35	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	350	454	
Differential Output Error (Δ V _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (Δ V _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns		0.25	0.5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5.0	
Phase Jitter (12kHz ~ 20MHz)	fs		67	100	

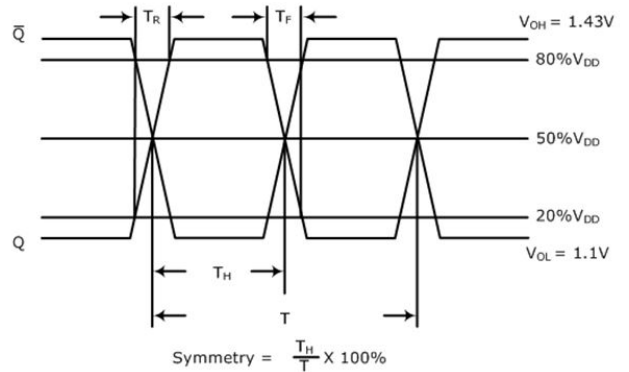
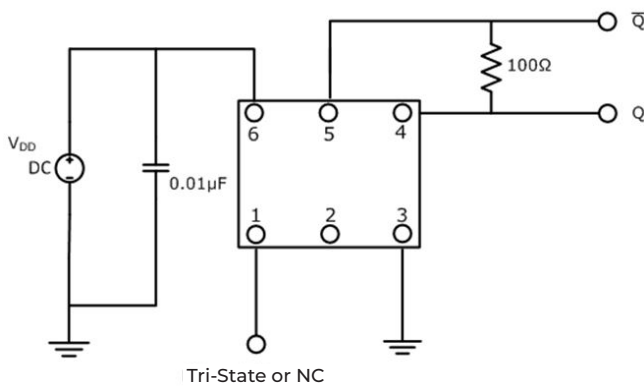
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

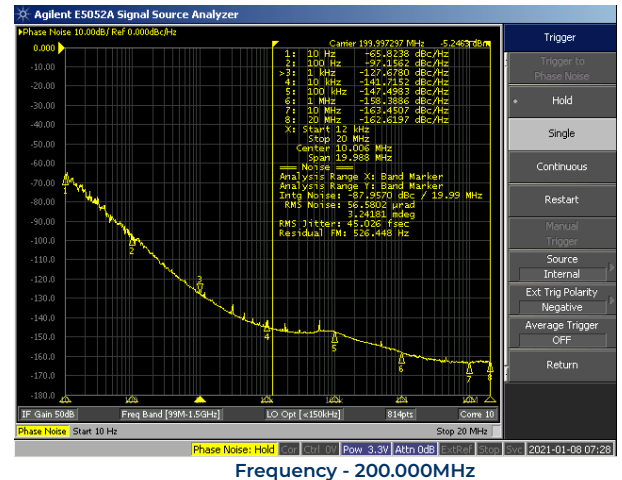
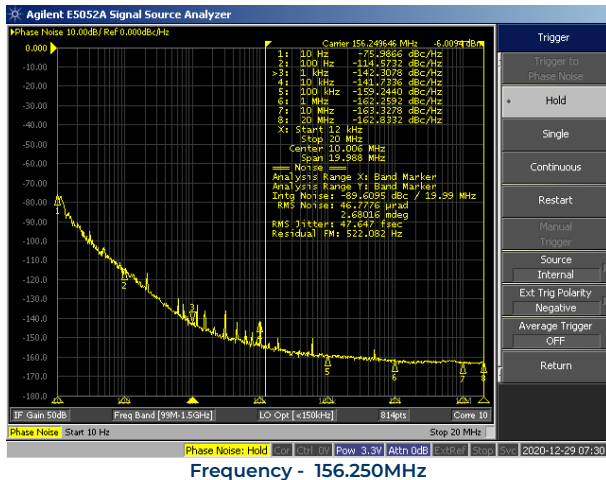


Test Circuit (LVDS)

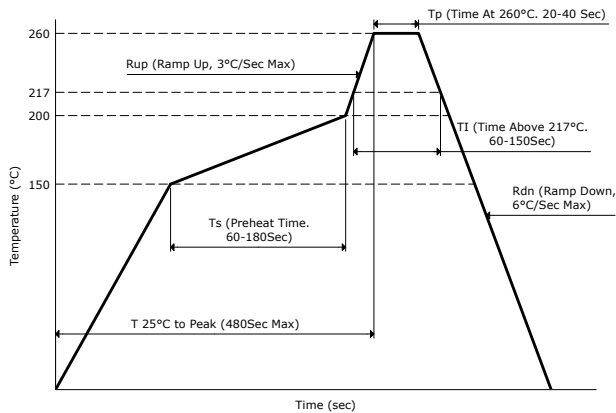
Waveform (LVDS)



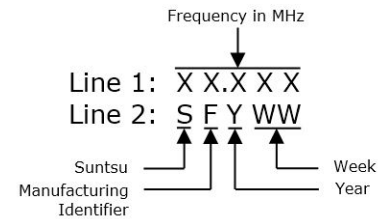
Typical Phase Noise Performance (Measured By Agilent E5052A)



Reflow Profile



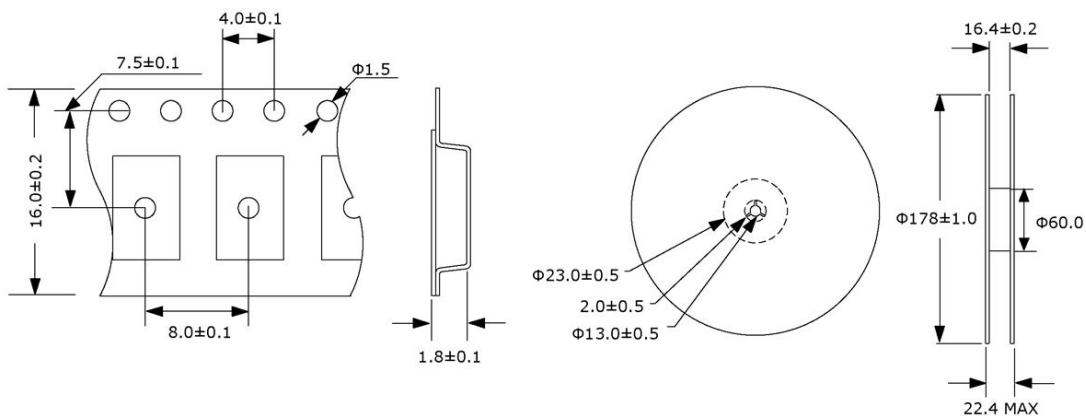
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

1,000pcs/Reel



Environmental Specifications

Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
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Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• LVPECL
• Ultra Low Phase Jitter (47fs Typical)
• Tape and Reel
• Fundamental or 3rd Overtone Crystal Design

Applications
• Fiber Channel
• Gigabit Ethernet
• PCI Express


Part Numbering Guide
SUO 75 P 3 A 48 1 - 156.250M

 SUNTSU ULTRA
LOW JITTER OSC
7.0mm x 5.0mm

LVPECL

 SUPPLY VOLTAGE
2: 2.5V \pm 5%
3: 3.3V \pm 5%

 FREQUENCY STABILITY
A: ± 50 ppm
B: ± 30 ppm
C: ± 25 ppm
*D: ± 20 ppm

 OPERATING TEMPERATURE
RANGE
07: 0°C - +70°C
16: -10°C - +60°C
17: -10°C - +70°C
27: -20°C - +70°C
38: -30°C - +85°C
48: -40°C - +85°C

 FREQUENCY
MHz
TRI-STATE
(ENABLE/DISABLE)
BLANK: No Connection
1: Pin 1


Cage Code : 4GUT4

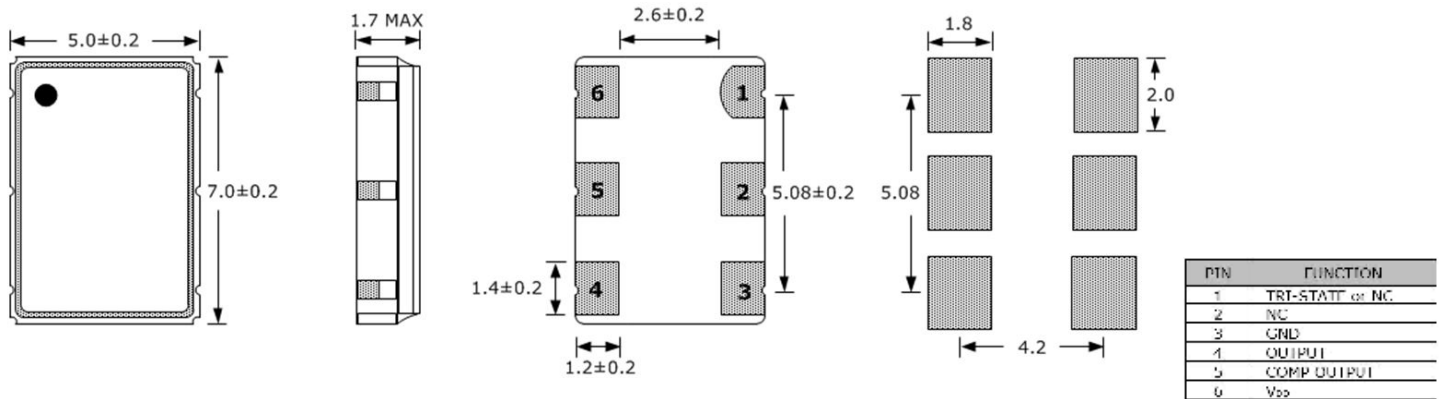
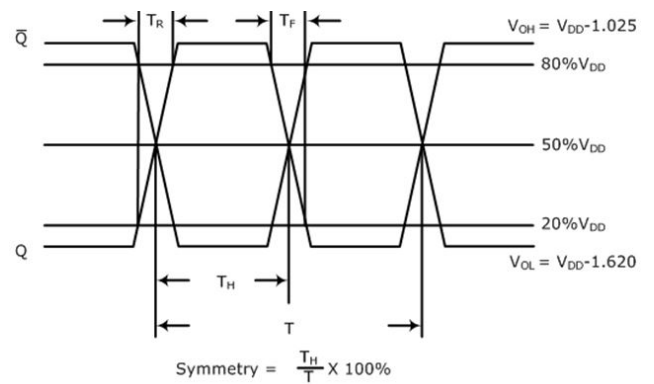
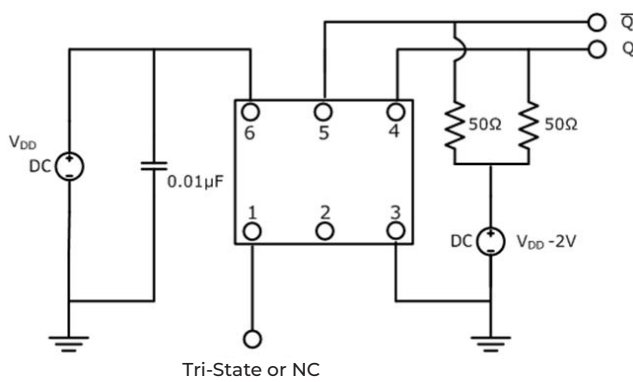
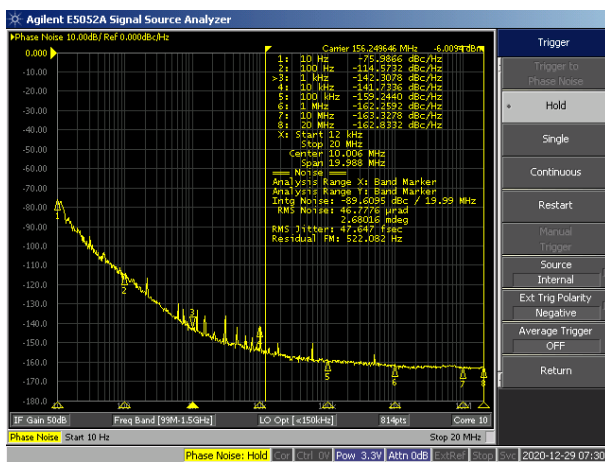
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

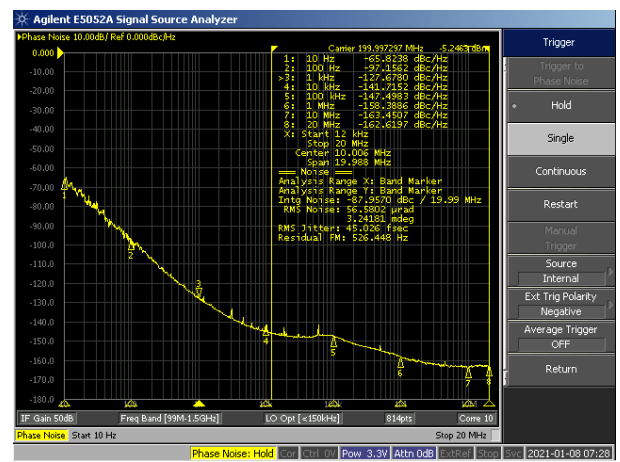
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		320	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD})	mA			70	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH} at 2.5V)	V	1.415		1.760	
Output Logic Levels Low (V _{OL} at 2.5V)	V	0.670		1.195	
Output Logic Levels High (V _{OH} at 3.3V)	V	2.215		2.420	
Output Logic Levels Low (V _{OL} at 3.3V)	V	1.470		1.745	
Rise (TR) and Fall (TF) Time	ns		0.15	0.3	Measured at 20% to 80% of Waveform
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5	
Phase Jitter (12kHz ~ 20MHz)	fs		47	100	

Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

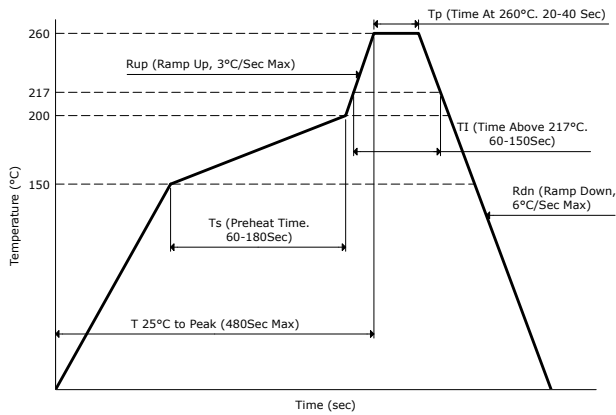

Test Circuit (LVPECL)
Waveform (LVPECL)

Typical Phase Noise Performance (Measured By Agilent E5052A)


Frequency - 156.250MHz

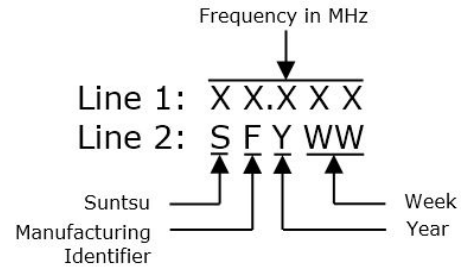


Frequency - 200.000MHz

Reflow Profile



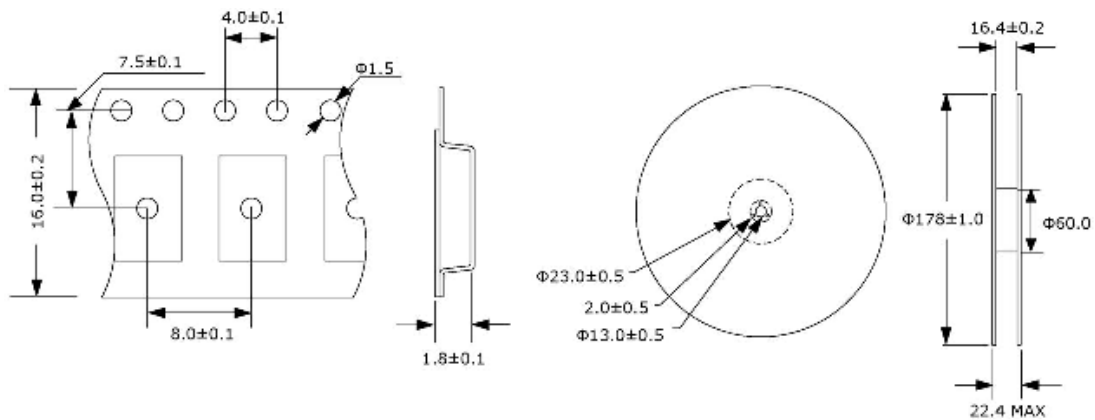
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

1,000pcs/Reel



Environmental Specifications

Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Solderability	MIL-STD-883, Method 2003
Moisture Sensitivity	J-STD-020, MSL 1

Mechanical Specifications

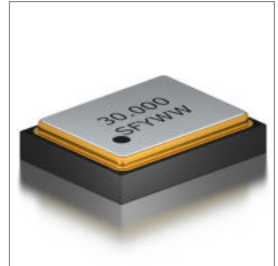
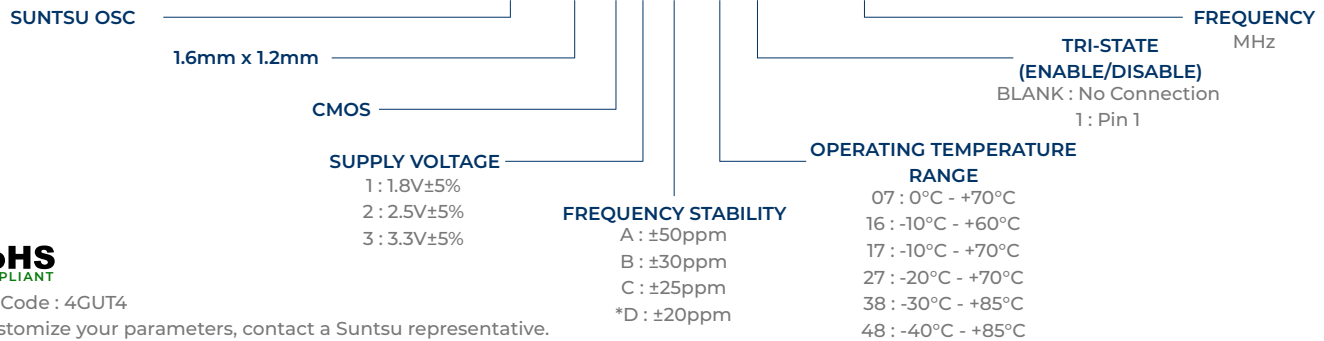
Mechanical Shock	MIL-STD-202, Method 213, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A
Moisture Resistance	MIL-STD-883, Method 1004
Resistance to Solvents	MIL-STD-202, Method 215
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features

- ± 20 ppm (Frequency Stability) Available
- Ceramic Package
- CMOS
- Tape and Reel

Applications

- Mobile Communication
- Portable Electronics
- PDA


Part Numbering Guide
SXO 11 C 3 A 48 1 - 30.000M


Cage Code : 4GUT4

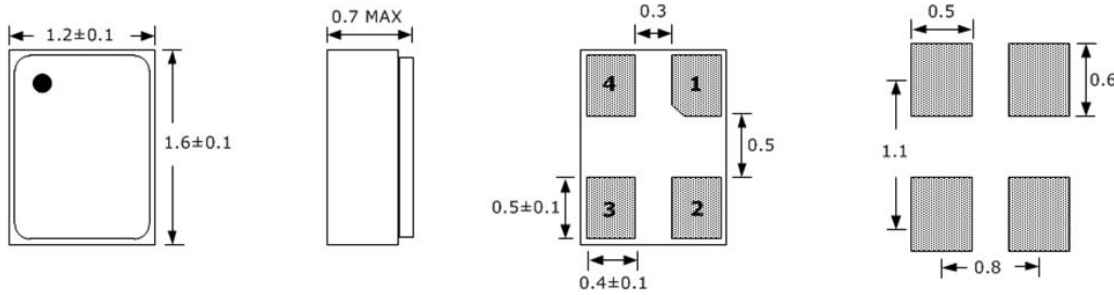
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	1		133	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Current (I _{DD})	mA			10	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	V _{DD} -0.4			
Output Logic Levels Low (V _{OL})	V			V _{DD} +0.4	
Rise (TR) and Fall (TF) Time	ns			4.5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			5.0	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

Outline Drawing & Land Pattern

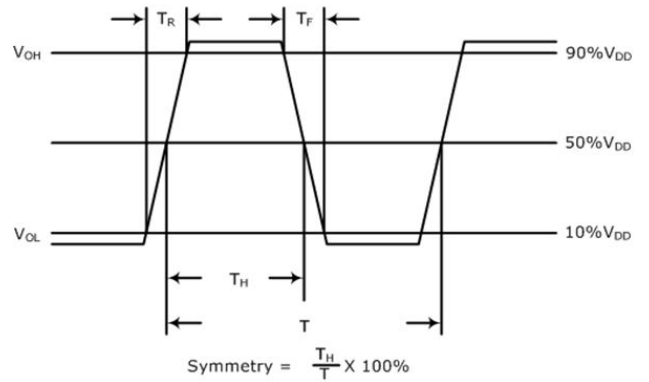
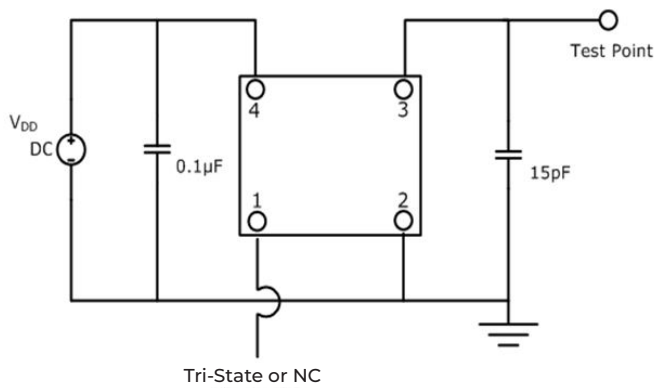
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



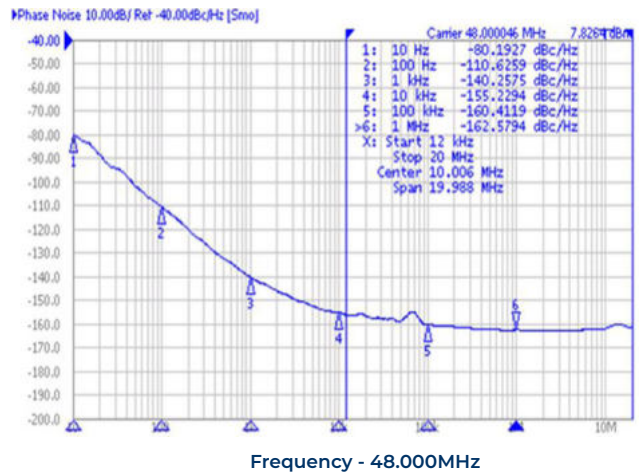
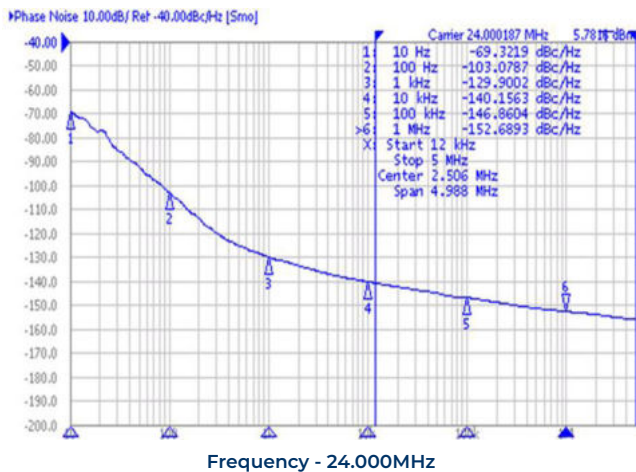
PIN	FUNCTION
1	TRI-STATE or NC
2	GND
3	OUTPUT
4	V _{DD}

Test Circuit (CMOS)

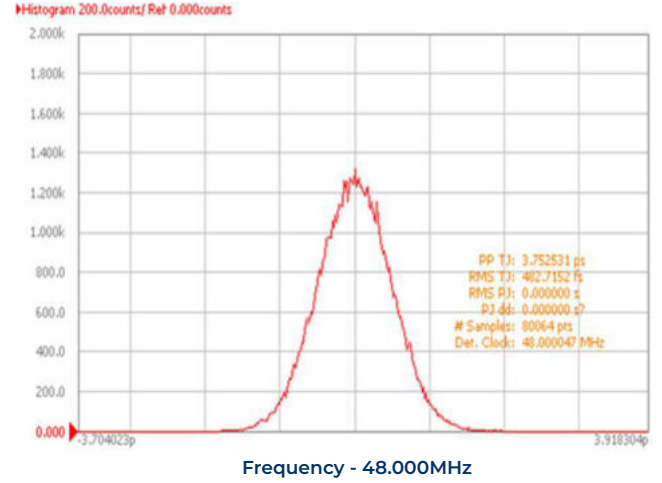
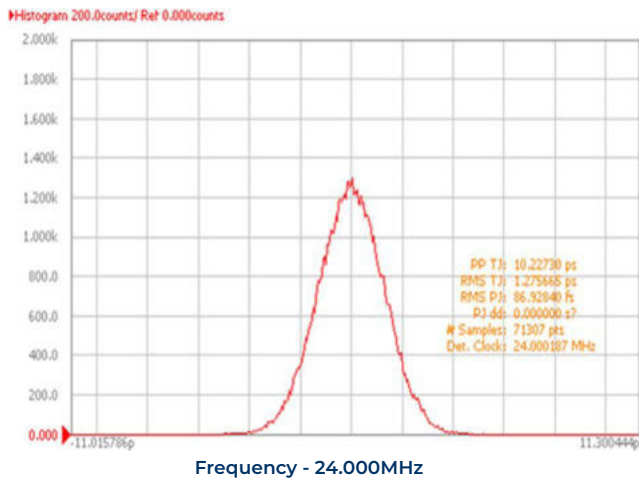
Waveform (CMOS)



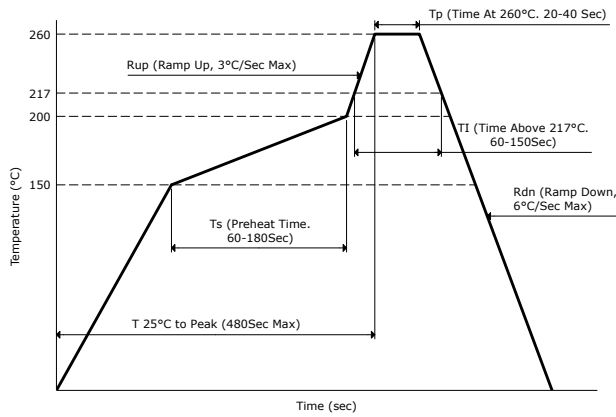
Typical Phase Noise Performance (Measured By Agilent E5052A)



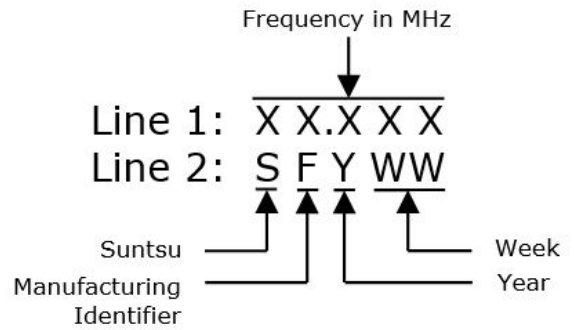
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



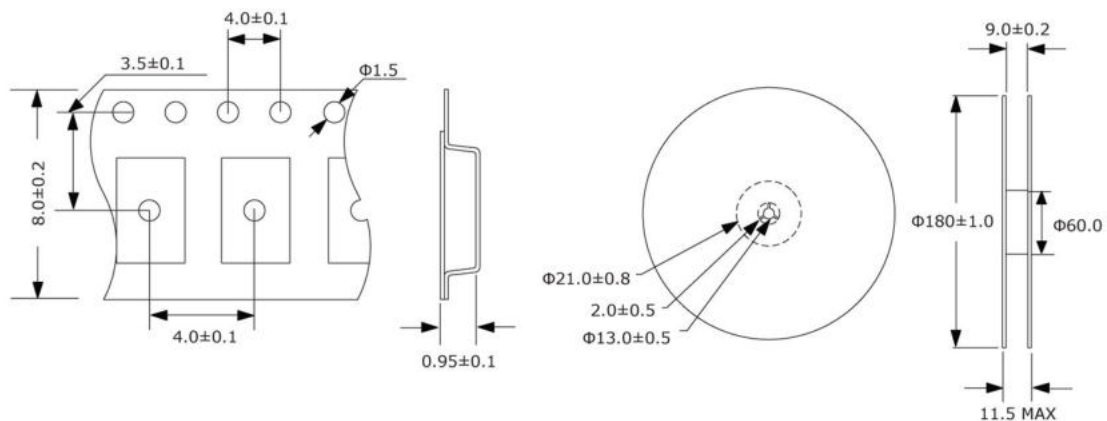
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

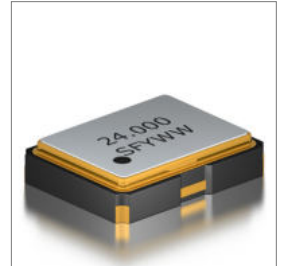
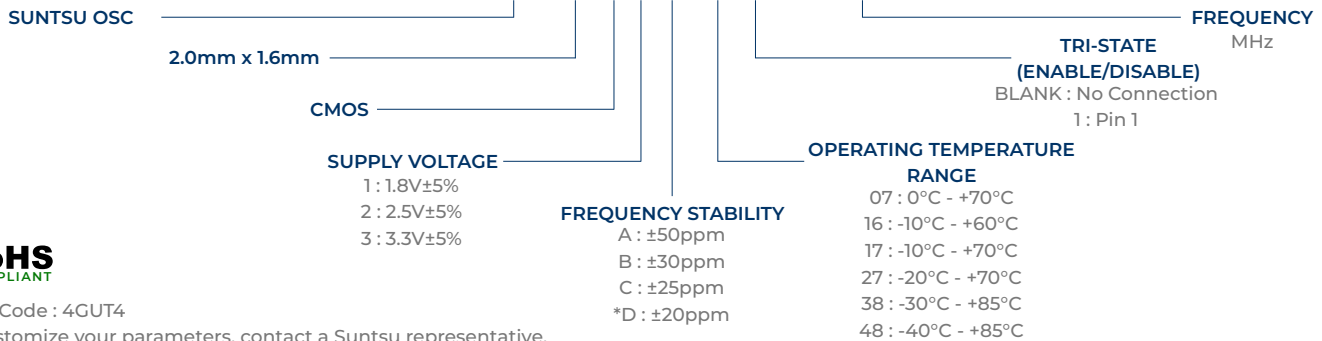
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±20ppm (Frequency Stability) Available Ceramic Package CMOS Tape and Reel

Applications
<ul style="list-style-type: none"> Mobile Communication Portable Electronics PDA


Part Numbering Guide
SXO 21 C 3 A 48 1 - 24.000M


Cage Code : 4GUT4

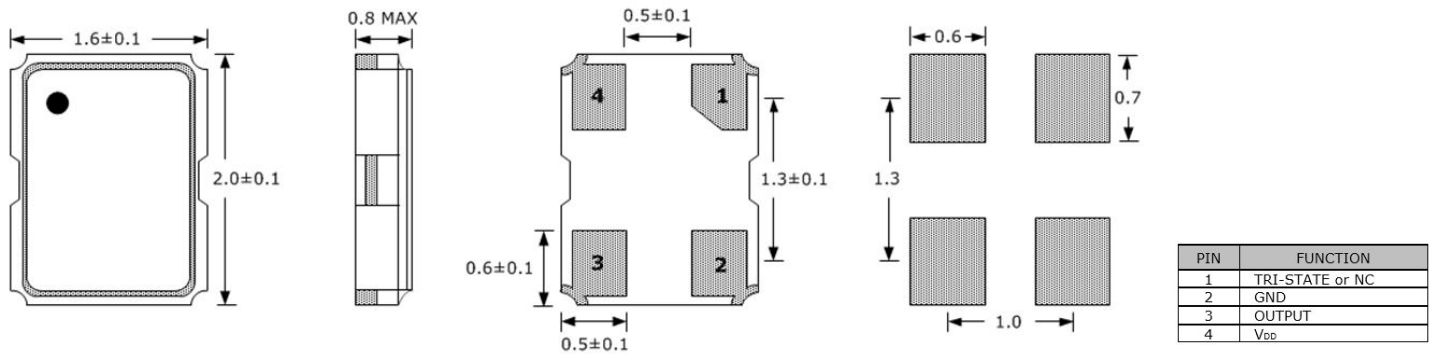
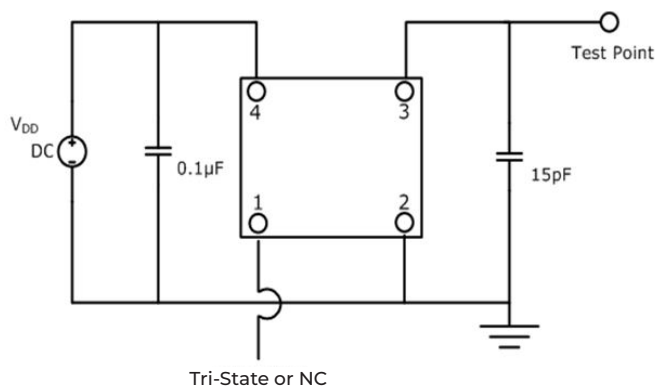
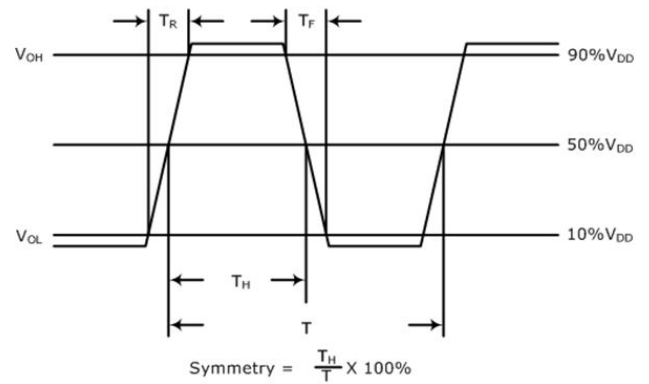
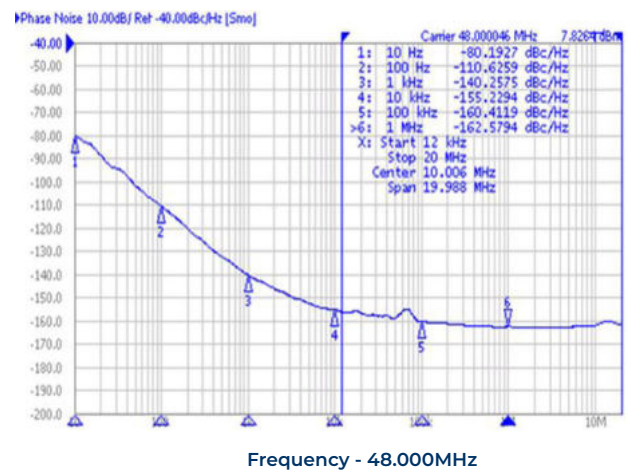
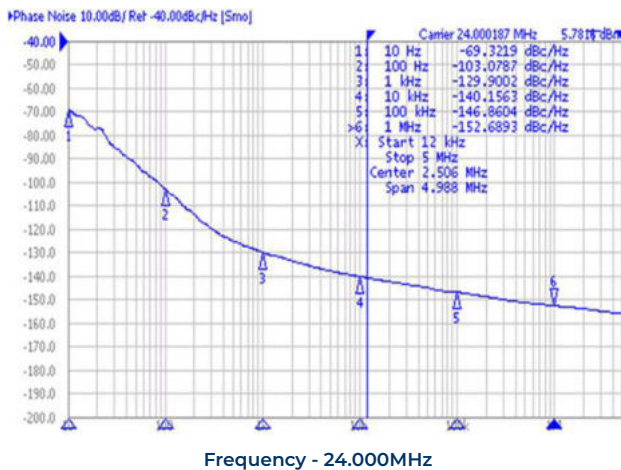
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

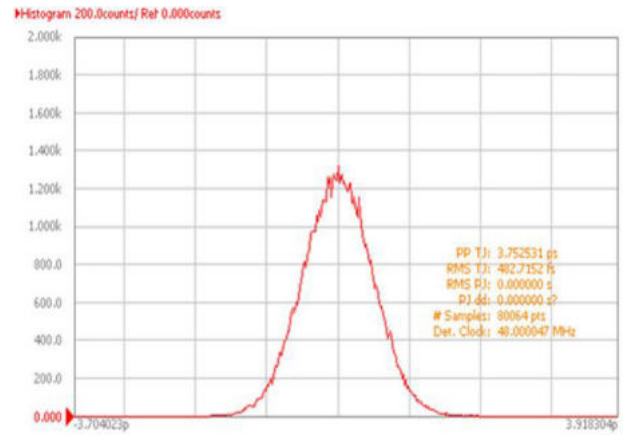
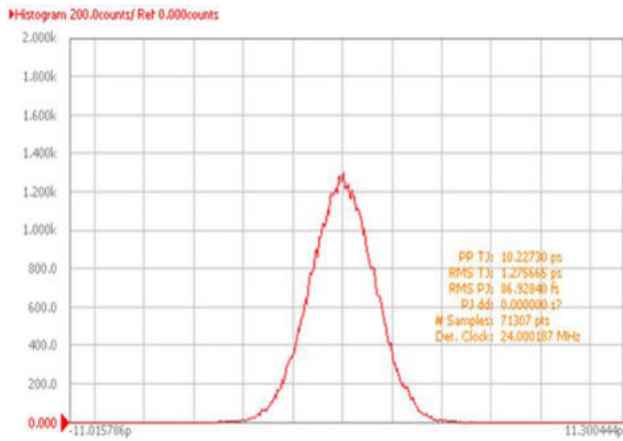
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	KHz	22.000	32.768	87.000	
Frequency Range	MHz	1		60	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Current (I _{DD}) - 1.8V option	mA			10	240µA max. from 22.000kHz to 87.000kHz
Current (I _{DD}) - 2.5V option	mA			10	240µA max. from 22.000kHz to 87.000kHz
Current (I _{DD}) - 3.3V option	mA			15	240µA max. from 22.000kHz to 87.000kHz
Standby Current	µA			10	From 22.000kHz to 87.000kHz
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			V _{DD} -0.4 min. from 22.000kHz to 87.000kHz
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	0.4 max. from 22.000kHz to 87.000kHz
Rise (TR) and Fall (TF) Time	ns			10	200ns max. from 22.000kHz to 87.000kHz
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	5ms max. from 22.000kHz to 87.000kHz
Phase Jitter (12kHz ~ 20MHz)	ps			1	N/A from 22.000kHz to 87.000kHz

Outline Drawing & Land Pattern

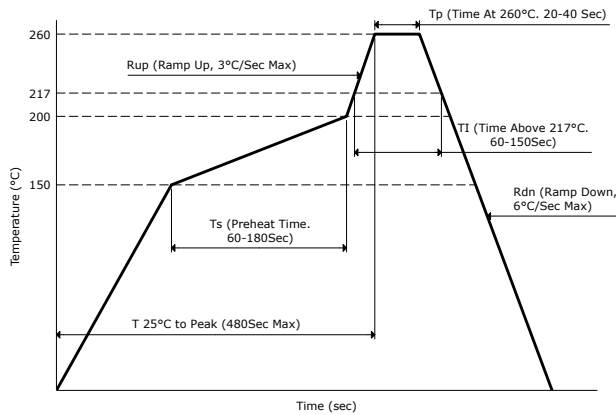
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.


Test Circuit (CMOS)

Waveform (CMOS)

Typical Phase Noise Performance (Measured By Agilent E5052A)


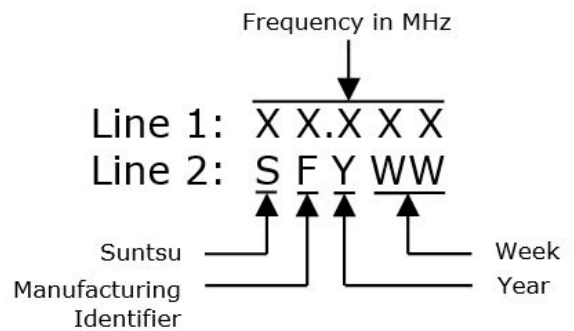
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



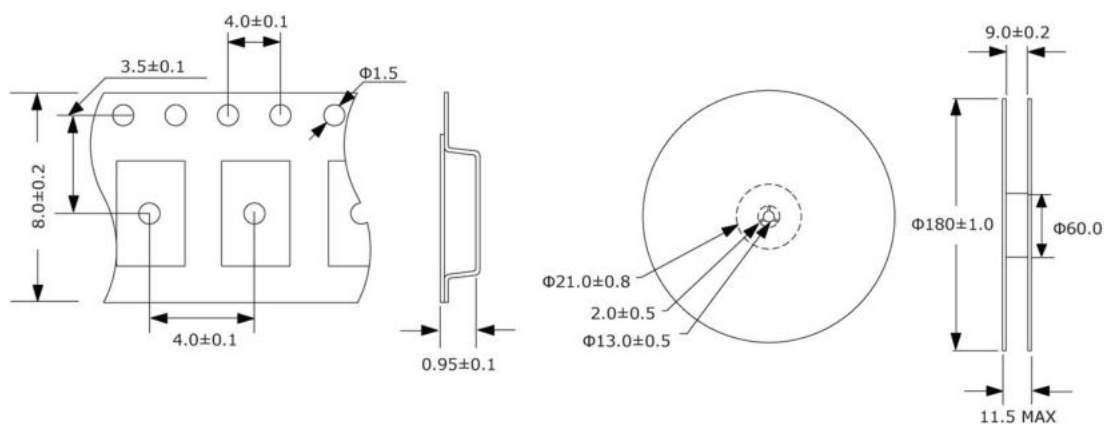
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

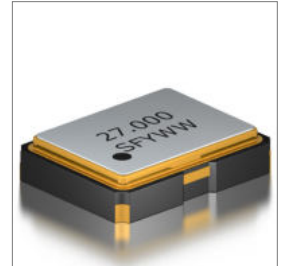
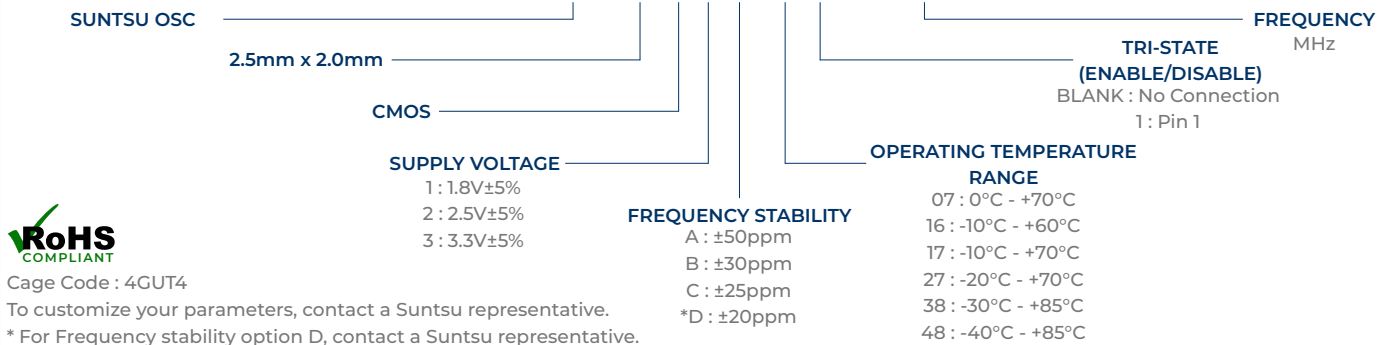
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• CMOS
• Tape and Reel

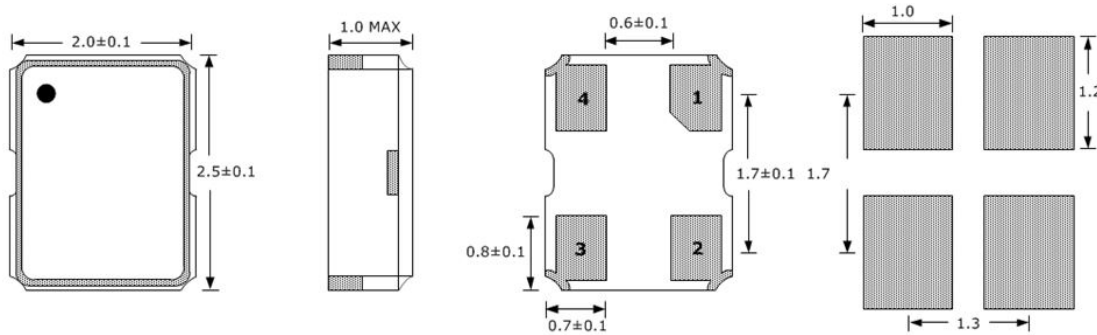
Applications
• Micro Processors
• SONET/SDH/DWDM
• Storage Area/Networking
• Digital Video
• Base Stations


Part Numbering Guide
SXO 22 C 3 A 48 1 - 27.000M


Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	KHz	32.768			
Frequency Range	MHz	1		110	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Frequency Range		1.8V	2.5V	3.3V	
Current (I _{DD})	mA	3	4	5	Maximum Value
1.0000MHz - 15.999MHz	mA	3	5	7	Maximum Value
16.000MHz - 39.999MHz	mA	5	7	10	Maximum Value
40.000MHz - 59.999MHz	mA	10	13	15	Maximum Value
60.000MHz - 110.000MHz	mA	15	20	35	Maximum Value
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			200	
32.768KHz	ns			10	
1.0000MHz - 15.999MHz	ns			8	
16.000MHz - 39.999MHz	ns			6	
40.000MHz - 59.999MHz	ns			4	
60.000MHz - 110.000MHz	ns				
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

Outline Drawing & Land Pattern

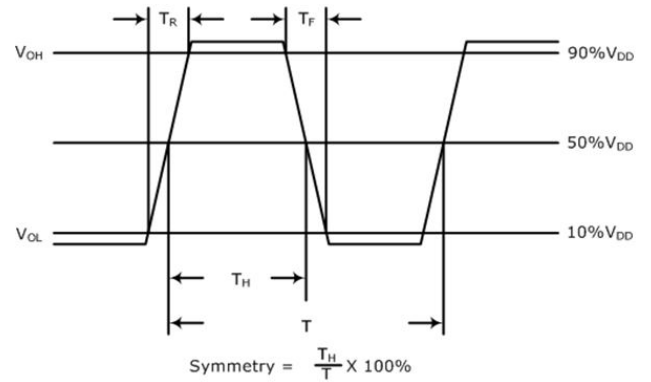
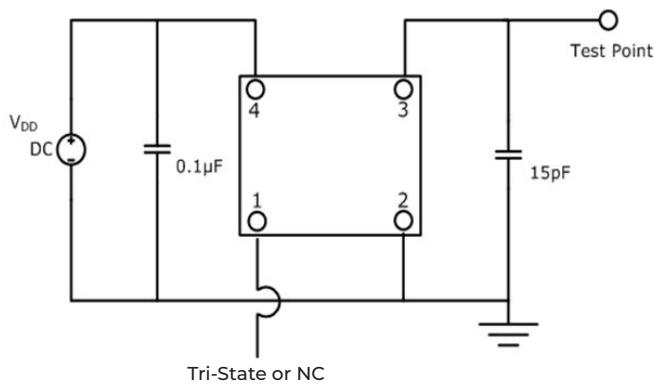
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



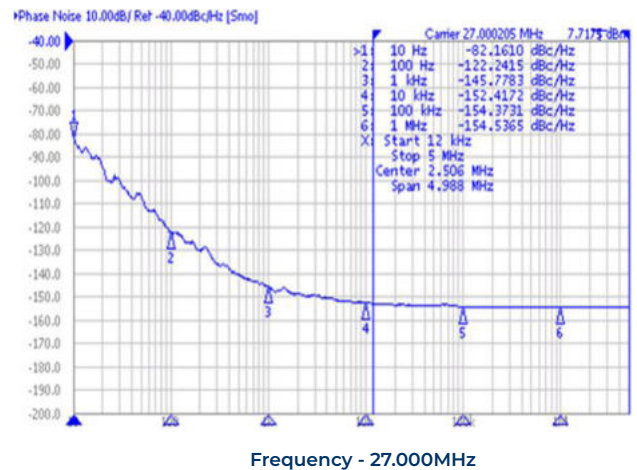
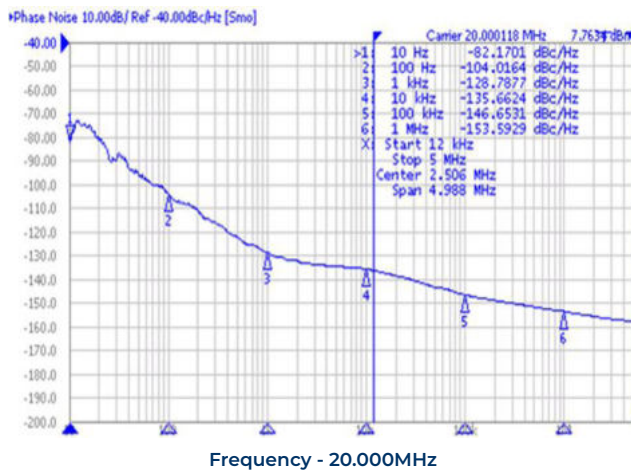
PIN	FUNCTION
1	TRI-STATE or NC
2	GND
3	OUTPUT
4	V _{DD}

Test Circuit (CMOS)

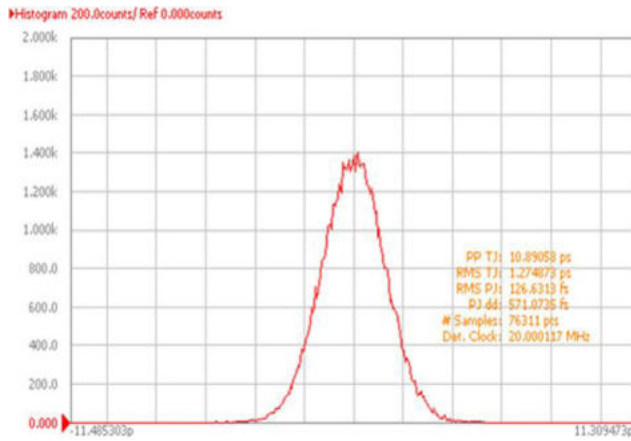
Waveform (CMOS)



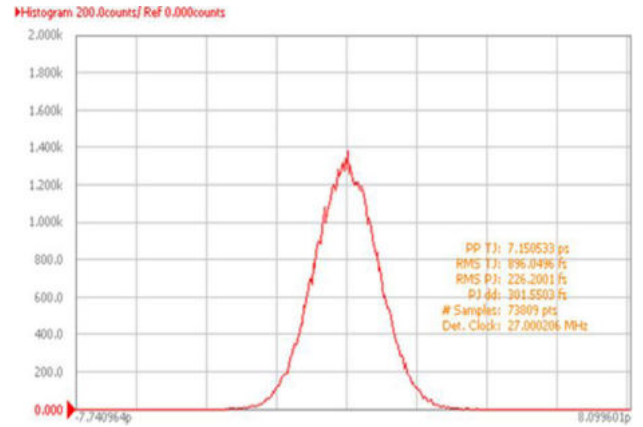
Typical Phase Noise Performance (Measured By Agilent E5052A)



Typical Jitter Performance (Measured By Agilent E5052A)

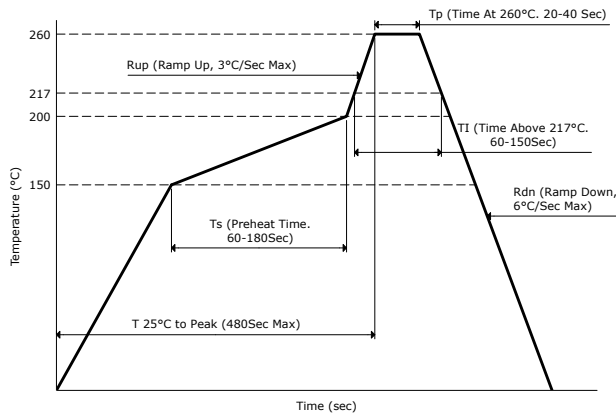


Frequency - 20.000MHz

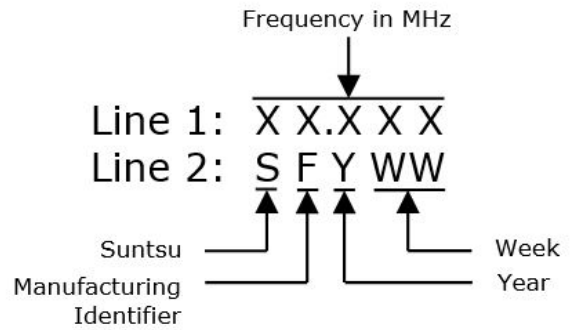


Frequency - 27.000MHz

Reflow Profile



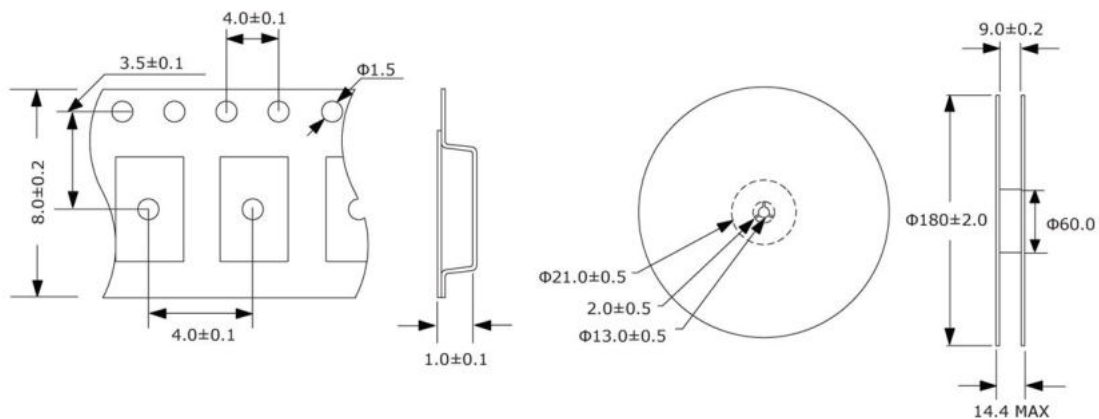
Part Marking



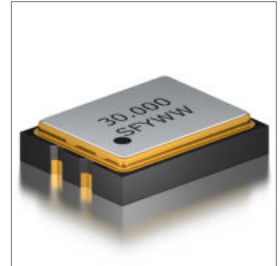
Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K



Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• CMOS
• Tape and Reel

Applications
• Micro Processors
• SONET/SDH/DWDM
• Storage Area/Networking
• Digital Video
• Base Stations

Part Numbering Guide

SXO 32 C 3 A 48 1 X - 30.000M

SUNTSU OSC

3.2mm x 2.5mm

CMOS

SUPPLY VOLTAGE

1 : 1.8V \pm 5%

2 : 2.5V \pm 5%

3 : 3.3V \pm 5%

FREQUENCY STABILITY

A : ± 50 ppm

B : ± 30 ppm

C : ± 25 ppm

*D : ± 20 ppm

OPERATING TEMPERATURE RANGE

07 : 0°C - +70°C

16 : -10°C - +60°C

17 : -10°C - +70°C

27 : -20°C - +70°C

38 : -30°C - +85°C

48 : -40°C - +85°C

FREQUENCY MHz

LOAD

BLANK : 15pF

X : 30pF

Y : 50pF

TRI-STATE (ENABLE/DISABLE)

BLANK : No Connection

1 : Pin 1

Cage Code : 4GUT4

To customize your parameters, contact a Suntsu representative.

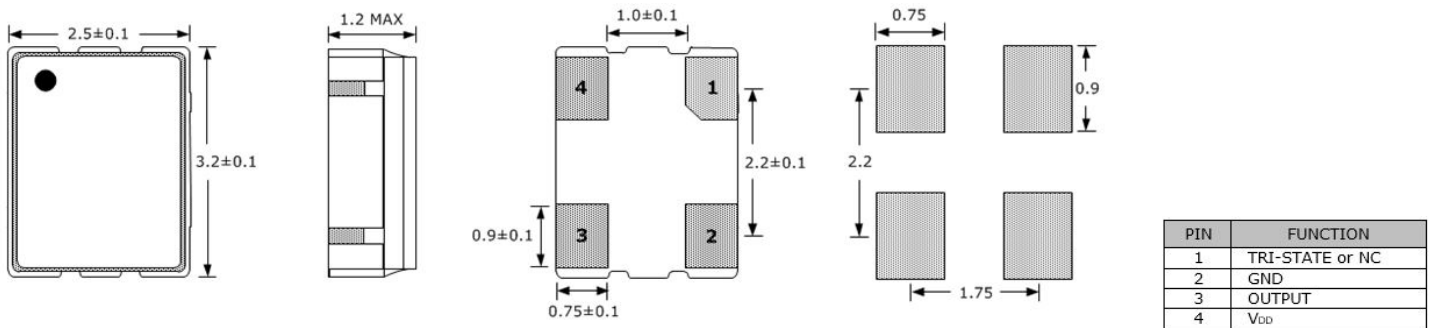
* For Frequency stability option D, contact a Suntsu representative.

** For operating temperatures up to -55-125°C contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	KHz	32.768			
Frequency Range	MHz	1		133	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Frequency Range		1.8V	2.5V	3.3V	
Current (I _{DD})	mA				Maximum Value
32.768KHz	mA	3	5	5	Maximum Value
1.0000MHz - 29.999MHz	mA	4	8	10	Maximum Value
30.000MHz - 74.999MHz	mA	6	15	17	Maximum Value
75.000MHz - 133.000MHz	mA	12	20	25	Maximum Value
Output Load (CMOS)	pF			15	See part numbering guide for options
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns				
32.768KHz	ns			200	
1.0000MHz - 29.999MHz	ns			10	
30.000MHz - 74.999MHz	ns			8	
75.000MHz - 133.000MHz	ns			5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

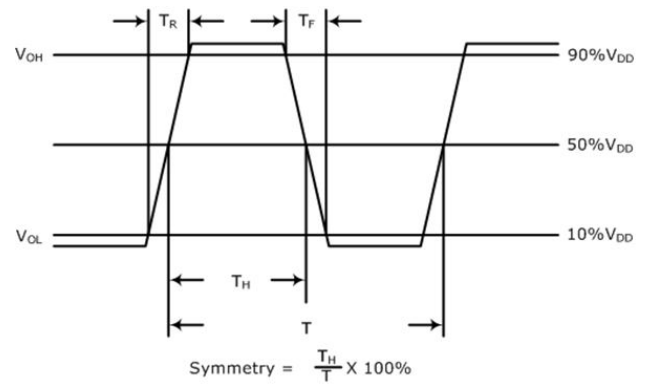
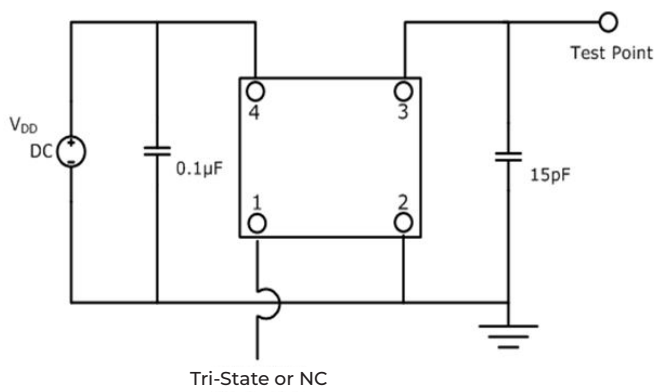
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

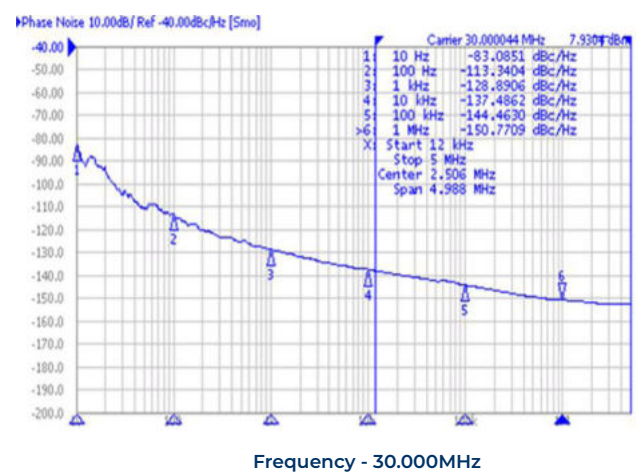
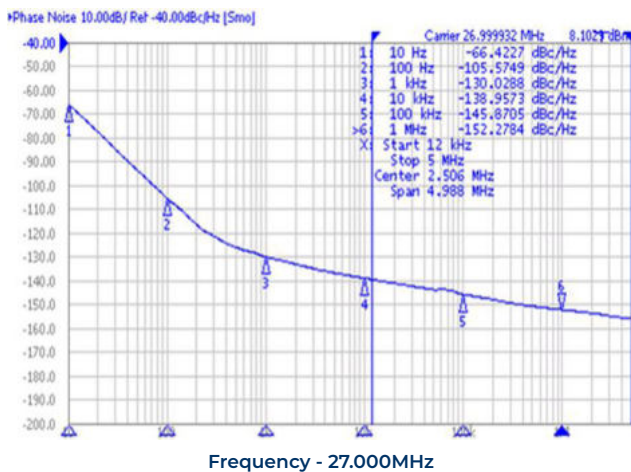


Test Circuit (CMOS)

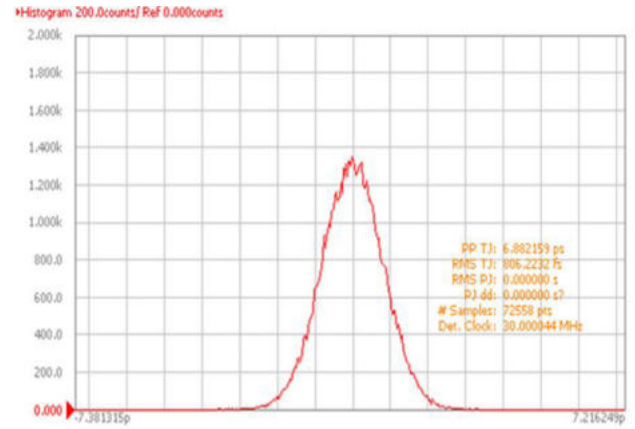
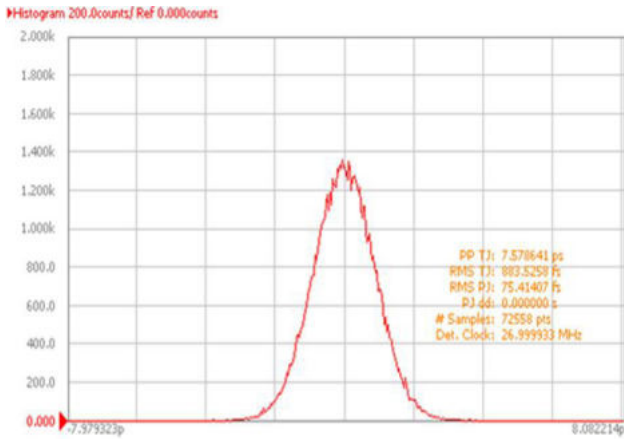
Waveform (CMOS)



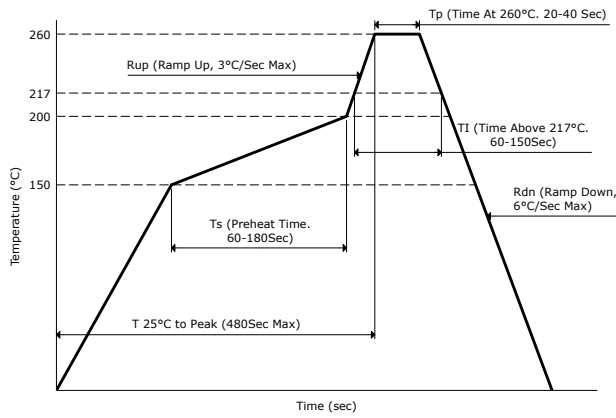
Typical Phase Noise Performance (Measured By Agilent E5052A)



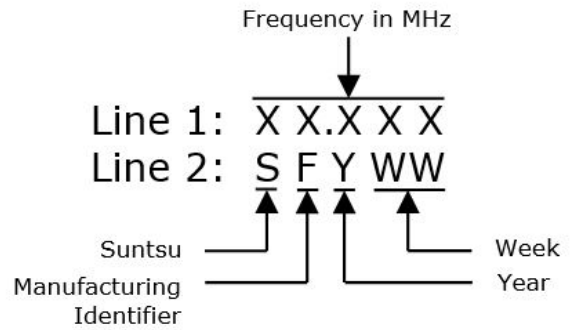
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



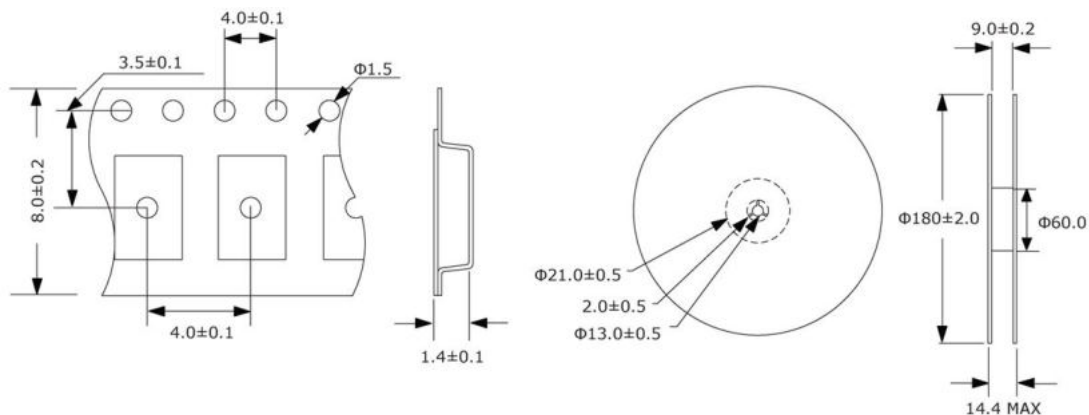
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

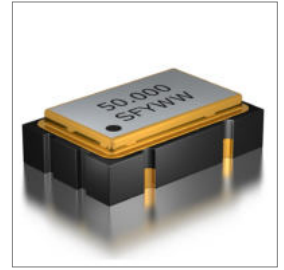
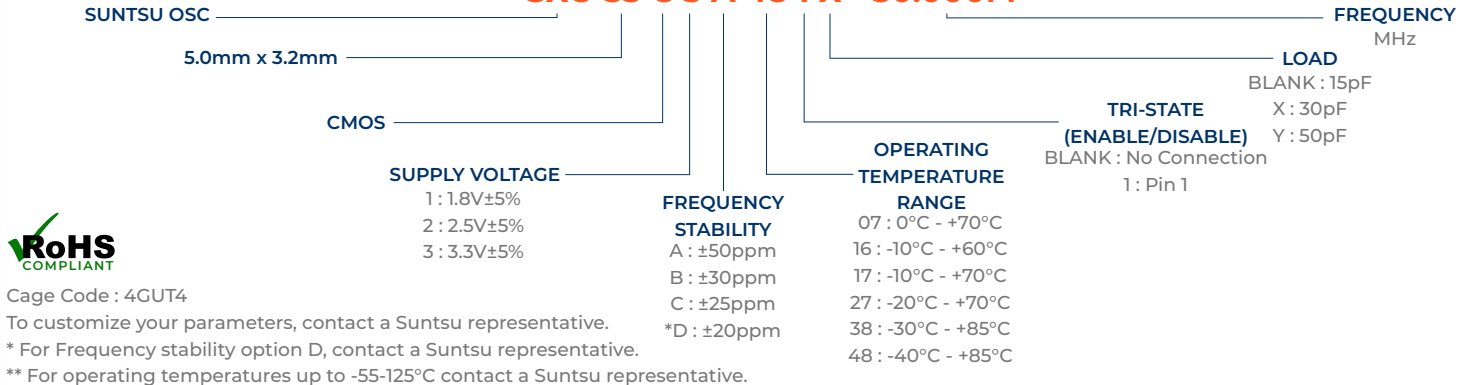
3,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• CMOS
• Tape and Reel

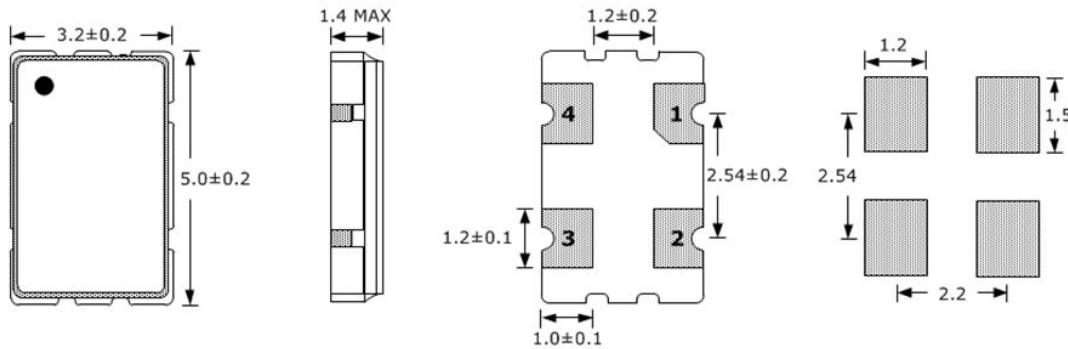
Applications
• Micro Processors
• SONET/SDH/DWDM
• Storage Area/Networking
• Digital Video
• Base Stations


Part Numbering Guide
SXO 53 C 3 A 48 1 X - 50.000M


Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	KHz	32.768			
Frequency Range	MHz	1		200	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Frequency Range		1.8V	2.5V	3.3V	
Current (I _{DD})	mA	5	5	5	Maximum Value
1.0000MHz - 34.999MHz	mA	8	10	16	Maximum Value
35.000MHz - 59.999MHz	mA	10	20	25	Maximum Value
60.000MHz - 99.000MHz	mA	25	30	40	Maximum Value
100.000MHz - 160.000MHz	mA	35	40	50	Maximum Value
Output Load (CMOS)	pF			15	See part numbering guide for options
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			200	
32.768KHz	ns			10	
1.0000MHz - 34.999MHz	ns			6	
35.000MHz - 99.999MHz	ns			3	
100.000MHz - 160.000MHz	ns				
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

Outline Drawing & Land Pattern

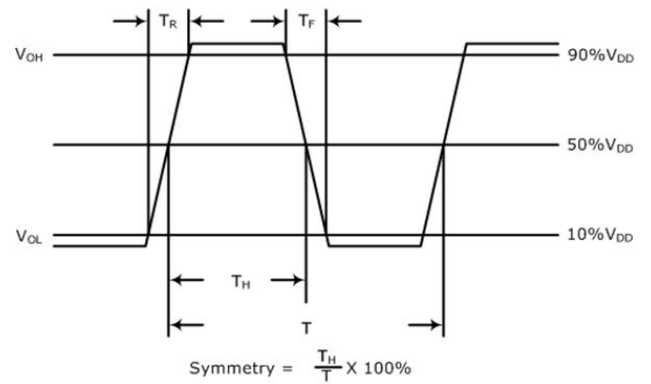
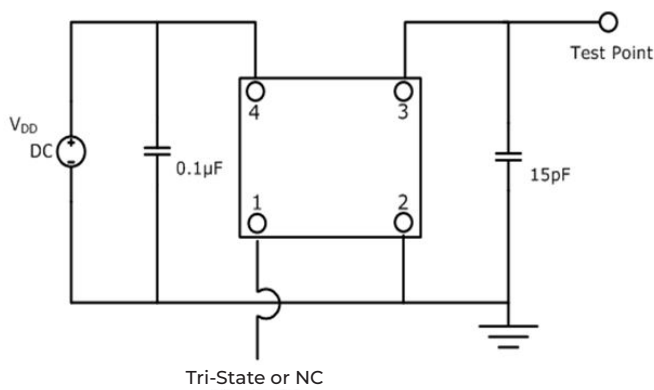
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



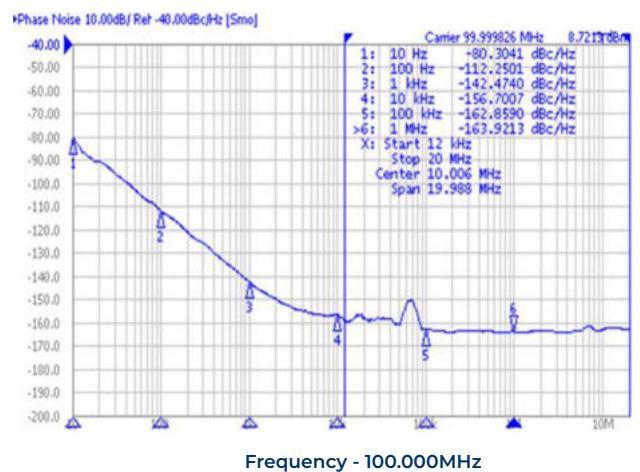
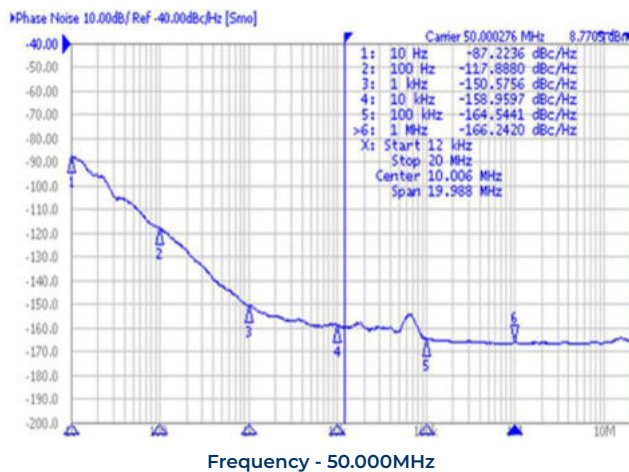
PIN	FUNCTION
1	TRI-STATE or NC
2	GND
3	OUTPUT
4	V _{DD}

Test Circuit (CMOS)

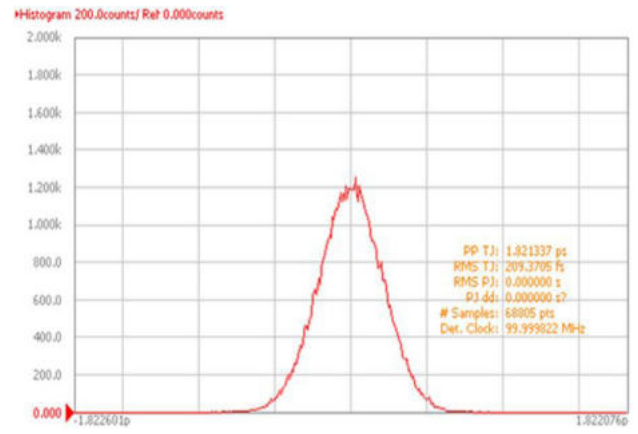
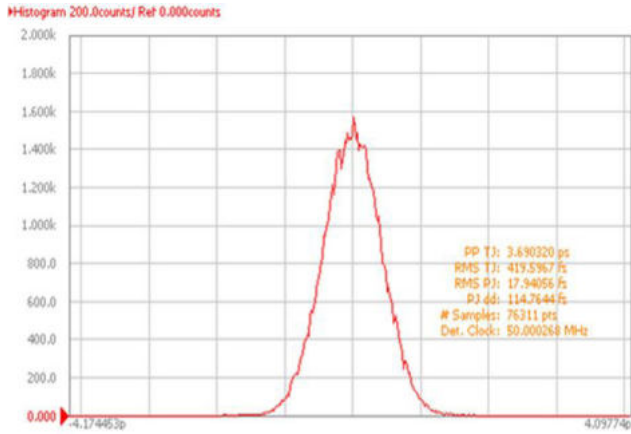
Waveform (CMOS)



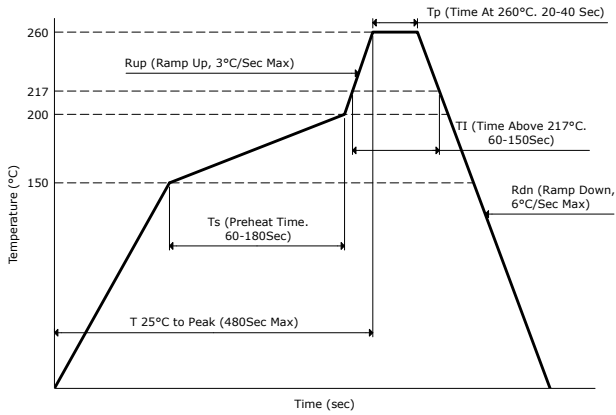
Typical Phase Noise Performance (Measured By Agilent E5052A)



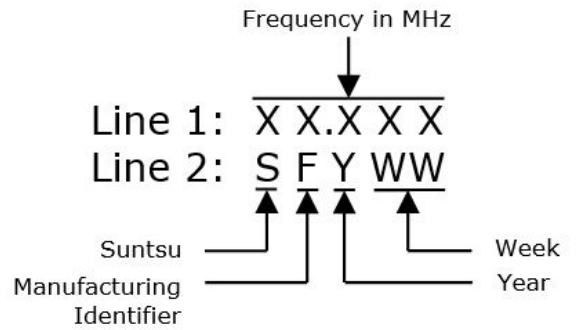
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



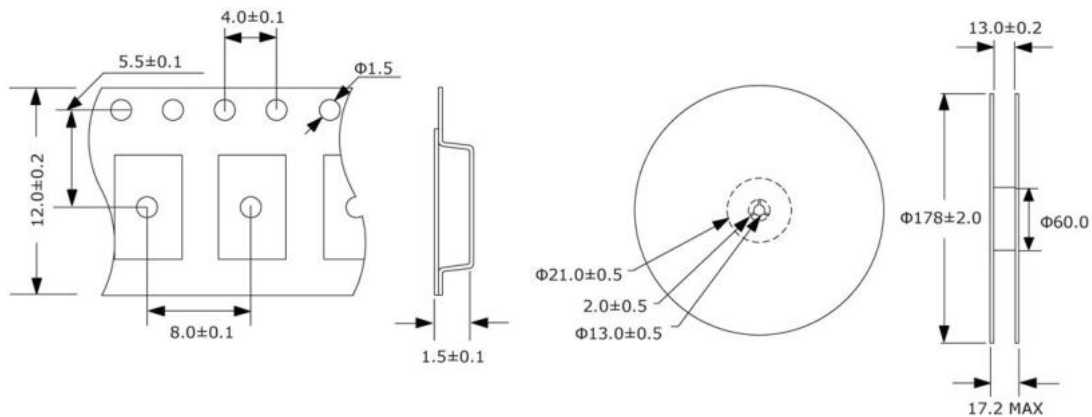
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

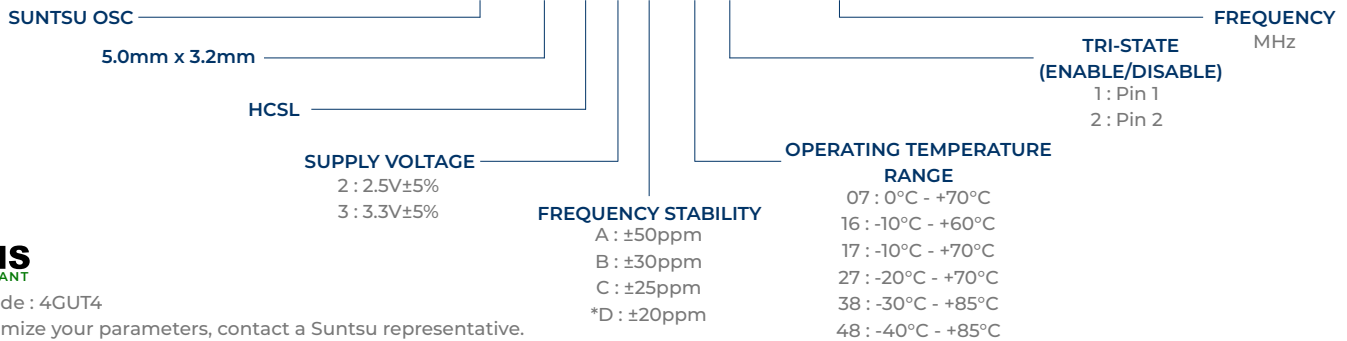
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±20ppm (Frequency Stability) Available Ceramic Package HCSL Programmed Oscillator Tape and Reel

Applications
<ul style="list-style-type: none"> Fiber Channel Gigabit Ethernet PCI Express


Part Numbering Guide
SXO 53 H 3 A 48 1 - 125.000M


Cage Code : 4GUT4

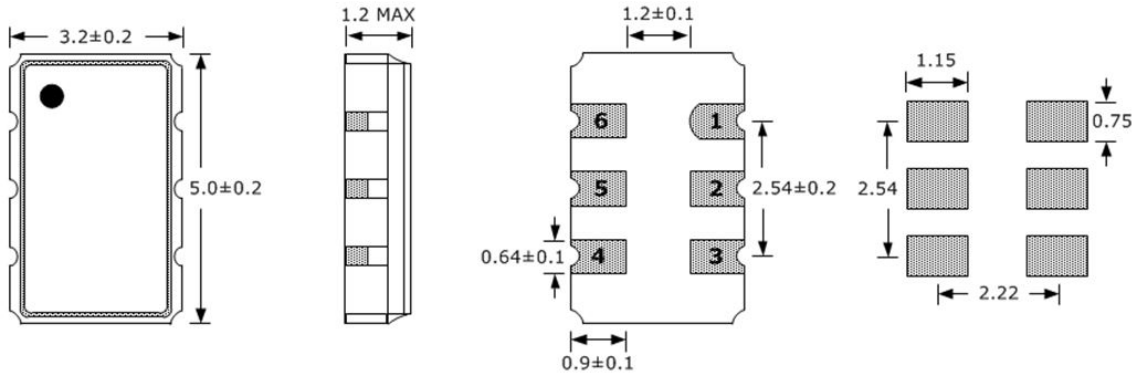
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

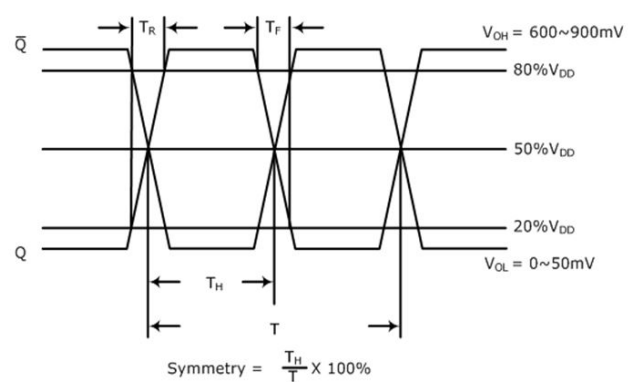
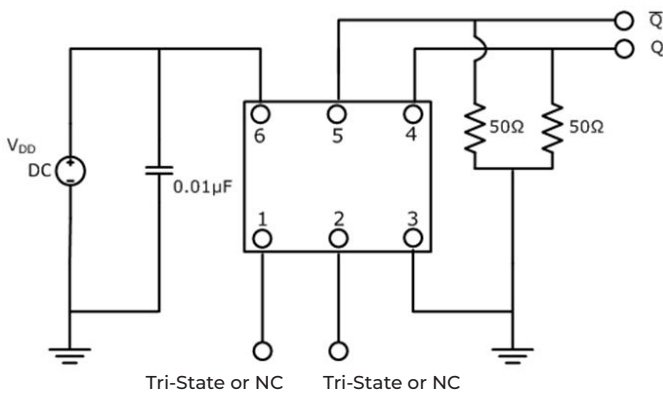
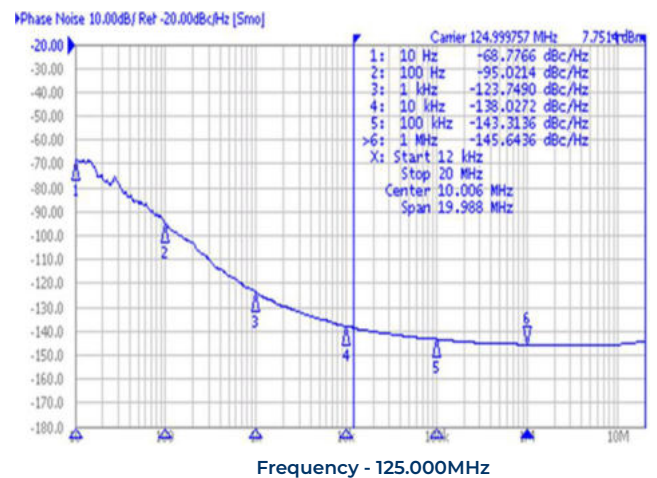
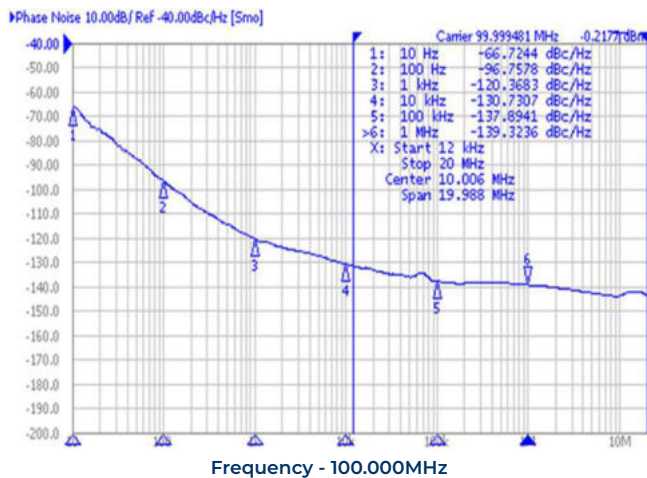
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		125	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			60	
Current (I _{DD}) - 3.3V option	mA			80	
Output Load (HCSL)	Ω			50	
Output Logic Levels High (V _{OH})	mV	600		900	
Output Logic Levels Low (V _{OL})	V	0		50	
Rise (TR) and Fall (TF) Time	ns		0.4	0.7	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1	

Outline Drawing & Land Pattern

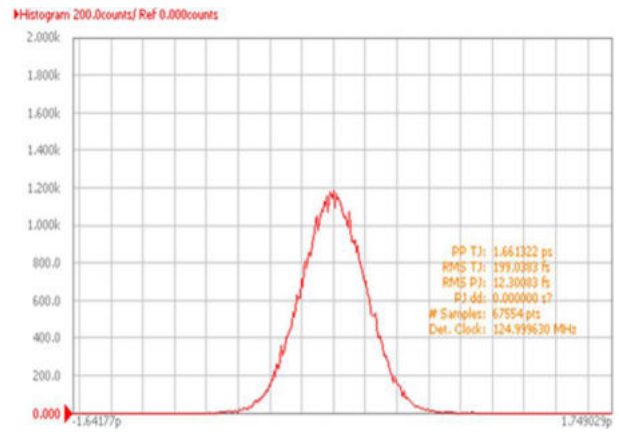
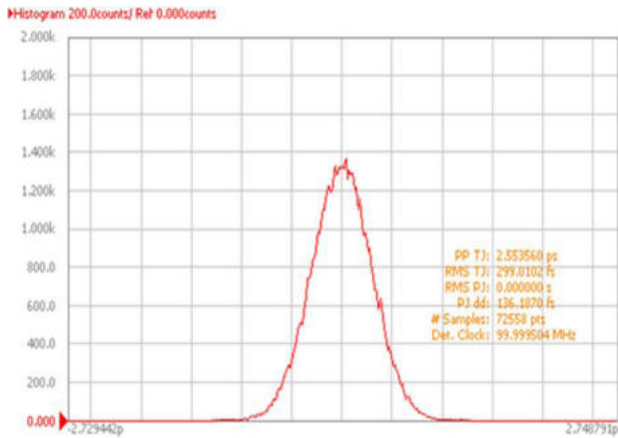
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



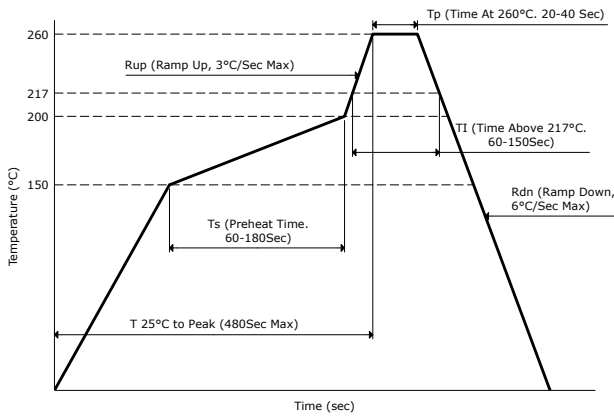
PIN	FUNCTION
1	E/D or NC
2	E/D or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (HCSL)
Waveform (HCSL)

Typical Phase Noise Performance (Measured By Agilent E5052A)


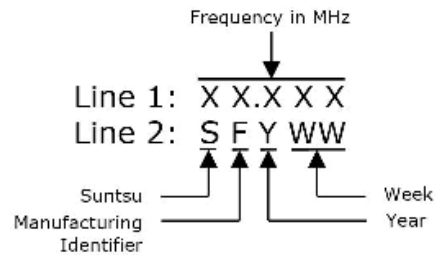
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



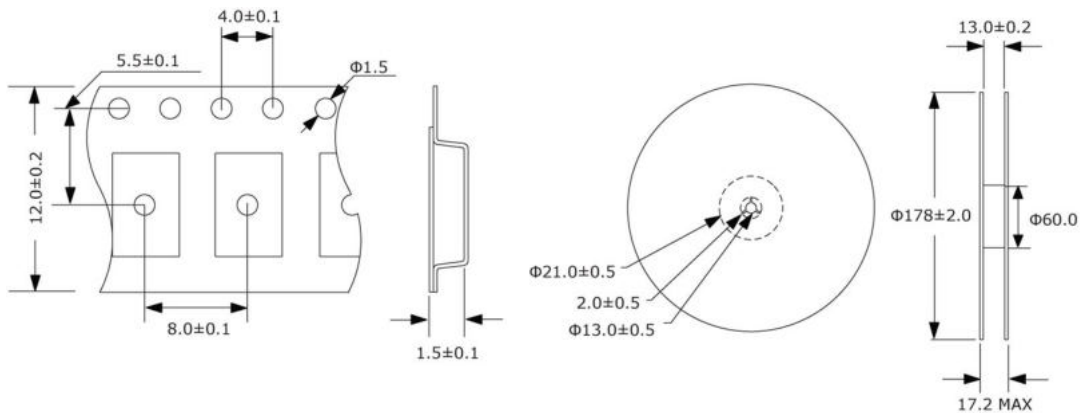
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

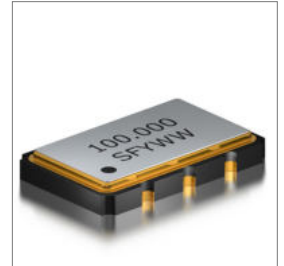
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±20ppm (Frequency Stability) Available Ceramic Package LVDS Tape and Reel

Applications
<ul style="list-style-type: none"> Fiber Channel Gigabit Ethernet PCI Express



Part Numbering Guide

SXO 53 L 3 A 48 1 - 100.000M

SUNTSU OSC

5.0mm x 3.2mm

LVDS

SUPPLY VOLTAGE

2 : 2.5V±5%

3 : 3.3V±5%

FREQUENCY STABILITY

A : ±50ppm

B : ±30ppm

C : ±25ppm

*D : ±20ppm

FREQUENCY MHz

TRI-STATE (ENABLE/DISABLE)

1 : Pin 1

2 : Pin 2

OPERATING TEMPERATURE RANGE

07 : 0°C - +70°C

16 : -10°C - +60°C

17 : -10°C - +70°C

27 : -20°C - +70°C

38 : -30°C - +85°C

48 : -40°C - +85°C

Cage Code : 4GUT4

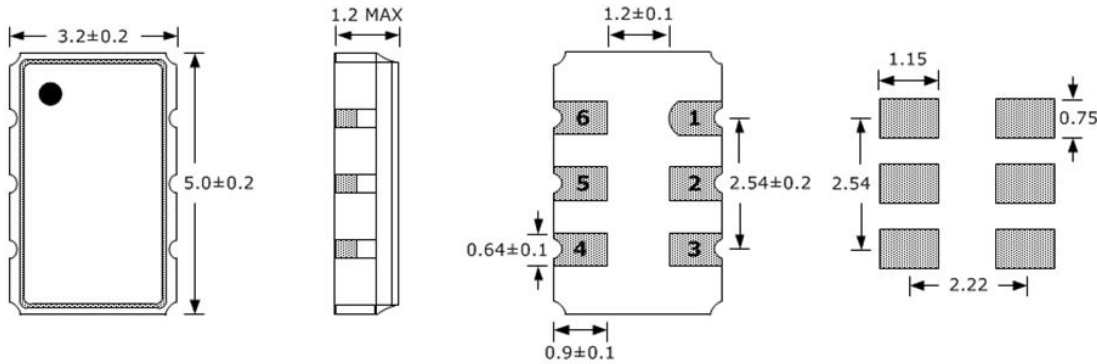
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	80		170	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD}) - 2.5V Option	mA			50	
Current (I _{DD}) - 3.3V Option	mA			60	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	330	454	
Differential Output Error (ΔV _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (ΔV _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns		0.4	0.8	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.4	1	

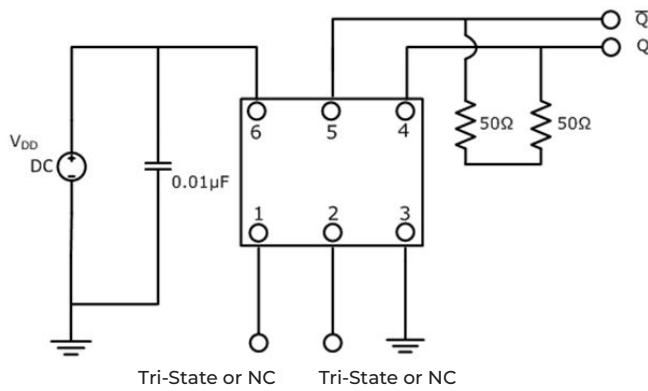
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

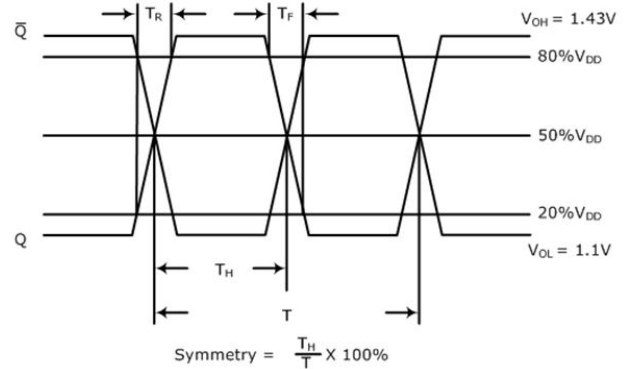


PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

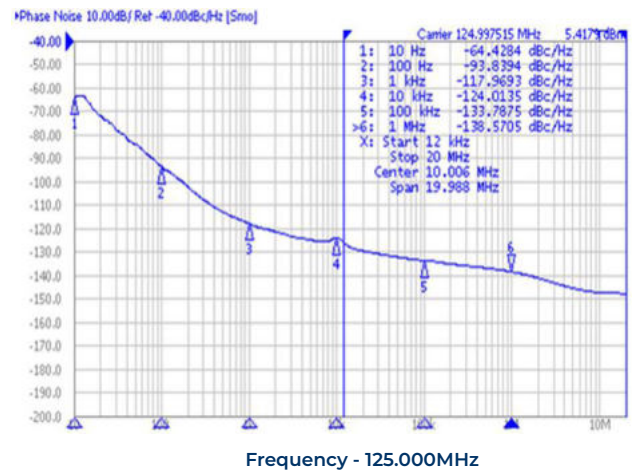
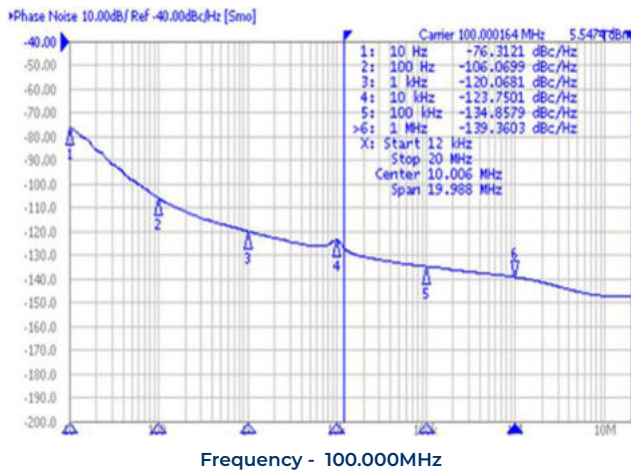
Test Circuit (LVDS)



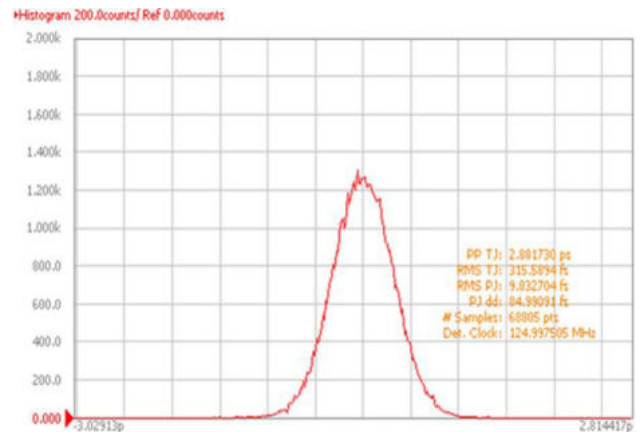
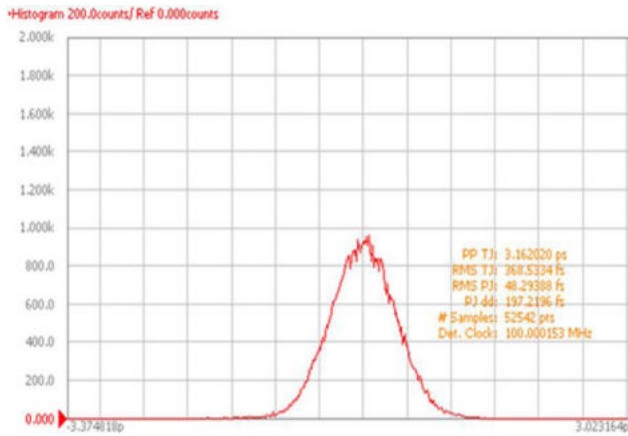
Waveform (LVDS)



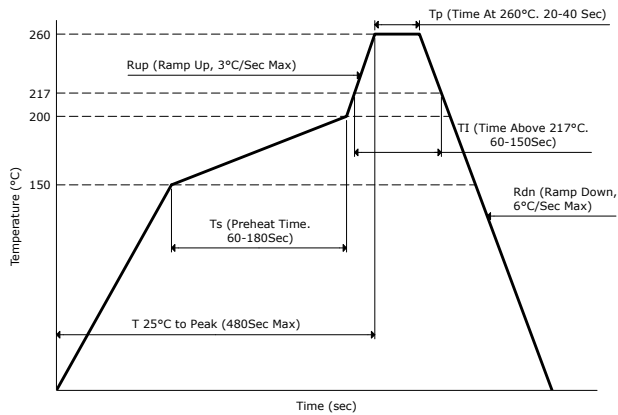
Typical Phase Noise Performance (Measured By Agilent E5052A)



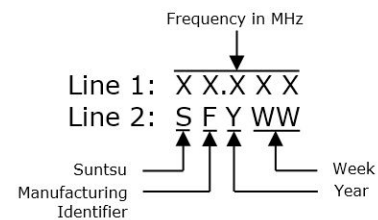
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



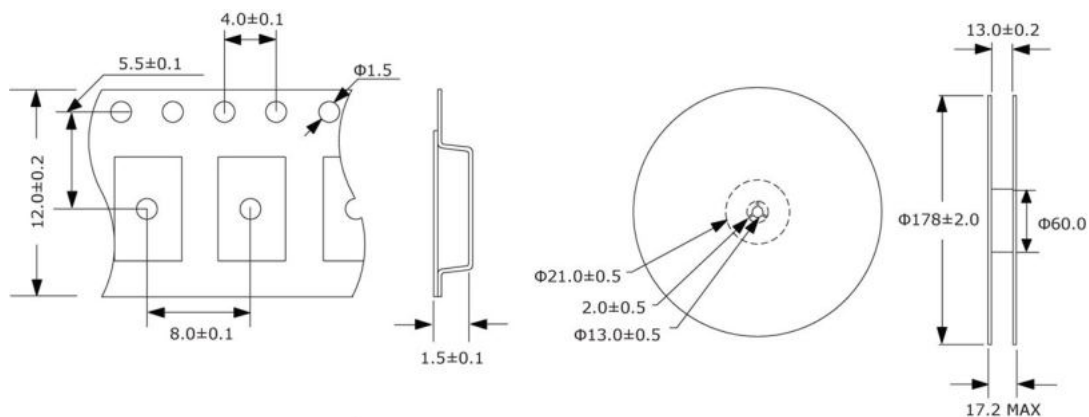
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

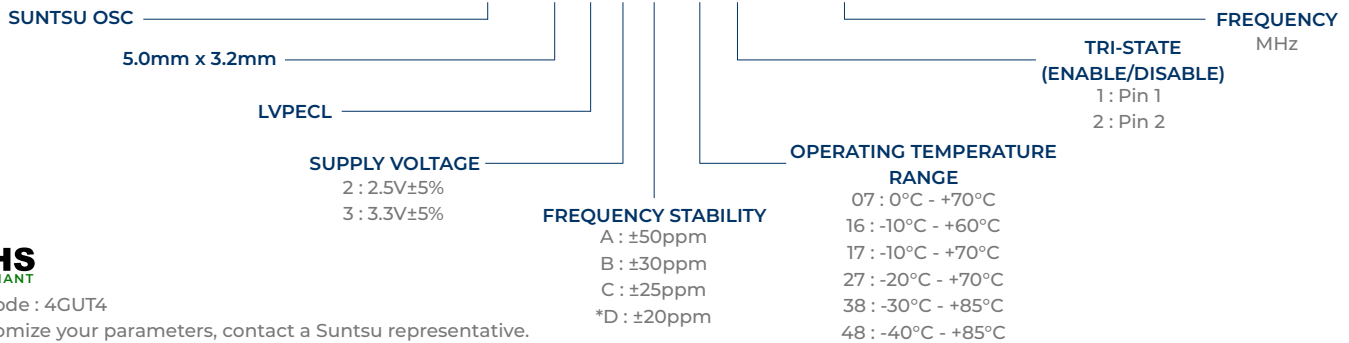
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±20ppm (Frequency Stability) Available Ceramic Package LVPECL Tape and Reel

Applications
<ul style="list-style-type: none"> Fiber Channel Gigabit Ethernet PCI Express


Part Numbering Guide
SXO 53 P 3 A 48 1 - 156.250M


Cage Code : 4GUT4

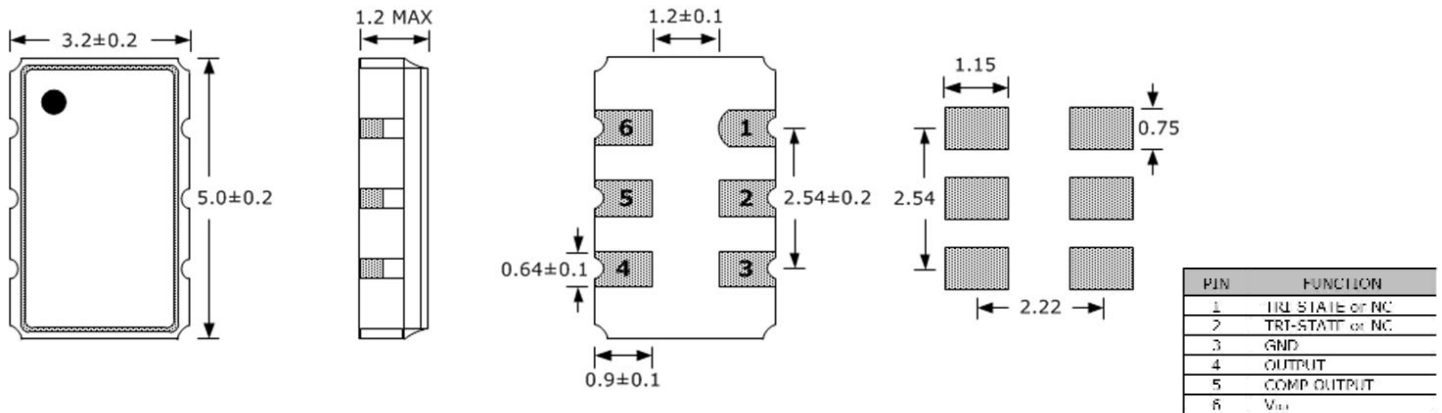
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	20		200	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			65	
Current (I _{DD}) - 3.3V option	mA			80	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	V	V _{DD} -1.025			
Output Logic Levels Low (V _{OL})	V			V _{DD} -1.62	
Rise (TR) and Fall (TF) Time	ns		0.4	0.8	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.4	1	

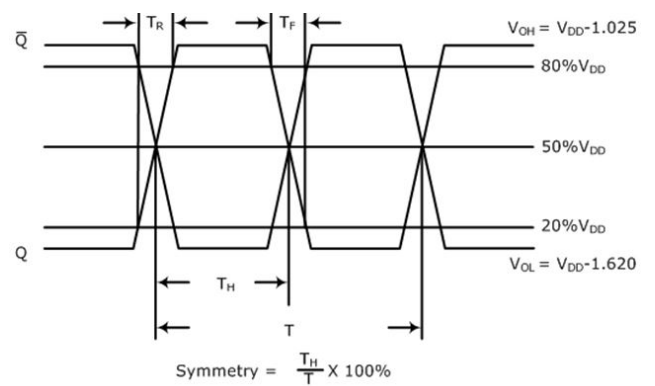
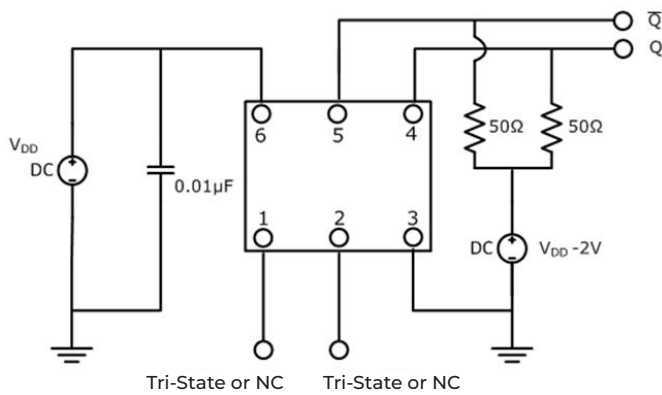
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

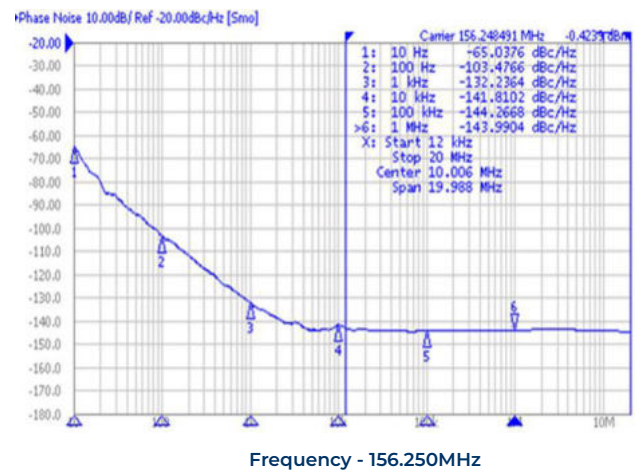
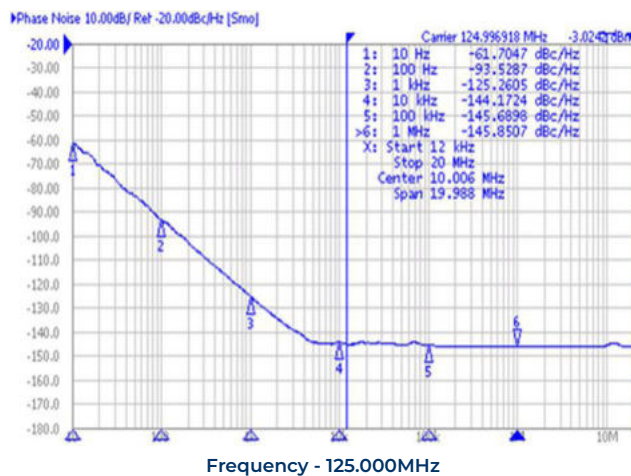


Test Circuit (LVPECL)

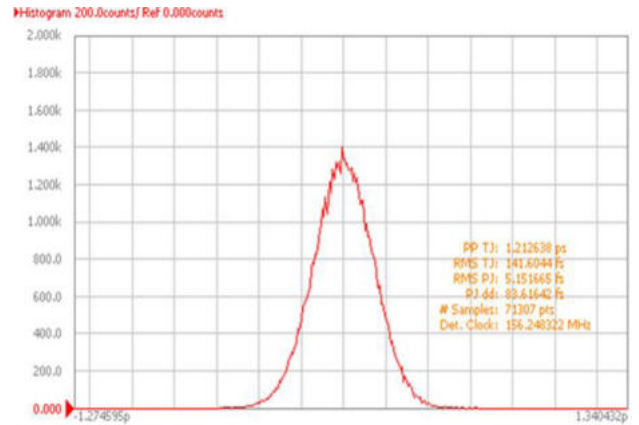
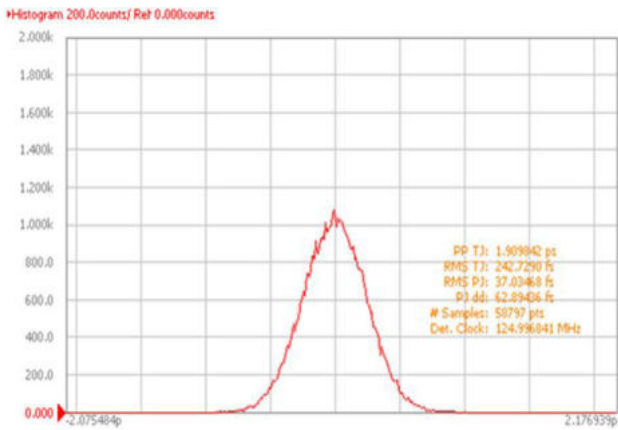
Waveform (LVPECL)



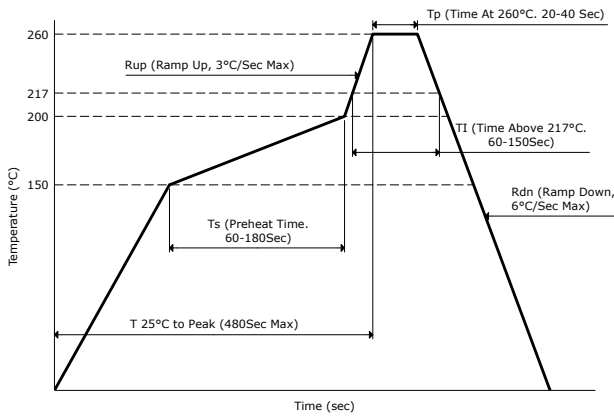
Typical Phase Noise Performance (Measured By Agilent E5052A)



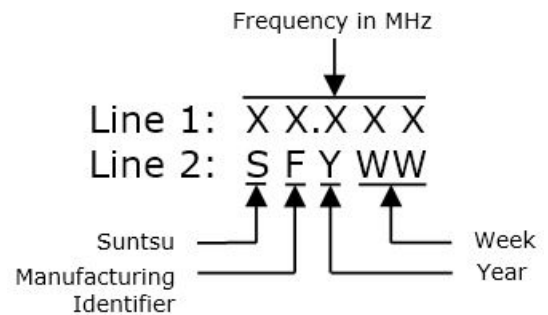
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



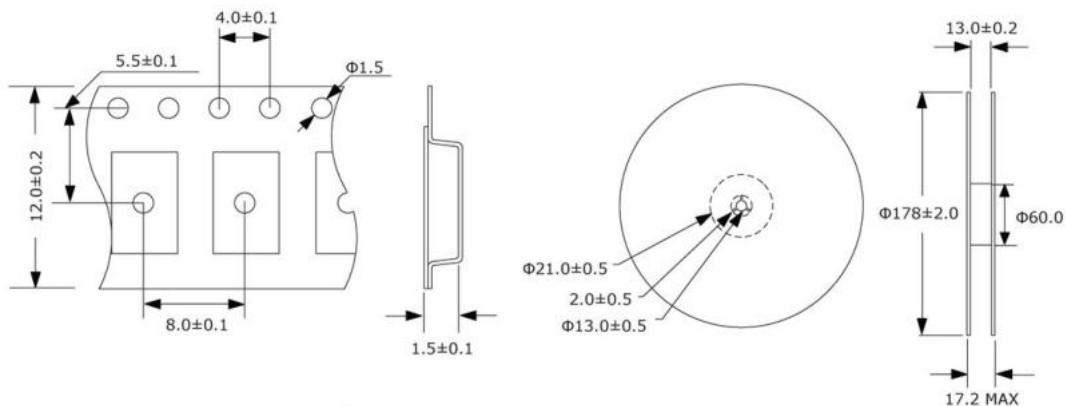
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

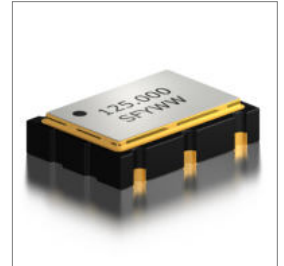
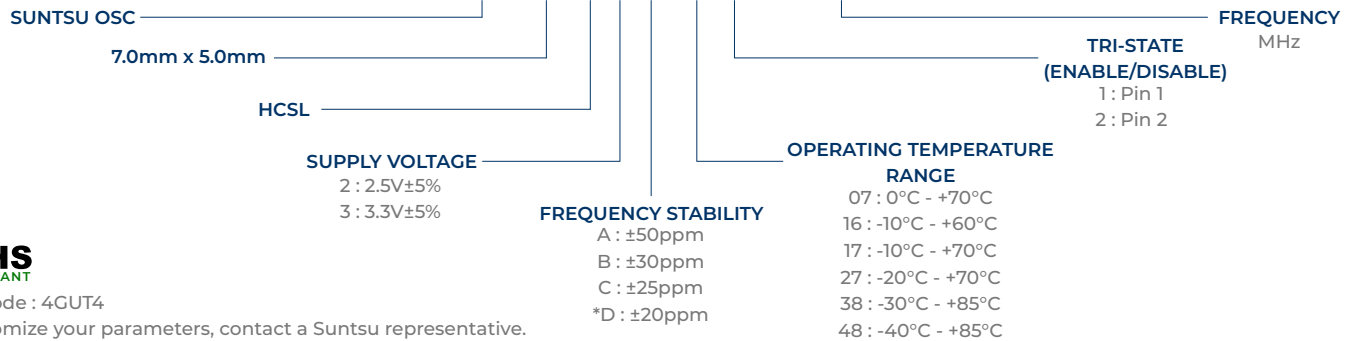
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> • ± 20ppm (Frequency Stability) Available • Ceramic Package • HCSL • Tape and Reel

Applications
<ul style="list-style-type: none"> • Fiber Channel • Gigabit Ethernet • PCI Express


Part Numbering Guide
SXO 75 H 3 A 48 1 - 125.000M


Cage Code : 4GUT4

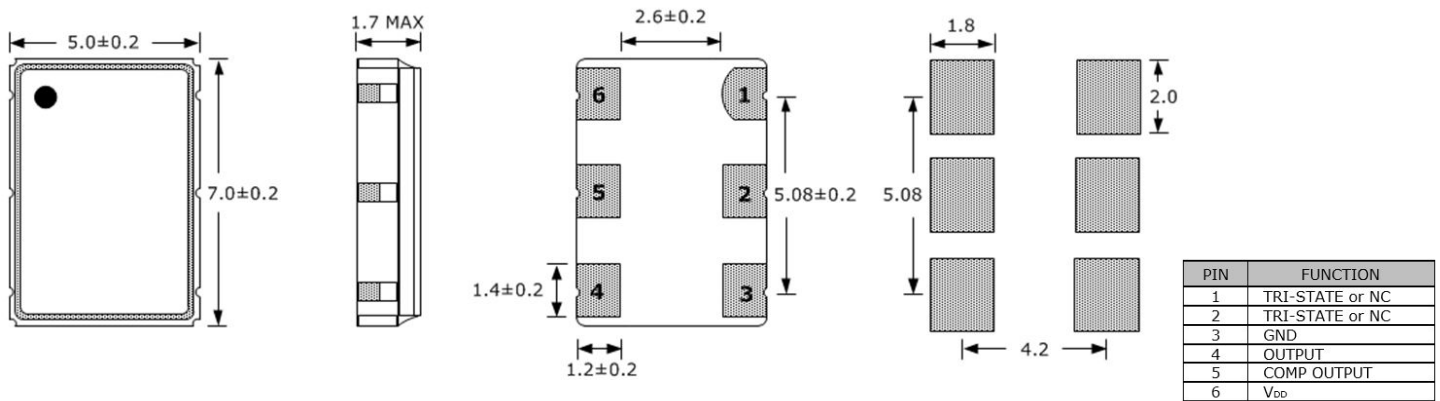
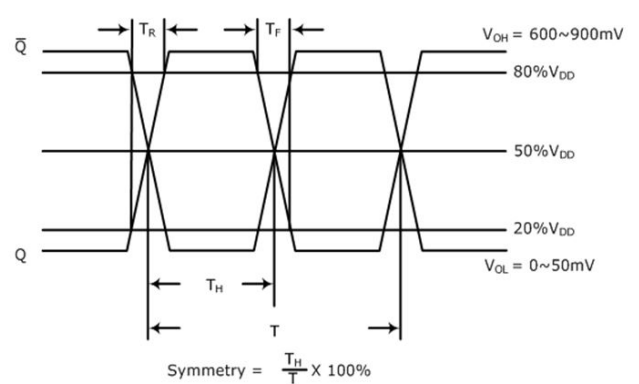
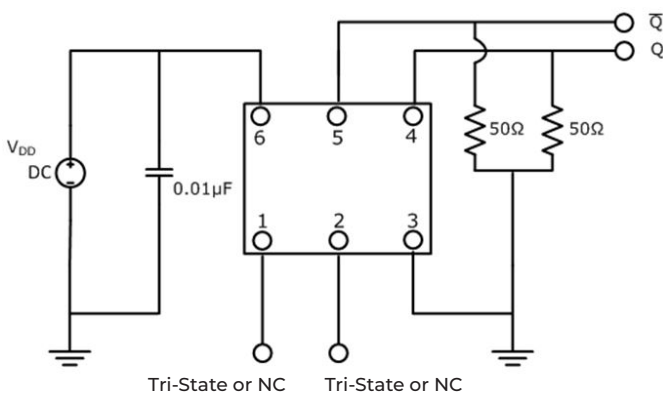
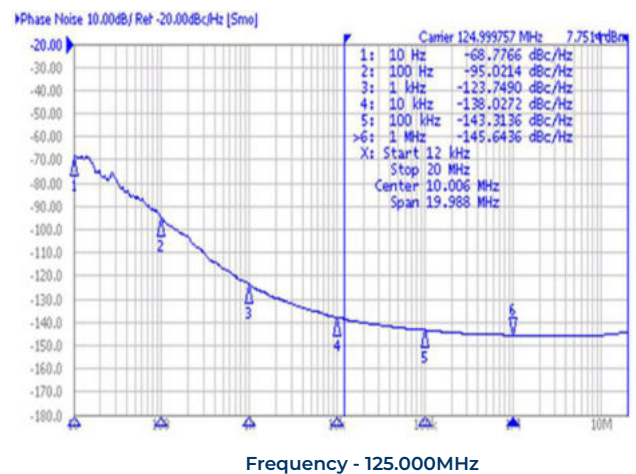
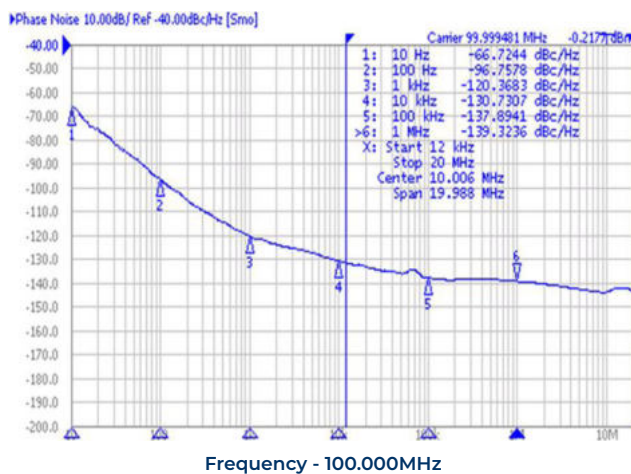
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

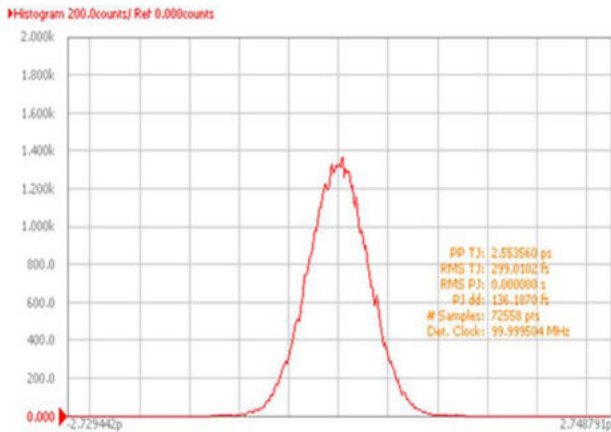
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	100		125	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			60	
Current (I _{DD}) - 3.3V option	mA			80	
Output Load (HCSL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	mV	600		900	
Output Logic Levels Low (V _{OL})	V	0		50	
Rise (TR) and Fall (TF) Time	ns		0.4	0.7	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.5	1	

Outline Drawing & Land Pattern

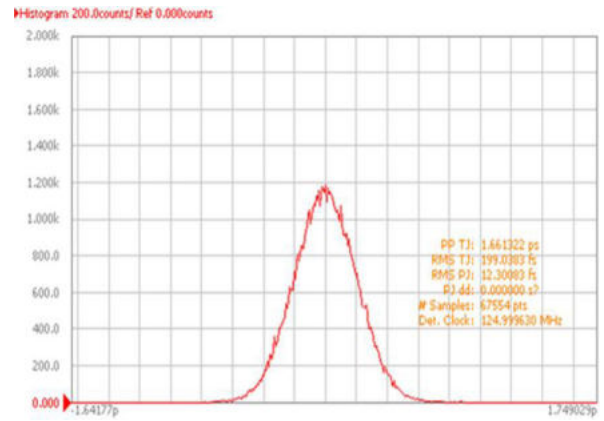
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.


Test Circuit (HCSL)
Waveform (HCSL)

Typical Phase Noise Performance (Measured By Agilent E5052A)


Typical Jitter Performance (Measured By Agilent E5052A)

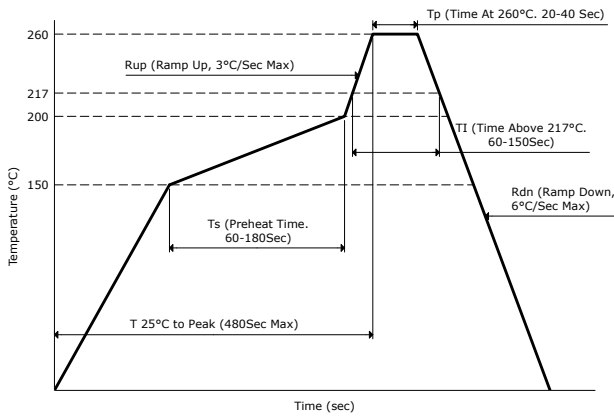


Frequency - 100.000MHz

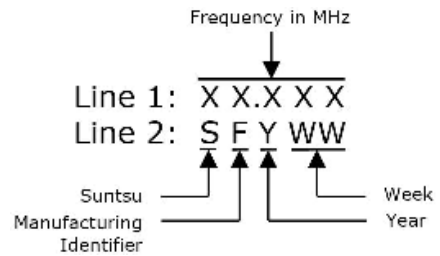


Frequency - 125.000MHz

Reflow Profile



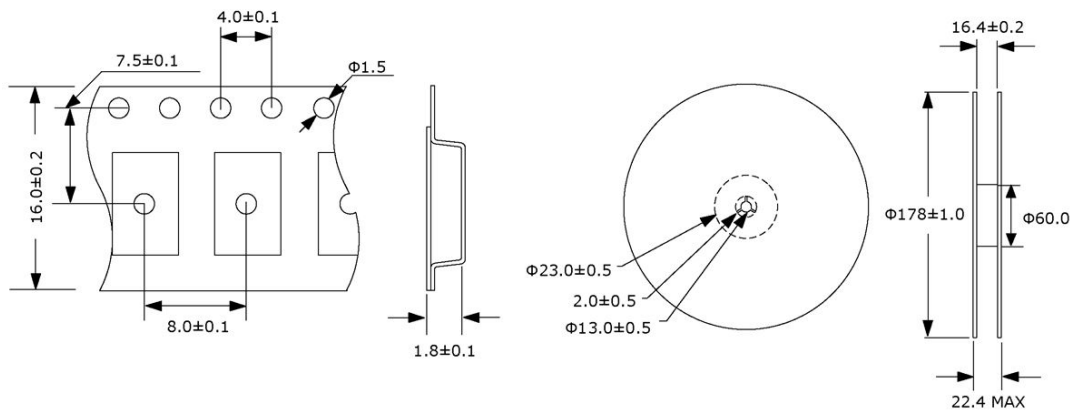
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

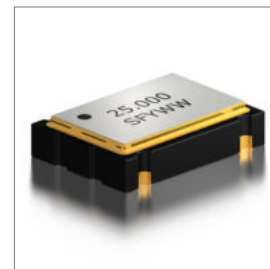
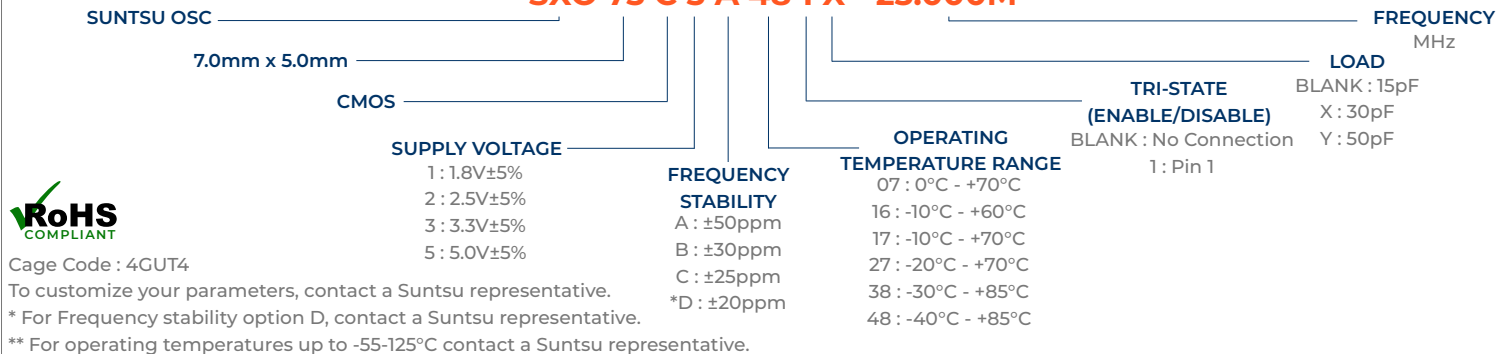
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
• ± 20 ppm (Frequency Stability) Available
• Ceramic Package
• CMOS
• Tape and Reel

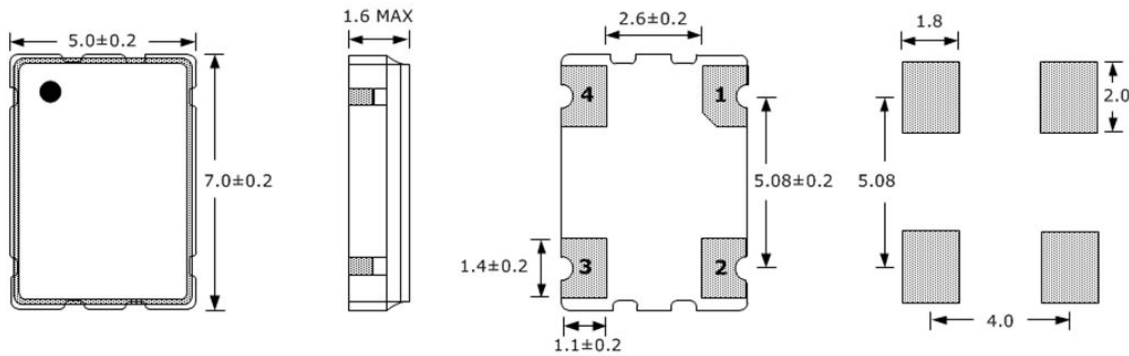
Applications
• Micro Processors
• SONET/SDH/DWDM
• Storage Area/Networking
• Digital Video
• Base Stations


Part Numbering Guide
SXO 75 C 3 A 48 1 X - 25.000M


Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	KHz	32.768*			(*32.768KHz not available in 5.0V)
Frequency Range	MHz	1		200*	(*125MHz Max for 5.0V Option)
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V option	V	1.710	1.8	1.890	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.75	5.0	5.25	
Frequency Range		1.8V	2.5V	3.3V / 5.0V	
Current (I _{DD})	mA	5	5	5 / *NA	Maximum Value (*32.768KHz not available in 5.0V)
1.0000MHz - 34.999MHz	mA	8	10	16 / 25	Maximum Value
35.000MHz - 59.999MHz	mA	10	20	25 / 40	Maximum Value
60.000MHz - 99.000MHz	mA	25	30	40 / 70	Maximum Value
100.000MHz - 200.000MHz	mA	35	50	65 / 90*	Maximum Value (*at 125MHz Max for 5.0V)
Output Load (CMOS)	pF			15	See part numbering guide for options
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			200	
32.768KHz	ns			10	
1.0000MHz - 34.999MHz	ns			6	
35.000MHz - 99.999MHz	ns			3	
100.000MHz - 200.000MHz	ns				
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

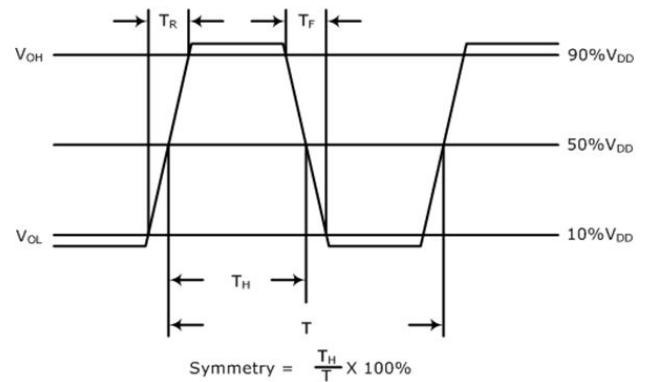
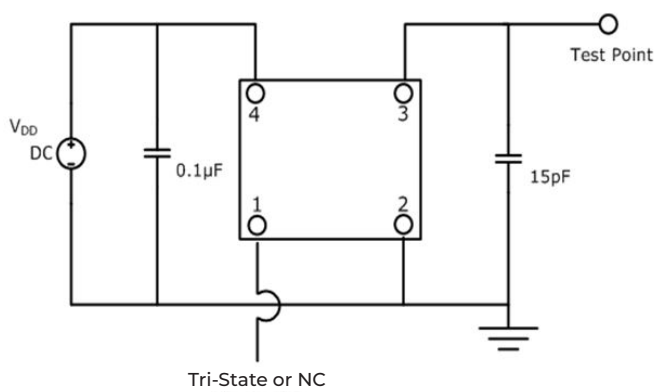
Outline Drawing & Land Pattern

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

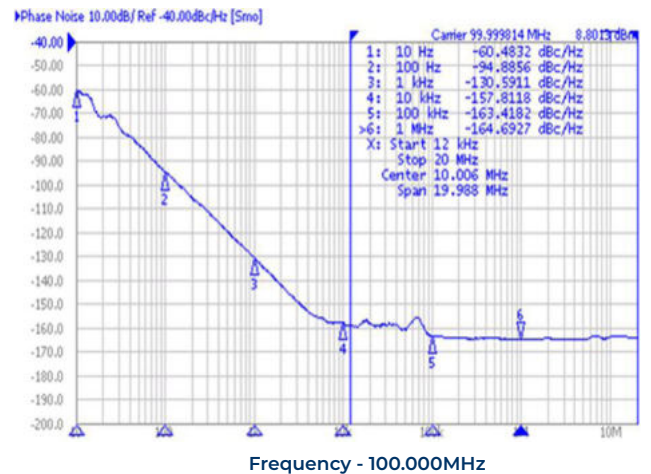
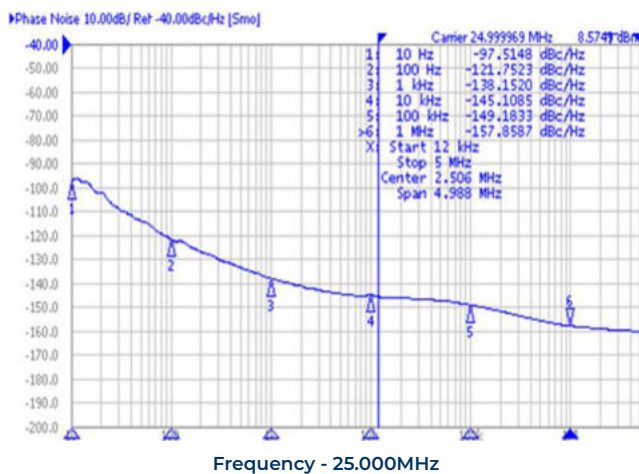


Test Circuit (CMOS)

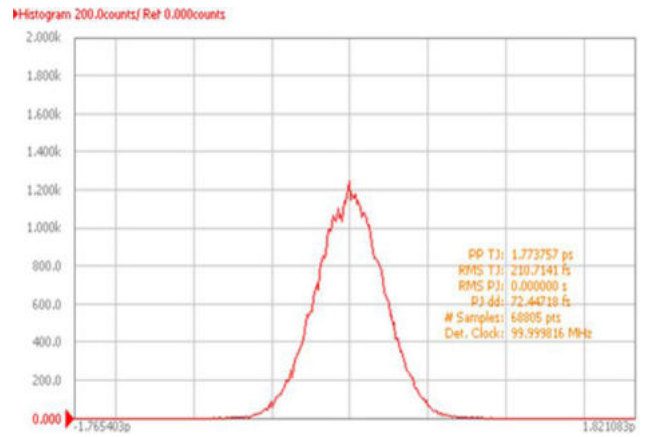
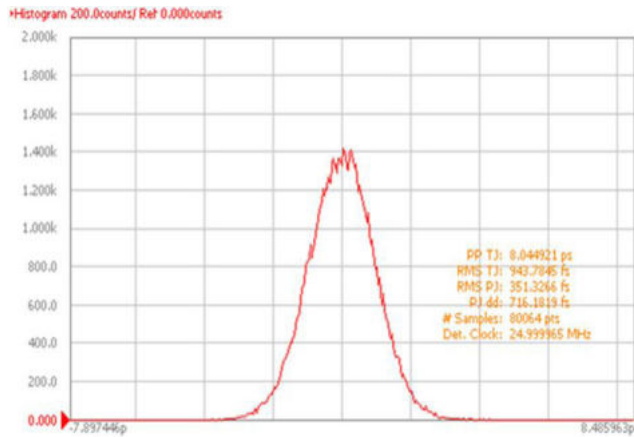
Waveform (CMOS)



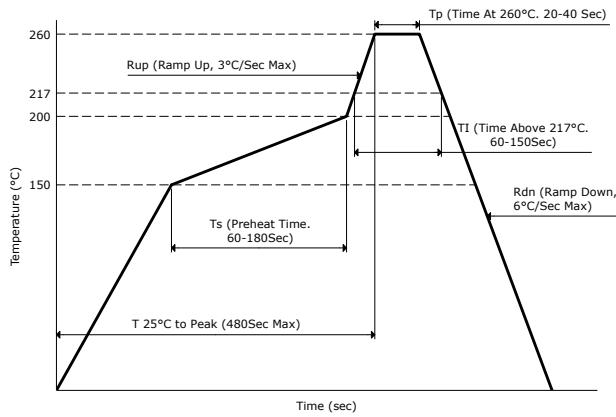
Typical Phase Noise Performance (Measured By Agilent E5052A)



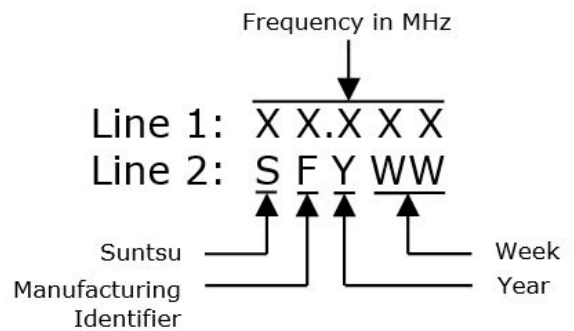
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



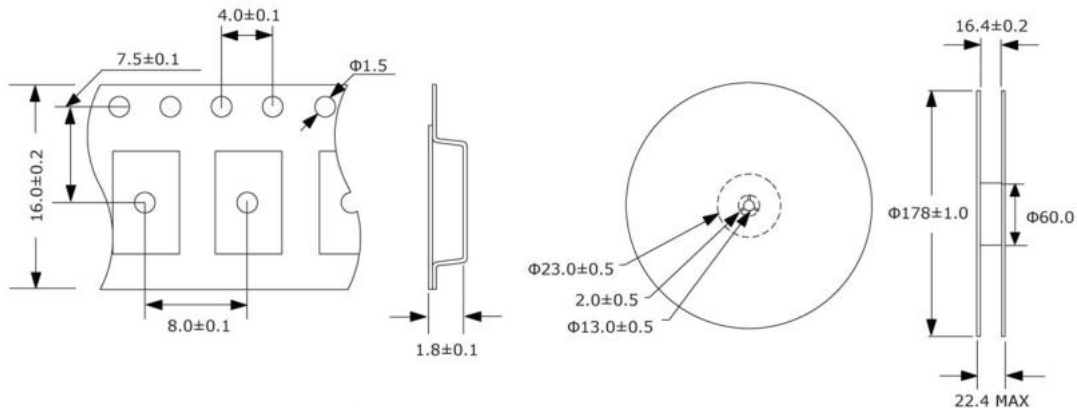
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

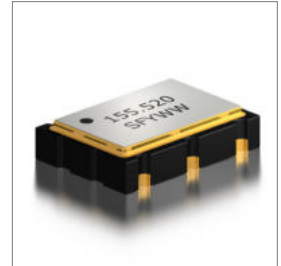
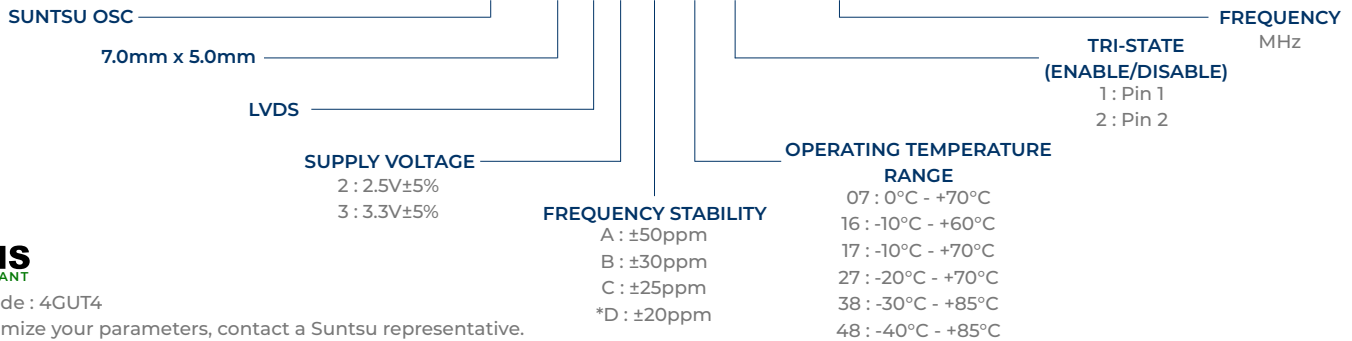
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±20ppm (Frequency Stability) Available Ceramic Package LVDS Tape and Reel

Applications
<ul style="list-style-type: none"> Fiber Channel Gigabit Ethernet PCI Express


Part Numbering Guide
SXO 75 L 3 A 48 1 - 155.520M


Cage Code : 4GUT4

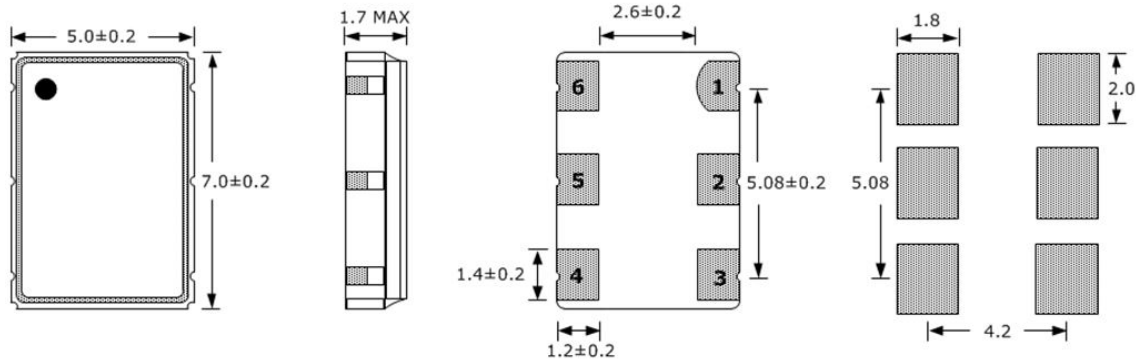
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	80		260	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V Option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V Option	V	3.135	3.3	3.465	
Current (I _{DD}) - 2.5V Option	mA			50	
Current (I _{DD}) - 3.3V Option	mA			60	
Output Load (LVDS)	Ω			100	
Output Logic Levels High (V _{OH})	V		1.43	1.6	
Output Logic Levels Low (V _{OL})	V	0.9	1.1		
Differential Output Voltage (V _{OD})	mV	247	330	454	
Differential Output Error (ΔV _{OD})	mV			50	
Offset Voltage (V _{OS})	V	1.125	1.250	1.375	
Offset Error (ΔV _{OS})	mV			50	
Rise (TR) and Fall (TF) Time	ns		0.4	0.8	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.4	1	

Outline Drawing & Land Pattern

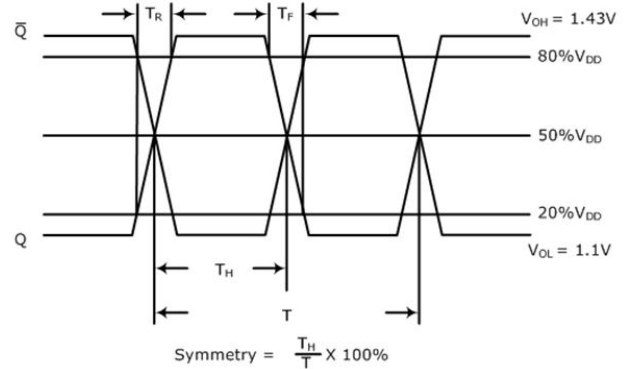
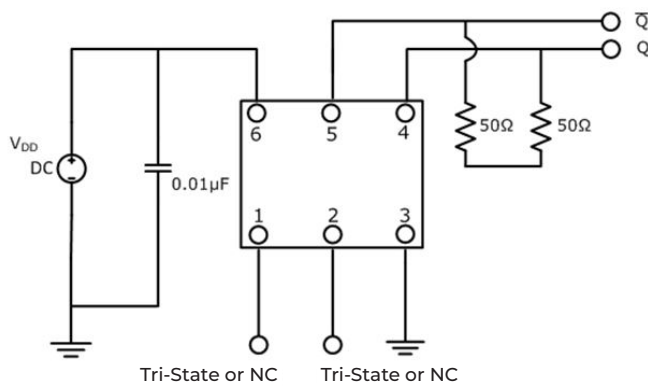
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



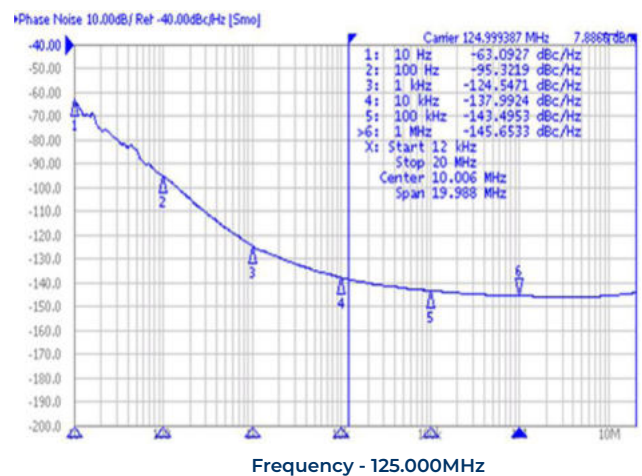
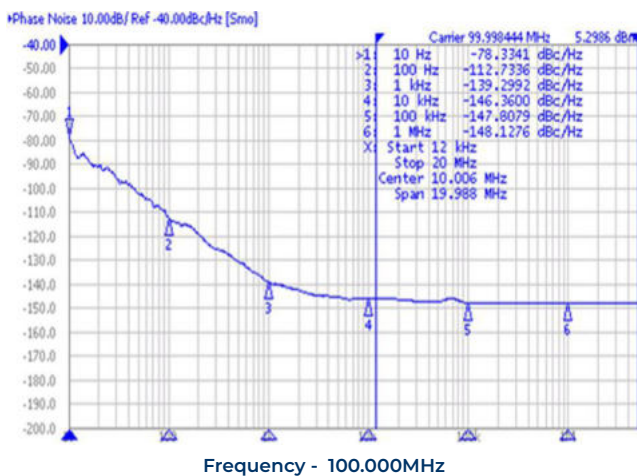
PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVDS)

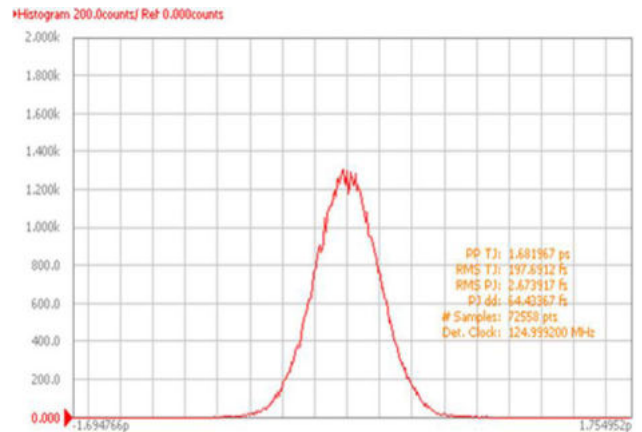
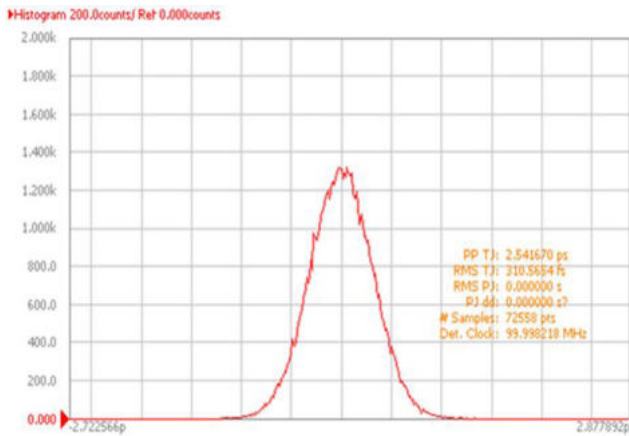
Waveform (LVDS)



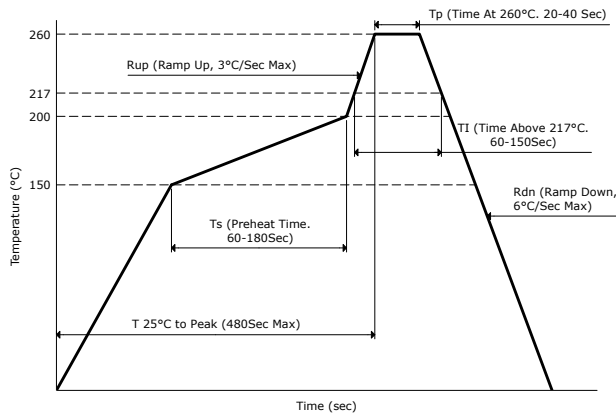
Typical Phase Noise Performance (Measured By Agilent E5052A)



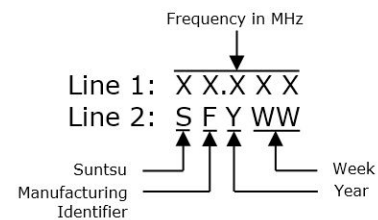
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



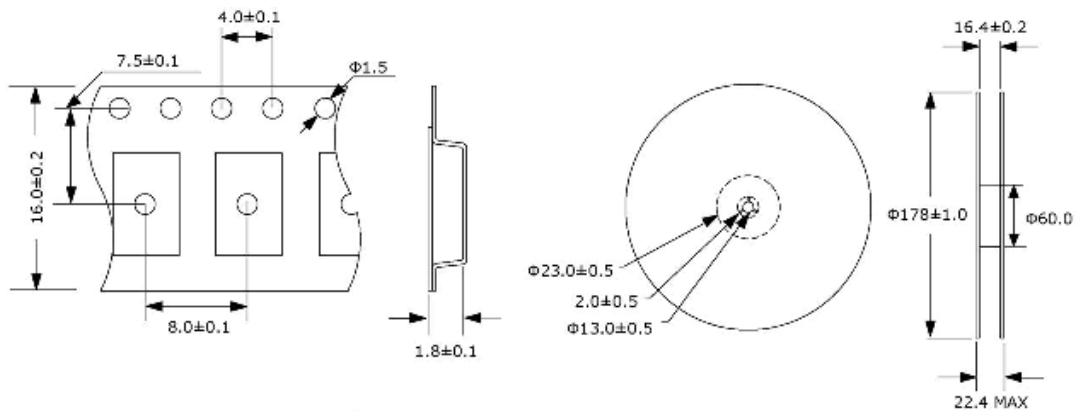
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

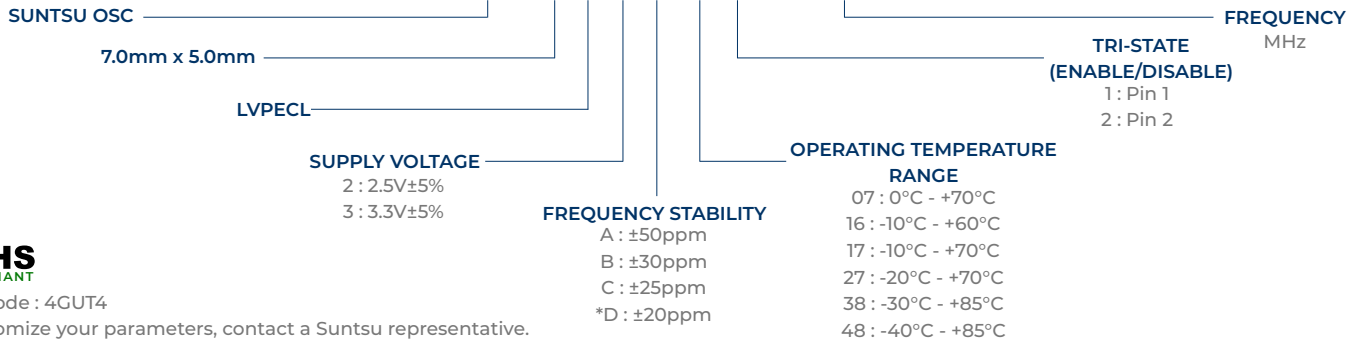
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> • ± 20ppm (Frequency Stability) Available • Ceramic Package • LVPECL • Tape and Reel

Applications
<ul style="list-style-type: none"> • Fiber Channel • Gigabit Ethernet • PCI Express


Part Numbering Guide
SXO 75 P 3 A 48 1 - 156.250M


Cage Code : 4GUT4

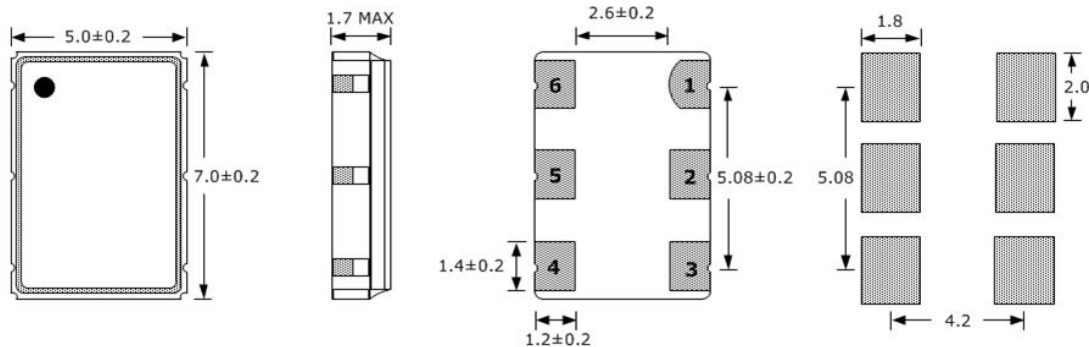
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	20		200	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.125	3.3	3.465	
Current (I _{DD}) - 2.5V option	mA			65	
Current (I _{DD}) - 3.3V option	mA			80	
Output Load (LVPECL)	Ω			50	50 Ω into V _{DD} -2.0V _{DC}
Output Logic Levels High (V _{OH})	V	V _{DD} -1.025			
Output Logic Levels Low (V _{OL})	V			V _{DD} -1.62	
Rise (TR) and Fall (TF) Time	ns		0.4	0.8	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps		0.4	1	

Outline Drawing & Land Pattern

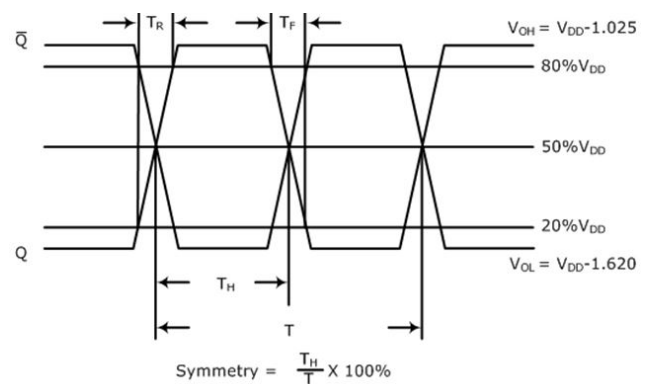
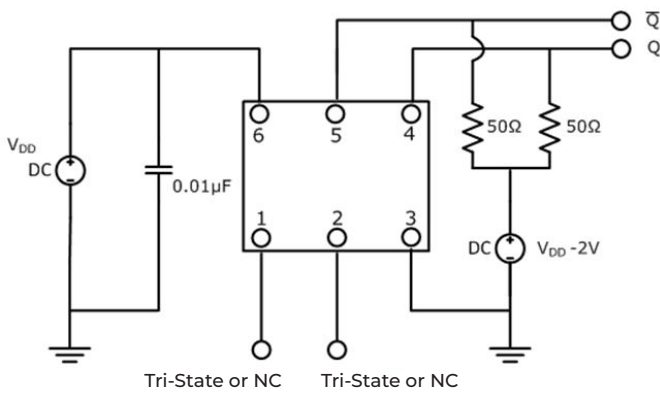
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



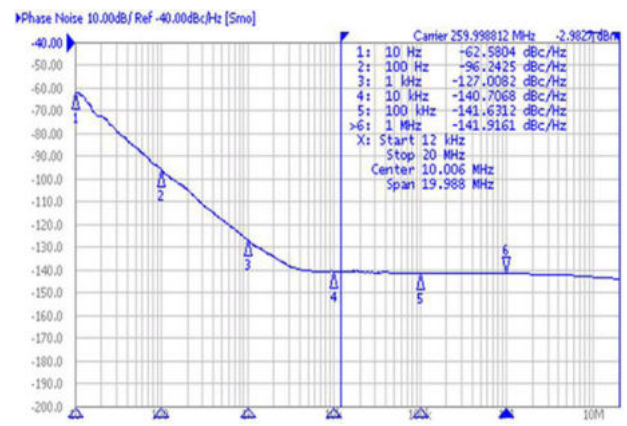
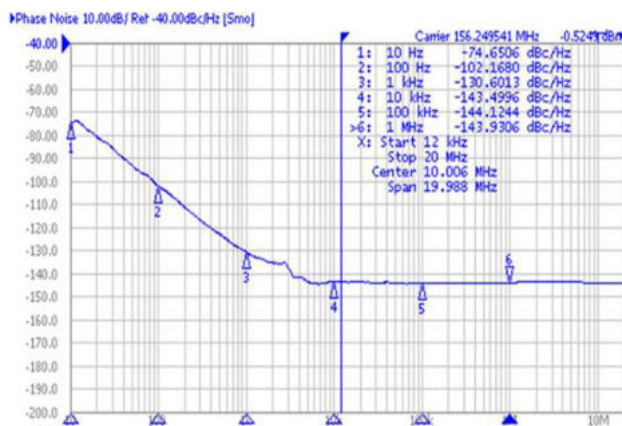
PIN	FUNCTION
1	TRI-STATE or NC
2	TRI-STATE or NC
3	GND
4	OUTPUT
5	COMP OUTPUT
6	V _{DD}

Test Circuit (LVPECL)

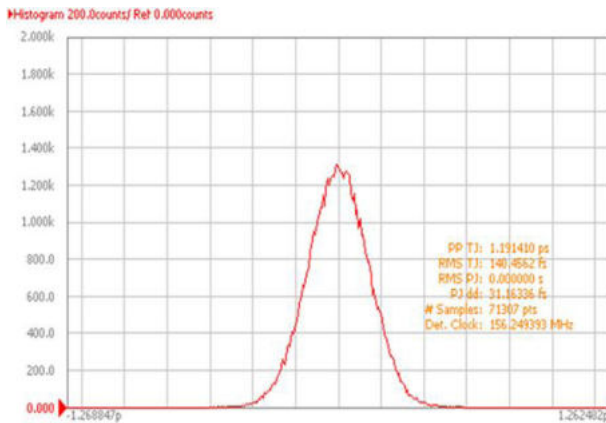
Waveform (LVPECL)



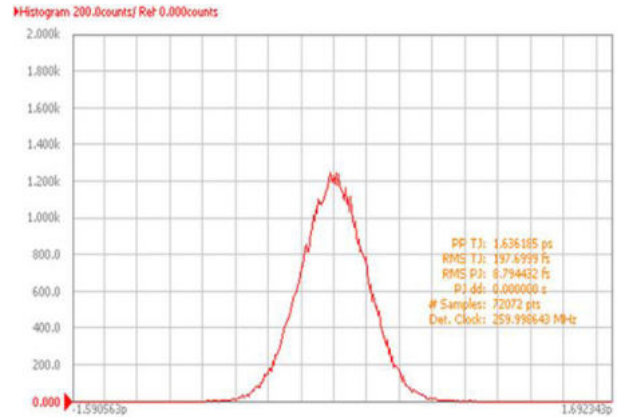
Typical Phase Noise Performance (Measured By Agilent E5052A)



Typical Jitter Performance (Measured By Agilent E5052A)

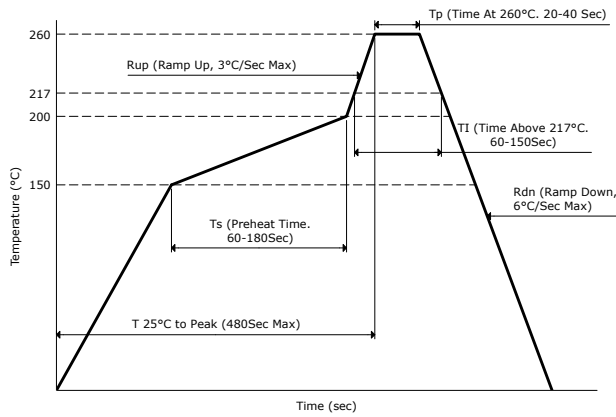


Frequency - 156.250MHz

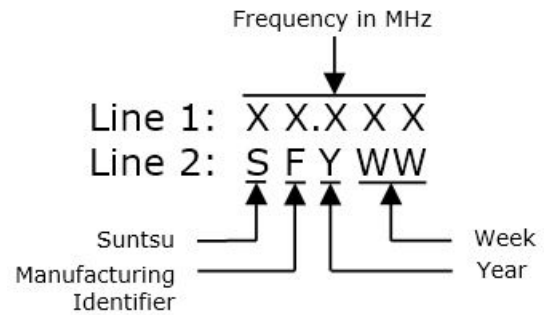


Frequency - 260.000MHz

Reflow Profile



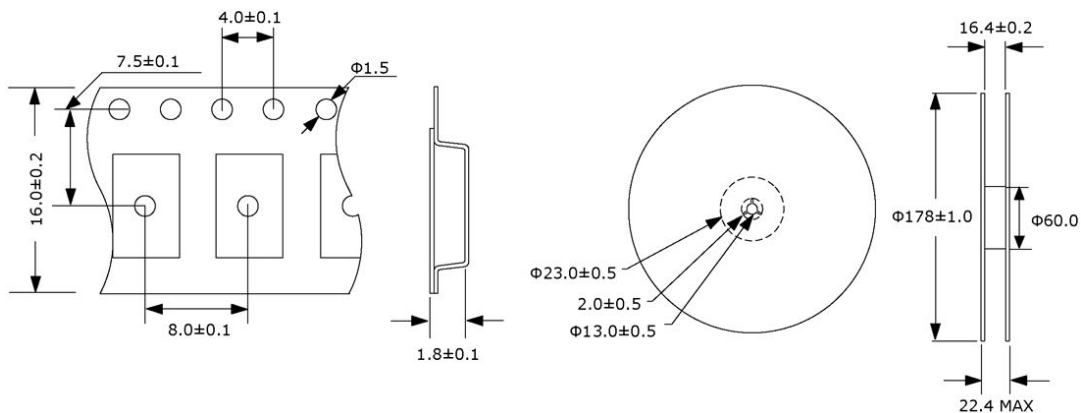
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

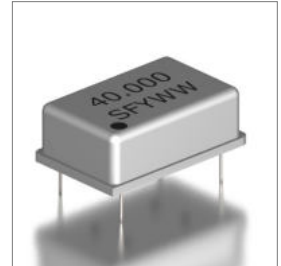
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±20ppm (Frequency Stability) Available Standard Full-Size Package CMOS/TTL Compatible

Applications
<ul style="list-style-type: none"> PC Monitor Vision Equipment Printer FAX



Part Numbering Guide

SXO FS C 3 A 48 1 - 40.000M

SUNTSU OSC

FULL SIZE

CMOS

SUPPLY VOLTAGE

2 : 2.5V±5%

3 : 3.3V±5%

5 : 5.0V±5%

FREQUENCY STABILITY

A : ±50ppm

B : ±30ppm

C : ±25ppm

*D : ±20ppm

OPERATING TEMPERATURE RANGE

07 : 0°C - +70°C

16 : -10°C - +60°C

17 : -10°C - +70°C

27 : -20°C - +70°C

38 : -30°C - +85°C

48 : -40°C - +85°C

FREQUENCY MHz

TRI-STATE (ENABLE/DISABLE)

BLANK : No Connection

1 : Pin 1

Cage Code : 4GUT4

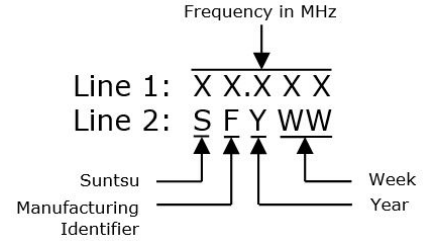
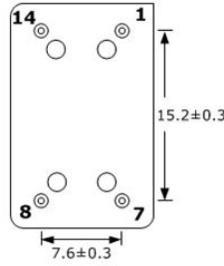
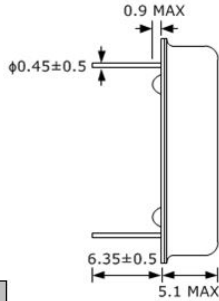
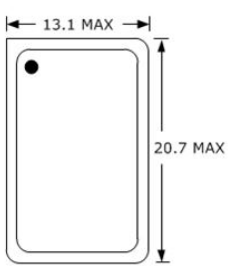
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	0.0327		155.52	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.750	5.0	5.250	
Current (I _{DD}) - 2.5V option	mA			20	
Current (I _{DD}) - 3.3V option	mA			30	
Current (I _{DD}) - 5.0V option	mA			40	
Output Load (CMOS)	pF			15	
Output Load (TTL)	TTL			10	
Output Logic Levels High (V _{OH}) - CMOS	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL}) - CMOS	V			0.1*V _{DD}	
Output Logic Levels High (V _{OH}) - TTL	V	2.4			
Output Logic Levels Low (V _{OL}) - TTL	V			0.4	
Rise (TR) and Fall (TF) Time	ns			5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

Outline Drawing & Part Marking

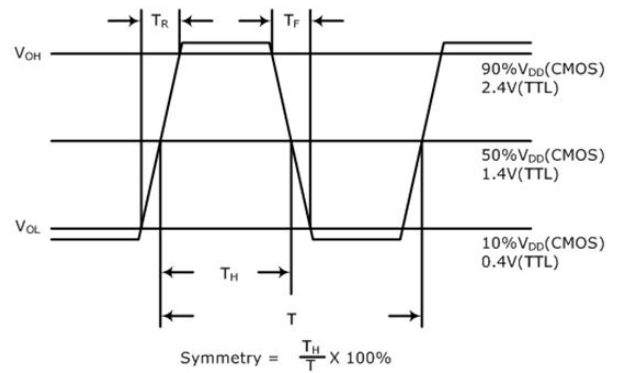
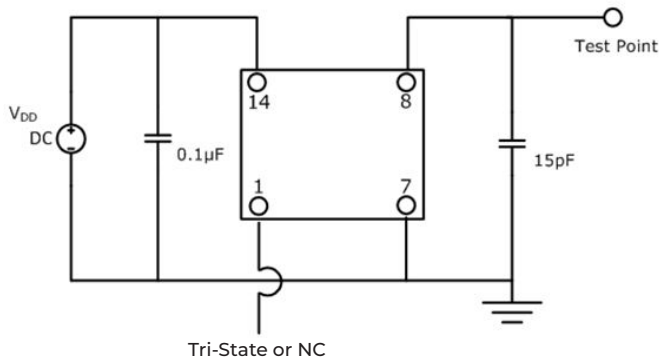
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



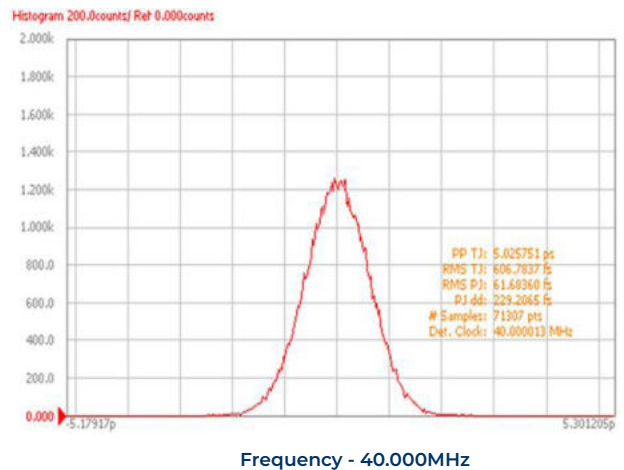
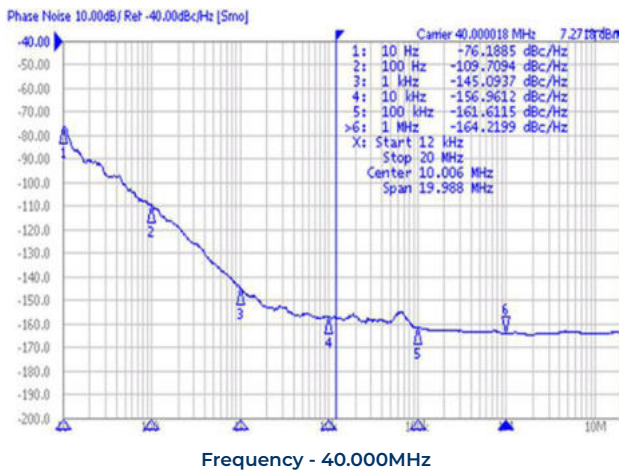
PIN	FUNCTION
1	TRI-STATE or NC
7	GND
8	OUTPUT
14	V _{DD}

Test Circuit (CMOS /TTL COMPATIBLE)

Waveform (CMOS /TTL COMPATIBLE)



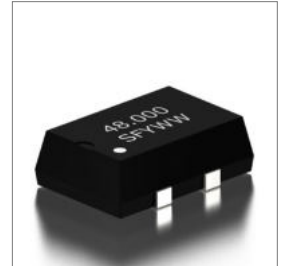
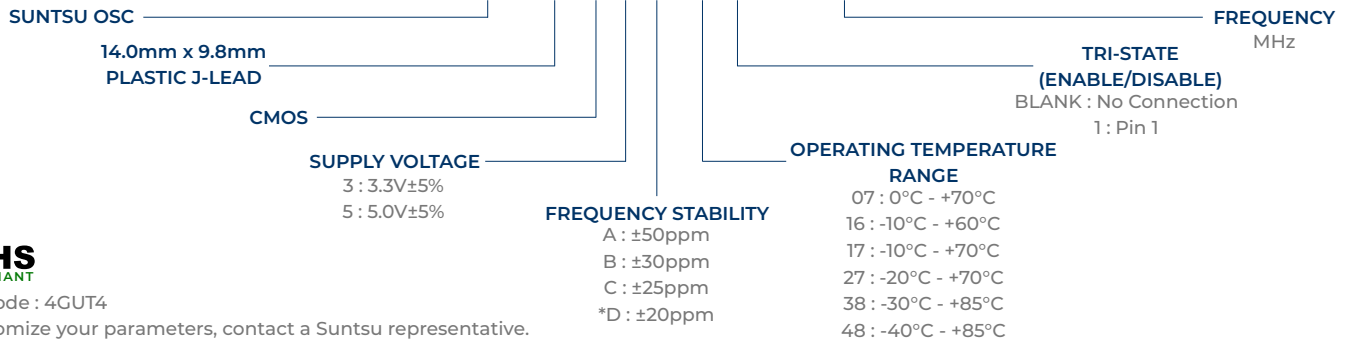
Typical Phase Noise & Jitter Performance (Measured By Agilent E5052A)



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> • ± 25ppm (Frequency Stability) Available • Plastic J-Lead Package • CMOS • Tape and Reel

Applications
<ul style="list-style-type: none"> • Micro Processors • FPGA • Storage Area/Networking • Digital Video • Portable Computers


Part Numbering Guide
SXO PJC 3 A 48 1 - 25.000M


Cage Code : 4GUT4

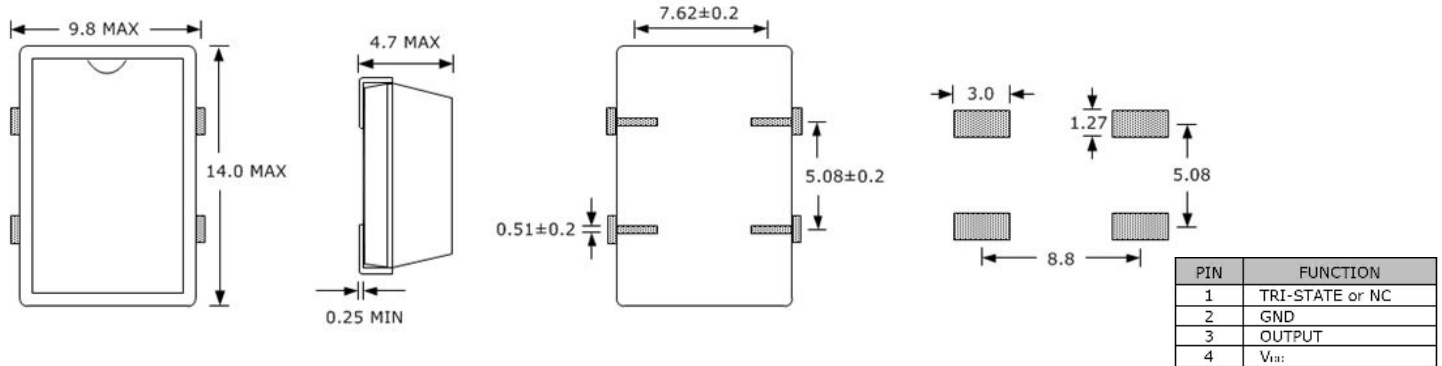
To customize your parameters, contact a Suntsu representative.

* For Frequency stability option D, contact a Suntsu representative.

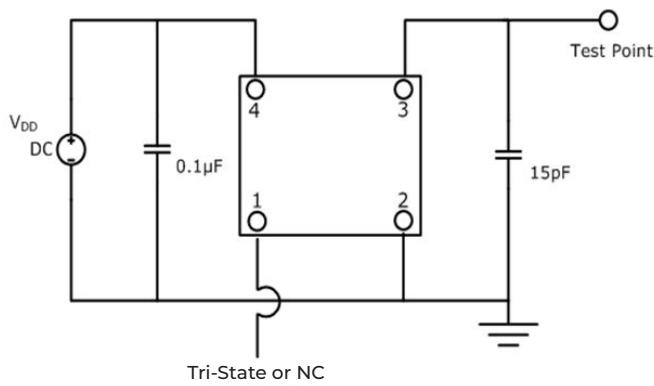
Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	1		125	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.750	5.0	5.250	
Current (I _{DD}) - 3.3V option	mA			35	
Current (I _{DD}) - 5.0V option	mA			45	
Output Load (CMOS)	pF			15	
Output Logic Levels High (V _{OH})	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL})	V			0.1*V _{DD}	
Rise (TR) and Fall (TF) Time	ns			7	
	ns			5	
	ns			4	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage(5.0V) - Enable	V	0.7*V _{DD}			No Connection
Tri-State Input Voltage(5.0V) - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			11	

Outline Drawing & Land Pattern

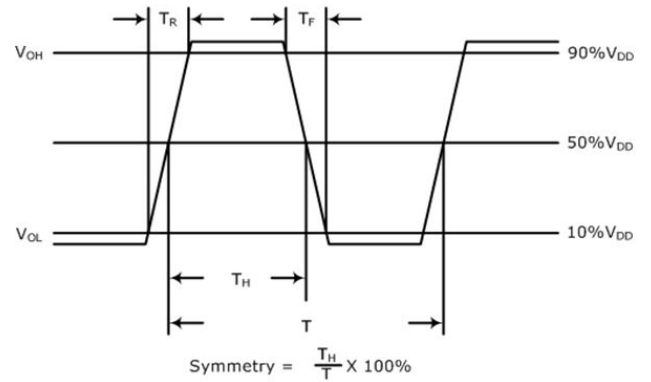
All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.



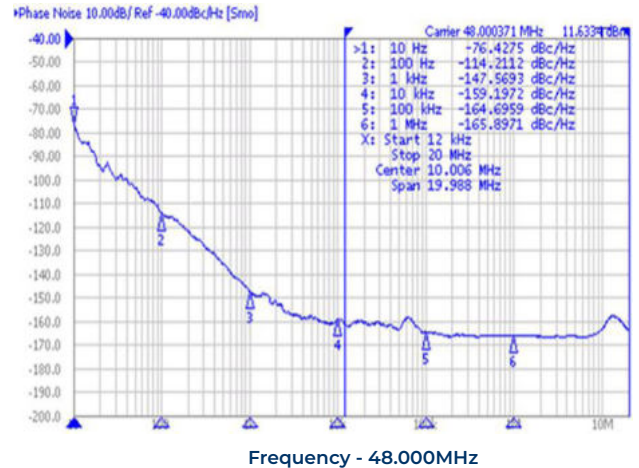
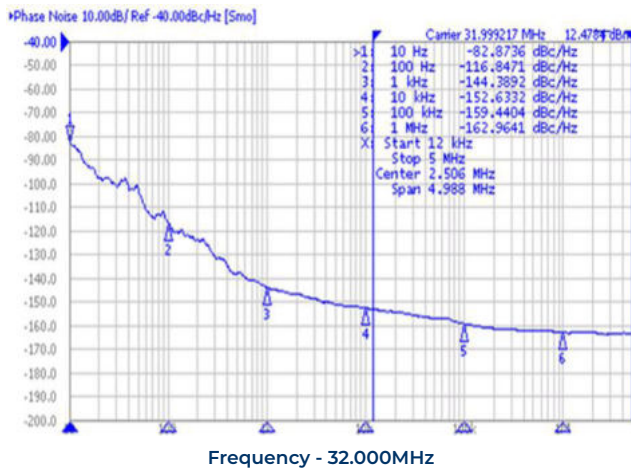
Test Circuit (CMOS)



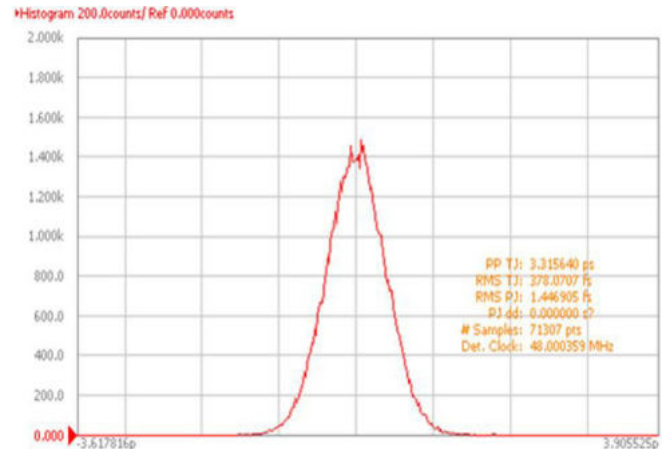
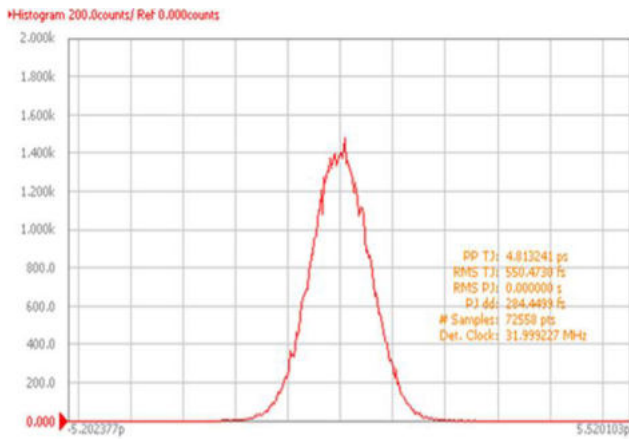
Waveform (CMOS)



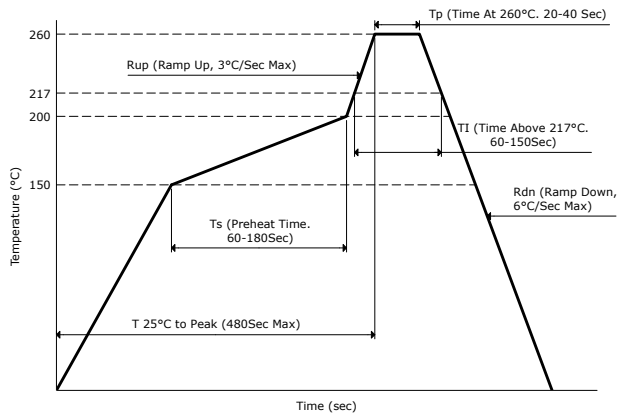
Typical Phase Noise Performance (Measured By Agilent E5052A)



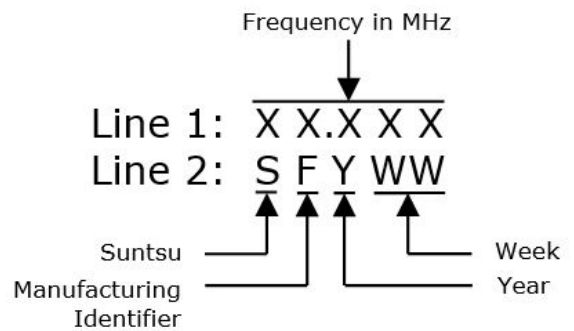
Typical Jitter Performance (Measured By Agilent E5052A)



Reflow Profile



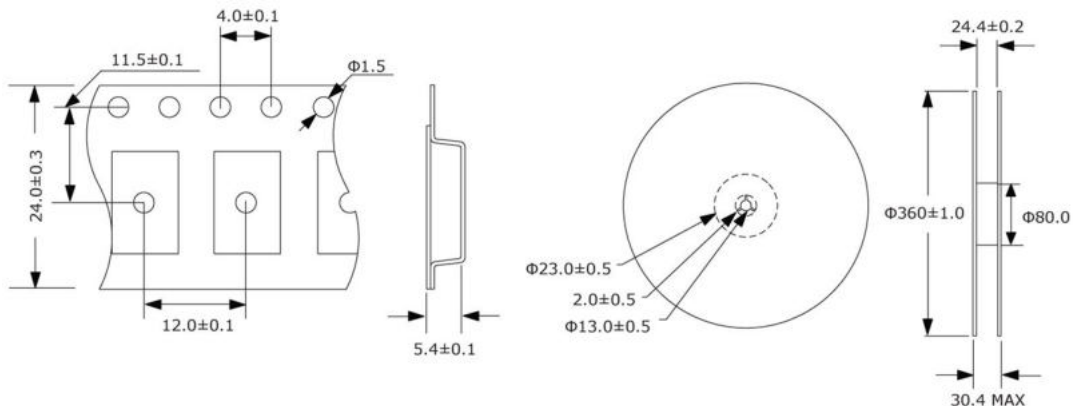
Part Marking



Tape And Reel Dimensions

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

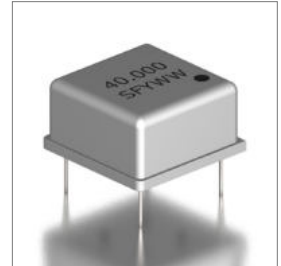
1,000pcs/Reel



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K

Features
<ul style="list-style-type: none"> ±20ppm (Frequency Stability) Available Standard Half-Size Package CMOS/TTL Compatible

Applications
<ul style="list-style-type: none"> PC Monitor Vision Equipment Printer FAX



Part Numbering Guide

SXO HS C 3 A 48 1 - 40.000M

SUNTSU OSC

HALF SIZE

CMOS

SUPPLY VOLTAGE

1 : 1.8V±5%

2 : 2.5V±5%

3 : 3.3V±5%

5 : 5.0V±5%

FREQUENCY STABILITY

A : ±50ppm

B : ±30ppm

C : ±25ppm

*D : ±20ppm

OPERATING TEMPERATURE RANGE

07 : 0°C - +70°C

16 : -10°C - +60°C

17 : -10°C - +70°C

27 : -20°C - +70°C

38 : -30°C - +85°C

48 : -40°C - +85°C

FREQUENCY
MHz

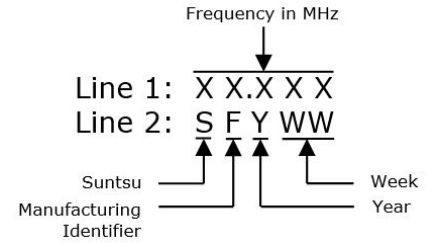
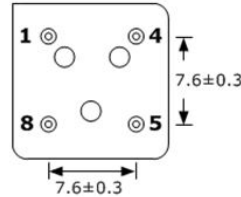
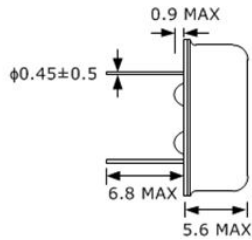
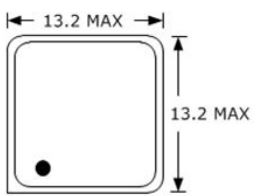
TRI-STATE (ENABLE/DISABLE)
BLANK : No Connection
1 : Pin 1

Cage Code : 4GUT4
To customize your parameters, contact a Suntsu representative.
* For Frequency stability option D, contact a Suntsu representative.

Electrical Parameters	Units	Minimum	Typical	Maximum	Remarks
Frequency Range	MHz	0.0327		155.52	
Frequency Stability (Includes Initial Tolerance at 25°C, Frequency Stability over Operating Temperature, Output Load Change, Supply Voltage Change, and First Year Aging at 25°C.)	ppm	-20		+20	See part numbering guide for options
Operating Temperature	°C	-40		+85	See part numbering guide for options
Storage Temperature	°C	-55		+125	
Supply Voltage (V _{DD}) - 1.8V option	V	1.620	1.8	1.980	
Supply Voltage (V _{DD}) - 2.5V option	V	2.375	2.5	2.625	
Supply Voltage (V _{DD}) - 3.3V option	V	3.135	3.3	3.465	
Supply Voltage (V _{DD}) - 5.0V option	V	4.750	5.0	5.250	
Current (I _{DD}) - 1.8V option	mA			10	
Current (I _{DD}) - 2.5V option	mA			20	
Current (I _{DD}) - 3.3V option	mA			30	
Current (I _{DD}) - 5.0V option	mA			40	
Output Load (CMOS)	pF			15	
Output Load (TTL)	TTL			10	
Output Logic Levels High (V _{OH}) - CMOS	V	0.9*V _{DD}			
Output Logic Levels Low (V _{OL}) - CMOS	V			0.1*V _{DD}	
Output Logic Levels High (V _{OH}) - TTL	V	2.4			
Output Logic Levels Low (V _{OL}) - TTL	V			0.4	
Rise (TR) and Fall (TF) Time	ns			5	
Symmetry (Duty Cycle)	%	45	50	55	
Tri-State Input Voltage - Enable	V	0.7*V _{DD}			
Tri-State Input Voltage - Disable	V			0.3*V _{DD}	
Start-Up Time	ms			10	
Phase Jitter (12kHz ~ 20MHz)	ps			1	

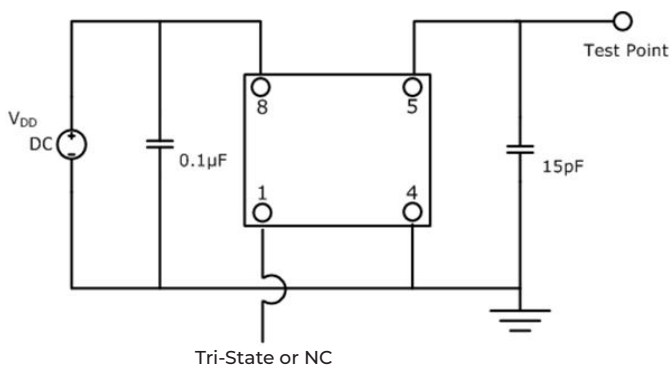
Outline Drawing & Part Marking

All dimensions are in millimeters (mm) unless otherwise noted. Drawings are not to scale.

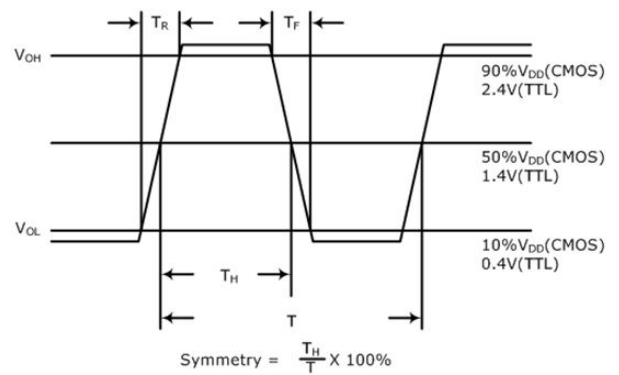


PIN	FUNCTION
1	TRI-STATE or NC
4	GND
5	OUTPUT
8	V _{DD}

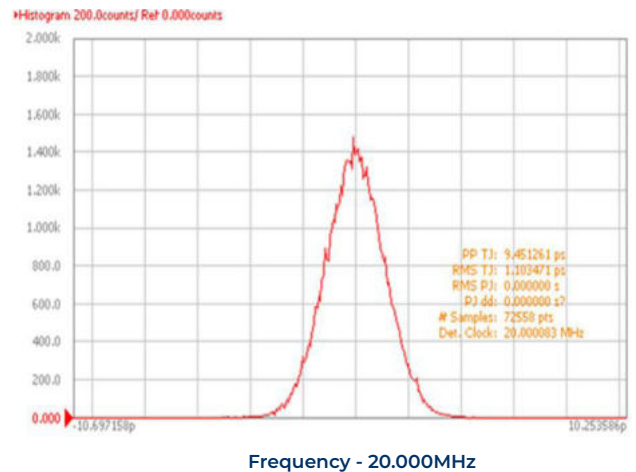
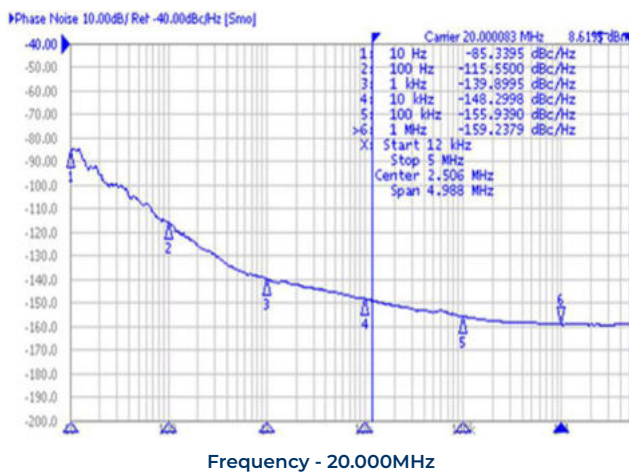
Test Circuit (CMOS /TTL COMPATIBLE)



Waveform (CMOS /TTL COMPATIBLE)



Typical Phase Noise & Jitter Performance (Measured By Agilent E5052A)



Environmental Specifications		Mechanical Specifications	
Temperature Cycling	MIL-STD-883, Method 1010, Condition B	Mechanical Shock	MIL-STD-202, Method 213, Condition B
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	Vibration	MIL-STD-883, Method 2007, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	Moisture Resistance	MIL-STD-883, Method 1004
Solderability	MIL-STD-883, Method 2003	Resistance to Solvents	MIL-STD-202, Method 215
Moisture Sensitivity	J-STD-020, MSL 1	Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K